



121-Ball NAND Flash with LPDDR2 MCP Features

NAND Flash with Mobile LPDDR2 121-Ball MCP

MT29RZ1B1CZZHGTN-25W.4M8, MT29RZ1C1CZZHGTN-25W.4M8

Features

- Micron® NAND Flash and LPDDR2 components
- RoHS-compliant, “green” package
- Separate NAND Flash and LPDDR2 interfaces
- Space-saving multichip package
- Low-voltage operation (1.70–1.95V)
- Wireless temperature range: –30°C to +85°C

NAND Flash-Specific Features

Organization

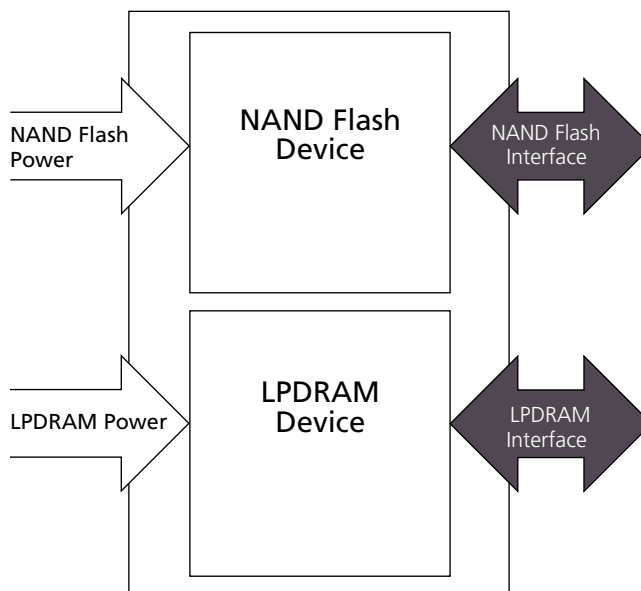
- Page size
 - x8: 2112 bytes (2048 + 64 bytes)
 - x16: 1056 words (1024 + 32 words)
- Block size: 64 pages (128K + 4K bytes)

Mobile LPDDR2-Specific Features

- Ultra-low-voltage 1.2V core power supply
- 1.2V HSUL-compatible inputs
- Programmable read and write latencies
- Programmable burst lengths: 4, 8, or 16
- Partial-array self refresh (PASR)
- Deep power-down (DPD) mode
- Selectable output drive strength
- Adjustable clock frequency and clock stop capabilities

Note: 1. For physical part markings, see the Part Number Chart.

Figure 1: MCP Block Diagram



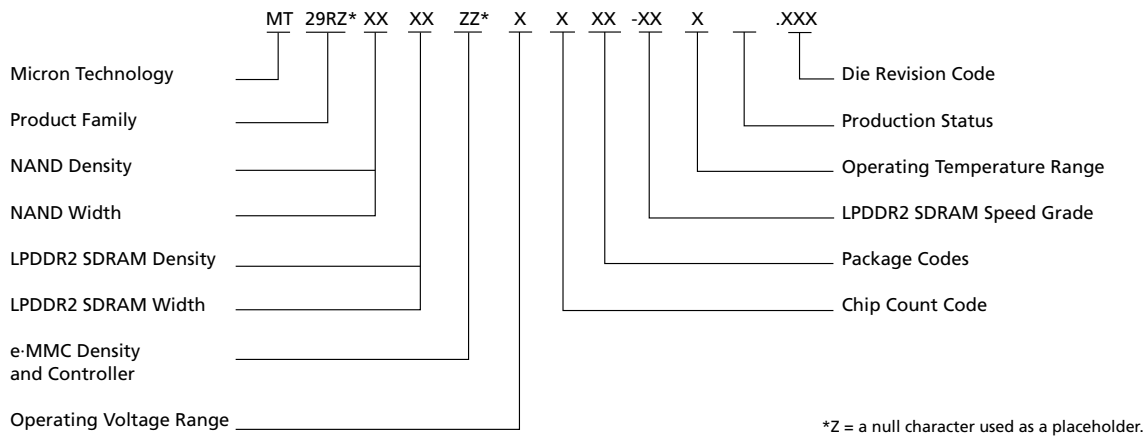


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Part Numbering Information

Micron NAND Flash and LPDRAM devices are available in different configurations and densities. The MCP/PoP part numbering guide is available at www.micron.com/numbering.

Figure 2: Part Number Chart



Device Marking

Due to the size of the package, the Micron-standard part number is not printed on the top of the device. Instead, an abbreviated device mark consisting of a 5-digit alphanumeric code is used. The abbreviated device marks are cross-referenced to the Micron part numbers at the FBGA Part Marking Decoder site: www.micron.com/decoder. To view the location of the abbreviated mark on the device, refer to customer service note CSN-11, "Product Mark/Label," at www.micron.com/csn.



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121-Ball NAND Flash with LPDDR2 MCP MCP General Description

MCP General Description

Micron MCP products combine NAND Flash and Mobile LPDRAM devices in a single MCP. These products target mobile applications with low-power, high-performance, and minimal package-footprint design requirements. The NAND Flash and Mobile LPDRAM devices are also members of the Micron discrete memory products portfolio.

The NAND Flash and Mobile LPDRAM devices are packaged with separate interfaces (no shared address, control, data, or power balls). This bus architecture supports an optimized interface to processors with separate NAND Flash and Mobile LPDRAM buses. The NAND Flash and Mobile LPDRAM devices have separate core power connections and share a common ground (that is, V_{SS} is tied together on the two devices).

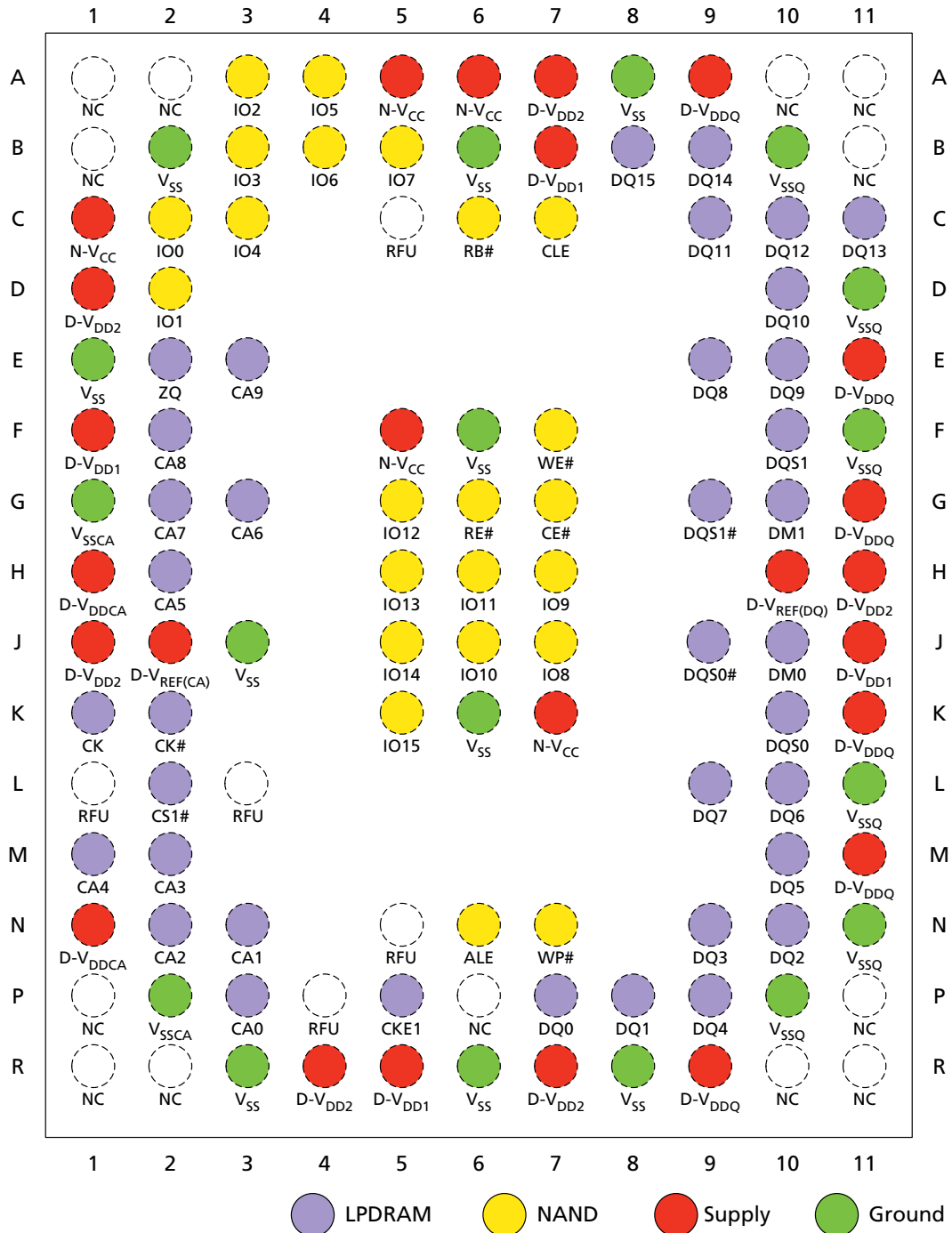
The bus architecture of this device also supports separate NAND Flash and Mobile LPDRAM functionality without concern for device interaction.



121-Ball NAND Flash with LPDDR2 MCP Ball Assignments and Descriptions

Ball Assignments and Descriptions

Figure 3: 121-Ball VFBGA (NAND x8/x16, LPDDR x16) Ball Assignments



Note: 1. IO8-IO15 pins are NC for the x8 NAND device.



121-Ball NAND Flash with LPDDR2 MCP Ball Assignments and Descriptions

Table 1: x8/x16 NAND Ball Descriptions

Symbol	Type	Description
ALE	Input	Address latch enable: When ALE is HIGH, addresses can be transferred to the on-chip address register.
CE#	Input	Chip enable: Gates transfers between the host system and the NAND device.
CLE	Input	Command latch enable: When CLE is HIGH, commands can be transferred to the on-chip command register.
RE#	Input	Read enable: Gates information from the NAND device to the host system.
WE#	Input	Write enable: Gates information from the host system to the NAND device.
WP#	Input	Write protect: Driving WP# LOW blocks ERASE and PROGRAM operations.
I/O[15:0]	Input/output	Data inputs/outputs: The bidirectional I/Os transfer address, data, and instruction information. Data is output only during READ operations; at other times the I/Os are inputs. IO8-IO16 pins are NC for the x8 NAND device.
R/B#	Output	Ready/busy: Open-drain, active-LOW output that indicates when an internal operation is in progress.
V _{CC}	Supply	V _{CC} : NAND power supply.



121-Ball NAND Flash with LPDDR2 MCP Ball Assignments and Descriptions

Table 2: x16 LPDDR2 Ball Descriptions

Symbol	Type	Description
CA[9:0]	Input	Command/address inputs: Provide the command and address inputs according to the command truth table.
CK, CK#	Input	Clock: CK and CK# are differential clock inputs. All CA inputs are sampled on both the positive and negative edge of CK. CS and CKE inputs are sampled at the positive edge of CK. AC timings are referenced to clock.
CKE1	Input	Clock enable.
CS1#	Input	Chip select.
DM[1:0]	Input	Data mask: DM is an input mask signal for write data. Although DM balls are input-only, the DM loading is designed to match that of DQ and DQS balls. DM[1:0] is DM for each of the two data bytes, respectively.
DQ[15:0]	Input/output	Data bus: Data inputs/outputs.
DQS[1:0] DQS#[1:0]	Input/output	Data strobe: Coordinates READ/WRITE transfers of data; one DQS/DQS# pair per DQ byte.
V _{DD1}	Supply	V _{DD1} : LPDDR2 power supply 1.
V _{DD2}	Supply	V _{DD2} : LPDDR2 power supply 2.
V _{DDCA}	Supply	V _{DDCA} : LPDDR2 CA power supply.
V _{DDQ}	Supply	V _{DDQ} : LPDDR2 I/O power supply.
V _{REFCA}	Supply	V _{REFCA} : LPDDR2 reference for CA pins.
V _{REFDQ}	Supply	V _{REFDQ} : LPDDR2 reference for DQ pins.
V _{SSCA}	Supply	V _{SSCA} : LPDDR2 I/O ground.
V _{SSQ}	Supply	V _{SSQ} : LPDDR2 I/O ground.
ZQ	Input	External impedance (240-Ohm): This signal is used to calibrate the device output impedance.



121-Ball NAND Flash with LPDDR2 MCP Ball Assignments and Descriptions

Table 3: Non-Device-Specific Descriptions

Symbol	Type	Description
V _{SS}	Supply	V _{SS} : Shared ground.
Symbol	Type	Description
DNU	–	Do not use: Must be grounded or left floating.
NC	–	No connect: Not internally connected.
RFU ¹	–	Reserved for future use.

Note: 1. Balls marked RFU may or may not be connected internally. These balls should not be used. Contact factory for details.



121-Ball NAND Flash with LPDDR2 MCP Electrical Specifications

Electrical Specifications

Table 4: Absolute Maximum Ratings

Parameters/Conditions	Symbol	Min	Max	Unit
V_{CC} and V_{DD1} supply voltage relative to V_{SS}	V_{CC}, V_{DD1}	-0.4	2.3	V
V_{DD2} supply voltage relative to V_{SS}	V_{DD2}	-0.4	1.8	V
V_{DDCA} and V_{DDQ} supply voltage relative to V_{SS}	V_{DDCA}, V_{DDQ}	-0.4	1.6	V
Voltage on any pin relative to V_{SS}	V_{IN}	-0.4	1.6 or ($V_{DDQ} + 0.3$), whichever is less	V
Storage temperature range	—	-55	+125	°C

Stresses greater than those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Table 5: Recommended Operating Conditions

Parameters	Symbol	Min	Typ	Max	Unit
Supply voltage	V_{CC}	1.70	1.80	1.95	V
Supply voltage	V_{DD1}	1.70	1.80	1.95	V
Supply voltage	V_{DD2}	1.14	1.20	1.30	V
I/O supply voltage	V_{DDCA}/V_{DDQ}	1.14	1.20	1.30	V
Operating temperature range	—	-30	—	+85	°C



121-Ball NAND Flash with LPDDR2 MCP Device Diagrams

Device Diagrams

Figure 4: 121-Ball (Single LPDDR2) Functional Block Diagram

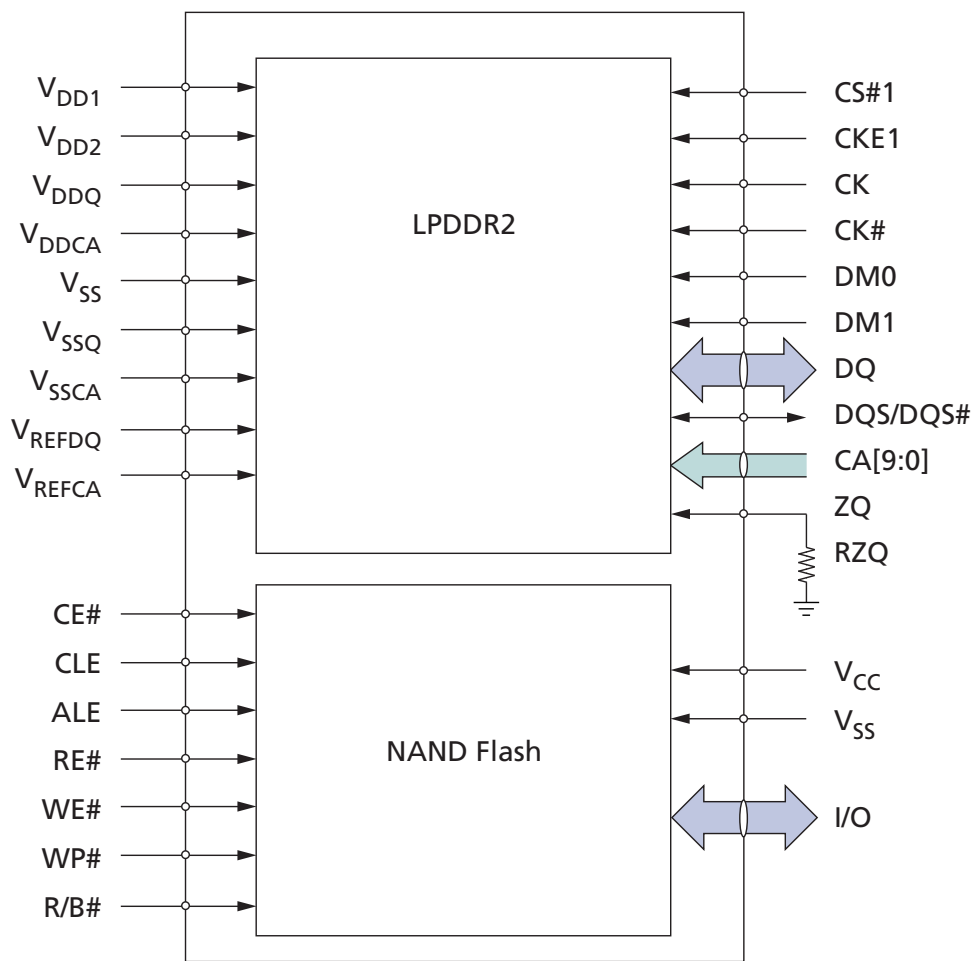


Table 6: Chip-Select Signal Assignments per Chip-Count Configuration

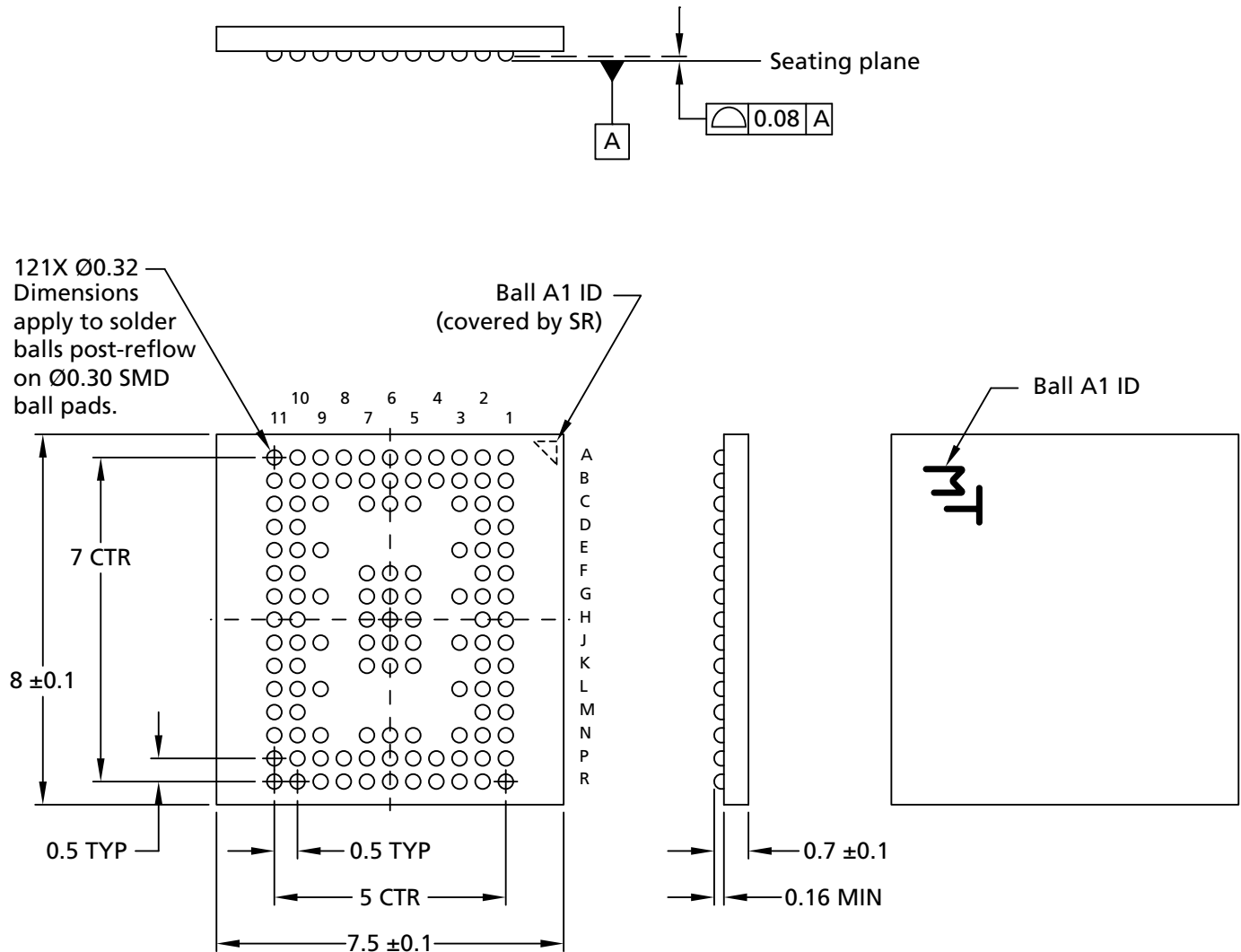
Chip Count	LPDDR2
1 NAND, 1 LPDRAM	CS1#, CKE1



121-Ball NAND Flash with LPDDR2 MCP Package Dimensions

Package Dimensions

Figure 5: 121-Ball VFBGA (Package Code: TN)



- Notes: 1. All dimensions are in millimeters.
2. ball material: LF35 (98.25% Sn, 1.2% Ag, 0.5% Cu, 0.05% Ni).



121-Ball NAND Flash with LPDDR2 MCP

1Gb: x8, x16 NAND Flash Memory

1Gb: x8, x16 NAND Flash Memory

Features

- Open NAND Flash Interface (ONFI) 1.0-compliant¹
- Single-level cell (SLC) technology
- Organization
 - Page size x8: 2112 bytes (2048 + 64 bytes)
 - Page size x16: 1056 words (1024 + 32 words)
 - Block size: 64 pages (128K + 4K bytes)
 - Device size: 1Gb: 1024 blocks
- Asynchronous I/O performance
 - ^tRC/^tWC: 20ns (TYP, 3.3V), 25ns (1.8V)
- Array performance
 - Read page: 25μs
 - Program page: 200μs (TYP, 3.3V and 1.8V)
 - Erase block: 700μs (TYP)
- Command set: ONFI NAND Flash Protocol
- Advanced command set
 - Program page cache mode
 - Read page cache mode
 - One-time programmable (OTP) mode
 - Read unique ID
 - Internal data move
 - Block lock (1.8V only)
- Operation status byte provides software method for detecting
 - Operation completion
 - Pass/fail condition
 - Write-protect status
- Internal data move operations supported within the device from which data is read
- Ready/busy# (R/B#) signal provides a hardware method for detecting operation completion
- WP# signal: write protect entire device
- First block (block address 00h) is valid when shipped from factory with ECC; for minimum required ECC, see Error Management.
- Block 0 requires 1-bit ECC if PROGRAM/ERASE cycles are less than 1000
- RESET (FFh) required as first command after power-on
- Alternate method of device initialization (Nand_Init) after power-up² (contact factory)
- Quality and reliability
 - Data retention: 10 years
 - Endurance: 100,000 PROGRAM/ERASE cycles
- Operating Voltage Range
 - V_{CC}: 2.7–3.6V
 - V_{CC}: 1.7–1.95V
- Operating temperature
 - Commercial: 0°C to +70°C
 - Industrial (IT): –40°C to +85°C

- Notes:
1. The ONFI 1.0 specification is available at www.onfi.org.
 2. Available only in the 1.8V VFBGA package.



121-Ball NAND Flash with LPDDR2 MCP General Description

General Description

Micron NAND Flash devices include an asynchronous data interface for high-performance I/O operations. These devices use a highly multiplexed 8-bit bus (I/Ox) to transfer commands, address, and data. There are five control signals used to implement the asynchronous data interface: CE#, CLE, ALE, WE#, and RE#. Additional signals control hardware write protection and monitor device status (R/B#).

This hardware interface creates a low pin-count device with a standard pinout that remains the same from one density to another, enabling future upgrades to higher densities with no board redesign.

A target is the unit of memory accessed by a chip enable signal. A target contains one or more NAND Flash die. A NAND Flash die is the minimum unit that can independently execute commands and report status. A NAND Flash die, in the ONFI specification, is referred to as a logical unit (LUN). There is at least one NAND Flash die per chip enable signal. For further details, see Device and Array Organization.



121-Ball NAND Flash with LPDDR2 MCP Architecture

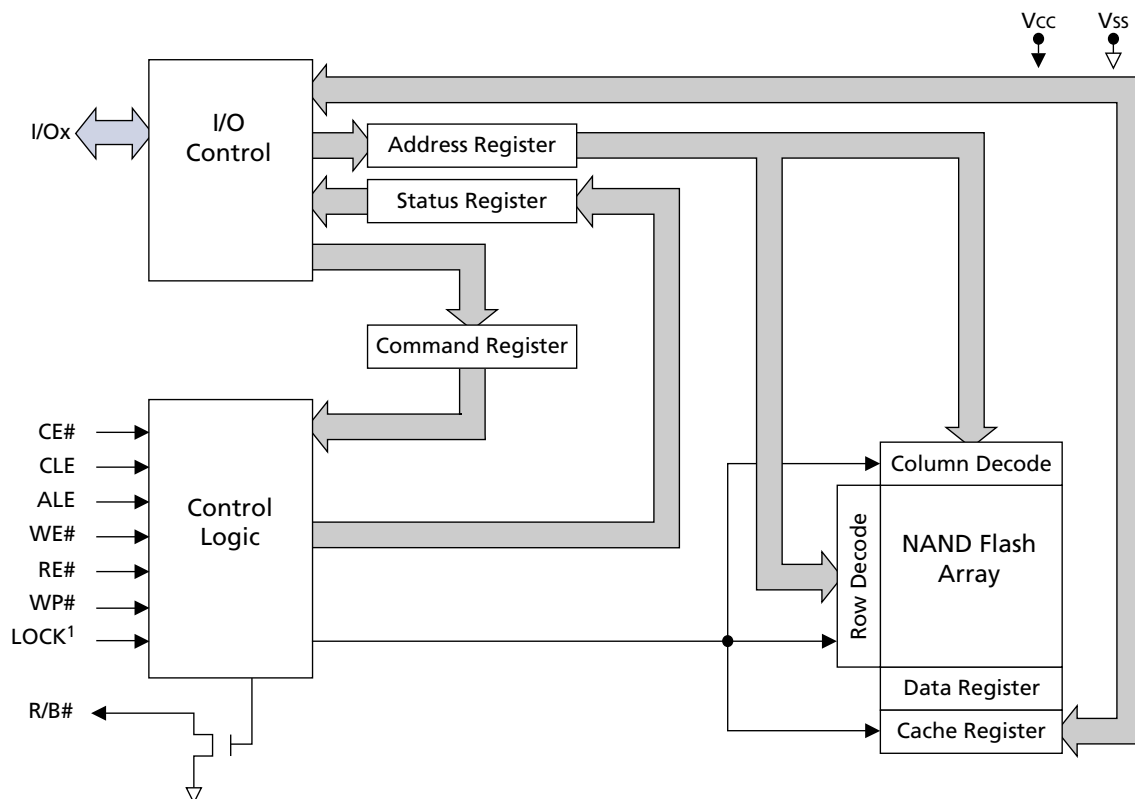
Architecture

These devices use NAND Flash electrical and command interfaces. Data, commands, and addresses are multiplexed onto the same pins and received by I/O control circuits. The commands received at the I/O control circuits are latched by a command register and are transferred to control logic circuits for generating internal signals to control device operations. The addresses are latched by an address register and sent to a row decoder to select a row address, or to a column decoder to select a column address.

Data is transferred to or from the NAND Flash memory array, byte by byte (x8) or word by word (x16), through a data register and a cache register.

The NAND Flash memory array is programmed and read using page-based operations and is erased using block-based operations. During normal page operations, the data and cache registers act as a single register. During cache operations, the data and cache registers operate independently to increase data throughput. The status register reports the status of die operations.

Figure 6: NAND Flash Die (LUN) Functional Block Diagram



Note: 1. The LOCK pin is used on the 1.8V device.



121-Ball NAND Flash with LPDDR2 MCP Device and Array Organization

Device and Array Organization

Figure 7: Array Organization – x8

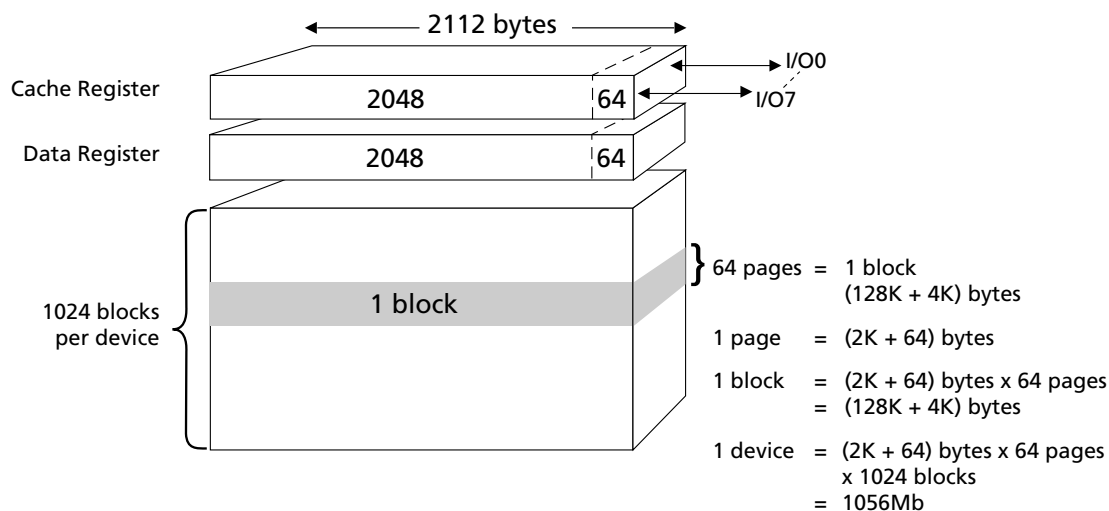


Table 7: Array Addressing (x8)

Cycle	I/O7	I/O6	I/O5	I/O4	I/OQ3	I/O2	I/O1	I/O0
First	CA7	CA6	CA5	CA4	CA3	CA2	CA1	CA0
Second	LOW	LOW	LOW	LOW	CA11 ¹	CA10	CA9	CA8
Third	BA7	BA6	PA5	PA4	PA3	PA2	PA1	PA0
Fourth	BA15	BA14	BA13	BA12	BA11	BA10	BA9	BA8

- Notes:
1. If CA11 is 1, then CA[10:6] must be 0.
 2. Block address concatenated with page address = actual page address; CAx = column address; PAx = page address; BAx = block address.



121-Ball NAND Flash with LPDDR2 MCP Device and Array Organization

Figure 8: Array Organization – x16

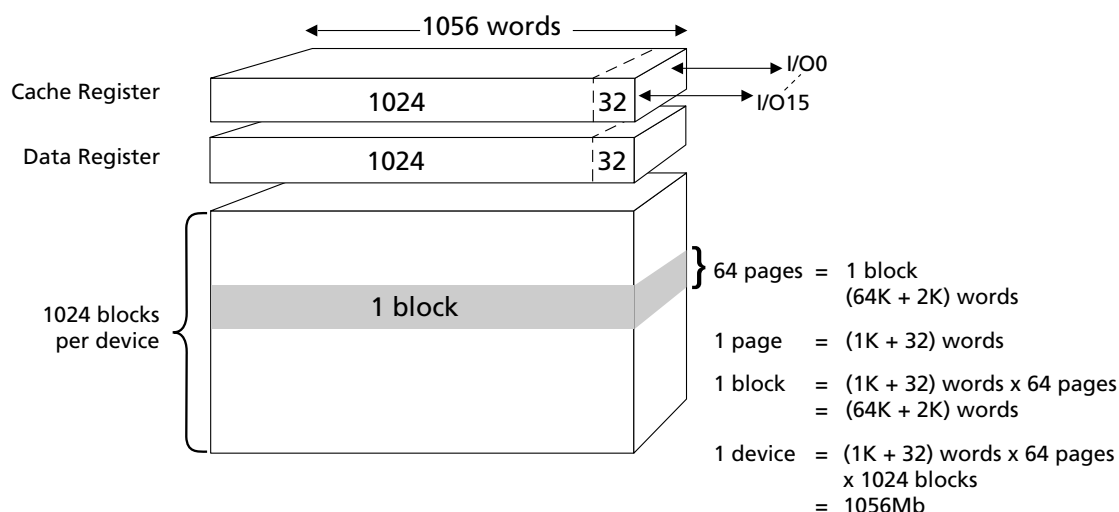


Table 8: Array Addressing (x16)

Cycle	I/O[15:8]	I/O7	I/O6	I/O5	I/O4	I/O3	I/O2	I/O1	I/O0
First	LOW	CA7	CA6	CA5	CA4	CA3	CA2	CA1	CA0
Second	LOW	LOW	LOW	LOW	LOW	LOW	CA10 ¹	CA9	CA8
Third	LOW	BA7	BA6	PA5	PA4	PA3	PA2	PA1	PA0
Fourth	LOW	BA15	BA14	BA13	BA12	BA11	BA10	BA9	BA8

- Notes:
1. If CA10 is 1, then CA[9:5] must be 0.
 2. Block address concatenated with page address = actual page address. CAx = column address; PAx = page address; BAx = block address.
 3. I/O[15:8] are not used during the addressing sequence and should be driven LOW.







121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

Asynchronous Interface Bus Operation

The bus on the device is multiplexed. Data I/O, addresses, and commands all share the same pins. I/O[15:8] are used only for data in the x16 configuration. Addresses and commands are always supplied on I/O[7:0].

The command sequence typically consists of a COMMAND LATCH cycle, address input cycles, and one or more data cycles, either READ or WRITE.

Table 9: Asynchronous Interface Mode Selection

Mode ¹	CE#	CLE	ALE	WE#	RE#	I/Ox	WP#
Standby ²	H	X	X	X	X	X	0V/V _{CC}
Command input	L	H	L		H	X	H
Address input	L	L	H		H	X	H
Data input	L	L	L		H	X	H
Data output	L	L	L	H		X	X
Write protect	X	X	X	X	X	X	L

Notes: 1. Mode selection settings for this table: H = Logic level HIGH; L = Logic level LOW; X = V_{IH} or V_{IL}.

2. WP# should be biased to CMOS LOW or HIGH for standby.

Asynchronous Enable/Standby

When the device is not performing an operation, the CE# pin is typically driven HIGH and the device enters standby mode. The memory will enter standby if CE# goes HIGH while data is being transferred and the device is not busy. This helps reduce power consumption.

The CE# “Don’t Care” operation enables the NAND Flash to reside on the same asynchronous memory bus as other Flash or SRAM devices. Other devices on the memory bus can then be accessed while the NAND Flash is busy with internal operations. This capability is important for designs that require multiple NAND Flash devices on the same bus.

A HIGH CLE signal indicates that a command cycle is taking place. A HIGH ALE signal signifies that an ADDRESS INPUT cycle is occurring.

Asynchronous Commands

An asynchronous command is written from I/O[7:0] to the command register on the rising edge of WE# when CE# is LOW, ALE is LOW, CLE is HIGH, and RE# is HIGH.

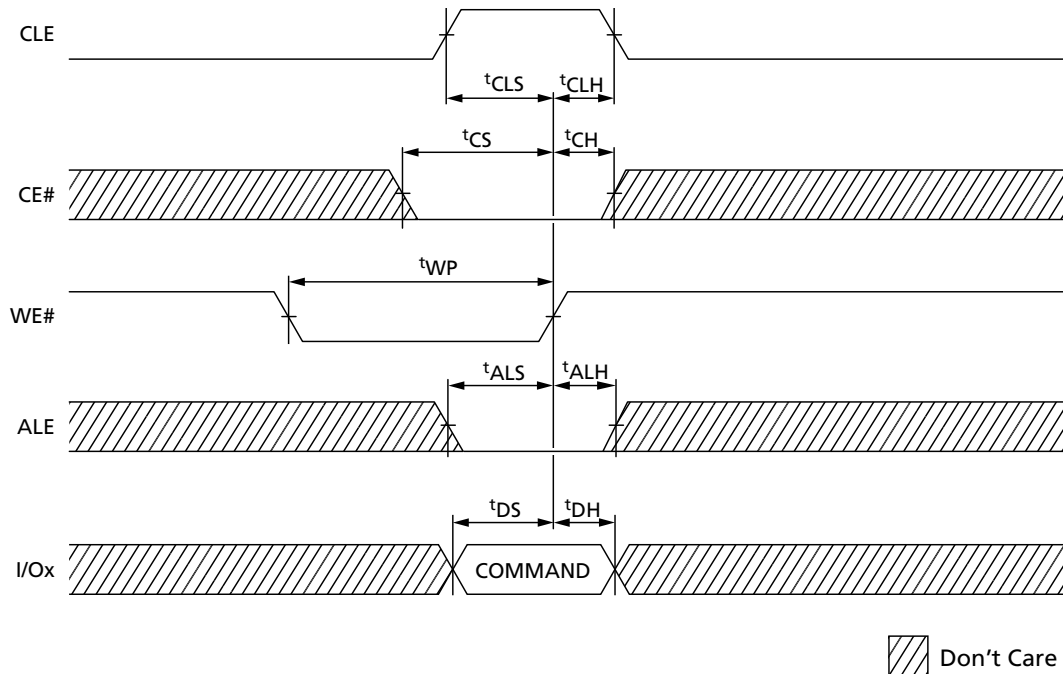
Commands are typically ignored by die (LUNs) that are busy (RDY = 0); however, some commands, including READ STATUS (70h), are accepted by die (LUNs) even when they are busy.

For devices with a x16 interface, I/O[15:8] must be written with zeros when a command is issued.



121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

Figure 9: Asynchronous Command Latch Cycle





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

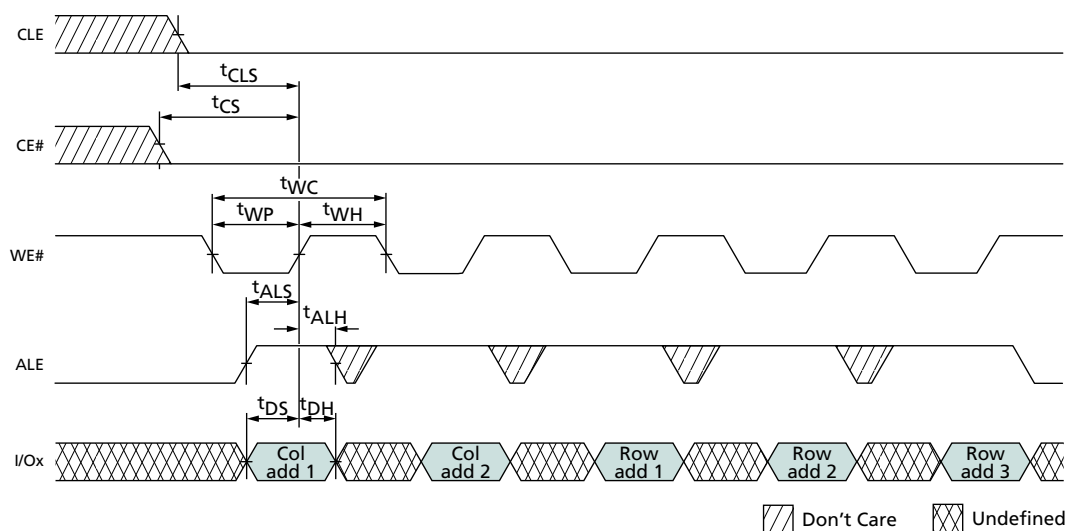
Asynchronous Addresses

An asynchronous address is written from I/O[7:0] to the address register on the rising edge of WE# when CE# is LOW, ALE is HIGH, CLE is LOW, and RE# is HIGH.

Bits that are not part of the address space must be LOW (see Device and Array Organization). The number of cycles required for each command varies. Refer to the command descriptions to determine addressing requirements.

Addresses are input on I/O[7:0] on x8 devices and on I/O[15:0] on x16 devices.

Figure 10: Asynchronous Address Latch Cycle





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

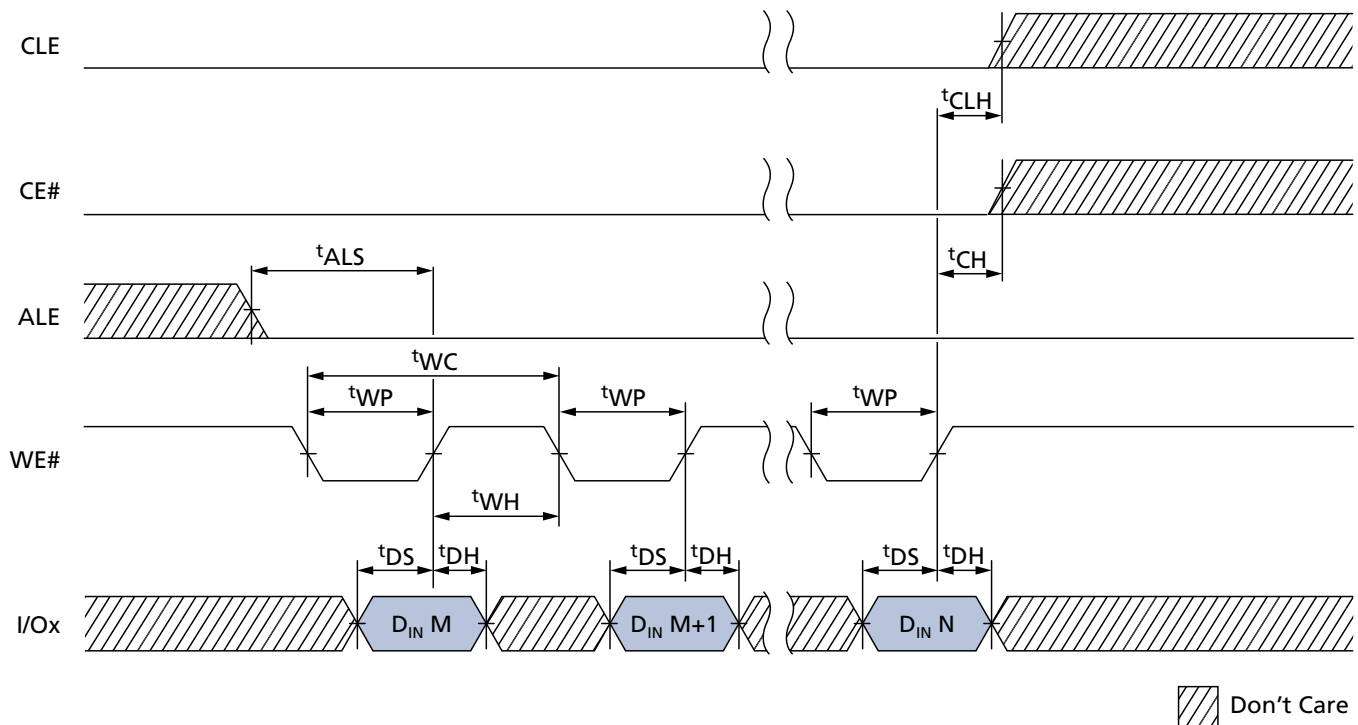
Asynchronous Data Input

Data is written to the cache register of the selected die (LUN) on the rising edge of WE# when CE# is LOW, ALE is LOW, CLE is LOW, and RE# is HIGH.

Data input is ignored by die (LUNs) that are not selected or are busy (RDY = 0). Data is written to the data register on the rising edge of WE# when CE#, CLE, and ALE are LOW, and the device is not busy.

Data is input on I/O[7:0] on x8 devices and on I/O[15:0] on x16 devices.

Figure 11: Asynchronous Data Input Cycles





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

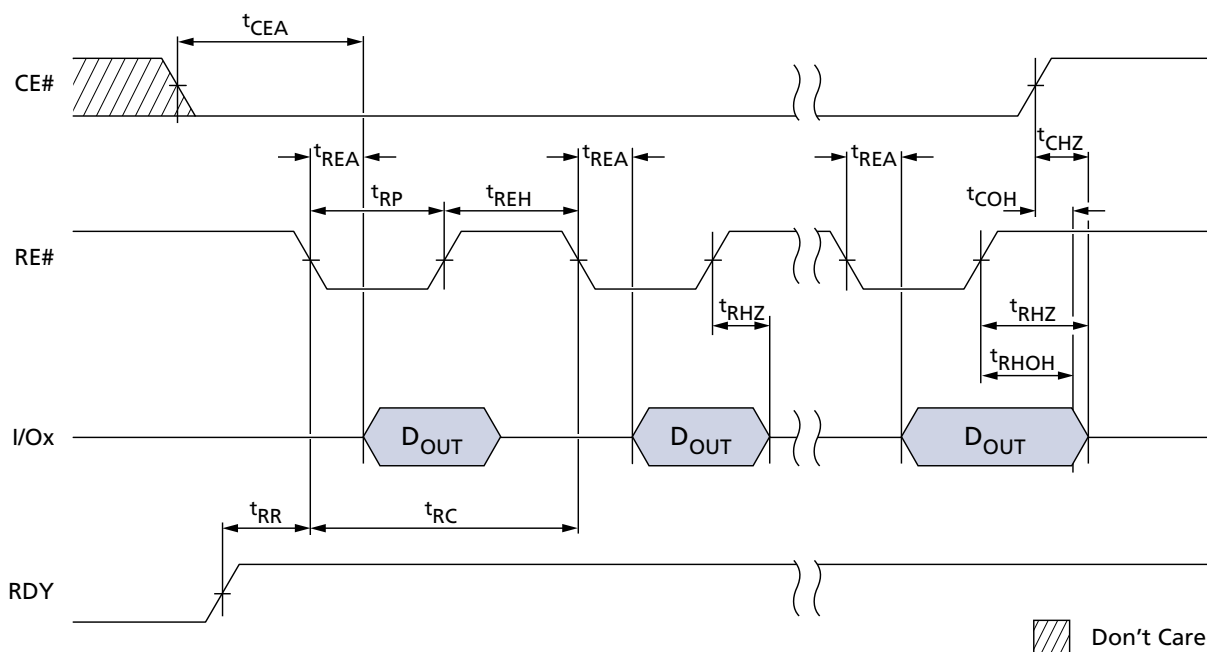
Asynchronous Data Output

Data can be output from a die (LUN) if it is in a READY state. Data output is supported following a READ operation from the NAND Flash array. Data is output from the cache register of the selected die (LUN) on the falling edge of RE# when CE# is LOW, ALE is LOW, CLE is LOW, and WE# is HIGH.

If the host controller is using a t_{RC} of 30ns or greater, the host can latch the data on the rising edge of RE# (see the figure below for proper timing). If the host controller is using a t_{RC} of less than 30ns, the host can latch the data on the next falling edge of RE#.

Data is output on I/O[7:0] on x8 devices and on I/O[15:0] on x16 devices.

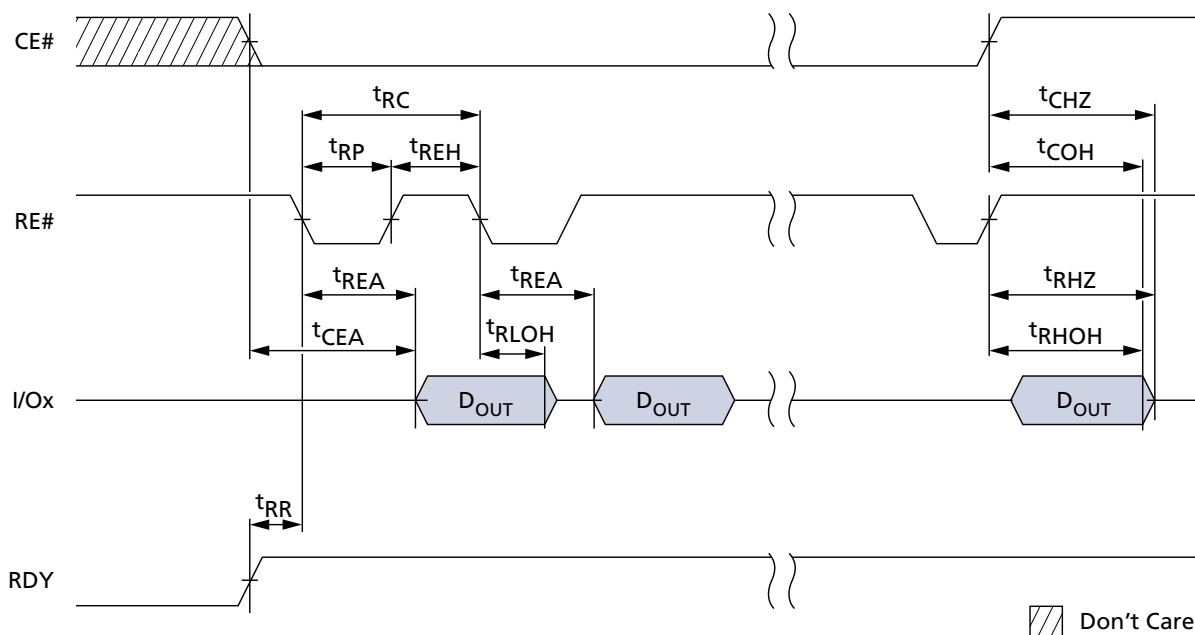
Figure 12: Asynchronous Data Output Cycles





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

Figure 13: Asynchronous Data Output Cycles (EDO Mode)



Write Protect#

The write protect# (WP#) signal enables or disables PROGRAM and ERASE operations to a target. When WP# is LOW, PROGRAM and ERASE operations are disabled. When WP# is HIGH, PROGRAM and ERASE operations are enabled.

It is recommended that the host drive WP# LOW during power-on until V_{CC} is stable to prevent inadvertent PROGRAM and ERASE operations (see Device Initialization for additional details).

WP# must be transitioned only when the target is not busy and prior to beginning a command sequence. After a command sequence is complete and the target is ready, WP# can be transitioned. After WP# is transitioned, the host must wait t_{WW} before issuing a new command.

The WP# signal is always an active input, even when CE# is HIGH. This signal should not be multiplexed with other signals.

Ready/Busy#

The ready/busy# (R/B#) signal provides a hardware method of indicating whether a target is ready or busy. A target is busy when one or more of its die (LUNs) are busy ($RDY = 0$). A target is ready when all of its die (LUNs) are ready ($RDY = 1$). Because each die (LUN) contains a status register, it is possible to determine the independent status of each die (LUN) by polling its status register instead of using the R/B# signal (see Status Operations for details regarding die (LUN) status).

This signal requires a pull-up resistor, R_p , for proper operation. R/B# is HIGH when the target is ready, and transitions LOW when the target is busy. The signal's open-drain



121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

driver enables multiple R/B# outputs to be OR-tied. Typically, R/B# is connected to an interrupt pin on the system controller.

The combination of R_p and capacitive loading of the R/B# circuit determines the rise time of the R/B# signal. The actual value used for R_p depends on the system timing requirements. Large values of R_p cause R/B# to be delayed significantly. Between the 10% and 90% points on the R/B# waveform, the rise time is approximately two time constants (TC).

$$T_C = R \times C$$

Where $R = R_p$ (resistance of pull-up resistor), and $C =$ total capacitive load.

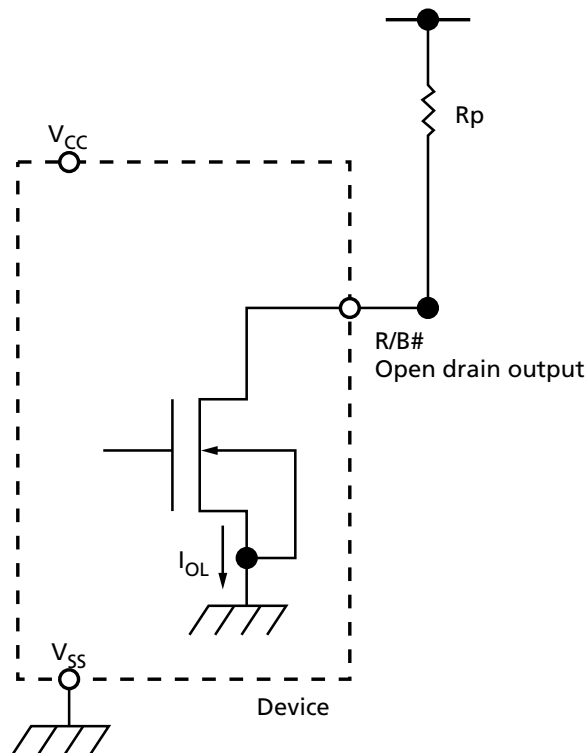
The fall time of the R/B# signal is determined mainly by the output impedance of the R/B# signal and the total load capacitance. Approximate R_p values using a circuit load of 100pF are provided in Figure 19 (page 34).

The minimum value for R_p is determined by the output drive capability of the R/B# signal, the output voltage swing, and V_{CC} .

$$R_p = \frac{V_{CC} (\text{MAX}) - V_{OL} (\text{MAX})}{I_{OL} + \Sigma I_{IL}}$$

Where ΣI_{IL} is the sum of the input currents of all devices tied to the R/B# pin.

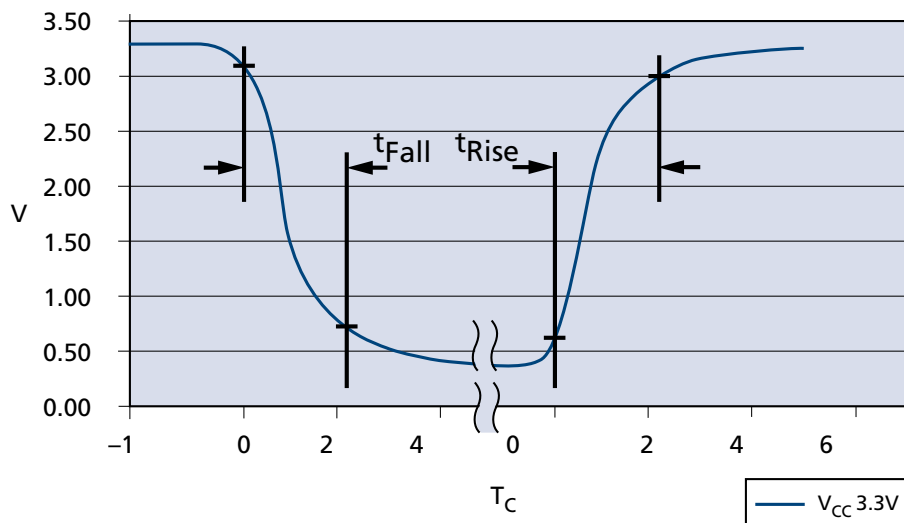
Figure 14: READ/BUSY# Open Drain





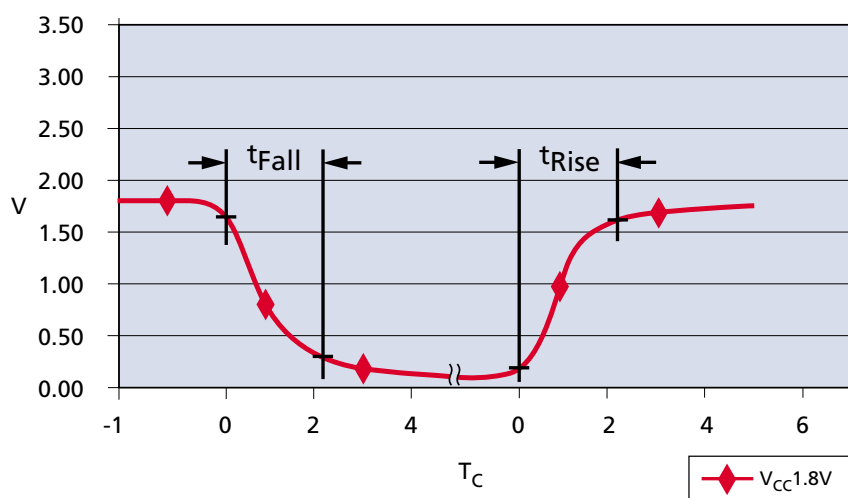
121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

Figure 15: t_{Fall} and t_{Rise} (3.3V V_{CC})



- Notes:
1. t_{Fall} and t_{Rise} calculated at 10% and 90% points.
 2. t_{Rise} dependent on external capacitance and resistive loading and output transistor impedance.
 3. t_{Rise} primarily dependent on external pull-up resistor and external capacitive loading.
 4. $t_{\text{Fall}} = 10\text{ns}$ at 3.3V.
 5. See TC values in Figure 19 (page 34) for approximate R_p value and TC.

Figure 16: t_{Fall} and t_{Rise} (1.8V V_{CC})



- Notes:
1. t_{Fall} and t_{Rise} are calculated at 10% and 90% points.
 2. t_{Rise} is primarily dependent on external pull-up resistor and external capacitive loading.
 3. $t_{\text{Fall}} \approx 7\text{ns}$ at 1.8V.
 4. See TC values in Figure 19 (page 34) for TC and approximate R_p value.



121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

Figure 17: I_{OL} vs. R_p ($V_{CC} = 3.3V$ V_{CC})

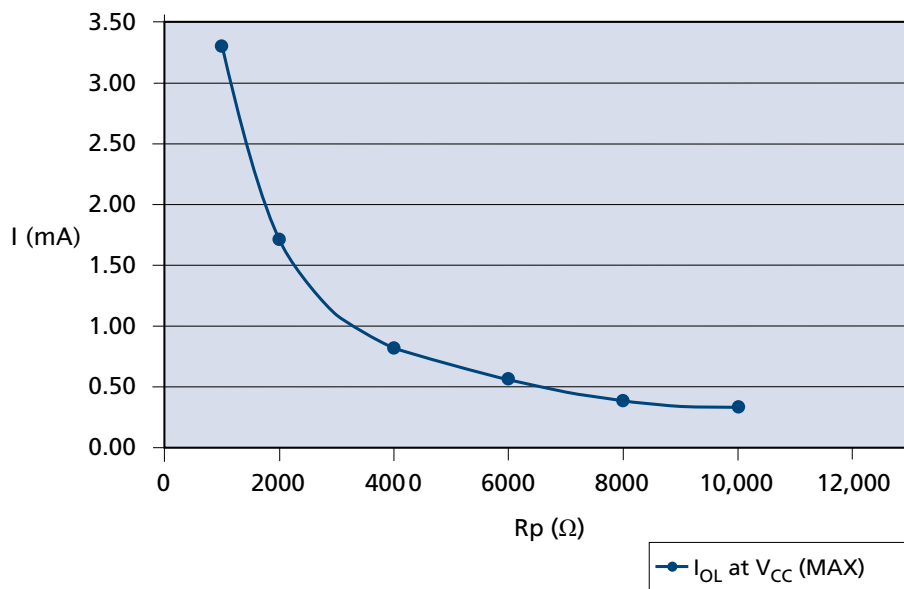
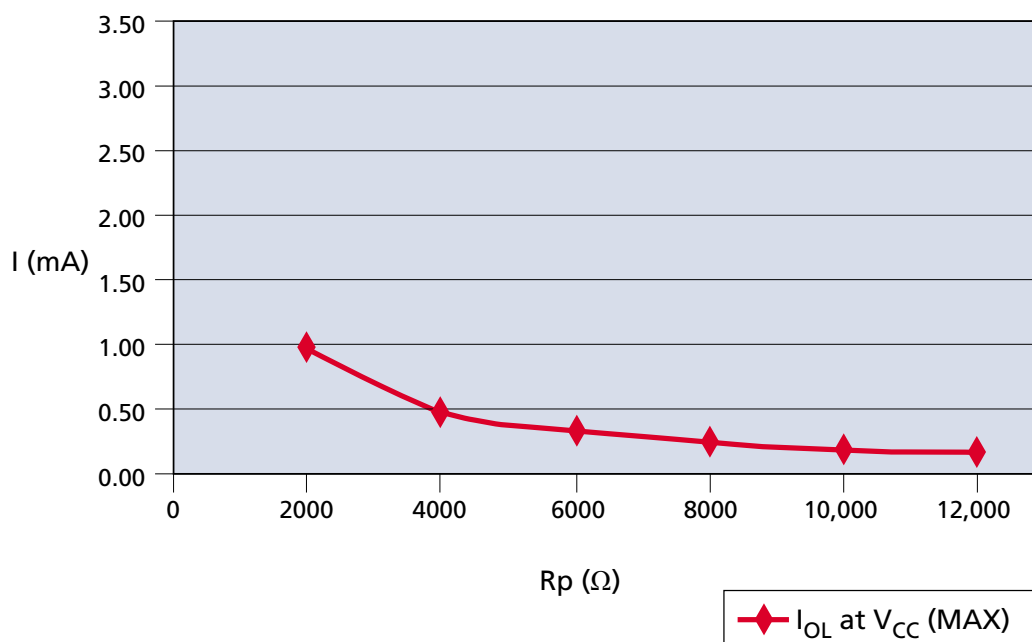


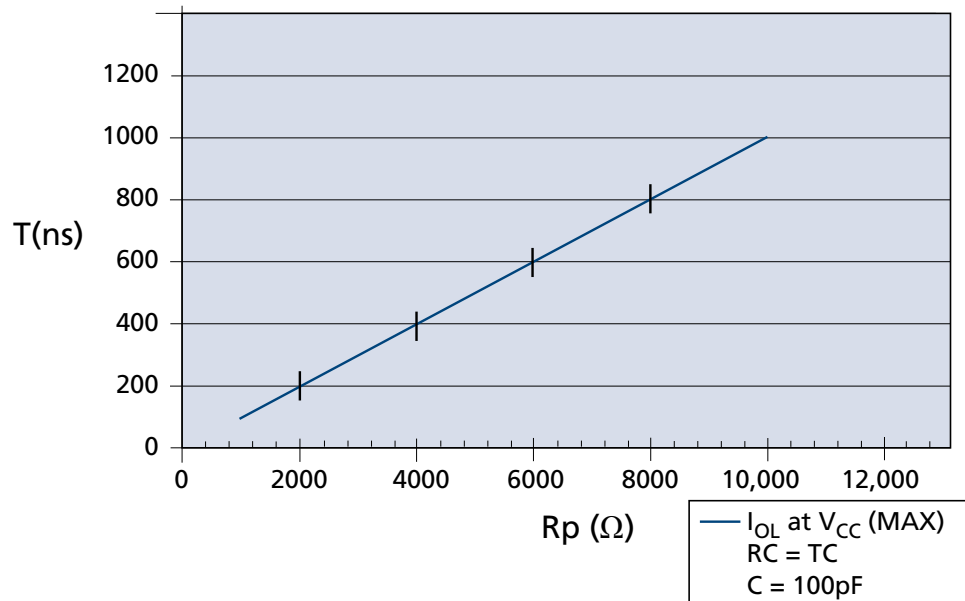
Figure 18: I_{OL} vs. R_p (1.8V V_{CC})





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Bus Operation

Figure 19: TC vs. Rp





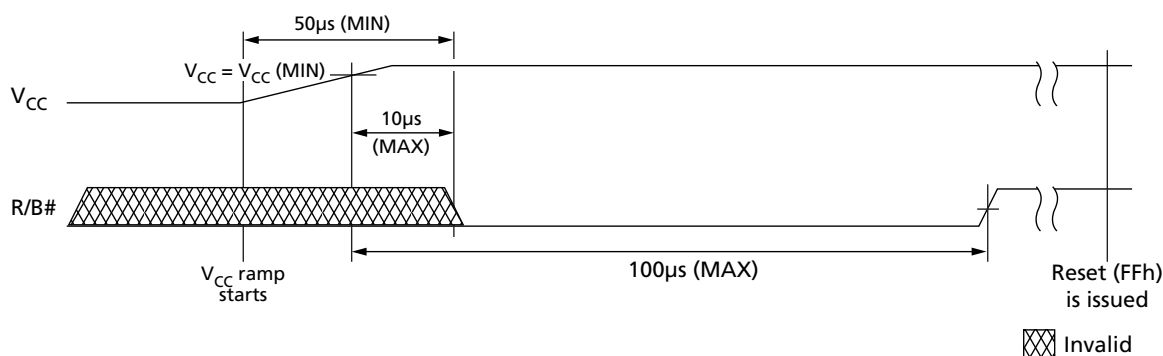
121-Ball NAND Flash with LPDDR2 MCP Device Initialization

Device Initialization

Micron NAND Flash devices are designed to prevent data corruption during power transitions. V_{CC} is internally monitored. (The $WP\#$ signal supports additional hardware protection during power transitions.) When ramping V_{CC} , use the following procedure to initialize the device:

1. Ramp V_{CC} .
2. The host must wait for $R/B\#$ to be valid and HIGH before issuing RESET (FFh) to any target. The $R/B\#$ signal becomes valid when $50\mu s$ has elapsed since the beginning the V_{CC} ramp, and $10\mu s$ has elapsed since V_{CC} reaches $V_{CC} (MIN)$.
3. If not monitoring $R/B\#$, the host must wait at least $100\mu s$ after V_{CC} reaches $V_{CC} (MIN)$. If monitoring $R/B\#$, the host must wait until $R/B\#$ is HIGH.
4. The asynchronous interface is active by default for each target. Each LUN draws less than an average of $10mA (I_{ST})$ measured over intervals of $1ms$ until the RESET (FFh) command is issued.
5. The RESET (FFh) command must be the first command issued to all targets ($CE\#s$) after the NAND Flash device is powered on. Each target will be busy for $1ms$ after a RESET command is issued. The RESET busy time can be monitored by polling $R/B\#$ or issuing the READ STATUS (70h) command to poll the status register.
6. The device is now initialized and ready for normal operation.

Figure 20: R/B# Power-On Behavior





121-Ball NAND Flash with LPDDR2 MCP Command Definitions

Command Definitions

Table 10: Command Set

Command	Command Cycle #1	Number of Valid Address Cycles	Data Input Cycles	Command Cycle #2	Valid While Selected LUN is Busy ¹	Notes
Reset Operations						
RESET	FFh	0	–	–	Yes	
Identification Operation						
READ ID	90h	1	–	–	No	
READ PARAMETER PAGE	ECh	1	–	–	No	
READ UNIQUE ID	EDh	1	–	–	No	
Feature Operations						
GET FEATURES	EEh	1	–	–	No	
SET FEATURES	EFh	1	4	–	No	
Status Operations						
READ STATUS	70h	0	–	–	Yes	
Column Address Operations						
RANDOM DATA READ	05h	2	–	E0h	No	
RANDOM DATA INPUT	85h	2	Optional	–	No	
PROGRAM FOR INTERNAL DATA MOVE	85h	4	Optional	–	No	2, 3
READ OPERATIONS						
READ MODE	00h	0	–	–	No	
READ PAGE	00h	4	–	30h	No	
READ PAGE CACHE SEQUENTIAL	31h	0	–	–	No	4
READ PAGE CACHE RANDOM	00h	4	–	31h	No	4
READ PAGE CACHE LAST	3Fh	0	–	–	No	4
Program Operations						
PROGRAM PAGE	80h	4	Yes	10h	No	
PROGRAM PAGE CACHE	80h	4	Yes	15h	No	5
Erase Operations						
ERASE BLOCK	60h	2	–	D0h	No	
Internal Data Move Operations						
READ FOR INTERNAL DATA MOVE	00h	4	–	35h	No	2
PROGRAM FOR INTERNAL DATA MOVE	85h		Optional	10h	No	3
Block Lock Operations						



121-Ball NAND Flash with LPDDR2 MCP Command Definitions

Table 10: Command Set (Continued)

Command	Command Cycle #1	Number of Valid Address Cycles	Data Input Cycles	Command Cycle #2	Valid While Selected LUN is Busy ¹	Notes
BLOCK UNLOCK LOW	23h	2	–	–	No	
BLOCK UNLOCK HIGH	24h	2	–	–	No	
BLOCK LOCK	2Ah	–	–	–	No	
BLOCK LOCK-TIGHT	2Ch	–	–	–	No	
BLOCK LOCK READ STATUS	7Ah	2	–	–	No	
One-Time Programmable (OTP) Operations						
OTP DATA LOCK BY PAGE (ONFI)	80h	4	No	10h	No	6
OTP DATA PROGRAM (ONFI)	80h	4	Yes	10h	No	6
OTP DATA READ (ONFI)	00h	4	No	30h	No	6

- Notes:
1. Busy means RDY = 0.
 2. Do not cross plane address boundaries when using READ FOR INTERNAL DATA MOVE and PROGRAM FOR INTERNAL DATA MOVE.
 3. PROGRAM FOR INTERNAL DATA MOVE operation is prohibited between even and odd blocks.
 4. Issuing a READ PAGE CACHE series (31h, 00h-31h, 3Fh) command when the array is busy (RDY = 1, ARDY = 0) is supported if the previous command was a READ PAGE (00h-30h) or READ PAGE CACHE series command; otherwise, it is prohibited.
 5. Issuing a PROGRAM PAGE CACHE (80h-15h) command when the array is busy (RDY = 1, ARDY = 0) is supported if the previous command was a PROGRAM PAGE CACHE (80h-15h) command; otherwise, it is prohibited.
 6. OTP commands can be entered only after issuing the SET FEATURES command with the feature address.



121-Ball NAND Flash with LPDDR2 MCP Reset Operations

Reset Operations

RESET (FFh)

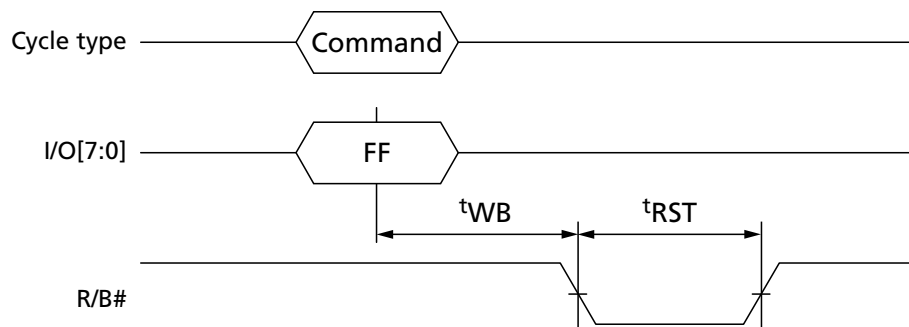
The RESET command is used to put the memory device into a known condition and to abort the command sequence in progress.

READ, PROGRAM, and ERASE commands can be aborted while the device is in the busy state. The contents of the memory location being programmed or the block being erased are no longer valid. The data may be partially erased or programmed, and is invalid. The command register is cleared and is ready for the next command. The data register and cache register contents are marked invalid.

The status register contains the value E0h when WP# is HIGH; otherwise it is written with a 60h value. R/B# goes LOW for t_{RST} after the RESET command is written to the command register.

The RESET command must be issued to all CE#s as the first command after power-on. The device will be busy for a maximum of 1ms.

Figure 21: RESET (FFh) Operation





121-Ball NAND Flash with LPDDR2 MCP Identification Operations

Identification Operations

READ ID (90h)

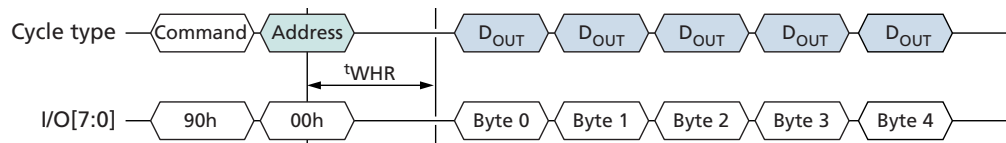
The READ ID (90h) command is used to read identifier codes programmed into the target. This command is accepted by the target only when all die (LUNs) on the target are idle.

Writing 90h to the command register puts the target in read ID mode. The target stays in this mode until another valid command is issued.

When the 90h command is followed by an 00h address cycle, the target returns a 5-byte identifier code that includes the manufacturer ID, device configuration, and part-specific information.

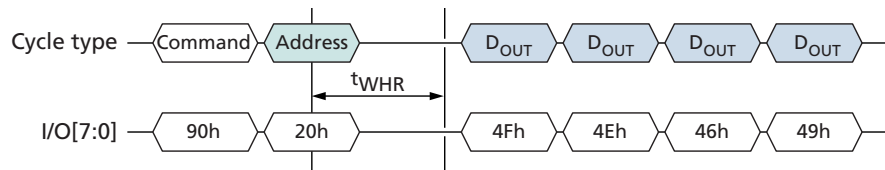
When the 90h command is followed by a 20h address cycle, the target returns the 4-byte ONFI identifier code.

Figure 22: READ ID (90h) with 00h Address Operation



Note: 1. See the READ ID Parameter tables for byte definitions.

Figure 23: READ ID (90h) with 20h Address Operation



Note: 1. See READ ID Parameter tables for byte definitions.



121-Ball NAND Flash with LPDDR2 MCP READ ID Parameter Tables

READ ID Parameter Tables

Table 11: READ ID Parameters for Address 00h

b = binary; h = hexadecimal

			Options	I/07	I/06	I/05	I/04	I/03	I/02	I/01	I/00	Value
Byte 0 – Manufacturer ID												
Manufacturer			Micron	0	0	1	0	1	1	0	0	2Ch
Byte 1 – Device ID												
MT29F1G08ABAEA			1Gb, x8, 3.3V	1	1	1	1	0	0	0	1	F1h
MT29F1G08ABBEA			1Gb, x8, 1.8V	1	0	1	0	0	0	0	1	A1h
MT29F1G16ABBEA			1Gb, x16, 1.8V	1	0	1	1	0	0	0	1	B1h
Byte 2												
Number of die per CE			1							0	0	00b
Cell type			SLC					0	0			00b
Number of simultaneously programmed pages			1			0	0					00b
Interleaved operations between multiple die			Not supported		0							0b
Cache programming			Supported	1								1b
Byte value			MT29F1G08ABAEA	1	0	0	0	0	0	0	0	80h
			MT29F1G08ABBEA	1	0	0	0	0	0	0	0	80h
			MT29F1G16ABBEA	1	0	0	0	0	0	0	0	80h
Byte 3												
Page size			2KB							0	1	01b
Spare area size (bytes)			64B						1			1b
Block size (without spare)			128KB			0	1					01b
Organization			x8		0							0b
			x16		1							1b
Serial access (MIN)	1.8V	25ns	0					0				0xxx0b
	3.3V	20ns	1					0				1xxx0b
Byte value			MT29F1G08ABAEA	1	0	0	1	0	1	0	1	95h
			MT29F1G08ABBEA	0	0	0	1	0	1	0	1	15h
			MT29F1G16ABBEA	0	1	0	1	0	1	0	1	55h
Byte 4												
Reserved										0	0	00b
Planes per CE# ¹			2					0	1			01b
Plane size			512Mb		0	0	0					000b
Reserved				0								0b



121-Ball NAND Flash with LPDDR2 MCP READ ID Parameter Tables

Table 11: READ ID Parameters for Address 00h (Continued)

b = binary; h = hexadecimal

	Options	I/07	I/06	I/05	I/04	I/03	I/02	I/01	I/00	Value
Byte value	MT29F1G08ABAEA	0	0	0	0	0	1	0	0	04h
	MT29F1G08ABB EA	0	0	0	0	0	1	0	0	04h
	MT29F1G16ABB EA	0	0	0	0	0	1	0	0	04h

Note: 1. Only single-plane operations are supported.

Table 12: READ ID Parameters for Address 20h

h = hexadecimal

Byte	Options	I/07	I/06	I/05	I/04	I/03	I/02	I/01	I/00	Value
0	"O"	0	1	0	0	1	1	1	1	4Fh
1	"N"	0	1	0	0	1	1	1	0	4Eh
2	"F"	0	1	0	0	0	1	1	0	46h
3	"I"	0	1	0	0	1	0	0	1	49h
4	Undefined	X	X	X	X	X	X	X	X	XXh



121-Ball NAND Flash with LPDDR2 MCP READ PARAMETER PAGE (ECh)

READ PARAMETER PAGE (ECh)

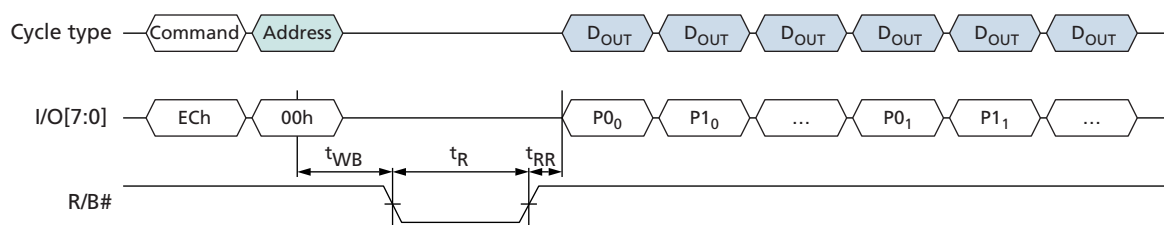
The READ PARAMETER PAGE (ECh) command is used to read the ONFI parameter page programmed into the target. This command is accepted by the target only when all die (LUNs) on the target are idle.

Writing ECh to the command register puts the target in read parameter page mode. The target stays in this mode until another valid command is issued.

When the ECh command is followed by an 00h address cycle, the target goes busy for t_R . If the READ STATUS (70h) command is used to monitor for command completion, the READ MODE (00h) command must be used to re-enable data output mode.

A minimum of three copies of the parameter page are stored in the device. Each parameter page is 256 bytes. If desired, the RANDOM DATA READ (05h-E0h) command can be used to change the location of data output.

Figure 24: READ PARAMETER (ECh) Operation





121-Ball NAND Flash with LPDDR2 MCP Parameter Page Data Structure Tables

Parameter Page Data Structure Tables

Table 13: Parameter Page Data Structure

h = hexadecimal

Byte	Description	Value
0–3	Parameter page signature	4Fh, 4Eh, 46h, 49h
4–5	Revision number	02h, 00h
6–7	Features supported	MT29F1G08ABAEAWP
		10h, 00h
		MT29F1G08ABBEAHC
		10h, 00h
		MT29F1G16ABBEAHC
		11h, 00h
		MT29F1G08ABBEAH4
		10h, 00h
		MT29F1G16ABBEAH4
		11h, 00h
		MT29F1G08ABAEAH4
		10h, 00h
		MT29F1G08ABAEA3W
		10h, 00h
		MT29F1G08ABBEA3W
		10h, 00h
		MT29F1G16ABBEA3W
		11h, 00h
8–9	Optional commands supported	3Fh, 00h
10–31	Reserved	00h, 00h
32–43	Device manufacturer	4Dh, 49h, 43h, 52h, 4Fh, 4Eh, 20h, 20h, 20h, 20h, 20h, 20h
44–63	Device model	MT29F1G08ABAEAWP
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 30h, 38h, 41h, 42h, 41h, 45h, 41h, 57h, 50h, 20h, 20h, 20h, 20h
		MT29F1G08ABBEAHC
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 30h, 38h, 41h, 42h, 42h, 45h, 41h, 48h, 43h, 20h, 20h, 20h, 20h
		MT29F1G16ABBEAHC
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 31h, 36h, 41h, 42h, 42h, 45h, 41h, 48h, 43h, 20h, 20h, 20h, 20h
		MT29F1G08ABBEAH4
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 30h, 38h, 41h, 42h, 42h, 45h, 41h, 48h, 34h, 20h, 20h, 20h, 20h
		MT29F1G16ABBEAH4
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 31h, 36h, 41h, 42h, 42h, 45h, 41h, 48h, 34h, 20h, 20h, 20h, 20h
		MT29F1G08ABAEAH4
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 30h, 38h, 41h, 42h, 41h, 45h, 41h, 48h, 34h, 20h, 20h, 20h, 20h
		MT29F1G08ABAEA3W
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 30h, 38h, 41h, 42h, 41h, 45h, 41h, 33h, 57h, 20h, 20h, 20h, 20h
		MT29F1G08ABBEA3W
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 30h, 38h, 41h, 42h, 42h, 45h, 41h, 33h, 57h, 20h, 20h, 20h, 20h
		MT29F1G16ABBEA3W
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 31h, 36h, 41h, 42h, 42h, 45h, 41h, 33h, 57h, 20h, 20h, 20h, 20h
		4Dh, 54h, 32h, 39h, 46h, 31h, 47h, 31h, 36h, 41h, 42h, 42h, 45h, 41h, 33h, 57h, 20h, 20h, 20h, 20h
64	Manufacturer ID	2Ch
65–66	Date code	00h, 00h
67–79	Reserved	00h, 00h



121-Ball NAND Flash with LPDDR2 MCP Parameter Page Data Structure Tables

Table 13: Parameter Page Data Structure (Continued)

h = hexadecimal

Byte	Description		Value
80–83	Number of data bytes per page		00h, 08h, 00h, 00h
84–85	Number of spare bytes per page		40h, 00h
86–89	Number of data bytes per partial page		00h, 02h, 00h, 00h
90–91	Number of spare bytes per partial page		10h, 00h
92–95	Number of pages per block		40h, 00h, 00h, 00h
96–99	Number of blocks per unit		00h, 04h, 00h, 00h
100	Number of logical units		01h
101	Number of address cycles		22h
102	Number of bits per cell		01h
103–104	Bad blocks maximum per unit		14h, 00h
105–106	Block endurance		01h, 05h
107	Guaranteed valid blocks at beginning of target		01h
108–109	Block endurance for guaranteed valid blocks		00h, 00h
110	Number of programs per page		04h
111	Partial programming attributes		00h
112	Number of bits ECC bits		04h
113	Number of interleaved address bits		00h
114	Interleaved operation attributes		00h
115–127	Reserved		00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h
128	I/O pin capacitance		0Ah
129–130	Timing mode support	MT29F1G08ABAEAWP	3Fh, 00h
		MT29F1G08ABBEAHC	1Fh, 00h
		MT29F1G16ABBEAHC	1Fh, 00h
		MT29F1G08ABBEAH4	1Fh, 00h
		MT29F1G16ABBEAH4	1Fh, 00h
		MT29F1G08ABAEAH4	3Fh, 00h
		MT29F1G08ABAEA3W	3Fh, 00h
		MT29F1G08ABBEA3W	1Fh, 00h
		MT29F1G16ABBEA3W	1Fh, 00h



h = hexadecimal

Byte	Description	Value
131–132	Program cache timing mode support	MT29F1G08ABAEAWP 3Fh, 00h
		MT29F1G08ABBEAHC 1Fh, 00h
		MT29F1G16ABBEAHC 1Fh, 00h
		MT29F1G08ABBEAH4 1Fh, 00h
		MT29F1G16ABBEAH4 1Fh, 00h
		MT29F1G08ABAEAH4 3Fh, 00h
		MT29F1G08ABAEA3W 3Fh, 00h
		MT29F1G08ABB EA3W 1Fh, 00h
		MT29F1G16ABB EA3W 1Fh, 00h
133–134	t ^{PROG} (MAX) page program time	58h, 02h
135–136	t ^{BERS} (MAX) block erase time	B8h, 0Bh
137–138	t ^R (MAX) page read time	19h, 00h
139–140	t ^{CCS} (MIN)	64h, 00h
141–163	Reserved	00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h, 00h,
164–165	Vendor-specific revision number	01h, 00h
166–253	Vendor-specific	01h, 00h, 00h, 02h, 04h, 80h, 01h, 81h, 04h, 01h, 02h, 01h, 0Ah, 00h,
254–255	Integrity CRC	Set at test
256–511	Value of bytes 0–255	
512–767	Value of bytes 0–255	
768+	Additional redundant parameter pages	



121-Ball NAND Flash with LPDDR2 MCP READ UNIQUE ID (EDh)

READ UNIQUE ID (EDh)

The READ UNIQUE ID (EDh) command is used to read a unique identifier programmed into the target. This command is accepted by the target only when all die (LUNs) on the target are idle.

Writing EDh to the command register puts the target in read unique ID mode. The target stays in this mode until another valid command is issued.

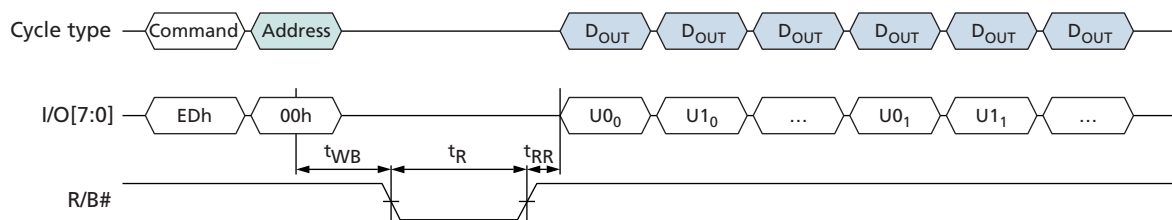
When the EDh command is followed by an 00h address cycle, the target goes busy for t_R . If the READ STATUS (70h) command is used to monitor for command completion, the READ MODE (00h) command must be used to re-enable data output mode.

After t_R completes, the host enables data output mode to read the unique ID. When the asynchronous interface is active, one data byte is output per RE# toggle.

Sixteen copies of the unique ID data are stored in the device. Each copy is 32 bytes. The first 16 bytes of a 32-byte copy are unique data, and the second 16 bytes are the complement of the first 16 bytes. The host should XOR the first 16 bytes with the second 16 bytes. If the result is 16 bytes of FFh, then that copy of the unique ID data is correct. In the event that a non-FFh result is returned, the host can repeat the XOR operation on a subsequent copy of the unique ID data. If desired, the RANDOM DATA READ (05h-E0h) command can be used to change the data output location.

The upper eight I/Os on a x16 device are not used and are a “Don’t Care” for x16 devices.

Figure 25: READ UNIQUE ID (EDh) Operation





121-Ball NAND Flash with LPDDR2 MCP Feature Operations

Feature Operations

The SET FEATURES (EFh) and GET FEATURES (EEh) commands are used to modify the target's default power-on behavior. These commands use a one-byte feature address to determine which subfeature parameters will be read or modified. Each feature address (in the 00h to FFh range) is defined below. The SET FEATURES (EFh) command writes subfeature parameters (P1–P4) to the specified feature address. The GET FEATURES command reads the subfeature parameters (P1–P4) at the specified feature address.

When a feature is set, by default it remains active until the device is power cycled. It is volatile. Unless otherwise specified in the features table, once a device is set it remains set, even if a RESET (FFh) command is issued. GET/SET FEATURES commands can be used after required RESET to enable features before system BOOT ROM process.

Table 14: Feature Address Definitions

Feature Address	Definition
00h	Reserved
01h	Timing mode
02h–7Fh	Reserved
80h	Programmable output drive strength
81h	Programmable RB# pull-down strength
82h–FFh	Reserved
90h	Array operation mode



121-Ball NAND Flash with LPDDR2 MCP Feature Operations

Table 15: Feature Address 90h – Array Operation Mode

Subfeature Parameter	Options	1/07	1/06	1/05	1/04	1/03	1/02	1/01	1/00	Value	Notes
P1											
Operation mode option	Normal	Reserved (0)							0	00h	1
	OTP operation	Reserved (0)							1	01h	
	OTP protection	Reserved (0)						1	1	03h	
		Reserved (0)								00h	
		Reserved (0)								00h	
P2											
Reserved		Reserved (0)								00h	
P3											
Reserved		Reserved (0)								00h	
P4											
Reserved		Reserved (0)								00h	

Note: 1. These bits are reset to 00h on power cycle.

SET FEATURES (EFh)

The SET FEATURES (EFh) command writes the subfeature parameters (P1–P4) to the specified feature address to enable or disable target-specific features. This command is accepted by the target only when all die (LUNs) on the target are idle.

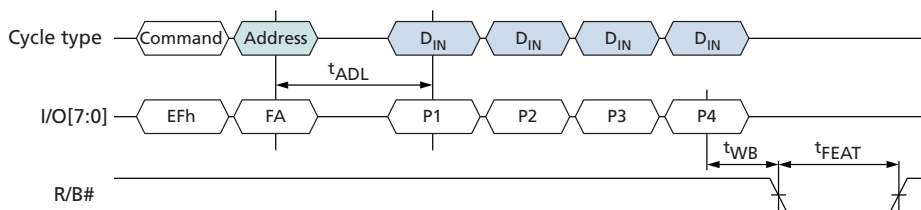
Writing EFh to the command register puts the target in the set features mode. The target stays in this mode until another command is issued.

The EFh command is followed by a valid feature address. The host waits for t_{ADL} before the subfeature parameters are input. When the asynchronous interface is active, one subfeature parameter is latched per rising edge of WE#.

After all four subfeature parameters are input, the target goes busy for t_{FEAT} . The READ STATUS (70h) command can be used to monitor for command completion.

Feature address 01h (timing mode) operation is unique. If SET FEATURES is used to modify the interface type, the target will be busy for t_{ITC} .

Figure 26: SET FEATURES (EFh) Operation





121-Ball NAND Flash with LPDDR2 MCP Feature Operations

GET FEATURES (EEh)

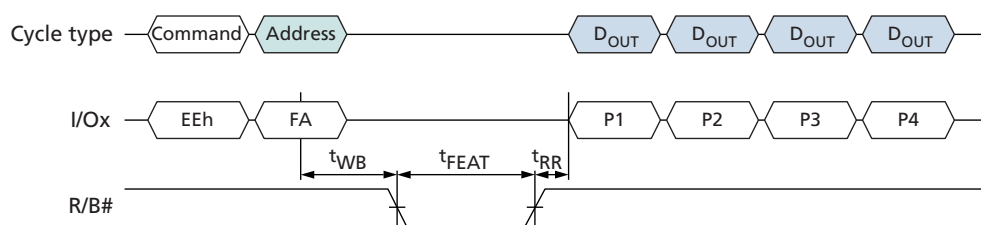
The GET FEATURES (EEh) command reads the subfeature parameters (P1–P4) from the specified feature address. This command is accepted by the target only when all die (LUNs) on the target are idle.

Writing EEh to the command register puts the target in get features mode. The target stays in this mode until another valid command is issued.

When the EEh command is followed by a feature address, the target goes busy for t_{FEAT} . If the READ STATUS (70h) command is used to monitor for command completion, the READ MODE (00h) command must be used to re-enable data output mode.

After t_{FEAT} completes, the host enables data output mode to read the subfeature parameters.

Figure 27: GET FEATURES (EEh) Operation





121-Ball NAND Flash with LPDDR2 MCP Feature Operations

Table 16: Feature Addresses 01h: Timing Mode

Subfeature Parameter	Options	I/O7	I/O6	I/O5	I/O4	I/O3	I/O2	I/O1	I/O0	Value	Notes
P1											
Timing mode	Mode 0 (default)						0	0	0	00h	1, 2
	Mode 1						0	0	1	01h	2
	Mode 2						0	1	0	02h	2
	Mode 3						0	1	1	03h	3
	Mode 4						1	0	0	04h	3
	Mode 5						1	0	1	05h	4
P2											
										00h	
P3											
										00h	
P4											
										00h	

- Notes:
1. The timing mode feature address is used to change the default timing mode. The timing mode should be selected to indicate the maximum speed at which the device will receive commands, addresses, and data cycles. The five supported settings for the timing mode are shown. The default timing mode is mode 0. The device returns to mode 0 when the device is power cycled. Supported timing modes are reported in the parameter page.
 2. Supported for both 1.8V and 3.3V.
 3. Supported for 3.3V only.
 4. Not supported.



121-Ball NAND Flash with LPDDR2 MCP Feature Operations

Table 17: Feature Addresses 80h: Programmable I/O Drive Strength

Subfeature Parameter	Options	I/O7	I/O6	I/O5	I/O4	I/O3	I/O2	I/O1	I/O0	Value	Notes
P1											
I/O drive strength	Full (default)							0	0	00h	1
	Three-quarters							0	1	01h	
	One-half							1	0	02h	
	One-quarter							1	1	03h	
P2											
										00h	
P3											
										00h	
P4											
										00h	

Note: 1. The programmable drive strength feature address is used to change the default I/O drive strength. Drive strength should be selected based on expected loading of the memory bus. This table shows the four supported output drive strength settings. The default drive strength is full strength. The device returns to the default drive strength mode when the device is power cycled. AC timing parameters may need to be relaxed if I/O drive strength is not set to full.

Table 18: Feature Addresses 81h: Programmable R/B# Pull-Down Strength

Subfeature Parameter	Options	I/O7	I/O6	I/O5	I/O4	I/O3	I/O2	I/O1	I/O0	Value	Notes
P1											
R/B# pull-down strength	Full (default)							0	0	00h	1
	Three-quarters							0	1	01h	
	One-half							1	0	02h	
	One-quarter							1	1	03h	
P2											
										00h	
P3											
										00h	
P4											
										00h	

Note: 1. This feature address is used to change the default R/B# pull-down strength. Its strength should be selected based on the expected loading of R/B#. Full strength is the default, power-on value.



121-Ball NAND Flash with LPDDR2 MCP Status Operations

Status Operations

Each die (LUN) provides its status independently of other die (LUNs) on the same target through its 8-bit status register.

After the READ STATUS (70h) command is issued, status register output is enabled. The contents of the status register are returned on I/O[7:0] for each data output request.

When the asynchronous interface is active and status register output is enabled, changes in the status register are seen on I/O[7:0] as long as CE# and RE# are LOW; it is not necessary to toggle RE# to see the status register update.

While monitoring the status register to determine when a data transfer from the Flash array to the data register (¹R) is complete, the host must issue the READ MODE (00h) command to disable the status register and enable data output (see Read Operations).

Table 19: Status Register Definition

SR Bit	Program Page	Program Page Cache Mode	Page Read	Page Read Cache Mode	Block Erase	Description
7	Write protect	Write protect	Write protect	Write protect	Write protect	0 = Protected 1 = Not protected
6	RDY	RDY ¹ cache	RDY	RDY ¹ cache	RDY	0 = Busy 1 = Ready
5	ARDY	ARDY ²	ARDY	ARDY ²	ARDY	Don't Care
4	–	–	–	–	–	Don't Care
3	–	–	–	–	–	Don't Care
2	–	–	–	–	–	Don't Care
1	FAILC (N - 1)	FAILC (N - 1)	Reserved	–	–	Don't Care
0	FAIL	FAIL (N)	–	–	FAIL	0 = Successful PROGRAM/ ERASE 1 = Error in PROGRAM/ ERASE

- Notes:
1. Status register bit 6 is 1 when the cache is ready to accept new data. R/B# follows bit 6.
 2. Status register bit 5 is 0 during the actual programming operation. If cache mode is used, this bit will be 1 when all internal operations are complete.



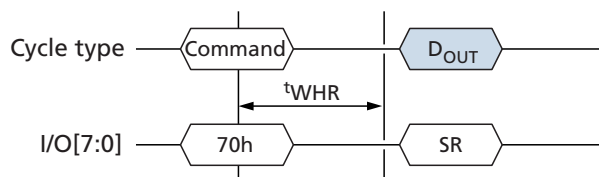
121-Ball NAND Flash with LPDDR2 MCP Status Operations

READ STATUS (70h)

The READ STATUS (70h) command returns the status of the last-selected die (LUN) on a target. This command is accepted by the last-selected die (LUN) even when it is busy (RDY = 0).

If there is only one die (LUN) per target, the READ STATUS (70h) command can be used to return status following any NAND command.

Figure 28: READ STATUS (70h) Operation





121-Ball NAND Flash with LPDDR2 MCP Column Address Operations

Column Address Operations

The column address operations affect how data is input to and output from the cache registers within the selected die (LUNs). These features provide host flexibility for managing data, especially when the host internal buffer is smaller than the number of data bytes or words in the cache register.

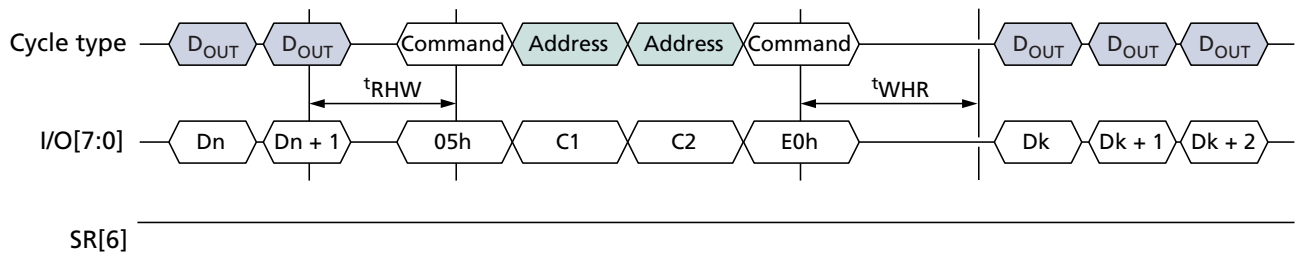
When the asynchronous interface is active, column address operations can address any byte in the selected cache register.

RANDOM DATA READ (05h-E0h)

The RANDOM DATA READ (05h-E0h) command changes the column address of the selected cache register and enables data output from the last selected die (LUN). This command is accepted by the selected die (LUN) when it is ready (RDY = 1; ARDY = 1). It is also accepted by the selected die (LUN) during CACHE READ operations (RDY = 1; ARDY = 0).

Writing 05h to the command register, followed by two column address cycles containing the column address, followed by the E0h command, puts the selected die (LUN) into data output mode. After the E0h command cycle is issued, the host must wait at least t_{WHR} before requesting data output. The selected die (LUN) stays in data output mode until another valid command is issued.

Figure 29: RANDOM DATA READ (05h-E0h) Operation





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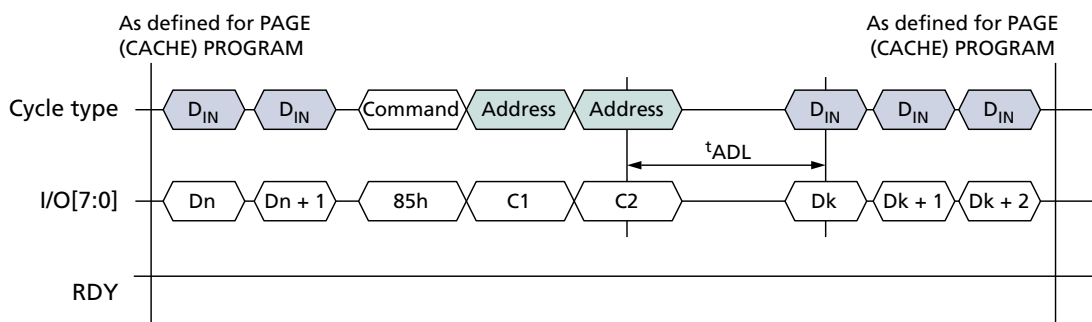
RANDOM DATA INPUT (85h)

The RANDOM DATA INPUT (85h) command changes the column address of the selected cache register and enables data input on the last-selected die (LUN). This command is accepted by the selected die (LUN) when it is ready (RDY = 1; ARDY = 1). It is also accepted by the selected die (LUN) during cache program operations (RDY = 1; ARDY = 0).

Writing 85h to the command register, followed by two column address cycles containing the column address, puts the selected die (LUN) into data input mode. After the second address cycle is issued, the host must wait at least t_{ADL} before inputting data. The selected die (LUN) stays in data input mode until another valid command is issued. Though data input mode is enabled, data input from the host is optional. Data input begins at the column address specified.

The RANDOM DATA INPUT (85h) command is allowed after the required address cycles are specified, but prior to the final command cycle (10h, 11h, 15h) of the following commands while data input is permitted: PROGRAM PAGE (80h-10h), PROGRAM PAGE CACHE (80h-15h), and PROGRAM FOR INTERNAL DATA MOVE (85h-10h).

Figure 30: RANDOM DATA INPUT (85h) Operation



PROGRAM FOR INTERNAL DATA INPUT (85h)

The PROGRAM FOR INTERNAL DATA INPUT (85h) command changes the row address (block and page) where the cache register contents will be programmed in the NAND Flash array. It also changes the column address of the selected cache register and enables data input on the specified die (LUN). This command is accepted by the selected die (LUN) when it is ready (RDY = 1; ARDY = 1). It is also accepted by the selected die (LUN) during cache programming operations (RDY = 1; ARDY = 0).

Write 85h to the command register. Then write two column address cycles and three row address cycles. This updates the page and block destination of the selected device for the addressed LUN and puts the cache register into data input mode. After the fifth address cycle is issued the host must wait at least t_{ADL} before inputting data. The selected LUN stays in data input mode until another valid command is issued. Though data input mode is enabled, data input from the host is optional. Data input begins at the column address specified.

The PROGRAM FOR INTERNAL DATA INPUT (85h) command is allowed after the required address cycles are specified, but prior to the final command cycle (10h, 11h, 15h) of the following commands while data input is permitted: PROGRAM PAGE (80h-10h),



121-Ball NAND Flash with LPDDR2 MCP Column Address Operations

PROGRAM PAGE CACHE (80h-15h), and PROGRAM FOR INTERNAL DATA MOVE (85h-10h). When used with these commands, the LUN address and plane select bits are required to be identical to the LUN address and plane select bits originally specified.

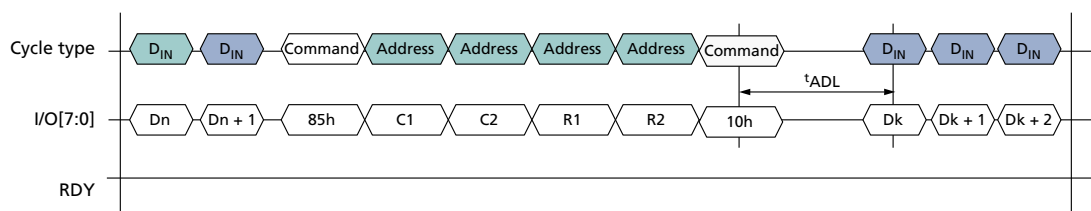
The PROGRAM FOR INTERNAL DATA INPUT (85h) command enables the host to modify the original page and block address for the data in the cache register to a new page and block address.

In devices that have more than one die (LUN) per target, the PROGRAM FOR INTERNAL DATA INPUT (85h) command can be used with other commands that support interleaved die (multi-LUN) operations.

The PROGRAM FOR INTERNAL DATA INPUT (85h) command can be used with the RANDOM DATA READ (05h-E0h) command to read and modify cache register contents in small sections prior to programming cache register contents to the NAND Flash array. This capability can reduce the amount of buffer memory used in the host controller.

The RANDOM DATA INPUT (85h) command can be used during the PROGRAM FOR INTERNAL DATA MOVE command sequence to modify one or more bytes of the original data. First, data is copied into the cache register using the 00h-35h command sequence, then the RANDOM DATA INPUT (85h) command is written along with the address of the data to be modified next. New data is input on the external data pins. This copies the new data into the cache register.

Figure 31: PROGRAM FOR INTERNAL DATA INPUT (85h) Operation





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Read Operations

The READ PAGE (00h-30h) command, when issued by itself, reads one page from the NAND Flash array to its cache register and enables data output for that cache register.

During data output the following commands can be used to read and modify the data in the cache registers: RANDOM DATA READ (05h-E0h) and RANDOM DATA INPUT (85h).

Read Cache Operations

To increase data throughput, the READ PAGE CACHE series (31h, 00h-31h) commands can be used to output data from the cache register while concurrently copying a page from the NAND Flash array to the data register.

To begin a read page cache sequence, begin by reading a page from the NAND Flash array to its corresponding cache register using the READ PAGE (00h-30h) command. R/B# goes LOW during t_R and the selected die (LUN) is busy (RDY = 0, ARDY = 0). After t_R (R/B# is HIGH and RDY = 1, ARDY = 1), issue either of these commands:

- READ PAGE CACHE SEQUENTIAL (31h) – copies the next sequential page from the NAND Flash array to the data register
- READ PAGE CACHE RANDOM (00h-31h) – copies the page specified in this command from the NAND Flash array to its corresponding data register

After the READ PAGE CACHE series (31h, 00h-31h) command has been issued, R/B# goes LOW on the target, and RDY = 0 and ARDY = 0 on the die (LUN) for t_{RCBSY} while the next page begins copying data from the array to the data register. After t_{RCBSY} , R/B# goes HIGH and the die's (LUN's) status register bits indicate the device is busy with a cache operation (RDY = 1, ARDY = 0). The cache register becomes available and the page requested in the READ PAGE CACHE operation is transferred to the data register. At this point, data can be output from the cache register, beginning at column address 0. The RANDOM DATA READ (05h-E0h) command can be used to change the column address of the data output by the die (LUN).

After outputting the desired number of bytes from the cache register, either an additional READ PAGE CACHE series (31h, 00h-31h) operation can be started or the READ PAGE CACHE LAST (3Fh) command can be issued.

If the READ PAGE CACHE LAST (3Fh) command is issued, R/B# goes LOW on the target, and RDY = 0 and ARDY = 0 on the die (LUN) for t_{RCBSY} while the data register is copied into the cache register. After t_{RCBSY} , R/B# goes HIGH and RDY = 1 and ARDY = 1, indicating that the cache register is available and that the die (LUN) is ready. Data can then be output from the cache register, beginning at column address 0. The RANDOM DATA READ (05h-E0h) command can be used to change the column address of the data being output.

For READ PAGE CACHE series (31h, 00h-31h, 3Fh), during the die (LUN) busy time, t_{RCBSY} , when RDY = 0 and ARDY = 0, the only valid commands are status operations (70h) and RESET (FFh). When RDY = 1 and ARDY = 0, the only valid commands during READ PAGE CACHE series (31h, 00h-31h) operations are status operations (70h), READ MODE (00h), READ PAGE CACHE series (31h, 00h-31h), RANDOM DATA READ (05h-E0h), and RESET (FFh).



121-Ball NAND Flash with LPDDR2 MCP Read Operations

READ MODE (00h)

The READ MODE (00h) command disables status output and enables data output for the last-selected die (LUN) and cache register after a READ operation (00h-30h, 00h-3Ah, 00h-35h) has been monitored with a status operation (70h). This command is accepted by the die (LUN) when it is ready (RDY = 1, ARDY = 1). It is also accepted by the die (LUN) during READ PAGE CACHE (31h, 00h-31h) operations (RDY = 1 and ARDY = 0).

READ PAGE (00h-30h)

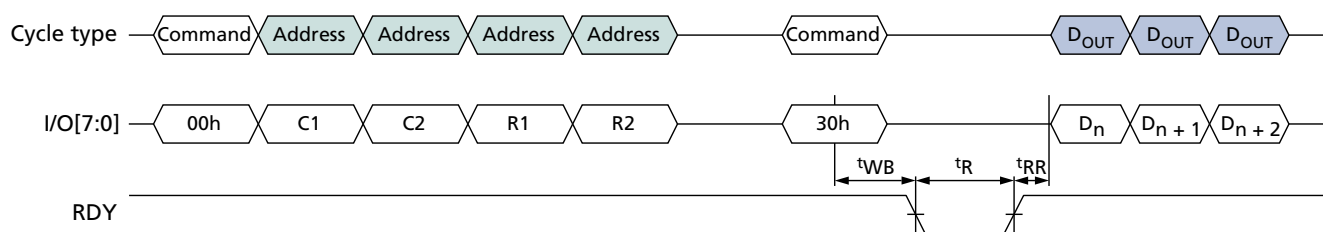
The READ PAGE (00h-30h) command copies a page from the NAND Flash array to its respective cache register and enables data output. This command is accepted by the die (LUN) when it is ready (RDY = 1, ARDY = 1).

To read a page from the NAND Flash array, write the 00h command to the command register, then write n address cycles to the address registers, and conclude with the 30h command. The selected die (LUN) will go busy (RDY = 0, ARDY = 0) for t_R as data is transferred.

To determine the progress of the data transfer, the host can monitor the target's R/B# signal or, alternatively, the status operations (70h) can be used. If the status operations are used to monitor the LUN's status, when the die (LUN) is ready (RDY = 1, ARDY = 1), the host disables status output and enables data output by issuing the READ MODE (00h) command. When the host requests data output, output begins at the column address specified.

During data output the RANDOM DATA READ (05h-E0h) command can be issued.

Figure 32: READ PAGE (00h-30h) Operation





121-Ball NAND Flash with LPDDR2 MCP Read Operations

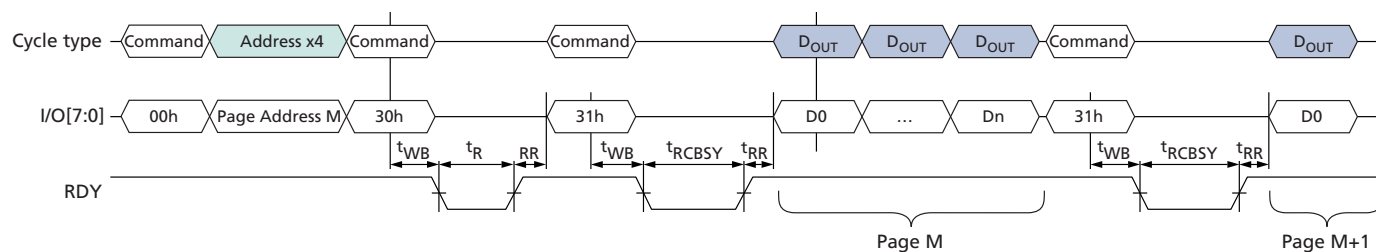
READ PAGE CACHE SEQUENTIAL (31h)

The READ PAGE CACHE SEQUENTIAL (31h) command reads the next sequential page within a block into the data register while the previous page is output from the cache register. This command is accepted by the die (LUN) when it is ready (RDY = 1, ARDY = 1). It is also accepted by the die (LUN) during READ PAGE CACHE (31h, 00h-31h) operations (RDY = 1 and ARDY = 0).

To issue this command, write 31h to the command register. After this command is issued, R/B# goes LOW and the die (LUN) is busy (RDY = 0, ARDY = 0) for t_{RCBSY} . After t_{RCBSY} , R/B# goes HIGH and the die (LUN) is busy with a cache operation (RDY = 1, ARDY = 0), indicating that the cache register is available and that the specified page is copying from the NAND Flash array to the data register. At this point, data can be output from the cache register beginning at column address 0. The RANDOM DATA READ (05h-E0h) command can be used to change the column address of the data being output from the cache register.

The READ PAGE CACHE SEQUENTIAL (31h) command can be used to cross block boundaries. If the READ PAGE CACHE SEQUENTIAL (31h) command is issued after the last page of a block is read into the data register, the next page read will be the next logical block in which the 31h command was issued. Do not issue the READ PAGE CACHE SEQUENTIAL (31h) to cross die (LUN) boundaries. Instead, issue the READ PAGE CACHE LAST (3Fh) command.

Figure 33: READ PAGE CACHE SEQUENTIAL (31h) Operation





121-Ball NAND Flash with LPDDR2 MCP Read Operations

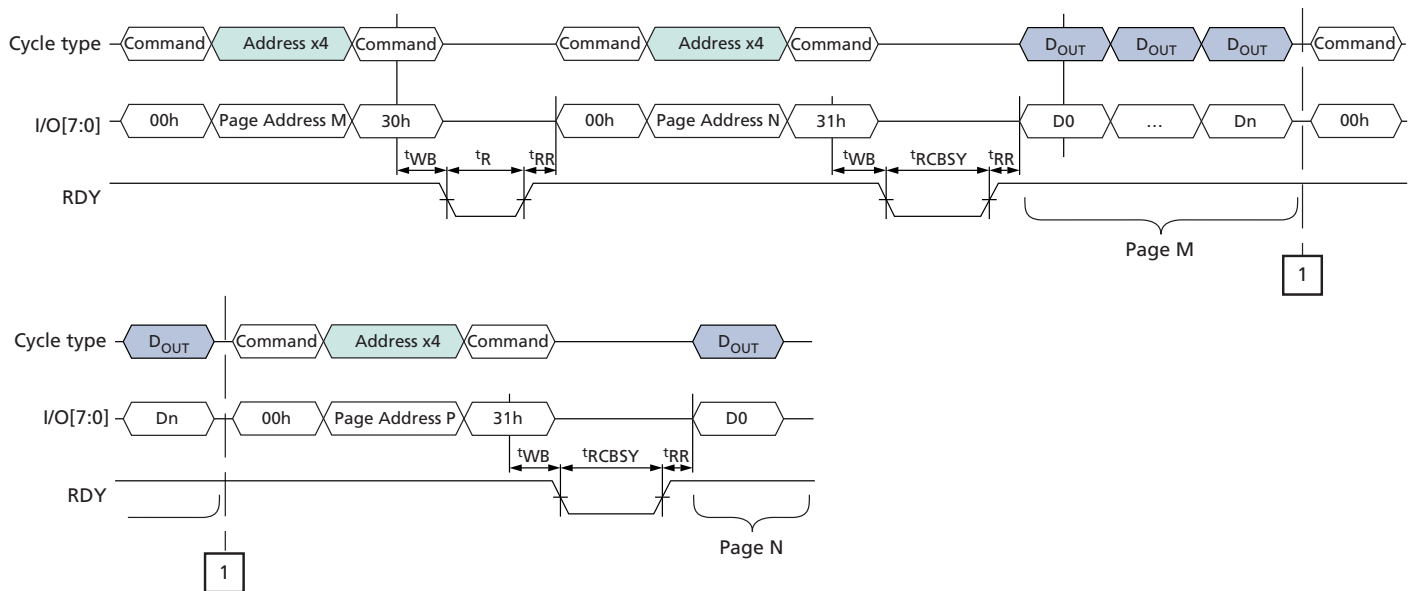
READ PAGE CACHE RANDOM (00h-31h)

The READ PAGE CACHE RANDOM (00h-31h) command reads the specified block and page into the data register while the previous page is output from the cache register. This command is accepted by the die (LUN) when it is ready (RDY = 1, ARDY = 1). It is also accepted by the die (LUN) during READ PAGE CACHE (31h, 00h-31h) operations (RDY = 1 and ARDY = 0).

To issue this command, write 00h to the command register, then write n address cycles to the address register, and conclude by writing 31h to the command register. The column address in the address specified is ignored. The die (LUN) address must match the same die (LUN) address as the previous READ PAGE (00h-30h) command or, if applicable, the previous READ PAGE CACHE RANDOM (00h-31h) command.

After this command is issued, R/B# goes LOW and the die (LUN) is busy (RDY = 0, ARDY = 0) for t_{RCBSY} . After t_{RCBSY} , R/B# goes HIGH and the die (LUN) is busy with a cache operation (RDY = 1, ARDY = 0), indicating that the cache register is available and that the specified page is copying from the NAND Flash array to the data register. At this point, data can be output from the cache register beginning at column address 0. The RANDOM DATA READ (05h-E0h) command can be used to change the column address of the data being output from the cache register.

Figure 34: READ PAGE CACHE RANDOM (00h-31h) Operation



READ PAGE CACHE LAST (3Fh)

The READ PAGE CACHE LAST (3Fh) command ends the read page cache sequence and copies a page from the data register to the cache register. This command is accepted by the die (LUN) when it is ready (RDY = 1, ARDY = 1). It is also accepted by the die (LUN) during READ PAGE CACHE (31h, 00h-31h) operations (RDY = 1 and ARDY = 0).

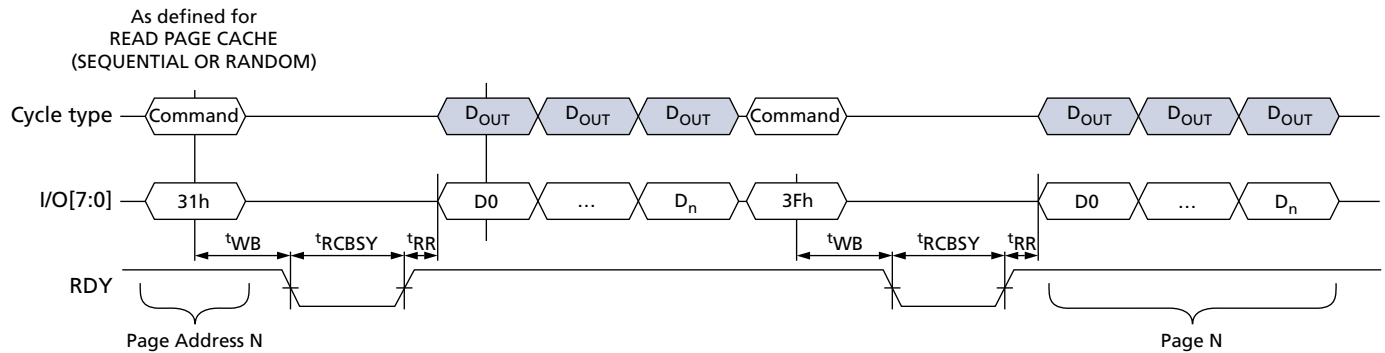
To issue the READ PAGE CACHE LAST (3Fh) command, write 3Fh to the command register. After this command is issued, R/B# goes LOW and the die (LUN) is busy



121-Ball NAND Flash with LPDDR2 MCP Read Operations

(RDY = 0, ARDY = 0) for t_{RCBSY} . After t_{RCBSY} , R/B# goes HIGH and the die (LUN) is ready (RDY = 1, ARDY = 1). At this point, data can be output from the cache register, beginning at column address 0. The RANDOM DATA READ (05h-E0h) command can be used to change the column address of the data being output from the cache register.

Figure 35: READ PAGE CACHE LAST (3Fh) Operation





121-Ball NAND Flash with LPDDR2 MCP Program Operations

Program Operations

Program operations are used to move data from the cache or data registers to the NAND array. During a program operation the contents of the cache and/or data registers are modified by the internal control logic.

Within a block, pages must be programmed sequentially from the least significant page address to the most significant page address (0, 1, 2,, 63). During a program operation, the contents of the cache and/or data registers are modified by the internal control logic.

Program Operations

The PROGRAM PAGE (80h-10h) command programs one page from the cache register to the NAND Flash array. When the die (LUN) is ready (RDY = 1, ARDY = 1), the host should check the FAIL bit to verify that the operation has completed successfully.

Program Cache Operations

The PROGRAM PAGE CACHE (80h-15h) command can be used to improve program operation system performance. When this command is issued, the die (LUN) goes busy (RDY = 0, ARDY = 0) while the cache register contents are copied to the data register, and the die (LUN) is busy with a program cache operation (RDY = 1, ARDY = 0). While the contents of the data register are moved to the NAND Flash array, the cache register is available for an additional PROGRAM PAGE CACHE (80h-15h) or PROGRAM PAGE (80h-10h) command.

For PROGRAM PAGE CACHE series (80h-15h) operations, during the die (LUN) busy times, $\overline{\text{C}}\text{BSY}$ and $\overline{\text{L}}\text{PROG}$, when RDY = 0 and ARDY = 0, the only valid commands are status operation (70h) and reset (FFh). When RDY = 1 and ARDY = 0, the only valid commands during PROGRAM PAGE CACHE series (80h-15h) operations are status operation (70h), PROGRAM PAGE CACHE (80h-15h), PROGRAM PAGE (80h-10h), RANDOM DATA INPUT (85h), PROGRAM FOR INTERNAL DATA INPUT (85h), and RESET (FFh).

PROGRAM PAGE (80h-10h)

The PROGRAM PAGE (80h-10h) command enables the host to input data to a cache register, and moves the data from the cache register to the specified block and page address in the array of the selected die (LUN). This command is accepted by the die (LUN) when it is ready (RDY = 1, ARDY = 1). It is also accepted by the die (LUN) when it is busy with a PROGRAM PAGE CACHE (80h-15h) operation (RDY = 1, ARDY = 0).

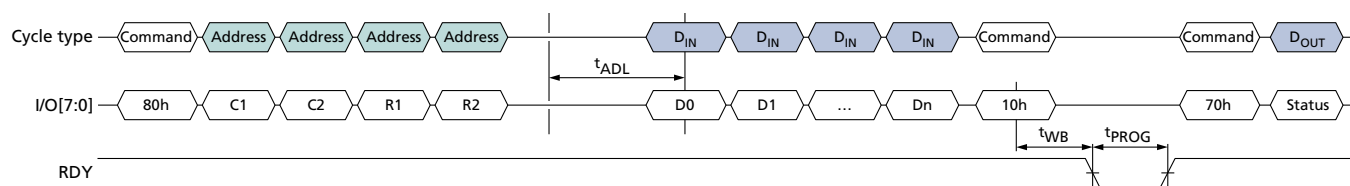
To input a page to the cache register and move it to the NAND array at the block and page address specified, write 80h to the command register. Issuing the 80h to the command register clears all of the cache registers' contents on the selected target. Write n address cycles containing the column address and row address. Data input cycles follow. Serial data is input beginning at the column address specified. At any time during the data input cycle the RANDOM DATA INPUT (85h) and PROGRAM FOR INTERNAL DATA INPUT (85h) commands may be issued. When data input is complete, write 10h to the command register. The selected LUN will go busy (RDY = 0, ARDY = 0) for $\overline{\text{L}}\text{PROG}$ as data is transferred.

To determine the progress of the data transfer, the host can monitor the target's R/B# signal or, alternatively, the status operation (70h) may be used. When the die (LUN) is ready (RDY = 1, ARDY = 1), the host should check the status of the FAIL bit.



121-Ball NAND Flash with LPDDR2 MCP Program Operations

Figure 36: PROGRAM PAGE (80h-10h) Operaton



PROGRAM PAGE CACHE (80h-15h)

The PROGRAM PAGE CACHE (80h-15h) command enables the host to input data to a cache register; copies the data from the cache register to the data register; then moves the data register contents to the specified block and page address in the array of the selected die (LUN). After the data is copied to the data register, the cache register is available for additional PROGRAM PAGE CACHE (80h-15h) or PROGRAM PAGE (80h-10h) commands. The PROGRAM PAGE CACHE (80h-15h) command is accepted by the die (LUN) when it is ready (RDY = 1, ARDY = 1). It is also accepted by the die (LUN) when busy with a PROGRAM PAGE CACHE (80h-15h) operation (RDY = 1, ARDY = 0).

To input a page to the cache register to move it to the NAND array at the block and page address specified, write 80h to the command register. Issuing the 80h to the command register clears all of the cache registers' contents on the selected target. Then write n address cycles containing the column address and row address. Data input cycles follow. Serial data is input beginning at the column address specified. At any time during the data input cycle the RANDOM DATA INPUT (85h) and PROGRAM FOR INTERNAL DATA INPUT (85h) commands may be issued. When data input is complete, write 15h to the command register. The selected LUN will go busy (RDY = 0, ARDY = 0) for t_{CBSY} to allow the data register to become available from a previous program cache operation, to copy data from the cache register to the data register, and then to begin moving the data register contents to the specified page and block address.

To determine the progress of t_{CBSY} , the host can monitor the target's R/B# signal or, alternatively, the status operation (70h) can be used. When the LUN's status shows that it is busy with a PROGRAM CACHE operation (RDY = 1, ARDY = 0), the host should check the status of the FAILC bit to see if a previous cache operation was successful.

If, after t_{CBSY} , the host wants to wait for the program cache operation to complete, without issuing the PROGRAM PAGE (80h-10h) command, the host should monitor ARDY until it is 1. The host should then check the status of the FAIL and FAILC bits.



121-Ball NAND Flash with LPDDR2 MCP Program Operations

Figure 37: PROGRAM PAGE CACHE (80h-15h) Operation (Start)

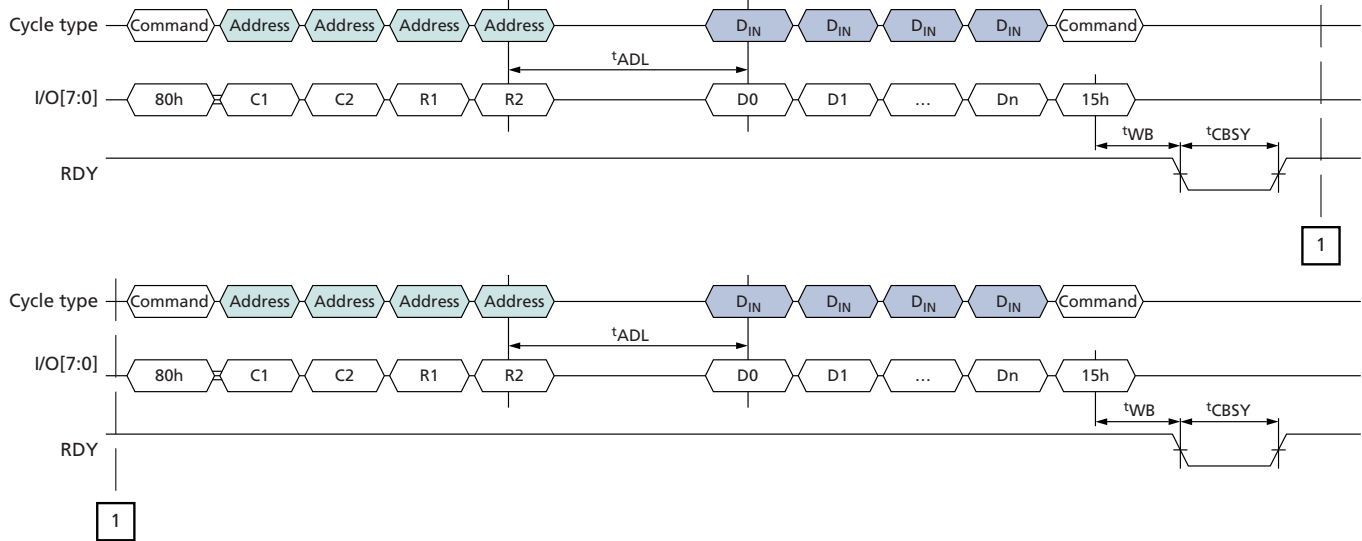
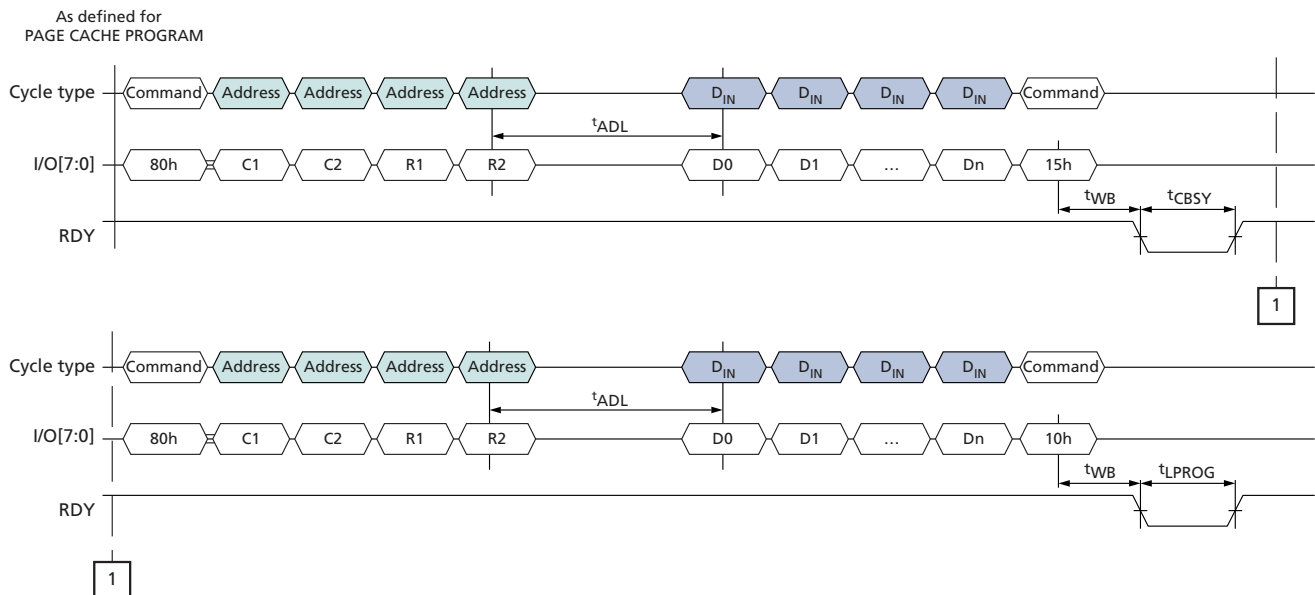


Figure 38: PROGRAM PAGE CACHE (80h-15h) Operation (End)





121-Ball NAND Flash with LPDDR2 MCP Erase Operations

Erase Operations

Erase operations are used to clear the contents of a block in the NAND Flash array to prepare its pages for program operations.

Erase Operations

The ERASE BLOCK (60h-D0h) command erases one block in the NAND Flash array. When the die (LUN) is ready (RDY = 1, ARDY = 1), the host should check the FAIL bit to verify that this operation completed successfully.

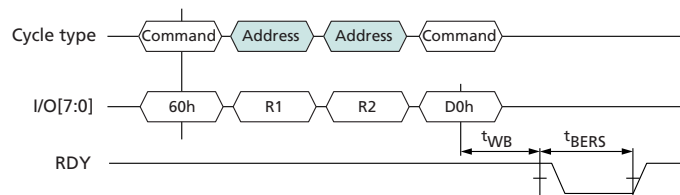
ERASE BLOCK (60h-D0h)

The ERASE BLOCK (60h-D0h) command erases the specified block in the NAND Flash array. This command is accepted by the die (LUN) when it is ready (RDY = 1, ARDY = 1).

To erase a block, write 60h to the command register. Then write two address cycles containing the row address; the page address is ignored. Conclude by writing D0h to the command register. The selected die (LUN) will go busy (RDY = 0, ARDY = 0) for t_{BERS} while the block is erased.

To determine the progress of an ERASE operation, the host can monitor the target's R/B# signal, or alternatively, the status operation (70h) can be used. When the die (LUN) is ready (RDY = 1, ARDY = 1) the host should check the status of the FAIL bit.

Figure 39: ERASE BLOCK (60h-D0h) Operation





121-Ball NAND Flash with LPDDR2 MCP Internal Data Move Operations

Internal Data Move Operations

Internal data move operations make it possible to transfer data within a device from one page to another using the cache register. This is particularly useful for block management and wear leveling. The INTERNAL DATA MOVE operation is restricted to only within even blocks or only within odd blocks.

The INTERNAL DATA MOVE operation is a two-step process consisting of a READ FOR INTERNAL DATA MOVE (00h-35h) and a PROGRAM FOR INTERNAL DATA MOVE (85h-10h) command. To move data from one page to another, first issue the READ FOR INTERNAL DATA MOVE (00h-35h) command. When the die (LUN) is ready (RDY = 1, ARDY = 1), the host can transfer the data to a new page by issuing the PROGRAM FOR INTERNAL DATA MOVE (85h-10h) command. When the die (LUN) is again ready (RDY = 1, ARDY = 1), the host should check the FAIL bit to verify that this operation completed successfully.

To prevent bit errors from accumulating over multiple INTERNAL DATA MOVE operations, it is recommended that the host read the data out of the cache register after the READ FOR INTERNAL DATA MOVE (00h-35h) completes and prior to issuing the PROGRAM FOR INTERNAL DATA MOVE (85h-10h) command. The RANDOM DATA READ (05h-E0h) command can be used to change the column address. The host should check the data for ECC errors and correct them. When the PROGRAM FOR INTERNAL DATA MOVE (85h-10h) command is issued, any corrected data can be input. The PROGRAM FOR INTERNAL DATA INPUT (85h) command can be used to change the column address.

Between the READ FOR INTERNAL DATA MOVE (00h-35h) and PROGRAM FOR INTERNAL DATA MOVE (85h-10h) commands, the following commands are supported: status operation (70h) and column address operations (05h-E0h, 85h). The RESET operation (FFh) can be issued after READ FOR INTERNAL DATA MOVE (00h-35h), but the contents of the cache registers on the target are not valid.

READ FOR INTERNAL DATA MOVE (00h-35h)

The READ FOR INTERNAL DATA MOVE (00h-35h) command is functionally identical to the READ PAGE (00h-30h) command, except that 35h is written to the command register instead of 30h.

It is recommended that the host read the data out of the device to verify the data prior to issuing the PROGRAM FOR INTERNAL DATA MOVE (85h-10h) command to prevent the propagation of data errors.



121-Ball NAND Flash with LPDDR2 MCP Internal Data Move Operations

Figure 40: READ FOR INTERNAL DATA MOVE (00h-35h) Operation

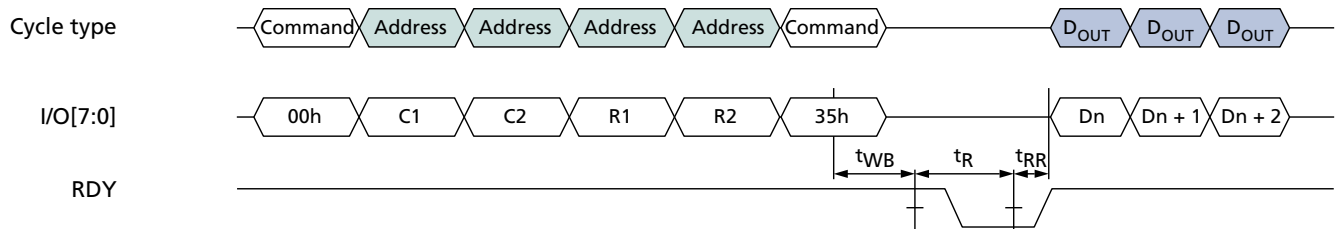
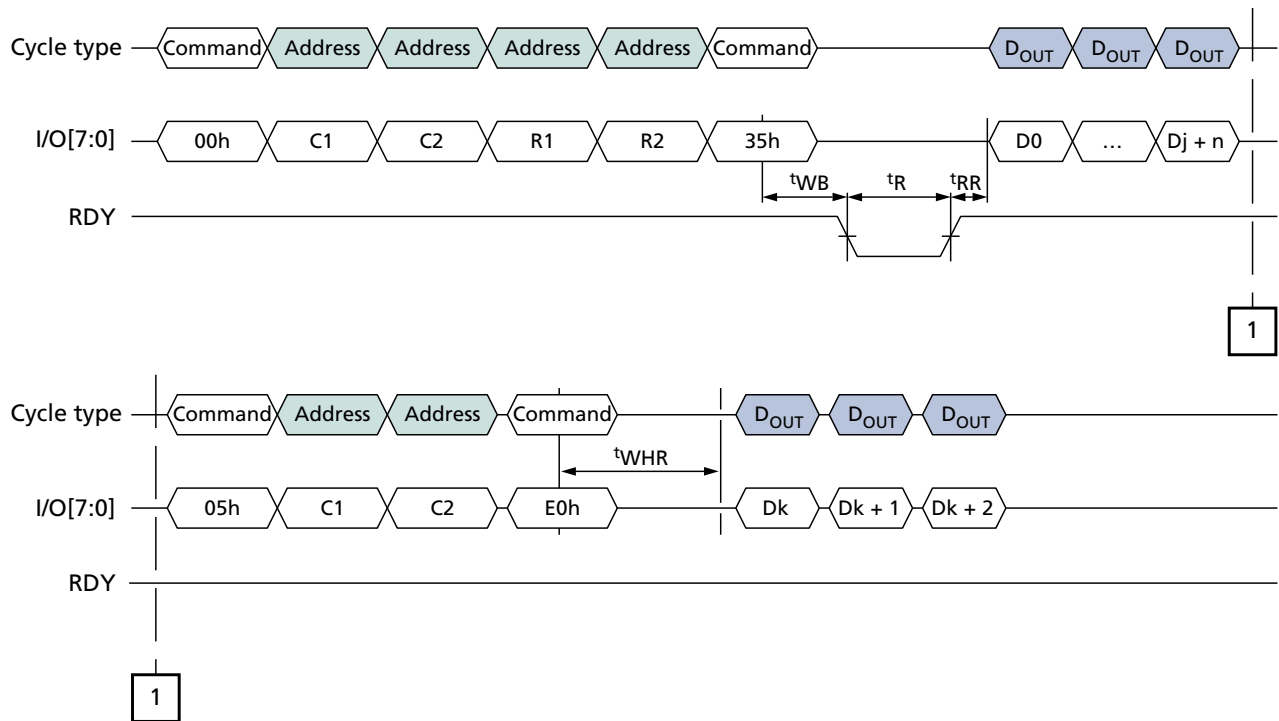


Figure 41: READ FOR INTERNAL DATA MOVE (00h-35h) with RANDOM DATA READ (05h-E0h)





121-Ball NAND Flash with LPDDR2 MCP Internal Data Move Operations

PROGRAM FOR INTERNAL DATA MOVE (85h-10h)

The PROGRAM FOR INTERNAL DATA MOVE (85h-10h) command is functionally identical to the PROGRAM PAGE (80h-10h) command, except that when 85h is written to the command register, cache register contents are not cleared.

Figure 42: PROGRAM FOR INTERNAL DATA MOVE (85h-10h)

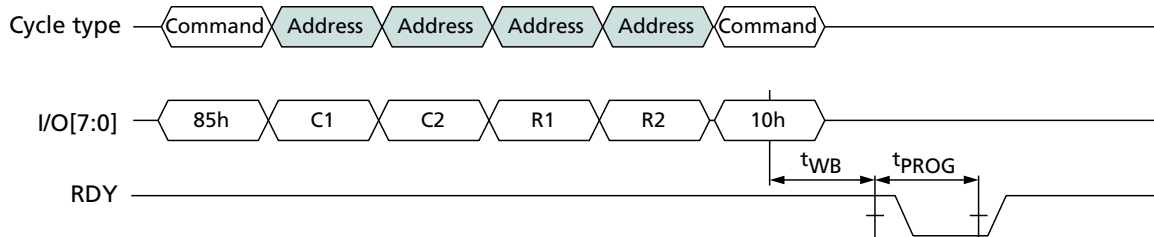
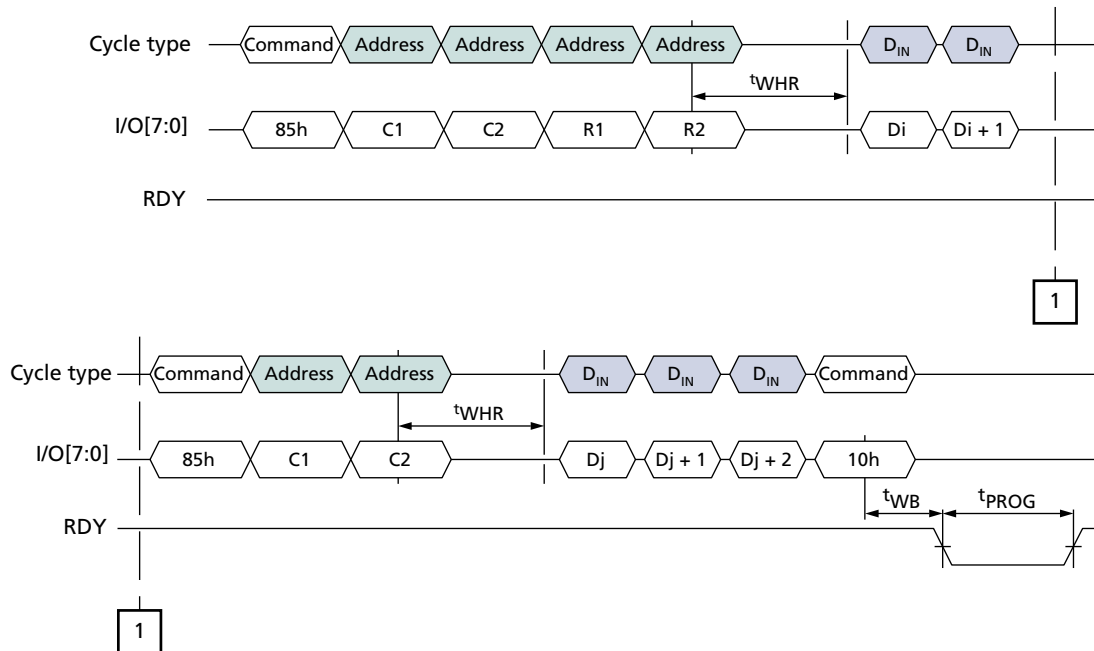


Figure 43: PROGRAM FOR INTERNAL DATA MOVE (85h-10h) with RANDOM DATA INPUT (85h)





121-Ball NAND Flash with LPDDR2 MCP Block Lock Feature

Block Lock Feature

The block lock feature protects either the entire device or ranges of blocks from being programmed and erased. Using the block lock feature is preferable to using WP# to prevent PROGRAM and ERASE operations.

Block lock is enabled and disabled at power-on through the LOCK pin. At power-on, if LOCK is LOW, all BLOCK LOCK commands are disabled. However if LOCK is HIGH at power-on, the BLOCK LOCK commands are enabled and, by default, all the blocks on the device are protected, or locked, from PROGRAM and ERASE operations, even if WP# is HIGH.

Before the contents of the device can be modified, the device must first be unlocked. Either a range of blocks or the entire device may be unlocked. PROGRAM and ERASE operations complete successfully only in the block ranges that have been unlocked. Blocks, once unlocked, can be locked again to protect them from further PROGRAM and ERASE operations.

Blocks that are locked can be protected further, or locked tight. When locked tight, the device's blocks can no longer be locked or unlocked until the device is power cycled.

WP# and Block Lock

The following is true when the block lock feature is enabled:

- Holding WP# LOW locks all blocks, provided the blocks are not locked tight.
- If WP# is held LOW to lock blocks, then returned to HIGH, a new UNLOCK command must be issued to unlock blocks.

UNLOCK (23h-24h)

By default at power-on, if LOCK is HIGH, all the blocks are locked and protected from PROGRAM and ERASE operations. The UNLOCK (23h) command is used to unlock a range of blocks. Unlocked blocks have no protection and can be programmed or erased.

The UNLOCK command uses two registers, a lower boundary block address register and an upper boundary block address register, and the invert area bit to determine what range of blocks are unlocked. When the invert area bit = 0, the range of blocks within the lower and upper boundary address registers are unlocked. When the invert area bit = 1, the range of blocks outside the boundaries of the lower and upper boundary address registers are unlocked. The lower boundary block address must be less than the upper boundary block address. The figures below show examples of how the lower and upper boundary address registers work with the invert area bit.

To unlock a range of blocks, issue the UNLOCK (23h) command followed by the appropriate address cycles that indicate the lower boundary block address. Then issue the 24h command followed by the appropriate address cycles that indicate the upper boundary block address. The least significant page address bit, PA0, should be set to 1 if setting the invert area bit; otherwise, it should be 0. The other page address bits should be 0.

Only one range of blocks can be specified in the lower and upper boundary block address registers. If after unlocking a range of blocks the UNLOCK command is again issued, the new block address range determines which blocks are unlocked. The previous unlocked block address range is not retained.



121-Ball NAND Flash with LPDDR2 MCP Block Lock Feature

Figure 44: Flash Array Protected: Invert Area Bit = 0

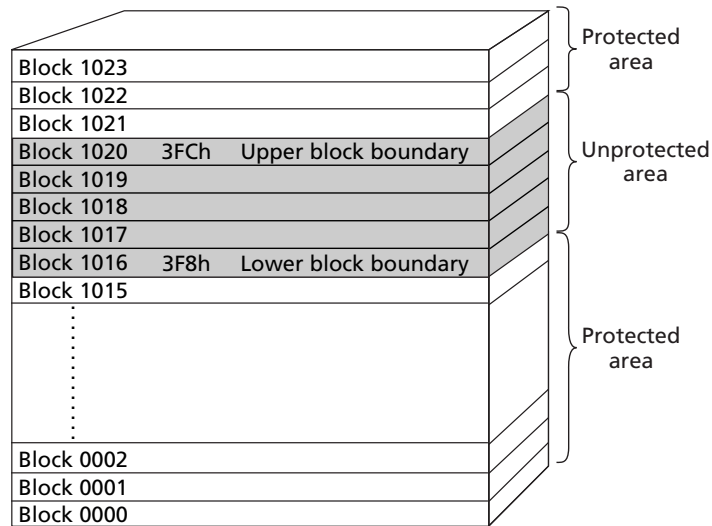
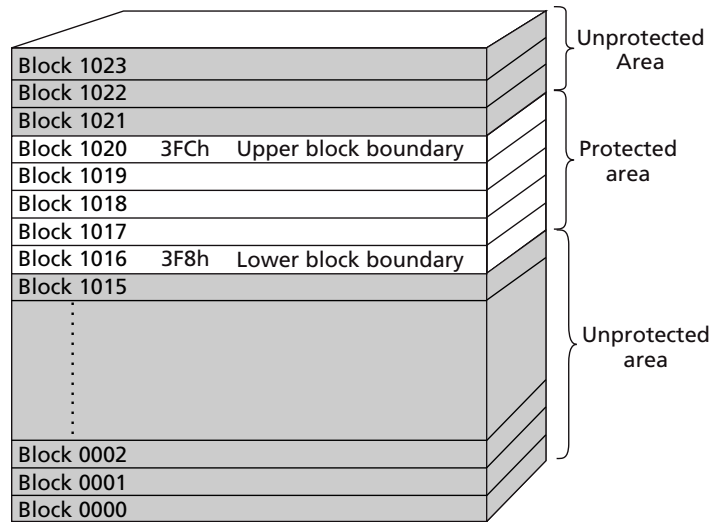


Figure 45: Flash Array Protected: Invert Area Bit = 1





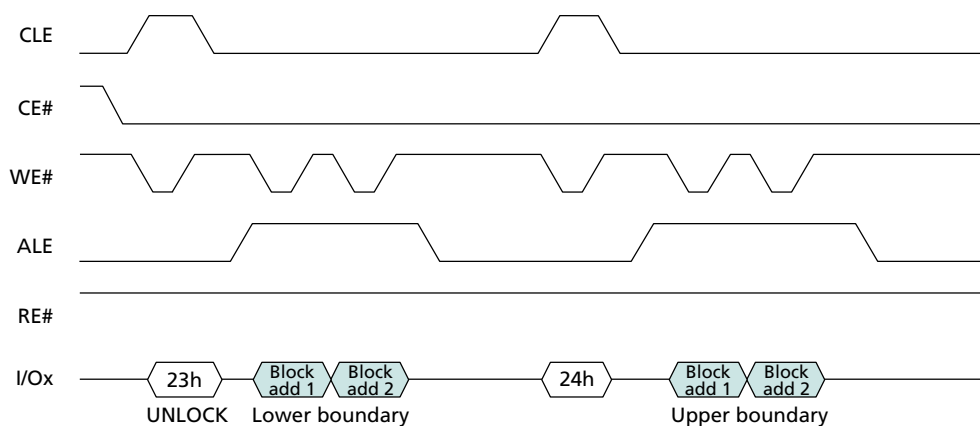
121-Ball NAND Flash with LPDDR2 MCP Block Lock Feature

Table 20: Block Lock Address Cycle Assignments

ALE Cycle	I/O[15:8] ¹	I/O7	I/O6	I/O5	I/O4	I/O3	I/O2	I/O1	I/O0
First	LOW	BA7	BA6	LOW	LOW	LOW	LOW	LOW	Invert area bit ²
Second	LOW	BA15	BA14	BA13	BA12	BA11	BA10	BA9	BA8

- Notes:
1. I/O[15:8] is applicable only for x16 devices.
 2. Invert area bit is applicable for 24h command; it may be LOW or HIGH for 23h command.

Figure 46: UNLOCK Operation





121-Ball NAND Flash with LPDDR2 MCP Block Lock Feature

LOCK (2Ah)

By default at power-on, if LOCK is HIGH, all the blocks are locked and protected from PROGRAM and ERASE operations. If portions of the device are unlocked using the UNLOCK (23h) command, they can be locked again using the LOCK (2Ah) command. The LOCK command locks all of the blocks in the device. Locked blocks are write-protected from PROGRAM and ERASE operations.

To lock all of the blocks in the device, issue the LOCK (2Ah) command.

When a PROGRAM or ERASE operation is issued to a locked block, R/B# goes LOW for t_{LBSY} . The PROGRAM or ERASE operation does not complete. Any READ STATUS command reports bit 7 as 0, indicating that the block is protected.

The LOCK (2Ah) command is disabled if LOCK is LOW at power-on or if the device is locked tight.

Figure 47: LOCK Operation





121-Ball NAND Flash with LPDDR2 MCP Block Lock Feature

LOCK TIGHT (2Ch)

The LOCK TIGHT (2Ch) command prevents locked blocks from being unlocked and also prevents unlocked blocks from being locked. When this command is issued, the UNLOCK (23h) and LOCK (2Ah) commands are disabled. This provides an additional level of protection against inadvertent PROGRAM and ERASE operations to locked blocks.

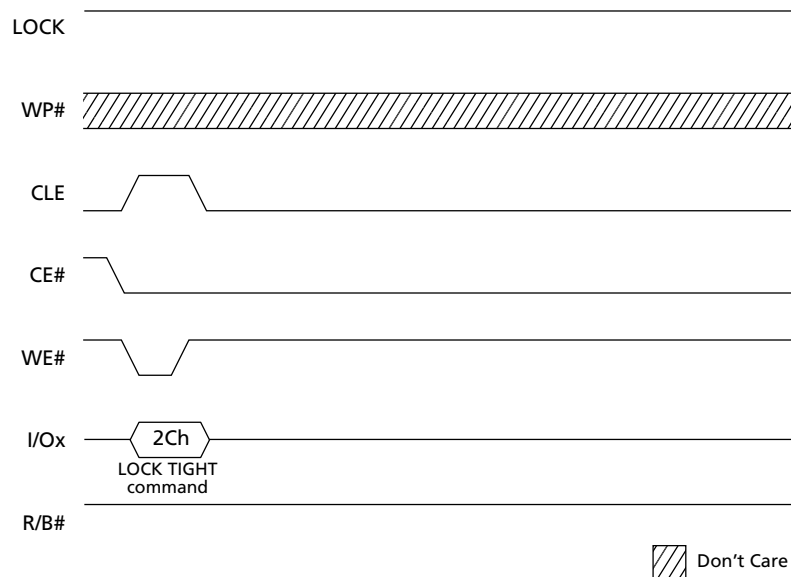
To implement LOCK TIGHT in all of the locked blocks in the device, verify that WP# is HIGH and then issue the LOCK TIGHT (2Ch) command.

When a PROGRAM or ERASE operation is issued to a locked block that has also been locked tight, R/B# goes LOW for t_{LBSY} . The PROGRAM or ERASE operation does not complete. The READ STATUS (70h) command reports bit 7 as 0, indicating that the block is protected. PROGRAM and ERASE operations complete successfully to blocks that were not locked at the time the LOCK TIGHT command was issued.

After the LOCK TIGHT command is issued, the command cannot be disabled via a software command. The only ways to disable the lock tight status is to power cycle the device. When the lock tight status is disabled, all of the blocks become locked, the same as if the LOCK (2Ah) command had been issued.

The LOCK TIGHT (2Ch) command is disabled if LOCK is LOW at power-on.

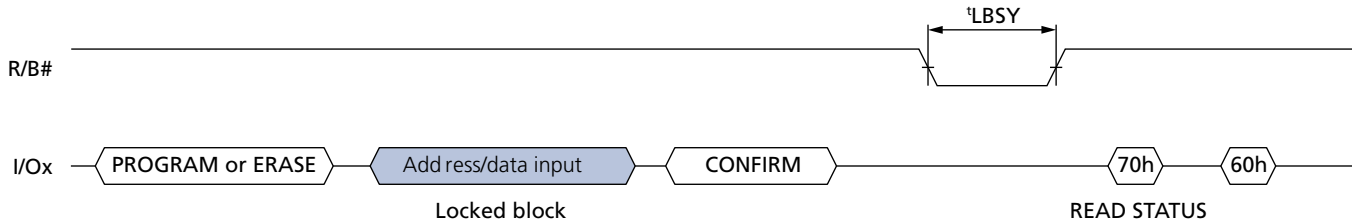
Figure 48: LOCK TIGHT Operation





121-Ball NAND Flash with LPDDR2 MCP Block Lock Feature

Figure 49: PROGRAM/ERASE Issued to Locked Block



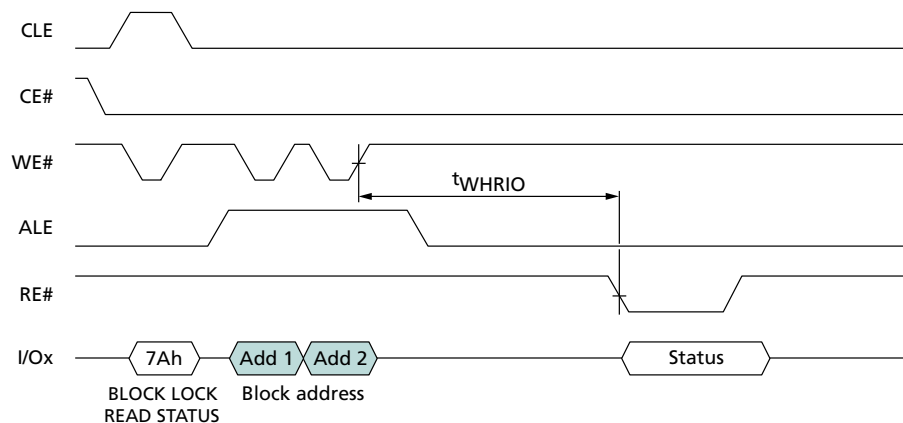
BLOCK LOCK READ STATUS (7Ah)

The BLOCK LOCK READ STATUS (7Ah) command is used to determine the protection status of individual blocks. The address cycles have the same format, as shown below, and the invert area bit should be set LOW. On the falling edge of RE# the I/O pins output the block lock status register, which contains the information on the protection status of the block.

Table 21: Block Lock Status Register Bit Definitions

Block Lock Status Register Definitions	I/O[7:3]	I/O2 (Lock#)	I/O1 (LT#)	I/O0 (LT)
Block is locked tight	X	0	0	1
Block is locked	X	0	1	0
Block is unlocked, and device is locked tight	X	1	0	1
Block is unlocked, and device is not locked tight	X	1	1	0

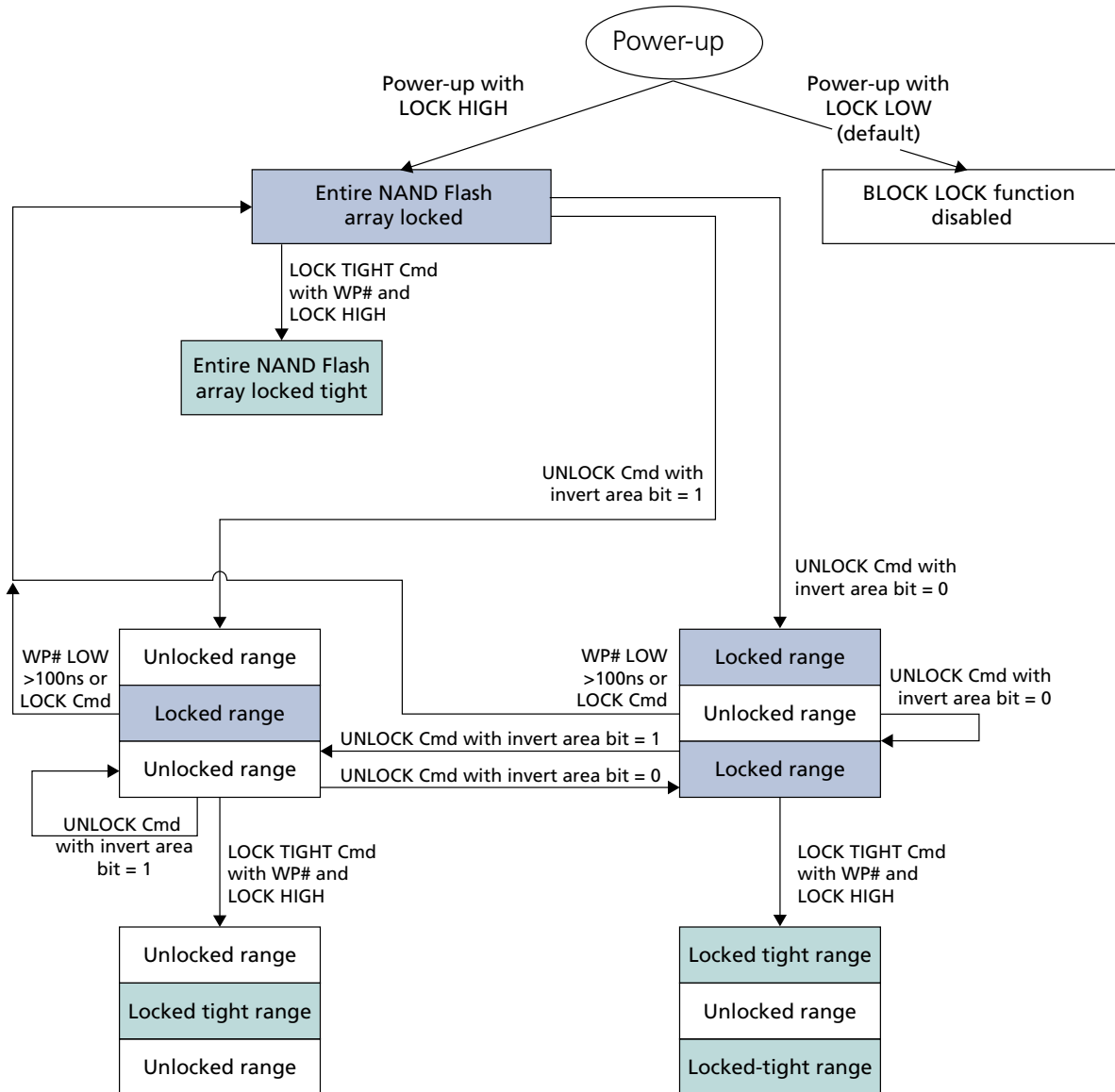
Figure 50: BLOCK LOCK READ STATUS





121-Ball NAND Flash with LPDDR2 MCP Block Lock Feature

Figure 51: BLOCK LOCK Flowchart





121-Ball NAND Flash with LPDDR2 MCP One-Time Programmable (OTP) Operations

One-Time Programmable (OTP) Operations

This Micron NAND Flash device offers a protected, one-time programmable NAND Flash memory area. Thirty full pages (2112 bytes per page) of OTP data are available on the device, and the entire range is guaranteed to be good. The OTP area is accessible only through the OTP commands. Customers can use the OTP area any way they choose; typical uses include programming serial numbers or other data for permanent storage.

The OTP area leaves the factory in an unwritten state (all bits are 1s). Programming or partial-page programming enables the user to program only 0 bits in the OTP area. The OTP area cannot be erased, whether it is protected or not. Protecting the OTP area prevents further programming of that area.

Micron provides a unique way to program and verify data before permanently protecting it and preventing future changes. The OTP area is only accessible while in OTP operation mode. To set the device to OTP operation mode, issue the SET FEATURE (EFh) command to feature address 90h and write 01h to P1, followed by three cycles of 00h to P2-P4. For parameters to enter OTP mode, see Features Operations.

When the device is in OTP operation mode, all subsequent PAGE READ (00h-30h) and PROGRAM PAGE (80h-10h) commands are applied to the OTP area. The OTP area is assigned to page addresses 02h-1Fh. To program an OTP page, issue the PROGRAM PAGE (80h-10h) command. The pages must be programmed in the ascending order. Similarly, to read an OTP page, issue the PAGE READ (00h-30h) command.

Protecting the OTP is done by entering OTP protect mode. To set the device to OTP protect mode, issue the SET FEATURE (EFh) command to feature address 90h and write 03h to P1, followed by three cycles of 00h to P2-P4.

To determine whether the device is busy during an OTP operation, either monitor R/B# or use the READ STATUS (70h) command.

To exit OTP operation or protect mode, write 00h to P1 at feature address 90h.



121-Ball NAND Flash with LPDDR2 MCP One-Time Programmable (OTP) Operations

OTP DATA PROGRAM (80h-10h)

The OTP DATA PROGRAM (80h-10h) command is used to write data to the pages within the OTP area. An entire page can be programmed at one time, or a page can be partially programmed up to eight times. Only the OTP area allows up to eight partial-page programs. The rest of the blocks support only four partial-page programs. There is no ERASE operation for OTP pages.

PROGRAM PAGE enables programming into an offset of an OTP page using two bytes of the column address (CA[12:0]). The command is compatible with the RANDOM DATA INPUT (85h) command. The PROGRAM PAGE command will not execute if the OTP area has been protected.

To use the PROGRAM PAGE command, issue the 80h command. Issue n address cycles. The first two address cycles are the column address. For the remaining cycles, select a page in the range of 02h-00h through 1Fh-00h. Next, write from 1–2112 bytes of data. After data input is complete, issue the 10h command. The internal control logic automatically executes the proper programming algorithm and controls the necessary timing for programming and verification.

R/B# goes LOW for the duration of the array programming time (t_{PROG}). The READ STATUS (70h) command is the only valid command for reading status in OTP operation mode. Bit 5 of the status register reflects the state of R/B#. When the device is ready, read bit 0 of the status register to determine whether the operation passed or failed (see Status Operations). Each OTP page can be programmed to 8 partial-page programming.

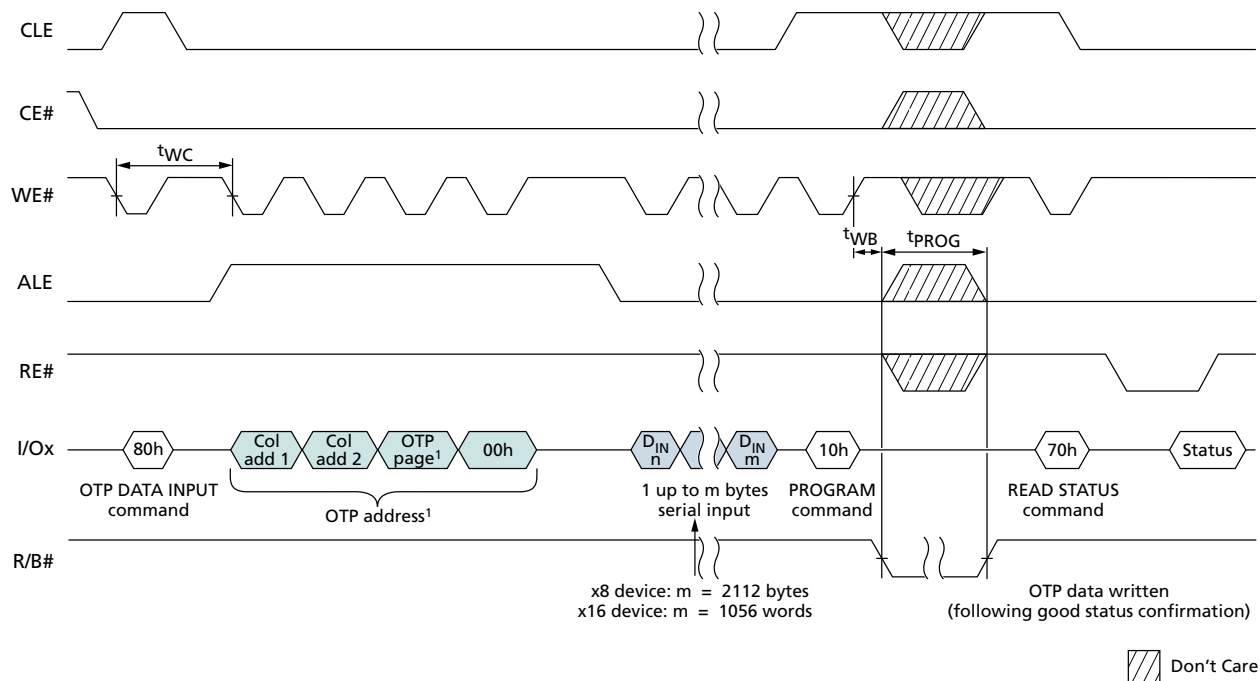


121-Ball NAND Flash with LPDDR2 MCP One-Time Programmable (OTP) Operations

RANDOM DATA INPUT (85h)

After the initial OTP data set is input, additional data can be written to a new column address with the RANDOM DATA INPUT (85h) command. The RANDOM DATA INPUT command can be used any number of times in the same page prior to the OTP PAGE WRITE (10h) command being issued.

Figure 52: OTP DATA PROGRAM (After Entering OTP Operation Mode)

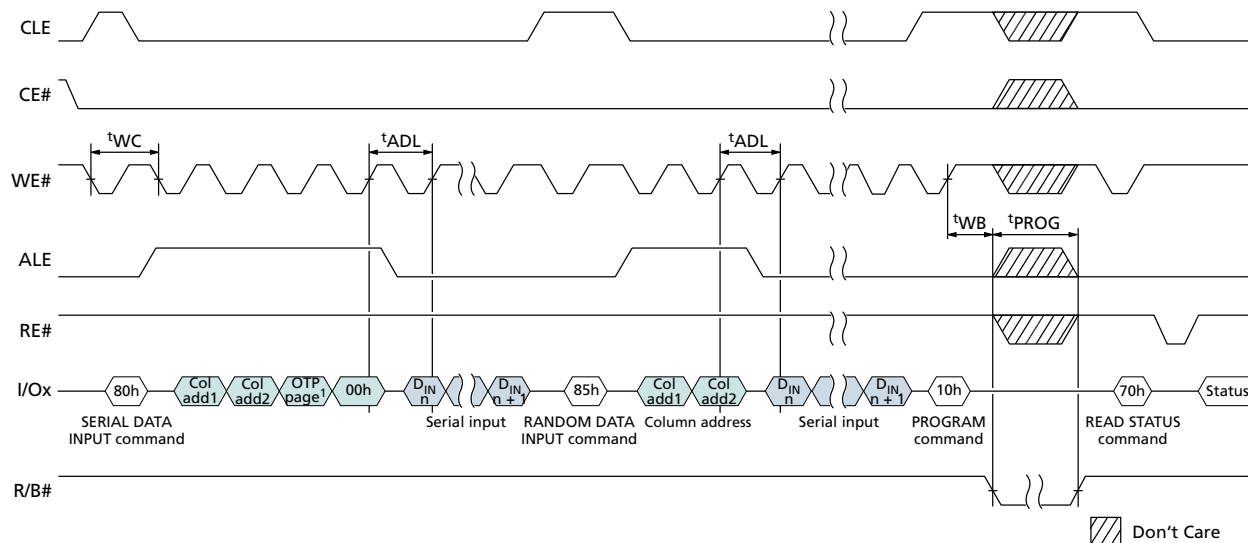


Note: 1. The OTP page must be within the 02h–1Fh range.



121-Ball NAND Flash with LPDDR2 MCP One-Time Programmable (OTP) Operations

Figure 53: OTP DATA PROGRAM Operation with RANDOM DATA INPUT (After Entering OTP Operation Mode)



Note: 1. The OTP page must be within the 02h–1Fh range.

OTP DATA PROTECT (80h-10h)

The OTP DATA PROTECT (80h-10h) command is used to prevent further programming of the pages in the OTP area. To protect the OTP area, the target must be in OTP operation mode.

To protect all data in the OTP area, issue the 80h command. Issue n address cycles including the column address, OTP protect page address and block address; the column and block addresses are fixed to 0. Next, write 00h data for the first byte location and issue the 10h command. R/B# goes LOW for the duration of the array programming time, t_{PROG} .

After the data is protected, it cannot be programmed further. When the OTP area is protected, the pages within the area are no longer programmable and cannot be unprotected.

The READ STATUS (70h) command is the only valid command for reading status in OTP operation mode. The RDY bit of the status register will reflect the state of R/B#. Use of the READ STATUS ENHANCED (78h) command is prohibited.

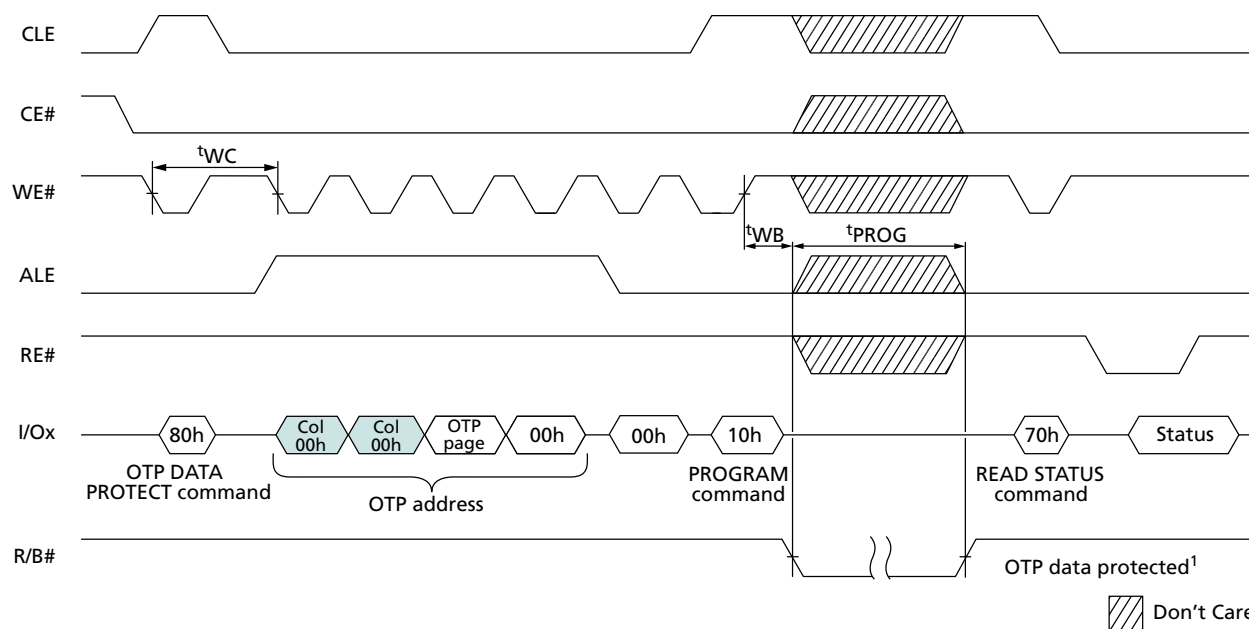
When the target is ready, read the FAIL bit of the status register to determine if the operation passed or failed.

If the OTP DATA PROTECT (80h-10h) command is issued after the OTP area has already been protected, R/B# goes LOW for t_{OBSY} . After t_{OBSY} , the status register is set to 60h.



121-Ball NAND Flash with LPDDR2 MCP One-Time Programmable (OTP) Operations

Figure 54: OTP DATA PROTECT Operation (After Entering OTP Protect Mode)



Note: 1. OTP data is protected following a good status confirmation.



121-Ball NAND Flash with LPDDR2 MCP One-Time Programmable (OTP) Operations

OTP DATA READ (00h-30h)

To read data from the OTP area, set the device to OTP operation mode, then issue the PAGE READ (00h-30h) command. Data can be read from OTP pages within the OTP area whether the area is protected or not.

To use the PAGE READ command for reading data from the OTP area, issue the 00h command, and then issue five address cycles: for the first two cycles, the column address; and for the remaining address cycles, select a page in the range of 02h-00h-00h through 1Fh-00h-00h. Lastly, issue the 30h command. The PAGE READ CACHE MODE command is not supported on OTP pages.

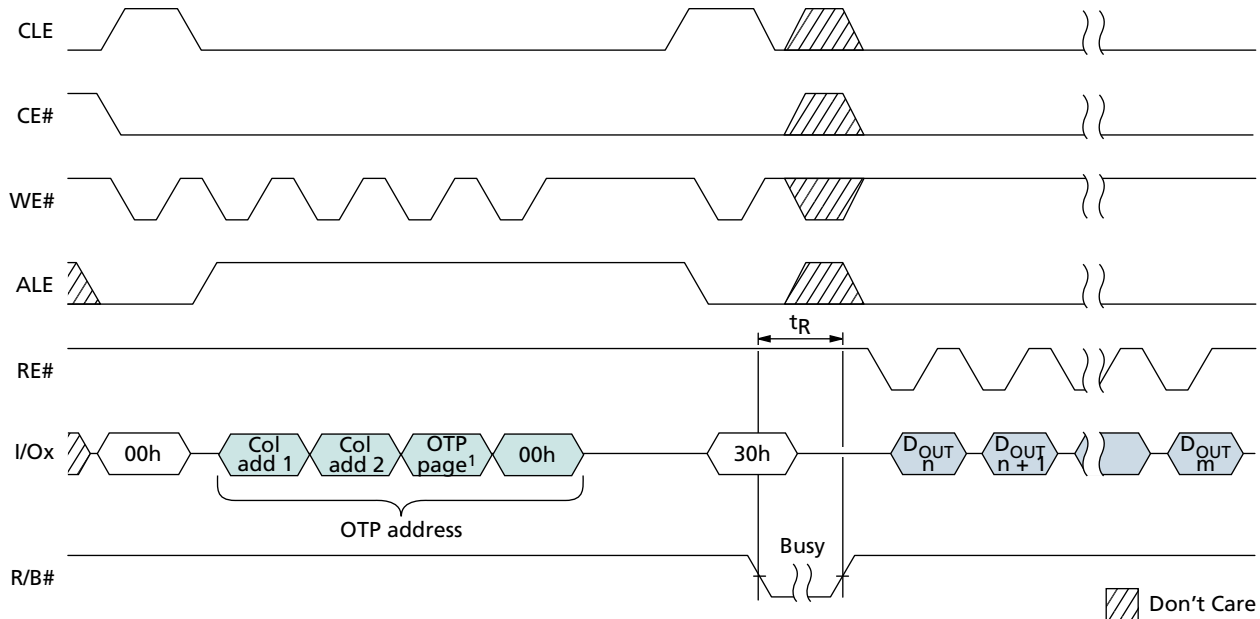
R/B# goes LOW ('R') while the data is moved from the OTP page to the data register. The READ STATUS (70h) command is the only valid command for reading status in OTP operation mode. Bit 5 of the status register reflects the state of R/B# (see Status Operations).

Normal READ operation timings apply to OTP read accesses. Additional pages within the OTP area can be selected by repeating the OTP DATA READ command.

The PAGE READ command is compatible with the RANDOM DATA OUTPUT (05h-E0h) command.

Only data on the current page can be read. Pulsing RE# outputs data sequentially.

Figure 55: OTP DATA READ

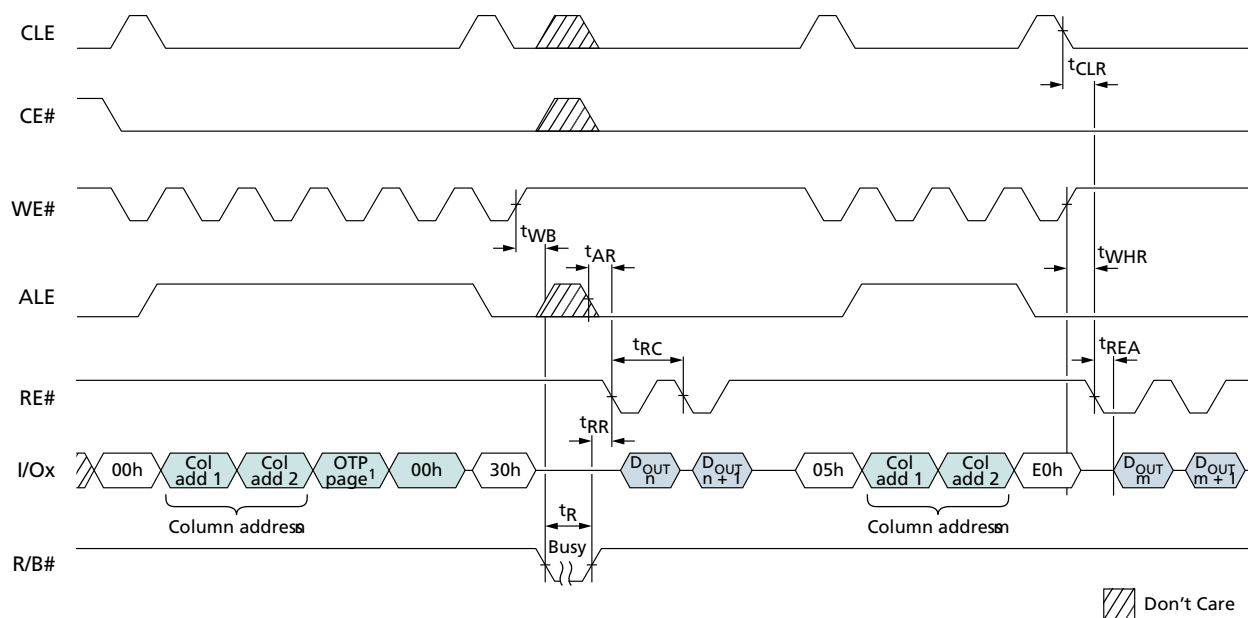


Note: 1. The OTP page must be within the 02h-1Fh range.



121-Ball NAND Flash with LPDDR2 MCP One-Time Programmable (OTP) Operations

Figure 56: OTP DATA READ with RANDOM DATA READ Operation



Note: 1. The OTP page must be within the range 02h–1Fh.



121-Ball NAND Flash with LPDDR2 MCP Error Management

Error Management

Each NAND Flash die (LUN) is specified to have a minimum number of valid blocks (NVB) of the total available blocks. This means the die (LUNs) could have blocks that are invalid when shipped from the factory. An invalid block is one that contains at least one page that has more bad bits than can be corrected by the minimum required ECC. Additional blocks can develop with use. However, the total number of available blocks per die (LUN) will not fall below NVB during the endurance life of the product.

Although NAND Flash memory devices could contain bad blocks, they can be used quite reliably in systems that provide bad block management and error-correction algorithms. This type of software environment ensures data integrity.

Internal circuitry isolates each block from other blocks, so the presence of a bad block does not affect the operation of the rest of the NAND Flash array.

NAND Flash devices are shipped from the factory erased. The factory identifies invalid blocks before shipping by attempting to program the bad block mark into every location in the first page of each invalid block. It may not be possible to program every location with the bad block mark. However, the first spare area location in each bad block is guaranteed to contain the bad block mark. This method is compliant with ONFI Factory Defect Mapping requirements. See the following table for the first spare area location and the bad block mark.

System software should check the first spare area location on the first page of each block prior to performing any PROGRAM or ERASE operations on the NAND Flash device. A bad block table can then be created, enabling system software to map around these areas. Factory testing is performed under worst-case conditions. Because invalid blocks could be marginal, it may not be possible to recover this information if the block is erased.

Over time, some memory locations may fail to program or erase properly. In order to ensure that data is stored properly over the life of the NAND Flash device, the following precautions are required:

- Always check status after a PROGRAM or ERASE operation
- Under typical conditions, use the minimum required ECC (see table below)
- Use bad block management and wear-leveling algorithms

The first block (physical block address 00h) for each CE# is guaranteed to be valid with ECC when shipped from the factory.

Table 22: Error Management Details

Description	Requirement
Minimum number of valid blocks (NVB) per LUN	1004
Total available blocks per LUN	1024
First spare area location	x8: byte 2048 x16: word 1024
Bad-block mark	x8: 00h x16: 0000h
Minimum required ECC	4-bit ECC per 528 bytes of data
Minimum required ECC for block 0 if PROGRAM/ERASE cycles are less than 1000	1-bit ECC per 528 bytes



121-Ball NAND Flash with LPDDR2 MCP Electrical Specifications

Electrical Specifications

Stresses greater than those listed can cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not guaranteed. Exposure to absolute maximum rating conditions for extended periods can affect reliability.

Table 23: Absolute Maximum Ratings

Voltage on any pin relative to V_{SS}

Parameter/Condition		Symbol	Min	Max	Unit
Voltage Input	3.3V	V_{IN}	-0.6	4.6	V
	1.8V		-0.6	2.4	V
V_{CC} supply voltage	3.3V	V_{CC}	-0.6	4.6	V
	1.8V		-0.6	2.4	V
Storage temperature		T_{STG}	-65	150	°C
Short circuit output current, I/Os		—	—	5	mA

Table 24: Recommended Operating Conditions

Parameter/Condition		Symbol	Min	Typ	Max	Unit
Operating temperature	Commercial	T_A	0	—	70	°C
	Industrial		-40	—	85	°C
V_{CC} supply voltage	3.3V	V_{CC}	2.7	3.3	3.6	V
	1.8V		1.7	1.8	1.95	V
Ground supply voltage		V_{SS}	0	0	0	V

Table 25: Valid Blocks

Parameter	Symbol	Device	Min	Max	Unit	Notes
Valid block number	NVB	3.3V/1.8V	1004	1024	blocks	1

Note: 1. Invalid blocks are blocks that contain one or more bad bits. The device may contain bad blocks upon shipment. Additional bad blocks may develop over time; however, the total number of available blocks will not drop below NVB during the endurance life of the device. Do not erase or program blocks marked invalid by the factory.



121-Ball NAND Flash with LPDDR2 MCP Electrical Specifications

Table 26: Capacitance

Description	Symbol	Max	Unit	Notes
Input capacitance	C_{IN}	10	pF	1, 2
Input/output capacitance (I/O)	C_{IO}	10	pF	1, 2

Notes: 1. These parameters are verified in device characterization and are not 100% tested.
2. Test conditions: $T_C = 25^\circ\text{C}$; $f = 1\text{ MHz}$; $V_{IN} = 0\text{V}$.

Table 27: Test Conditions

Parameter		Value	Notes
Input pulse levels		0.0V to V_{CC}	
Input rise and fall times		5ns	
Input and output timing levels		$V_{CC}/2$	
Output load	3.3V	1 TTL GATE and $CL = 30\text{pF}$	1
	1.8V	1 TTL GATE and $CL = 30\text{pF}$	1

Note: 1. These parameters are verified in device characterization and are not 100% tested.



121-Ball NAND Flash with LPDDR2 MCP

Electrical Specifications – AC Characteristics and Operating Conditions

Electrical Specifications – AC Characteristics and Operating Conditions

Table 28: AC Characteristics: Command, Data, and Address Input (3.3V)

Note 1 applies to all

Parameter	Symbol	Min	Max	Unit	Notes
ALE to data start	t_{ADL}	70	–	ns	2
ALE hold time	t_{ALH}	5	–	ns	
ALE setup time	t_{ALS}	10	–	ns	
CE# hold time	t_{CH}	5	–	ns	
CLE hold time	t_{CLH}	5	–	ns	
CLE setup time	t_{CLS}	10	–	ns	
CE# setup time	t_{CS}	15	–	ns	
Data hold time	t_{DH}	5	–	ns	
Data setup time	t_{DS}	7	–	ns	
WRITE cycle time	t_{WC}	20	–	ns	2
WE# pulse width HIGH	t_{WH}	7	–	ns	2
WE# pulse width	t_{WP}	10	–	ns	2
WP# transition to WE# LOW	t_{WW}	100	–	ns	

- Notes:
1. Operating mode timings meet ONFI timing mode 5 parameters.
 2. Timing for t_{ADL} begins in the address cycle, on the final rising edge of WE#, and ends with the first rising edge of WE# for data input.

Table 29: AC Characteristics: Command, Data, and Address Input (1.8V)

Note 1 applies to all

Parameter	Symbol	Min	Max	Unit	Notes
ALE to data start	t_{ADL}	70	–	ns	2
ALE hold time	t_{ALH}	5	–	ns	
ALE setup time	t_{ALS}	10	–	ns	
CE# hold time	t_{CH}	5	–	ns	
CLE hold time	t_{CLH}	5	–	ns	
CLE setup time	t_{CLS}	10	–	ns	
CE# setup time	t_{CS}	20	–	ns	
Data hold time	t_{DH}	5	–	ns	
Data setup time	t_{DS}	10	–	ns	
WRITE cycle time	t_{WC}	25	–	ns	2
WE# pulse width HIGH	t_{WH}	10	–	ns	2
WE# pulse width	t_{WP}	12	–	ns	2
WP# transition to WE# LOW	t_{WW}	100	–	ns	

- Notes:
1. Operating mode timings meet ONFI timing mode 4 parameters.
 2. Timing for t_{ADL} begins in the address cycle on the final rising edge of WE#, and ends with the first rising edge of WE# for data input.



121-Ball NAND Flash with LPDDR2 MCP

Electrical Specifications – AC Characteristics and Operating Conditions

Table 30: AC Characteristics: Normal Operation (3.3V)

Note 1 applies to all

Parameter	Symbol	Min	Max	Unit	Notes
ALE to RE# delay	t_{AR}	10	–	ns	
CE# access time	t_{CEA}	–	25	ns	
CE# HIGH to output High-Z	t_{CHZ}	–	50	ns	2
CLE to RE# delay	t_{CLR}	10	–	ns	
CE# HIGH to output hold	t_{COH}	15	–	ns	
Output High-Z to RE# LOW	t_{IR}	0	–	ns	
READ cycle time	t_{RC}	20	–	ns	
RE# access time	t_{REA}	–	16	ns	
RE# HIGH hold time	t_{REH}	7	–	ns	
RE# HIGH to output hold	t_{RHOH}	15	–	ns	
RE# HIGH to WE# LOW	t_{RHW}	100	–	ns	
RE# HIGH to output High-Z	t_{RHZ}	–	100	ns	2
RE# LOW to output hold	t_{RLOH}	5	–	ns	
RE# pulse width	t_{RP}	10	–	ns	
Ready to RE# LOW	t_{RR}	20	–	ns	
Reset time (READ/PROGRAM/ERASE)	t_{RST}	–	5/10/500	μ s	3
WE# HIGH to busy	t_{WB}	–	100	ns	
WE# HIGH to RE# LOW	t_{WHR}	60	–	ns	

- Notes:
1. AC characteristics may need to be relaxed if I/O drive strength is not set to full.
 2. Transition is measured ± 200 mV from steady-state voltage with load. This parameter is sampled and not 100% tested.
 3. The first time the RESET (FFh) command is issued while the device is idle, the device will go busy for a maximum of 1ms. Thereafter, the device goes busy for a maximum of 5 μ s.

Table 31: AC Characteristics: Normal Operation (1.8V)

Note 1 applies to all

Parameter	Symbol	Min	Max	Unit	Notes
ALE to RE# delay	t_{AR}	10	–	ns	
CE# access time	t_{CEA}	–	25	ns	
CE# HIGH to output High-Z	t_{CHZ}	–	50	ns	2
CLE to RE# delay	t_{CLR}	10	–	ns	
CE# HIGH to output hold	t_{COH}	15	–	ns	
Output High-Z to RE# LOW	t_{IR}	0	–	ns	
READ cycle time	t_{RC}	25	–	ns	
RE# access time	t_{REA}	–	22	ns	
RE# HIGH hold time	t_{REH}	10	–	ns	
RE# HIGH to output hold	t_{RHOH}	15	–	ns	
RE# HIGH to WE# LOW	t_{RHW}	100	–	ns	



121-Ball NAND Flash with LPDDR2 MCP

Electrical Specifications – AC Characteristics and Operating Conditions

Table 31: AC Characteristics: Normal Operation (1.8V) (Continued)

Note 1 applies to all

Parameter	Symbol	Min	Max	Unit	Notes
RE# HIGH to output High-Z	t_{RHZ}	–	65	ns	2
RE# LOW to output hold	t_{RLOH}	3	–	ns	
RE# pulse width	t_{RP}	12	–	ns	
Ready to RE# LOW	t_{RR}	20	–	ns	
Reset time (READ/PROGRAM/ERASE)	t_{RST}	–	5/10/500	μs	3
WE# HIGH to busy	t_{WB}	–	100	ns	
WE# HIGH to RE# LOW	t_{WHR}	80	–	ns	

- Notes:
1. AC characteristics may need to be relaxed if I/O drive strength is not set to full.
 2. Transition is measured $\pm 200\text{mV}$ from steady-state voltage with load. This parameter is sampled and not 100% tested.
 3. The first time the RESET (FFh) command is issued while the device is idle, the device will be busy for a maximum of 1ms. Thereafter, the device is busy for a maximum of 5 μs .



121-Ball NAND Flash with LPDDR2 MCP

Electrical Specifications – DC Characteristics and Operating Conditions

Electrical Specifications – DC Characteristics and Operating Conditions

Table 32: DC Characteristics and Operating Conditions (3.3V)

Parameter	Conditions	Symbol	Min	Typ	Max	Unit	Notes
Sequential READ current	$t_{RC} = t_{RC} \text{ (MIN)}; CE\# = V_{IL}; I_{OUT} = 0\text{mA}$	I_{CC1}	–	25	35	mA	
PROGRAM current	–	I_{CC2}	–	25	35	mA	
ERASE current	–	I_{CC3}	–	25	35	mA	
Standby current (TTL)	$CE\# = V_{IH}; WP\# = 0V/V_{CC}$	I_{SB1}	–	–	1	mA	
Standby current (CMOS)	$CE\# = V_{CC} - 0.2V; WP\# = 0V/V_{CC}$	I_{SB2}	–	20	100	μA	
Staggered power-up current	Rise time = 1ms Line capacitance = $0.1\mu\text{F}$	I_{ST}	–	–	10 per die	mA	1
Input leakage current	$V_{IN} = 0V \text{ to } V_{CC}$	I_{LI}	–	–	± 10	μA	
Output leakage current	$V_{OUT} = 0V \text{ to } V_{CC}$	I_{LO}	–	–	± 10	μA	
Input high voltage	I/O[7:0], I/O[15:0], CE#, CLE, ALE, WE#, RE#, WP#	V_{IH}	$0.8 \times V_{CC}$	–	$V_{CC} + 0.3$	V	
Input low voltage, all inputs	–	V_{IL}	-0.3	–	$0.2 \times V_{CC}$	V	
Output high voltage	$I_{OH} = -400\mu\text{A}$	V_{OH}	$0.67 \times V_{CC}$	–	–	V	3
Output low voltage	$I_{OL} = 2.1\text{mA}$	V_{OL}	–	–	0.4	V	3
Output low current	$V_{OL} = 0.4V$	$I_{OL} \text{ (R/B\#)}$	8	10	–	mA	2

- Notes:
1. Measurement is taken with 1ms averaging intervals and begins after V_{CC} reaches $V_{CC}(\text{MIN})$.
 2. $I_{OL} \text{ (R/B\#)}$ may need to be relaxed if R/B pull-down strength is not set to full.
 3. V_{OH} and V_{OL} may need to be relaxed if I/O drive strength is not set to full.



121-Ball NAND Flash with LPDDR2 MCP

Electrical Specifications – DC Characteristics and Operating Conditions

Table 33: DC Characteristics and Operating Conditions (1.8V)

Parameter	Conditions	Symbol	Min	Typ	Max	Unit	Notes
Sequential READ current	$t_{RC} = t_{RC}(\text{MIN}); CE\# = V_{IL}; I_{OUT} = 0\text{mA}$	I_{CC1}	–	13	20	mA	1, 2
PROGRAM current	–	I_{CC2}	–	10	20	mA	1, 2
ERASE current	–	I_{CC3}	–	10	20	mA	1, 2
Standby current (TTL)	$CE\# = V_{IH}; WP\# = 0V/V_{CC}$	I_{SB1}	–	–	1	mA	
Standby current (CMOS)	$CE\# = V_{CC} - 0.2V; WP\# = 0V/V_{CC}$	I_{SB2}	–	10	50	μA	
Staggered power-up current	Rise time = 1ms Line capacitance = 0.1 μF	I_{ST}	–	–	10 per die	mA	3
Input leakage current	$V_{IN} = 0V \text{ to } V_{CC}$	I_{LI}	–	–	± 10	μA	
Output leakage current	$V_{OUT} = 0V \text{ to } V_{CC}$	I_{LO}	–	–	± 10	μA	
Input high voltage	I/O[7:0], I/O[15:0], CE#, CLE, ALE, WE#, RE#, WP#	V_{IH}	$0.8 \times V_{CC}$	–	$V_{CC} + 0.3$	V	
Input low voltage, all inputs	–	V_{IL}	–0.3	–	$0.2 \times V_{CC}$	V	
Output high voltage	$I_{OH} = -100\mu\text{A}$	V_{OH}	$V_{CC} - 0.1$	–	–	V	4
Output low voltage	$I_{OL} = +100\mu\text{A}$	V_{OL}	–	–	0.1	V	4
Output low current (R/B#)	$V_{OL} = 0.2V$	$I_{OL}(\text{R/B}\#)$	3	4	–	mA	5

- Notes:
1. Typical and maximum values are for single-plane operation only.
 2. Values are for single-die operations. Values could be higher for interleaved-die operations.
 3. Measurement is taken with 1ms averaging intervals and begins after V_{CC} reaches $V_{CC}(\text{MIN})$.
 4. Test conditions for V_{OH} and V_{OL} .
 5. DC characteristics may need to be relaxed if R/B# pull-down strength is not set to full.



121-Ball NAND Flash with LPDDR2 MCP

Electrical Specifications – Program/Erase Characteristics

Electrical Specifications – Program/Erase Characteristics

Table 34: Program/Erase Characteristics

Parameter	Symbol	Typ	Max	Unit	Notes
Number of partial-page programs	NOP	–	4	cycles	
BLOCK ERASE operation time	t_{BERS}	0.7	3	ms	
Busy time for PROGRAM CACHE operation	t_{CBSY}	3	600	μs	2
Cache read busy time	t_{RCBSY}	3	25	μs	
Busy time for SET FEATURES and GET FEATURES operations	t_{FEAT}	–	1	μs	
Busy time for OTP DATA PROGRAM operation if OTP is protected	t_{OBSY}	–	30	μs	
PROGRAM PAGE operation time	t_{PROG}	200	600	μs	3
Data transfer from Flash array to data register	t_R	–	25	μs	4

- Notes:
1. Applies to entire table: Typical is nominal voltage and room temperature.
 2. t_{CBSY} MAX time depends on timing between internal program completion and data-in.
 3. Typical program time is defined as the time within which more than 50% of the pages are programmed at nominal voltage and room temperature.
 4. AC characteristics may need to be relaxed if I/O drive strength is not set to full.



121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

Asynchronous Interface Timing Diagrams

Figure 57: RESET Operation

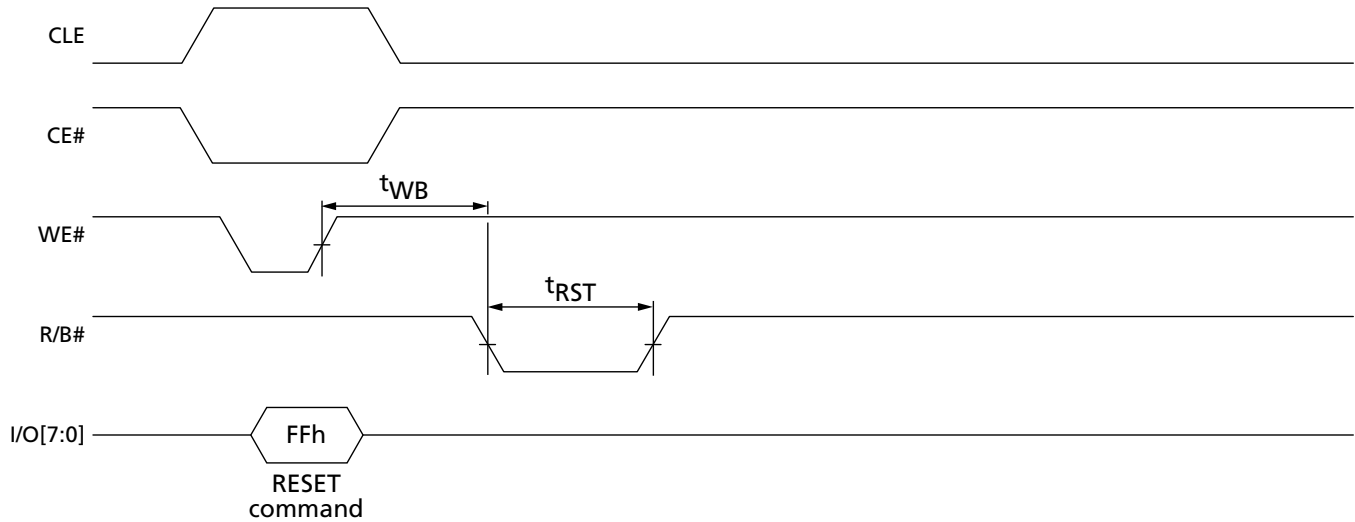
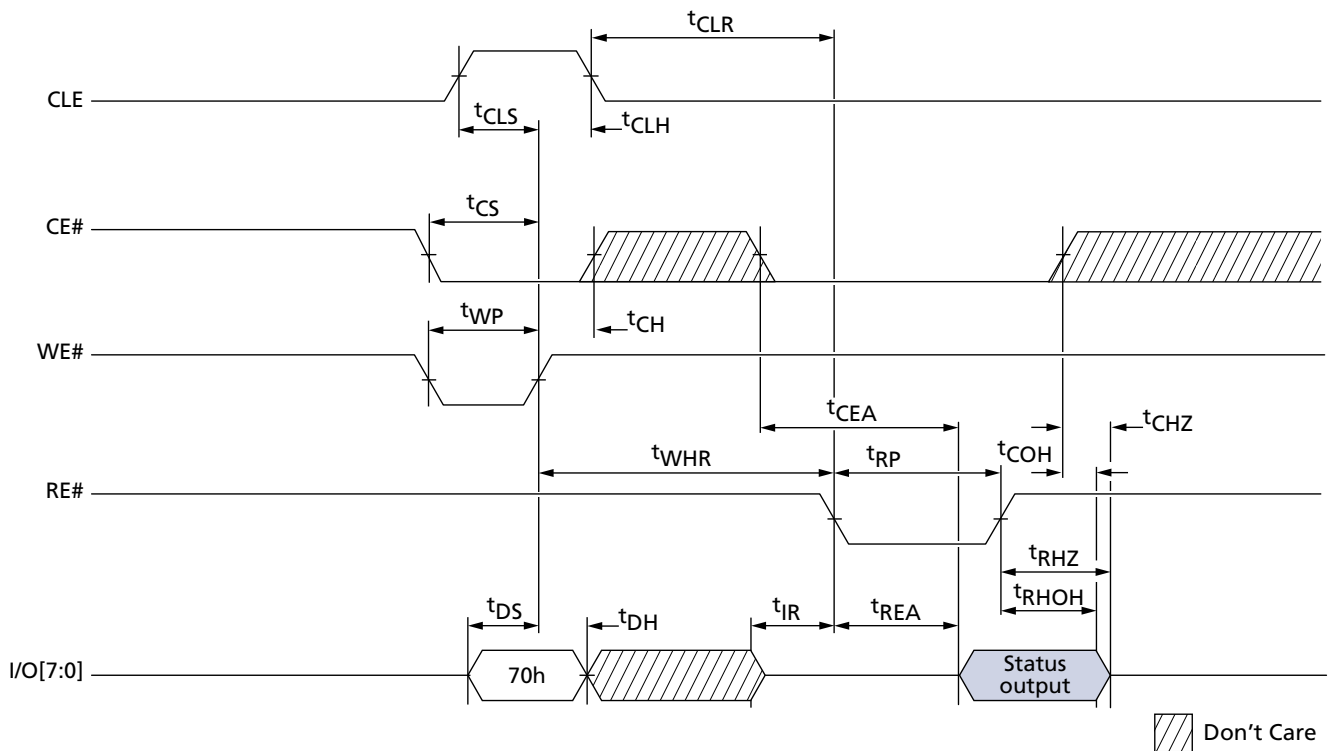


Figure 58: READ STATUS Cycle





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

Figure 59: READ PARAMETER PAGE

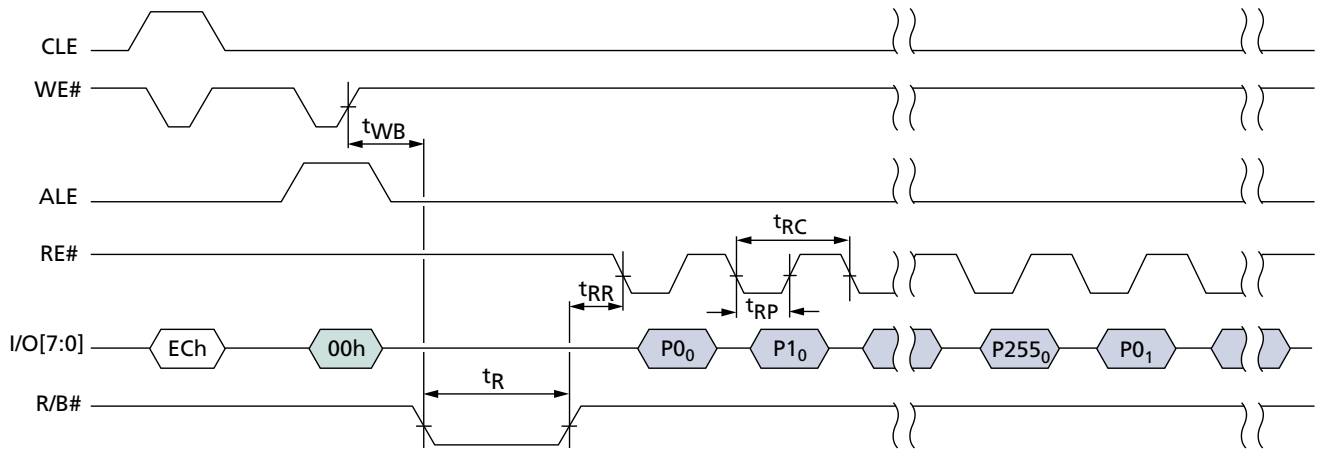
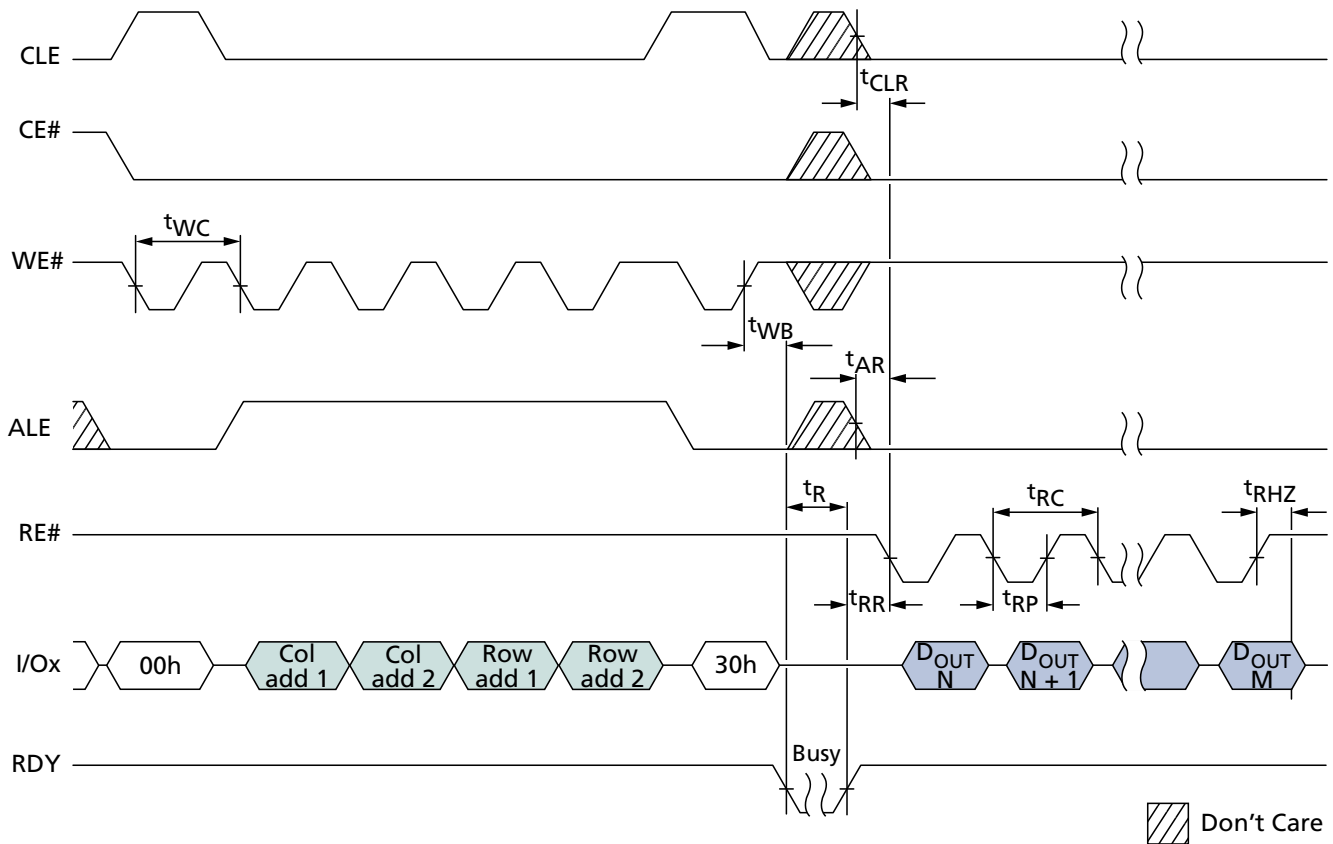


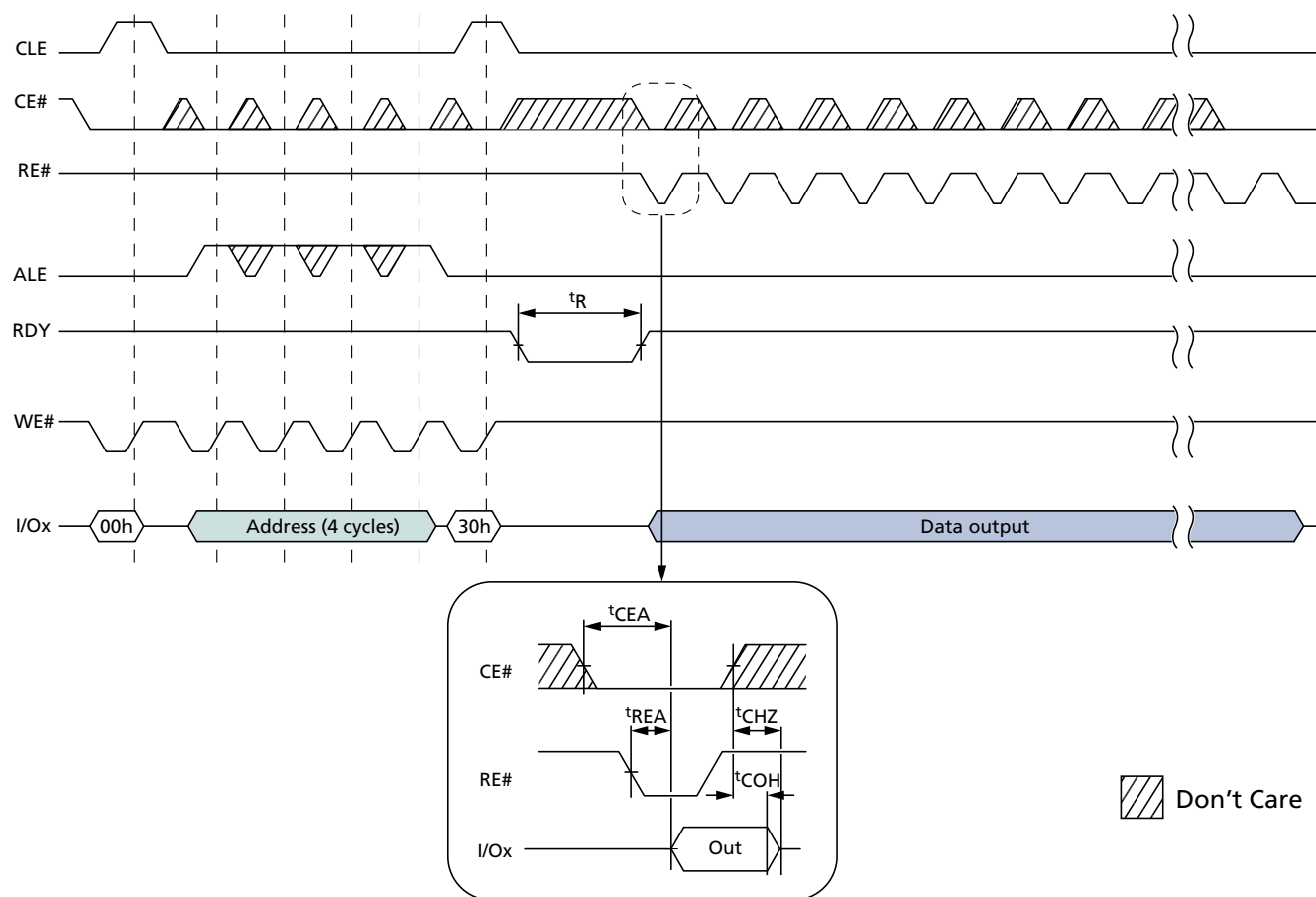
Figure 60: READ PAGE





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

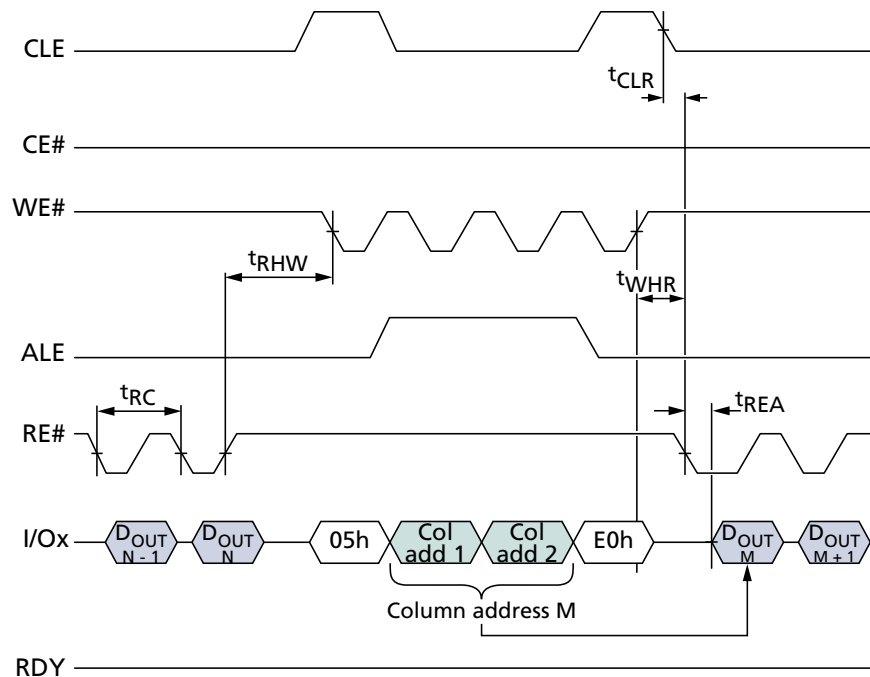
Figure 61: READ PAGE Operation with CE# "Don't Care"





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

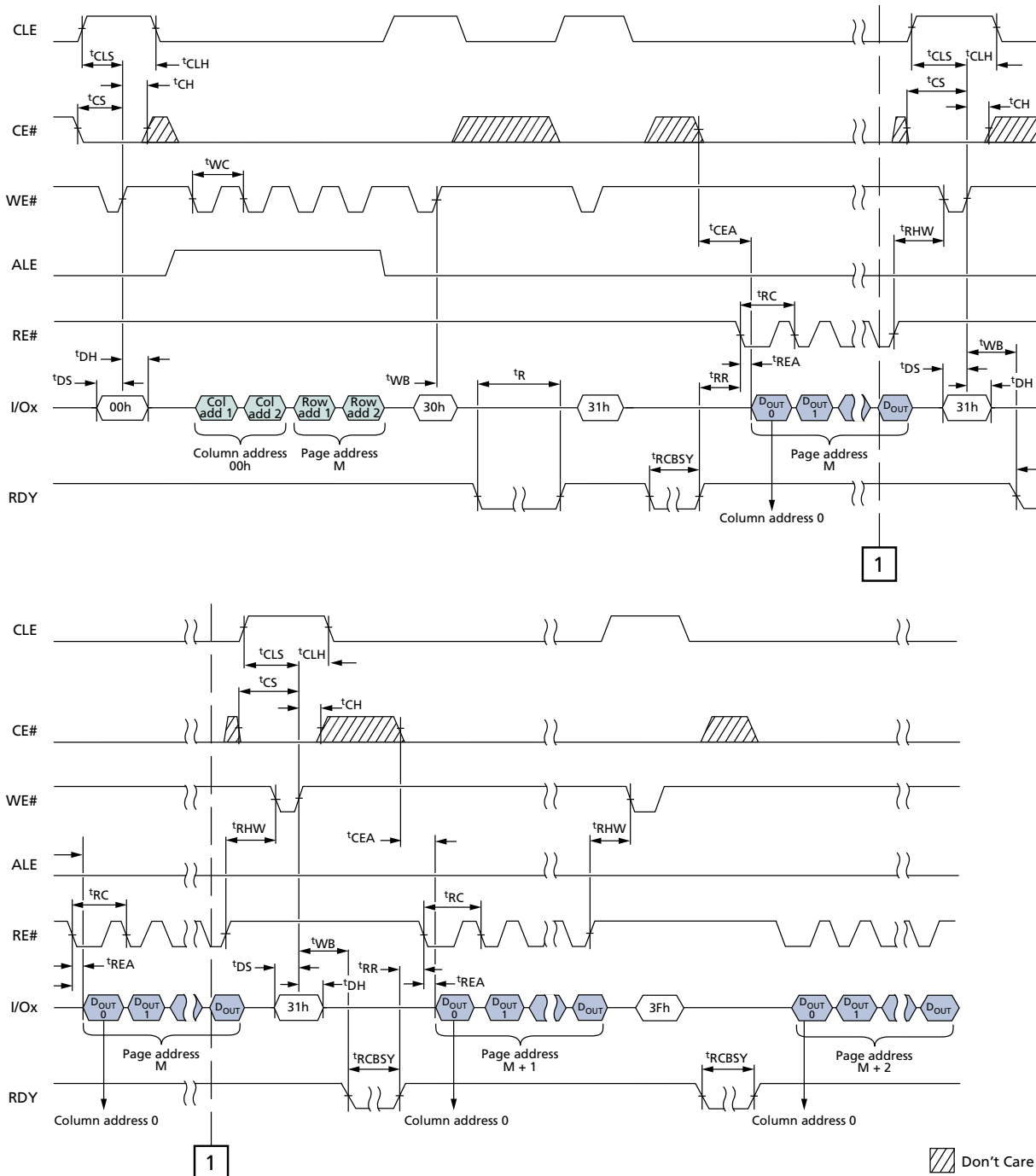
Figure 62: RANDOM DATA READ





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

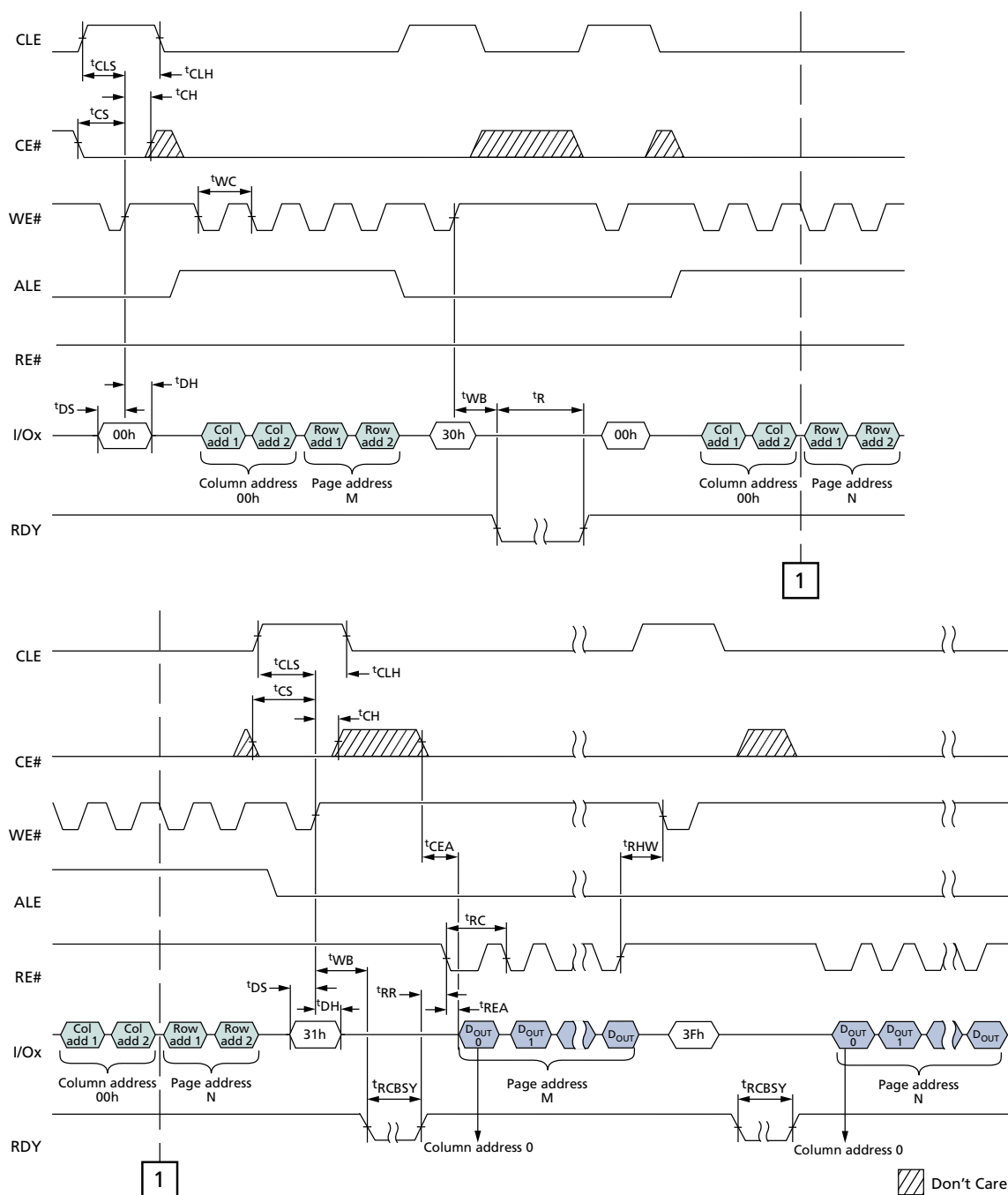
Figure 63: READ PAGE CACHE SEQUENTIAL





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

Figure 64: READ PAGE CACHE RANDOM





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

Figure 65: READ ID Operation

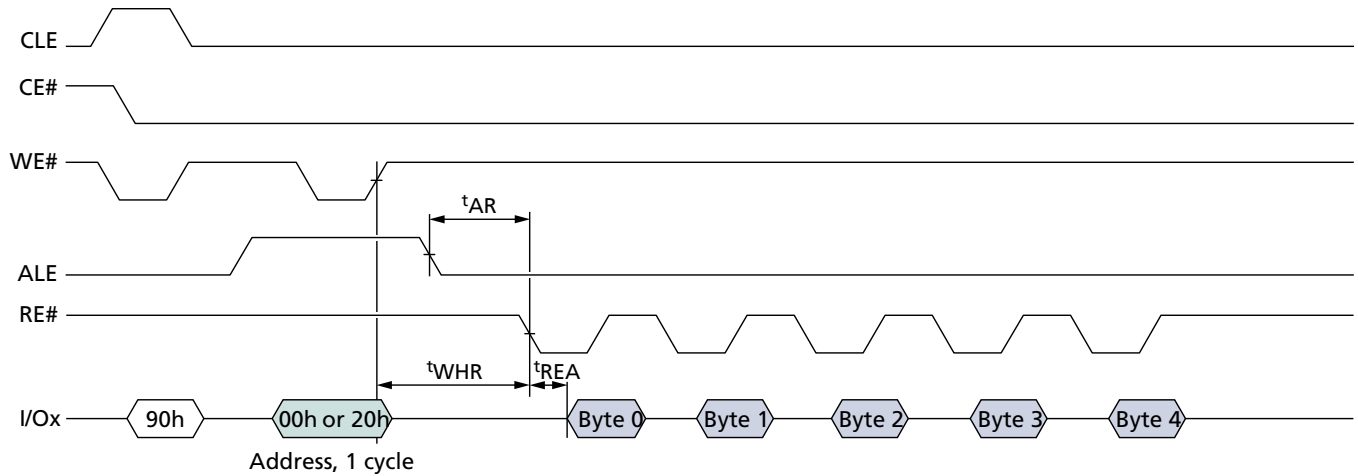
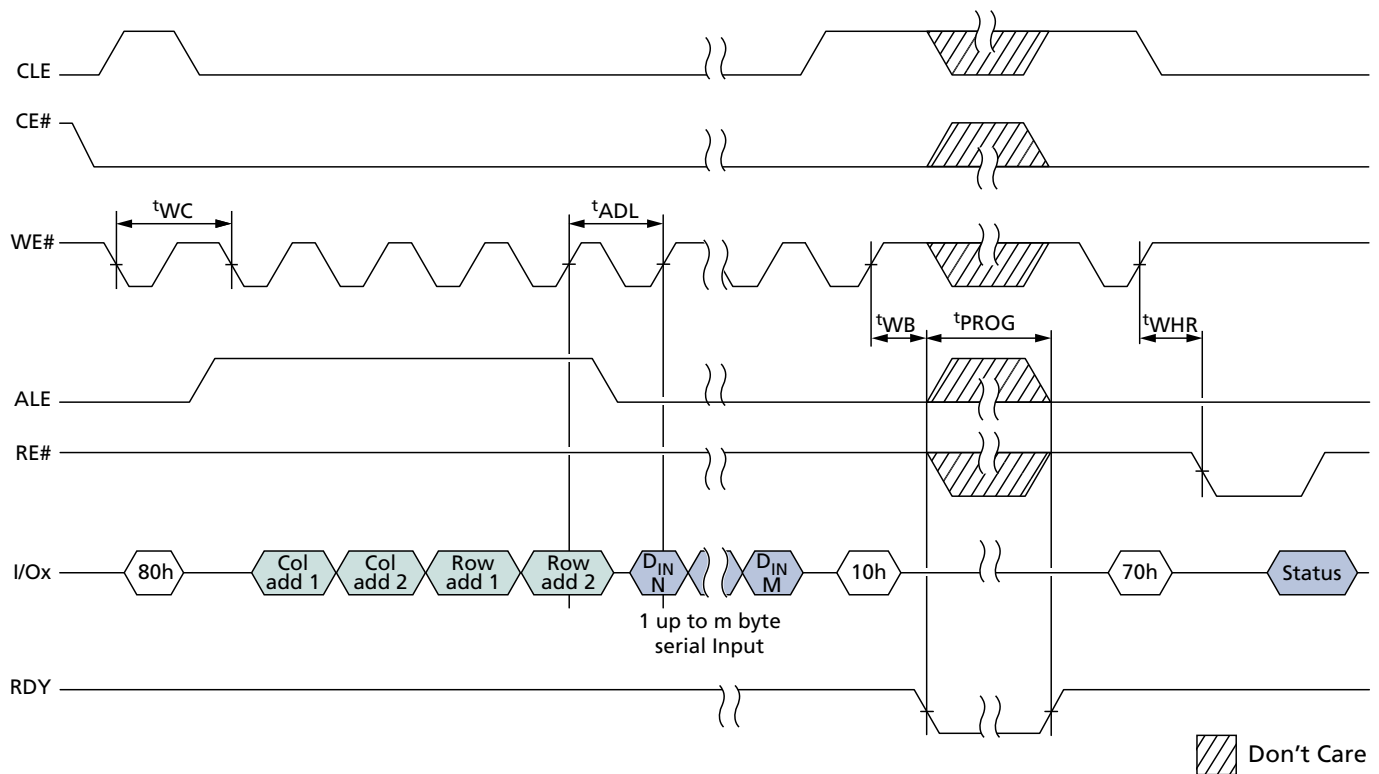


Figure 66: PROGRAM PAGE Operation





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

Figure 67: PROGRAM PAGE Operation with CE# "Don't Care"

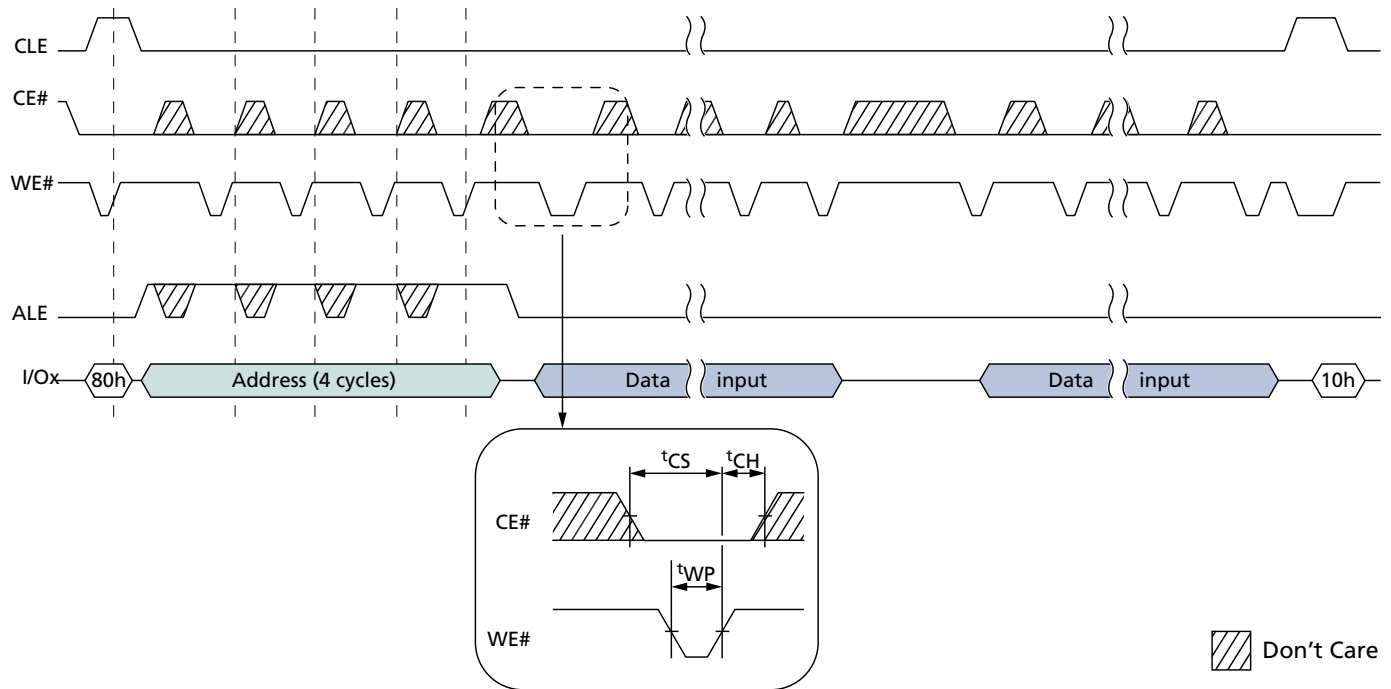
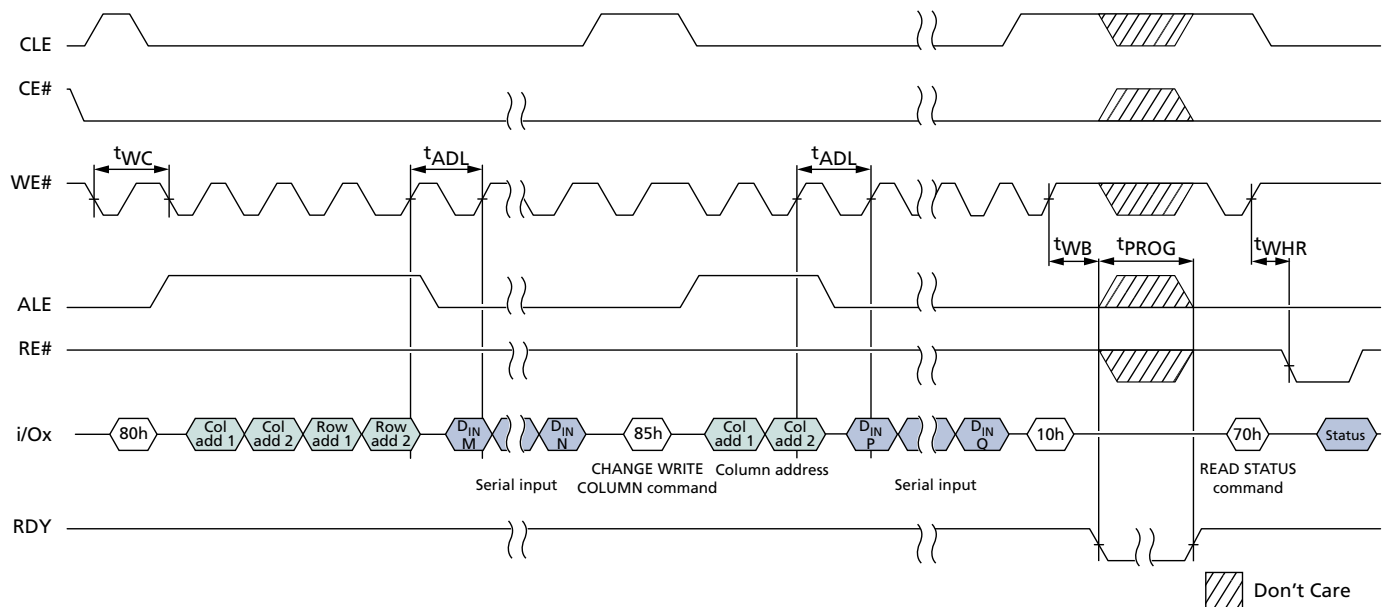


Figure 68: PROGRAM PAGE Operation with RANDOM DATA INPUT





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

Figure 69: PROGRAM PAGE CACHE

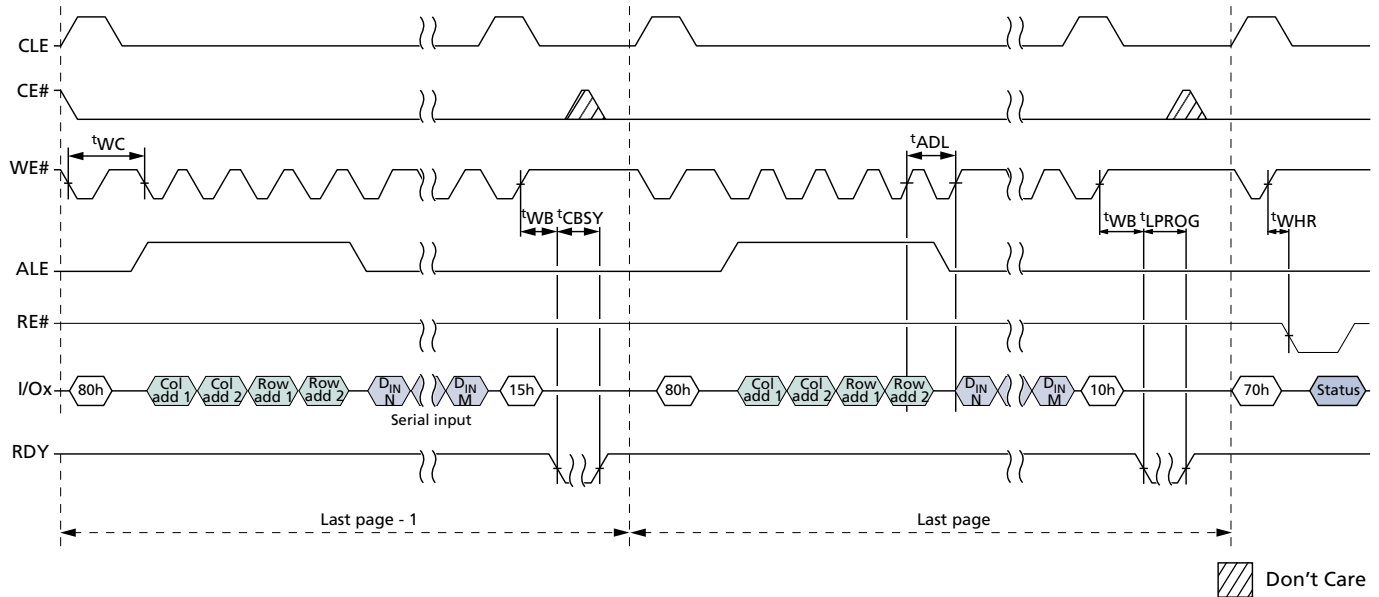
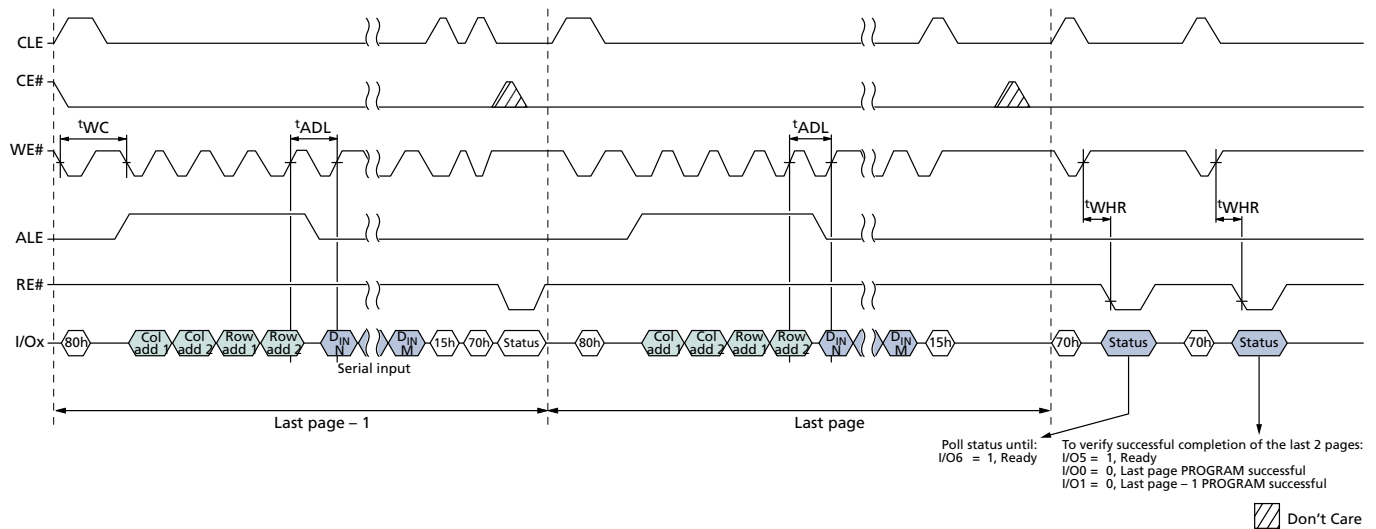


Figure 70: PROGRAM PAGE CACHE Ending on 15h





121-Ball NAND Flash with LPDDR2 MCP Asynchronous Interface Timing Diagrams

Figure 71: INTERNAL DATA MOVE

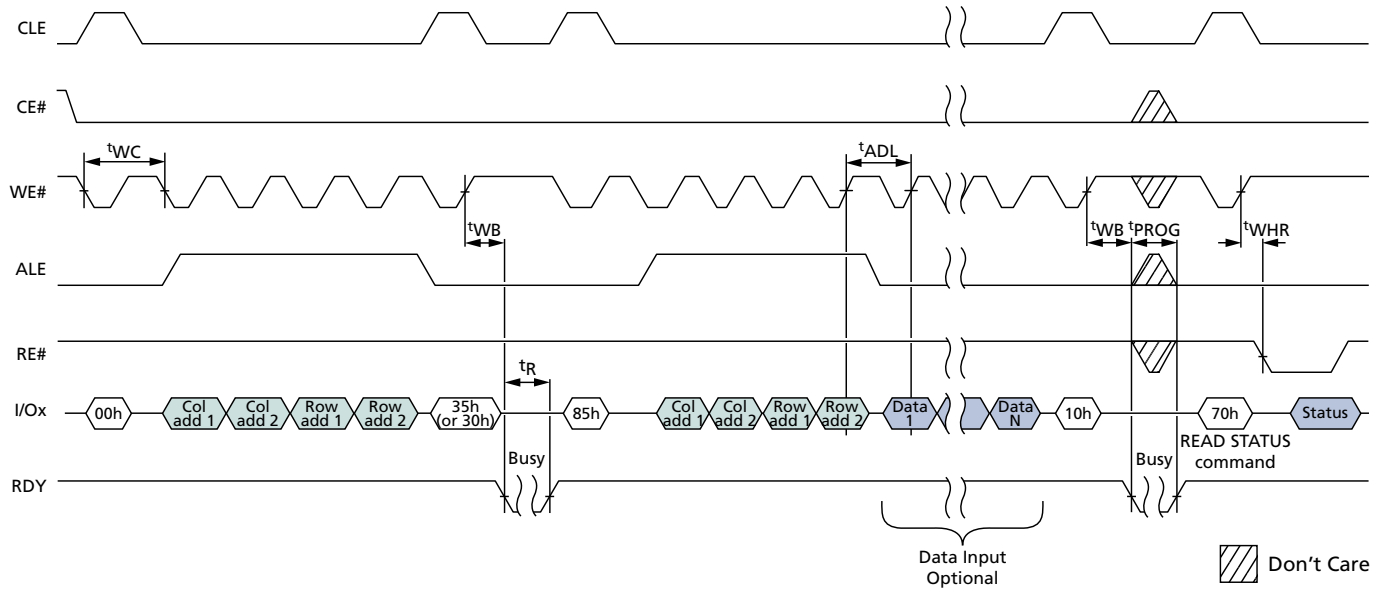
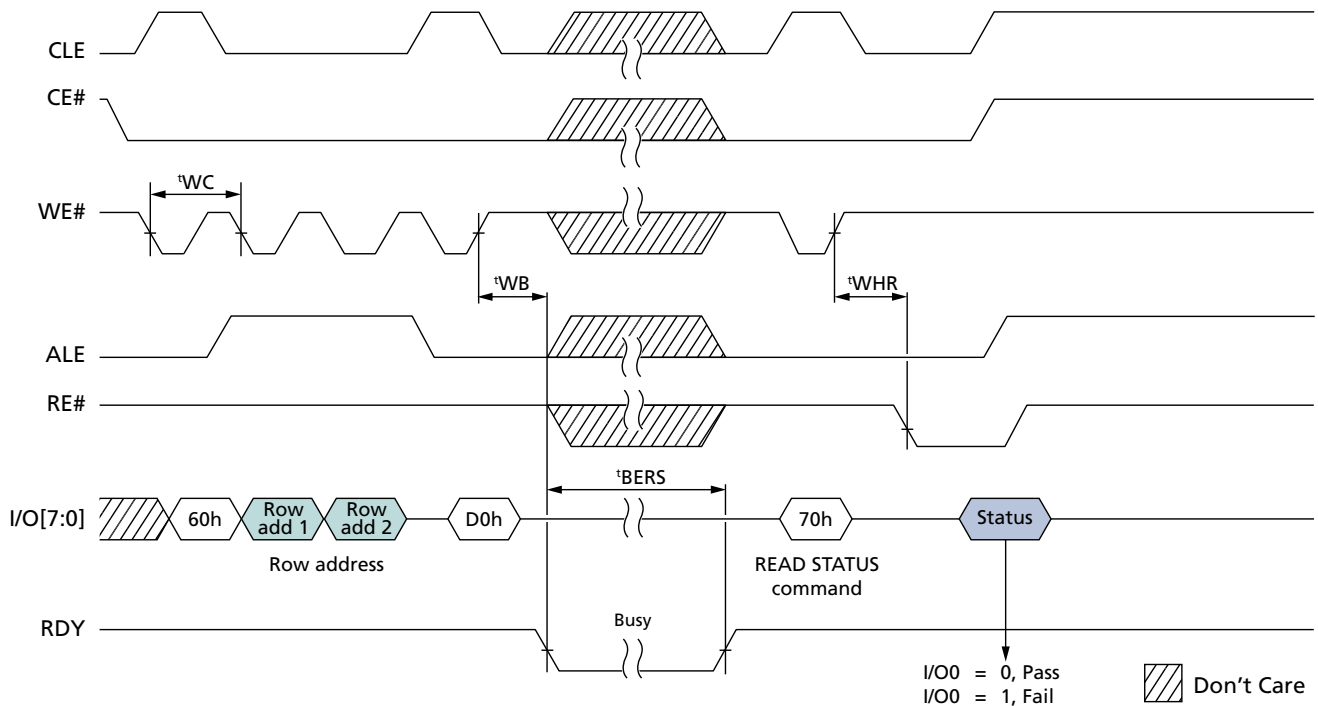


Figure 72: ERASE BLOCK Operation





121-Ball NAND Flash with LPDDR2 MCP 1Gb: x16 Mobile LPDDR2 SDRAM

1Gb: x16 Mobile LPDDR2 SDRAM

Features

- Ultra low-voltage core and I/O power supplies
 - $V_{DD2} = 1.14\text{--}1.30\text{V}$
 - $V_{DDCA}/V_{DDQ} = 1.14\text{--}1.30\text{V}$
 - $V_{DD1} = 1.70\text{--}1.95\text{V}$
- Clock frequency range
 - 400–10 MHz (data rate range: 800–20 Mb/s/pin)
- Four-bit prefetch DDR architecture
- Eight internal banks for concurrent operation
- Multiplexed, double data rate, command/address inputs; commands entered on every CK edge
- Bidirectional/differential data strobe per byte of data (DQS/DQS#)
- Programmable READ and WRITE latencies (RL/WL)
- Programmable burst lengths: 4, 8, or 16
- Per-bank refresh for concurrent operation
- On-chip temperature sensor to control self refresh rate
- Partial-array self refresh (PASR)
- Deep power-down mode (DPD)
- Selectable output drive strength (DS)
- Clock stop capability
- RoHS-compliant, “green” packaging

Table 35: Configuration Addressing

Architecture	64 Meg x 16	32 Meg x 32
Die configuration	8 Meg x 16 x 8 banks	4 Meg x 32 x 8 banks
Row addressing	8K (A[12:0])	8K (A[12:0])
Column addressing	1K (A[9:0])	512 (A[8:0])
Number of die	1	1
Number of channels	1	1
Die per rank	1	1
Ranks per channel	1	1

**121-Ball NAND Flash with LPDDR2 MCP
1Gb: x16 Mobile LPDDR2 SDRAM****General Description**

The 1Gb Mobile Low-Power DDR2 SDRAM (LPDDR2) is a high-speed CMOS, dynamic random-access memory containing 1,073,741,824 bits. The LPDDR2-S4 device is internally configured as an eight-bank DRAM. Each of the x16's 134,217,728-bit banks is organized as 8192 rows by 1024 columns by 16 bits. Each of the x32's 134,217,728-bit banks is organized as 8192 rows by 512 columns by 32 bits.

General Notes

Throughout the data sheet, figures and text refer to DQs as "DQ." DQ should be interpreted as any or all DQ collectively, unless specifically stated otherwise.

"DQS" and "CK" should be interpreted as DQS, DQS# and CK, CK# respectively, unless specifically stated otherwise. "BA" includes all BA pins used for a given density.

Complete functionality may be described throughout the entire document. Any page or diagram may have been simplified to convey a topic and may not be inclusive of all requirements.

Any specific requirement takes precedence over a general statement.

Any functionality not specifically stated herein is considered undefined, illegal, is not supported, and will result in unknown operation.

In timing diagrams, "CMD" is used as an indicator only. Actual signals occur on CA[9:0].

V_{REF} indicates V_{REFCA} and V_{REFDQ} .



121-Ball NAND Flash with LPDDR2 MCP I_{DD} Specifications

I_{DD} Specifications

Table 36: 64 Meg x 16 I_{DD} Specifications

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V

Parameter	Supply	Speed Grade		Unit
		-25	-3	
I _{DD01}	V _{DD1}	7	7	mA
I _{DD02}	V _{DD2}	38	38	
I _{DD0,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD2P1}	V _{DD1}	600	600	μA
I _{DD2P2}	V _{DD2}	1600	1600	
I _{DD2P,in}	V _{DDCA} + V _{DDQ}	100	100	
I _{DD2PS1}	V _{DD1}	600	600	μA
I _{DD2PS2}	V _{DD2}	1600	1600	
I _{DD2PS,in}	V _{DDCA} + V _{DDQ}	100	100	
I _{DD2N1}	V _{DD1}	0.6	0.6	mA
I _{DD2N2}	V _{DD2}	13	12	
I _{DD2N,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD2NS1}	V _{DD1}	0.6	0.6	mA
I _{DD2NS2}	V _{DD2}	7	7	
I _{DD2NS,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD3P1}	V _{DD1}	1400	1400	μA
I _{DD3P2}	V _{DD2}	5	5	mA
I _{DD3P,in}	V _{DDCA} + V _{DDQ}	100	100	μA
I _{DD3PS1}	V _{DD1}	1400	1400	μA
I _{DD3PS2}	V _{DD2}	5	5	mA
I _{DD3PS,in}	V _{DDCA} + V _{DDQ}	100	100	μA
I _{DD3N1}	V _{DD1}	1.5	1.5	mA
I _{DD3N2}	V _{DD2}	16	15	
I _{DD3N,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD3NS1}	V _{DD1}	1.5	1.5	mA
I _{DD3NS2}	V _{DD2}	10	10	
I _{DD3NS,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD4R1}	V _{DD1}	2	2	mA
I _{DD4R2}	V _{DD2}	110	95	
I _{DD4R,in}	V _{DDCA}			
I _{DD4W1}	V _{DD1}	2	2	mA
I _{DD4W2}	V _{DD2}	120	110	
I _{DD4W,in}	V _{DDCA} + V _{DDQ}	1	1	



121-Ball NAND Flash with LPDDR2 MCP I_{DD} Specifications

Table 36: 64 Meg x 16 I_{DD} Specifications (Continued)
 $V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14\text{--}1.30\text{V}; V_{DD1} = 1.70\text{--}1.95\text{V}$

Parameter	Supply	Speed Grade		Unit
		-25	-3	
I _{DD51}	V _{DD1}	23	23	mA
I _{DD52}	V _{DD2}	80	80	
I _{DD5,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD5AB1}	V _{DD1}	2	2	mA
I _{DD5AB2}	V _{DD2}	13	12	
I _{DD5AB,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD61}	V _{DD1}	85	85	μA
I _{DD62}	V _{DD2}	250	250	
I _{DD6,in}	V _{DDCA} + V _{DDQ}	10	10	
I _{DD81}	V _{DD1}	50	50	μA
I _{DD82}	V _{DD2}	50	50	
I _{DD8,in}	V _{DDCA} + V _{DDQ}	8	8	

Table 37: 32Meg x 32 I_{DD} Specifications
 $V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14\text{--}1.30\text{V}; V_{DD1} = 1.70\text{--}1.95\text{V}$

Parameter	Supply	Speed Grade		Unit
		-25	-3	
I _{DD01}	V _{DD1}	7	7	mA
I _{DD02}	V _{DD2}	38	38	
I _{DD0,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD2P1}	V _{DD1}	600	600	μA
I _{DD2P2}	V _{DD2}	1600	1600	
I _{DD2P,in}	V _{DDCA} + V _{DDQ}	100	100	
I _{DD2PS1}	V _{DD1}	600	600	μA
I _{DD2PS2}	V _{DD2}	1600	1600	
I _{DD2PS,in}	V _{DDCA} + V _{DDQ}	100	100	
I _{DD2N1}	V _{DD1}	0.6	0.6	mA
I _{DD2N2}	V _{DD2}	13	12	
I _{DD2N,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD2NS1}	V _{DD1}	0.6	0.6	mA
I _{DD2NS2}	V _{DD2}	7	7	
I _{DD2NS,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD3P1}	V _{DD1}	1400	1400	μA
I _{DD3P2}	V _{DD2}	5	5	mA
I _{DD3P,in}	V _{DDCA} + V _{DDQ}	100	100	μA
I _{DD3PS1}	V _{DD1}	1400	1400	μA



121-Ball NAND Flash with LPDDR2 MCP I_{DD} Specifications

Table 37: 32Meg x 32 I_{DD} Specifications (Continued)
 $V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14\text{--}1.30\text{V}; V_{DD1} = 1.70\text{--}1.95\text{V}$

Parameter	Supply	Speed Grade		Unit
		-25	-3	
I _{DD3PS2}	V _{DD2}	5	5	mA
I _{DD3PS,in}	V _{DDCA} + V _{DDQ}	100	100	μA
I _{DD3N1}	V _{DD1}	1.5	1.5	mA
I _{DD3N2}	V _{DD2}	16	15	
I _{DD3N,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD3NS1}	V _{DD1}	1.5	1.5	mA
I _{DD3NS2}	V _{DD2}	10	10	
I _{DD3NS,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD4R1}	V _{DD1}	2	2	mA
I _{DD4R2}	V _{DD2}	150	125	
I _{DD4R,in}	V _{DDCA}			
I _{DD4W1}	V _{DD1}	2	2	mA
I _{DD4W2}	V _{DD2}	165	140	
I _{DD4W,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD51}	V _{DD1}	23	23	mA
I _{DD52}	V _{DD2}	80	80	
I _{DD5,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD5AB1}	V _{DD1}	2	2	mA
I _{DD5AB2}	V _{DD2}	13	12	
I _{DD5AB,in}	V _{DDCA} + V _{DDQ}	1	1	
I _{DD61}	V _{DD1}	85	85	μA
I _{DD62}	V _{DD2}	250	250	
I _{DD6,in}	V _{DDCA} + V _{DDQ}	10	10	
I _{DD81}	V _{DD1}	50	50	μA
I _{DD82}	V _{DD2}	50	50	
I _{DD8,in}	V _{DDCA} + V _{DDQ}	8	8	



121-Ball NAND Flash with LPDDR2 MCP I_{DD} Specifications

Table 38: I_{DD6} Partial-Array Self Refresh Current

V_{DD2}, V_{DDQ}, V_{DDCA} = 1.14–1.30V; V_{DD1} = 1.70–1.95V

PASR	Supply	Value	Unit
Full array	V _{DD1}	85	μA
	V _{DD2}	250	
	V _{DDi}	10	
1/2 array	V _{DD1}	60	
	V _{DD2}	140	
	V _{DDi}	10	
1/4 array	V _{DD1}	50	
	V _{DD2}	85	
	V _{DDi}	10	



121-Ball NAND Flash with LPDDR2 MCP I_{DD} Specifications

Figure 73: I_{DD61} Typical Self Refresh Current vs. Temperature

TBD



121-Ball NAND Flash with LPDDR2 MCP I_{DD} Specifications

Figure 74: I_{DD62} Typical Self Refresh Current vs. Temperature

TBD



121-Ball NAND Flash with LPDDR2 MCP Functional Description

Functional Description

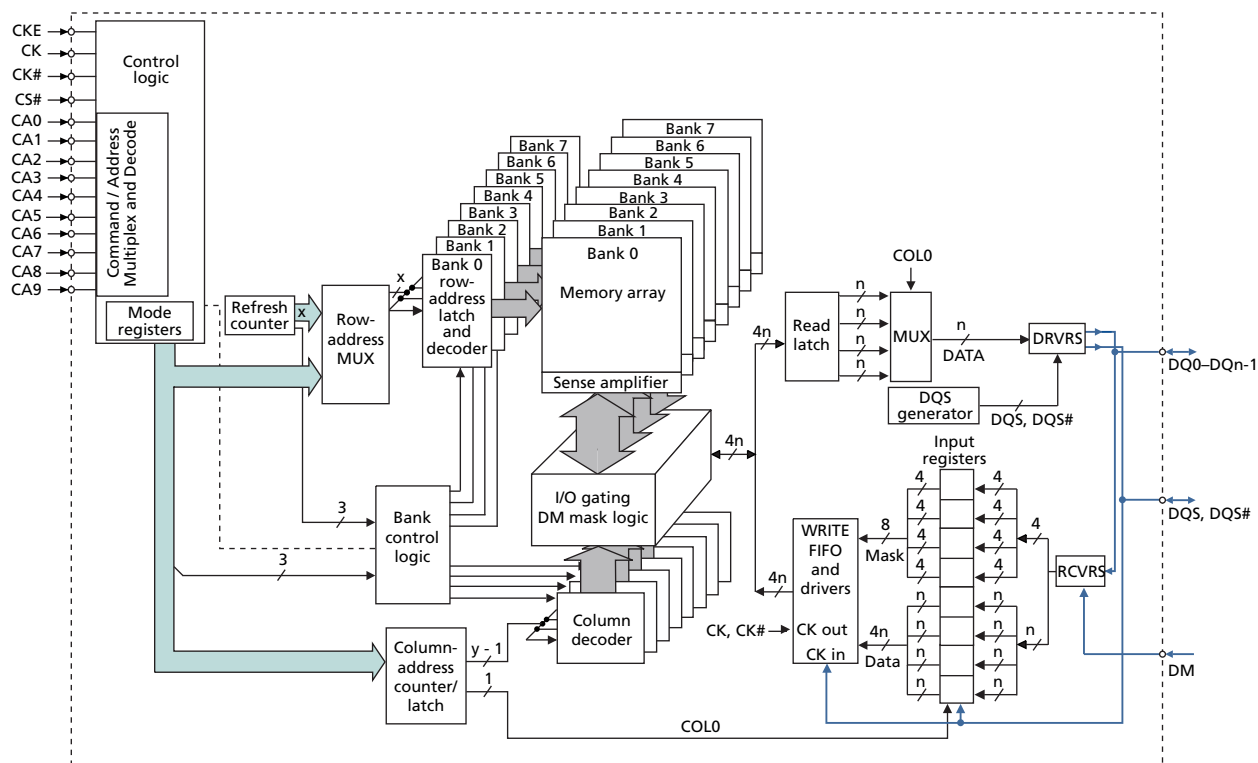
Mobile LPDDR2 is a high-speed SDRAM internally configured as a 4- or 8-bank memory device. LPDDR2 devices use a double data rate architecture on the command/address (CA) bus to reduce the number of input pins in the system. The 10-bit CA bus is used to transmit command, address, and bank information. Each command uses one clock cycle, during which command information is transferred on both the rising and falling edges of the clock.

LPDDR2-S4 devices use a double data rate architecture on the DQ pins to achieve high-speed operation. The double data rate architecture is essentially a $4n$ prefetch architecture with an interface designed to transfer two data bits per DQ every clock cycle at the I/O pins. A single read or write access for the LPDDR2-S4 effectively consists of a single $4n$ -bit-wide, one-clock-cycle data transfer at the internal SDRAM core and four corresponding n -bit-wide, one-half-clock-cycle data transfers at the I/O pins.

Read and write accesses are burst oriented; accesses start at a selected location and continue for a programmed number of locations in a programmed sequence.

Accesses begin with the registration of an ACTIVATE command followed by a READ or WRITE command. The address and BA bits registered coincident with the ACTIVATE command are used to select the row and bank to be accessed. The address bits registered coincident with the READ or WRITE command are used to select the bank and the starting column location for the burst access.

Figure 75: Functional Block Diagram





121-Ball NAND Flash with LPDDR2 MCP Power-Up

Power-Up

The following sequence must be used to power up the device. Unless specified otherwise, this procedure is mandatory (see Figure 76 (page 113)). Power-up and initialization by means other than those specified will result in undefined operation.

1. Voltage Ramp

While applying power (after T_a), CKE must be held LOW ($\leq 0.2 \times V_{DDCA}$), and all other inputs must be between V_{ILmin} and V_{IHmax} . The device outputs remain at High-Z while CKE is held LOW.

On or before the completion of the voltage ramp (T_b), CKE must be held LOW. DQ, DM, DQS, and DQS# voltage levels must be between V_{SSQ} and V_{DDQ} during voltage ramp to avoid latchup. CK, CK#, CS#, and CA input levels must be between V_{SSCA} and V_{DDCA} during voltage ramp to avoid latchup.

The following conditions apply for voltage ramp:

- T_a is the point when any power supply first reaches 300mV.
- Noted conditions apply between T_a and power-down (controlled or uncontrolled).
- T_b is the point at which all supply and reference voltages are within their defined operating ranges.
- Power ramp duration t_{INIT0} ($T_b - T_a$) must not exceed 20ms.
- For supply and reference voltage operating conditions, see the Recommended DC Operating Conditions table.
- The voltage difference between any of V_{SS} , V_{SSQ} , and V_{SSCA} pins must not exceed 100mV.

Voltage Ramp Completion

After T_a is reached:

- V_{DD1} must be greater than $V_{DD2} - 200mV$
- V_{DD1} and V_{DD2} must be greater than $V_{DDCA} - 200mV$
- V_{DD1} and V_{DD2} must be greater than $V_{DDQ} - 200mV$
- V_{REF} must always be less than all other supply voltages

Beginning at T_b , CKE must remain LOW for at least $t_{INIT1} = 100ns$, after which CKE can be asserted HIGH. The clock must be stable at least $t_{INIT2} = 5 \times t_{CK}$ prior to the first CKE LOW-to-HIGH transition (T_c). CKE, CS#, and CA inputs must observe setup and hold requirements (t_{IS} , t_{IH}) with respect to the first rising clock edge (and to subsequent falling and rising edges).

If any MRRs are issued, the clock period must be within the range defined for t_{CKb} (18ns to 100ns). MRWs can be issued at normal clock frequencies as long as all AC timings are met. Some AC parameters (for example, t_{DQSCK}) could have relaxed timings (such as t_{DQSCKb}) before the system is appropriately configured. While keeping CKE HIGH, NOP commands must be issued for at least $t_{INIT3} = 200\mu s$ (T_d).

2. RESET Command

After t_{INIT3} is satisfied, the MRW RESET command must be issued (T_d). An optional PRECHARGE ALL command can be issued prior to the MRW RESET command.

Wait at least t_{INIT4} while keeping CKE asserted and issuing NOP commands.



121-Ball NAND Flash with LPDDR2 MCP Power-Up

3. MRRs and Device Auto Initialization (DAI) Polling

After t_{INIT4} is satisfied (T_e), only MRR commands and power-down entry/exit commands are supported. After T_e , CKE can go LOW in alignment with power-down entry and exit specifications (see Power-Down (page 165)).

The MRR command can be used to poll the DAI bit, which indicates when device auto initialization is complete; otherwise, the controller must wait a minimum of t_{INIT5} , or until the DAI bit is set, before proceeding.

Because the memory output buffers are not properly configured by T_e , some AC parameters must use relaxed timing specifications before the system is appropriately configured.

After the DAI bit (MR0, DAI) is set to zero by the memory device (DAI complete), the device is in the idle state (T_f). DAI status can be determined by issuing the MRR command to MR0.

The device sets the DAI bit no later than t_{INIT5} after the RESET command. The controller must wait at least t_{INIT5} or until the DAI bit is set before proceeding.

4. ZQ Calibration

After t_{INIT5} (T_f), the MRW initialization calibration (ZQ calibration) command can be issued to the memory (MR10).

This command is used to calibrate output impedance over process, voltage, and temperature. In systems where more than one Mobile LPDDR2 device exists on the same bus, the controller must not overlap MRW ZQ calibration commands. The device is ready for normal operation after t_{ZQINIT} .

5. Normal Operation

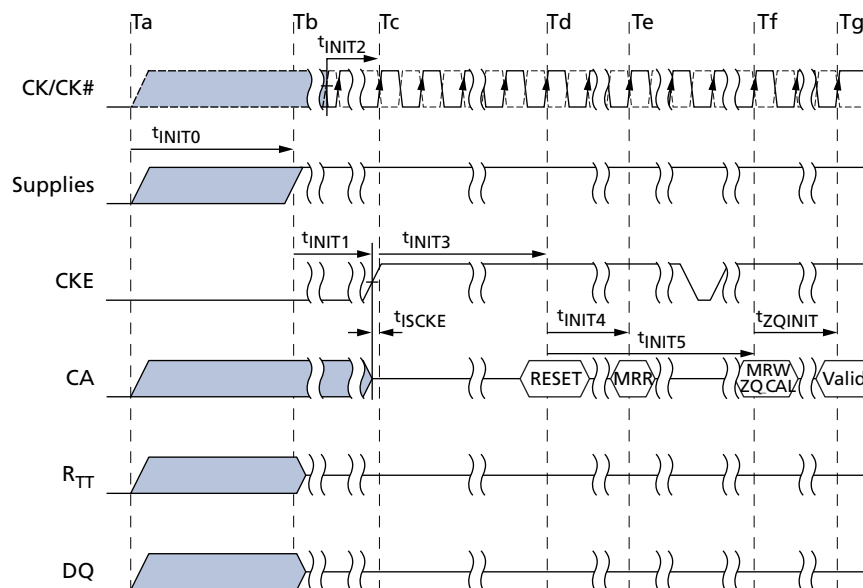
After (T_g), MRW commands must be used to properly configure the memory (output buffer drive strength, latencies, etc.). Specifically, MR1, MR2, and MR3 must be set to configure the memory for the target frequency and memory configuration.

After the initialization sequence is complete, the device is ready for any valid command. After T_g , the clock frequency can be changed using the procedure described in Input Clock Frequency Changes and Clock Stop with CKE HIGH (page 174).



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Figure 76: Voltage Ramp and Initialization Sequence



Note: 1. High-Z on the CA bus indicates valid NOP.

Table 39: Initialization Timing Parameters

Note:

The t_{INIT0} maximum specification is not a tested limit and should be used as a general guideline. For voltage ramp times exceeding $t_{INIT0\ MAX}$, please contact the factory.

Parameter	Value		Unit	Comment
	Min	Max		
t_{INIT0}	–	20	ms	Maximum voltage ramp time
t_{INIT1}	100	–	ns	Minimum CKE LOW time after completion of voltage ramp
t_{INIT2}	5	–	t_{CK}	Minimum stable clock before first CKE HIGH
t_{INIT3}	200	–	μs	Minimum idle time after first CKE assertion
t_{INIT4}	1	–	μs	Minimum idle time after RESET command
t_{INIT5}	–	10	μs	Maximum duration of device auto initialization
t_{ZQINIT}	1	–	μs	ZQ initial calibration (S4 devices only)
t_{CKb}	18	100	ns	Clock cycle time during boot

Initialization After RESET (Without Voltage Ramp)

If the RESET command is issued before or after the power-up initialization sequence, the reinitialization procedure must begin at Td.

Power-Off

While powering off, CKE must be held LOW ($\leq 0.2 \times V_{DDCA}$); all other inputs must be between V_{ILmin} and V_{IHmax} . The device outputs remain at High-Z while CKE is held LOW.



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DQ, DM, DQS, and DQS# voltage levels must be between V_{SSQ} and V_{DDQ} during the power-off sequence to avoid latchup. CK, CK#, CS#, and CA input levels must be between V_{SSCA} and V_{DDCA} during the power-off sequence to avoid latchup.

Tx is the point where any power supply drops below the minimum value specified in the Recommended DC Operating Conditions table.

Tz is the point where all power supplies are below 300mV. After Tz, the device is powered off.

Required Power Supply Conditions Between Tx and Tz:

- V_{DD1} must be greater than $V_{DD2} - 200\text{mV}$
- V_{DD1} must be greater than $V_{DDCA} - 200\text{mV}$
- V_{DD1} must be greater than $V_{DDQ} - 200\text{mV}$
- V_{REF} must always be less than all other supply voltages

The voltage difference between V_{SS} , V_{SSQ} , and V_{SSCA} must not exceed 100mV.

For supply and reference voltage operating conditions, see Recommended DC Operating Conditions table.

Uncontrolled Power-Off

When an uncontrolled power-off occurs, the following conditions must be met:

- At Tx, when the power supply drops below the minimum values specified in the Recommended DC Operating Conditions table, all power supplies must be turned off and all power-supply current capacity must be at zero, except for any static charge remaining in the system.
- After Tz (the point at which all power supplies first reach 300mV), the device must power off. The time between Tx and Tz must not exceed t_{POFF} . During this period, the relative voltage between power supplies is uncontrolled. V_{DD1} and V_{DD2} must decrease with a slope lower than $0.5\text{ V}/\mu\text{s}$ between Tx and Tz.

An uncontrolled power-off sequence can occur a maximum of 400 times over the life of the device.

Table 40: Power-Off Timing

Parameter	Symbol	Min	Max	Unit
Maximum power-off ramp time	t_{POFF}	–	2	sec

Mode Register Definition

LPDDR2 devices contain a set of mode registers used for programming device operating parameters, reading device information and status, and for initiating special operations such as DQ calibration, ZQ calibration, and device reset.

Mode Register Assignments and Definitions

The MRR command is used to read from a register. The MRW command is used to write to a register. An “R” in the access column of the mode register assignment table indicates read-only; a “W” indicates write-only; “R/W” indicates read or write capable or enabled.



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Table 41: Mode Register Assignments

Notes 1–5 apply to all parameters and conditions

MR#	MA[7:0]	Function	Access	OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0	Link	
0	00h	Device info	R	RFU			RZQI		DNVI	DI	DAI	go to MR0	
1	01h	Device feature 1	W	nWR (for AP)			WC	BT	BL			go to MR1	
2	02h	Device feature 2	W	RFU			RL and WL					go to MR2	
3	03h	I/O config-1	W	RFU			DS					go to MR3	
4	04h	SDRAM refresh rate	R	TUF	RFU			Refresh rate				go to MR4	
5	05h	Basic config-1	R	LPDDR2 Manufacturer ID									go to MR5
6	06h	Basic config-2	R	Revision ID1									go to MR6
7	07h	Basic config-3	R	Revision ID2									go to MR7
8	08h	Basic config-4	R	I/O width		Density			Type			go to MR8	
9	09h	Test mode	W	Vendor-specific test mode									go to MR9
10	0Ah	I/O calibration	W	Calibration code									go to MR10
11–15	0Bh ~ 0Fh	Reserved	–	RFU									go to MR11
16	10h	PASR_Bank	W	Bank mask									go to MR16
17	11h	PASR_Seg	W	Segment mask									go to MR17
18–19	12h–13h	Reserved	–	RFU									go to MR18
20–31	14h–1Fh	Reserved for NVM										MR20–MR30	
32	20h	DQ calibration pattern A	R	See Table 78 (page 161).									go to MR32
33–39	21h–27h	Do not use											go to MR33
40	28h	DQ calibration pattern B	R	See Table 78 (page 161).									go to MR40
41–47	29h–2Fh	Do not use											go to MR41
48–62	30h–3Eh	Reserved	–	RFU									go to MR48
63	3Fh	RESET	W	X									go to MR63
64–126	40h–7Eh	Reserved	–	RFU									go to MR64
127	7Fh	Do not use											go to MR127
128–190	80h–BEh	Reserved for vendor use		RVU									go to MR128
191	BFh	Do not use											go to MR191
192–254	C0h–FEh	Reserved for vendor use		RVU									go to MR192
255	FFh	Do not use											go to MR255

- Notes:
1. RFU bits must be set to 0 during MRW.
 2. RFU bits must be read as 0 during MRR.
 3. For READs to a write-only or RFU register, DQS will be toggled and undefined data is returned.
 4. RFU mode registers must not be written.
 5. WRITEs to read-only registers must have no impact on the functionality of the device.



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Table 42: MR0 Device Information (MA[7:0] = 00h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
RFU			RZQI		DNVI	DI	DAI

Table 43: MR0 Op-Code Bit Definitions

Notes 1–4 apply to all parameters and conditions

Register Information	Tag	Type	OP	Definition
Device auto initialization status	DAI	Read-only	OP0	0b: DAI complete
				1b: DAI in progress
Device information	DI	Read-only	OP1	0b
				1b: NVM
Data not valid information	DNVI	Read-only	OP2	0b: DNVI not supported
Built-in self test for RZQ information	RZQI	Read-only	OP[4:3]	00b: RZQ self test not supported
				01b: ZQ pin might be connected to V _{DDCA} or left floating
				10b: ZQ pin might be shorted to ground
				11b: ZQ pin self test complete; no error condition detected

- Notes:
1. If RZQI is supported, it will be set upon completion of the MRW ZQ initialization calibration.
 2. If ZQ is connected to V_{DDCA} to set default calibration, OP[4:3] must be set to 01. If ZQ is not connected to V_{DDCA}, either OP[4:3] = 01 or OP[4:3] = 10 could indicate a ZQ-pin assembly error. It is recommended that the assembly error be corrected.
 3. In the case of a possible assembly error (either OP[4:3] = 01 or OP[4:3] = 10, as defined above), the device will default to factory trim settings for R_{ON} and will ignore ZQ calibration commands. In either case, the system might not function as intended.
 4. If a ZQ self test returns a value of 11b, this indicates that the device has detected a resistor connection to the ZQ pin. Note that this result cannot be used to validate the ZQ resistor value, nor does it indicate that the ZQ resistor tolerance meets the specified limits (240 ohms ±1%).

Table 44: MR1 Device Feature 1 (MA[7:0] = 01h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
nWR (for AP)			WC	BT	BL		

Table 45: MR1 Op-Code Bit Definitions

Feature	Type	OP	Definition	Notes
BL = burst length	Write-only	OP[2:0]	010b: BL4 (default)	
			011b: BL8	
			100b: BL16	
			All others: Reserved	



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Table 45: MR1 Op-Code Bit Definitions (Continued)

Feature	Type	OP	Definition	Notes
BT = burst type	Write-only	OP3	0b: Sequential (default)	
			1b: Interleaved	
WC = wrap control	Write-only	OP4	0b: Wrap (default)	
			1b: No wrap	
nWR = number of ^t WR clock cycles	Write-only	OP[7:5]	001b: nWR = 3 (default)	1
			010b: nWR = 4	
			011b: nWR = 5	
			100b: nWR = 6	
			101b: nWR = 7	
			110b: nWR = 8	
			All others: Reserved	

Note: 1. The programmed value in nWR register is the number of clock cycles that determines when to start internal precharge operation for a WRITE burst with AP enabled. It is determined by RU (^tWR/^tCK).

Table 46: Burst Sequence by Burst Length (BL), Burst Type (BT), and Wrap Control (WC)

Notes 1–5 apply to all parameters and conditions

Notes 1-5 apply to all parameters and conditions																						
BL	BT	C3	C2	C1	C0	WC	Burst Cycle Number and Burst Address Sequence															
							1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
4	Any	X	X	0b	0b	Wrap	0	1	2	3												
		X	X	1b	0b		2	3	0	1												
	Any	X	X	X	0b	No wrap	y	y + 1	y + 2	y + 3												
8	Seq	X	0b	0b	0b	Wrap	0	1	2	3	4	5	6	7								
		X	0b	1b	0b		2	3	4	5	6	7	0	1								
		X	1b	0b	0b		4	5	6	7	0	1	2	3								
		X	1b	1b	0b		6	7	0	1	2	3	4	5								
	Int	X	0b	0b	0b	0	1	2	3	4	5	6	7									
		X	0b	1b	0b	2	3	0	1	6	7	4	5									
		X	1b	0b	0b	4	5	6	7	0	1	2	3									
		X	1b	1b	0b	6	7	4	5	2	3	0	1									
	Any	X	X	X	0b	No wrap	Illegal (not supported)															



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Table 46: Burst Sequence by Burst Length (BL), Burst Type (BT), and Wrap Control (WC) (Continued)

Notes 1–5 apply to all parameters and conditions

BL	BT	C3	C2	C1	C0	WC	Burst Cycle Number and Burst Address Sequence															
							1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
16	Seq	0b	0b	0b	0b	Wrap	0	1	2	3	4	5	6	7	8	9	A	B	C	D	E	F
		0b	0b	1b	0b		2	3	4	5	6	7	8	9	A	B	C	D	E	F	0	1
		0b	1b	0b	0b		4	5	6	7	8	9	A	B	C	D	E	F	0	1	2	3
		0b	1b	1b	0b		6	7	8	9	A	B	C	D	E	F	0	1	2	3	4	5
		1b	0b	0b	0b		8	9	A	B	C	D	E	F	0	1	2	3	4	5	6	7
		1b	0b	1b	0b		A	B	C	D	E	F	0	1	2	3	4	5	6	7	8	9
		1b	1b	0b	0b		C	D	E	F	0	1	2	3	4	5	6	7	8	9	A	B
		1b	1b	1b	0b		E	F	0	1	2	3	4	5	6	7	8	9	A	B	C	D
	Int	X	X	X	0b	Illegal (not supported)																
	Any	X	X	X	0b	Illegal (not supported)																
						No wrap																

- Notes:
1. C0 input is not present on CA bus. It is implied zero.
 2. For BL = 4, the burst address represents C[1:0].
 3. For BL = 8, the burst address represents C[2:0].
 4. For BL = 16, the burst address represents C[3:0].
 5. For no-wrap, BL4, the burst must not cross the page boundary or the sub-page boundary. The variable y can start at any address with C0 equal to 0, but must not start at any address shown in the following table.

Table 47: No-Wrap Restrictions

Width	64Mb	128Mb/256Mb	512Mb/1Gb/2Gb	4Gb/8Gb
Cannot cross full-page boundary				
x16	FE, FF, 00, 01	1FE, 1FF, 000, 001	3FE, 3FF, 000, 001	7FE, 7FF, 000, 001
x32	7E, 7F, 00, 01	FE, FF, 00, 01	1FE, 1FF, 000, 001	3FE, 3FF, 000, 001
Cannot cross sub-page boundary				
x16	7E, 7F, 80, 81	0FE, 0FF, 100, 101	1FE, 1FF, 200, 201	3FE, 3FF, 400, 401
x32	None	None	None	None

Note: 1. No-wrap BL = 4 data orders shown are prohibited.

Table 48: MR2 Device Feature 2 (MA[7:0] = 02h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
RFU				RL and WL			



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Table 49: MR2 Op-Code Bit Definitions

Feature	Type	OP	Definition
RL and WL	Write-only	OP[3:0]	0001b: RL3/WL1 (default)
			0010b: RL4/WL2
			0011b: RL5/WL2
			0100b: RL6/WL3
			0101b: RL7/WL4
			0110b: RL8/WL4
			All others: Reserved

Table 50: MR3 I/O Configuration 1 (MA[7:0] = 03h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
RFU				DS			

Table 51: MR3 Op-Code Bit Definitions

Feature	Type	OP	Definition
DS	Write-only	OP[3:0]	0000b: Reserved
			0001b: 34.3 ohm typical
			0010b: 40 ohm typical (default)
			0011b: 48 ohm typical
			0100b: 60 ohm typical
			0101b: Reserved
			0110b: 80 ohm typical
			0111b: 120 ohm typical
			All others: Reserved

Table 52: MR4 Device Temperature (MA[7:0] = 04h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
TUF	RFU				SDRAM refresh rate		



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Table 53: MR4 Op-Code Bit Definitions

Notes 1–8 apply to all parameters and conditions

Feature	Type	OP	Definition
SDRAM refresh rate	Read-only	OP[2:0]	000b: SDRAM low temperature operating limit exceeded
			001b: $4 \times t_{REFI}$, $4 \times t_{REFIpb}$, $4 \times t_{REFW}$
			010b: $2 \times t_{REFI}$, $2 \times t_{REFIpb}$, $2 \times t_{REFW}$
			011b: $1 \times t_{REFI}$, $1 \times t_{REFIpb}$, $1 \times t_{REFW}$ ($\leq 85^{\circ}\text{C}$)
			100b: Reserved
			101b: $0.25 \times t_{REFI}$, $0.25 \times t_{REFIpb}$, $0.25 \times t_{REFW}$, do not derate SDRAM AC timing
			110b: $0.25 \times t_{REFI}$, $0.25 \times t_{REFIpb}$, $0.25 \times t_{REFW}$, derate SDRAM AC timing
			111b: SDRAM high temperature operating limit exceeded
Temperature update flag (TUF)	Read-only	OP7	0b: OP[2:0] value has not changed since last read of MR4
			1b: OP[2:0] value has changed since last read of MR4

- Notes:
1. A MODE REGISTER READ from MR4 will reset OP7 to 0.
 2. OP7 is reset to 0 at power-up.
 3. If OP2 = 1, the device temperature is greater than 85°C .
 4. OP7 is set to 1 if OP[2:0] has changed at any time since the last MR4 read.
 5. The device might not operate properly when OP[2:0] = 000b or 111b.
 6. For specified operating temperature range and maximum operating temperature, refer to the Operating Temperature Range table.
 7. LPDDR2 devices must be derated by adding 1.875ns to the following core timing parameters: t_{RCD} , t_{RC} , t_{RAS} , t_{RP} , and t_{RRD} . The t_{DQSCK} parameter must be derated as specified in AC Timing. Prevailing clock frequency specifications and related setup and hold timings remain unchanged.
 8. The recommended frequency for reading MR4 is provided in Temperature Sensor (page 158).

Table 54: MR5 Basic Configuration 1 (MA[7:0] = 05h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
LPDDR2 Manufacturer ID							

Table 55: MR5 Op-Code Bit Definitions

Feature	Type	OP	Definition
Manufacturer ID	Read-only	OP[7:0]	00000011b: Elpida
			All others: Reserved

Table 56: MR6 Basic Configuration 2 (MA[7:0] = 06h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Revision ID1							

Note: 1. MR6 is vendor-specific.



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Table 57: MR6 Op-Code Bit Definitions

Feature	Type	OP	Definition
Revision ID1	Read-only	OP[7:0]	0000 0000b: Version A

Table 58: MR7 Basic Configuration 3 (MA[7:0] = 07h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Revision ID2							

Table 59: MR7 Op-Code Bit Definitions

Feature	Type	OP	Definition
Revision ID2	Read-only	OP[7:0]	0000 0000b: Version A

Note: 1. MR7 is vendor-specific.

Table 60: MR8 Basic Configuration 4 (MA[7:0] = 08h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
I/O width		Density				Type	

Table 61: MR8 Op-Code Bit Definitions

Feature	Type	OP	Definition
Type	Read-only	OP[1:0]	00b
			01b
			10b: NVM
			11b: Reserved
Density	Read-only	OP[5:2]	0000b: 64Mb
			0001b: 128Mb
			0010b: 256Mb
			0011b: 512Mb
			0100b: 1Gb
			0101b: 2Gb
			0110b: 4Gb
			0111b: 8Gb
			1000b: 16Gb
			1001b: 32Gb
			All others: Reserved
I/O width	Read-only	OP[7:6]	00b: x32
			01b: x16
			10b: x8
			11b: not used



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Table 62: MR9 Test Mode (MA[7:0] = 09h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Vendor-specific test mode							

Table 63: MR10 Calibration (MA[7:0] = 0Ah)

	OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
S4	Calibration code							

Table 64: MR10 Op-Code Bit Definitions

Notes 1–4 apply to all parameters and conditions

Feature	Type	OP	Definition
Calibration code	Write-only	OP[7:0]	0xFF: Calibration command after initialization
			0xAB: Long calibration
			0x56: Short calibration
			0xC3: ZQRESET
			All others: Reserved

- Notes:
1. Host processor must not write MR10 with reserved values.
 2. The device ignores calibration commands when a reserved value is written into MR10.
 3. See AC timing table for the calibration latency.
 4. If ZQ is connected to V_{SSCA} through R_{ZQ} , either the ZQ calibration function (see MRW ZQ Calibration Commands (page 163)) or default calibration (through the ZQRESET command) is supported. If ZQ is connected to V_{DDCA} , the device operates with default calibration, and ZQ calibration commands are ignored. In both cases, the ZQ connection must not change after power is supplied to the device.

Table 65: MR[11:15] Reserved (MA[7:0] = 0Bh–0Fh)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Reserved							

Table 66: MR16 PASR Bank Mask (MA[7:0] = 010h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Bank mask (4-bank or 8-bank)							

Table 67: MR16 Op-Code Bit Definitions

Feature	Type	OP	Definition
Bank[7:0] mask	Write-only	OP[7:0]	0b: refresh enable to the bank = unmasked (default)
			1b: refresh blocked = masked

Note: 1. For 4-bank devices, only OP[3:0] are used.



121-Ball NAND Flash with LPDDR2 MCP Mode Register Definition

Table 68: MR17 PASR Segment Mask (MA[7:0] = 011h)

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
Segment mask							

Note: 1. This table applies for 1Gb to 8Gb devices only.

Table 69: MR17 PASR Segment Mask Definitions

Feature	Type	OP	Definition
Segment[7:0] mask	Write-only	OP[7:0]	0b: refresh enable to the segment: = unmasked (default)
			1b: refresh blocked: = masked

Table 70: MR17 PASR Row Address Ranges in Masked Segments

Segment	OP	Segment Mask	1Gb	2Gb, 4Gb	8Gb
			R[12:10]	R[13:11]	R[14:12]
0	0	XXXXXXX1		000b	
1	1	XXXXXX1X		001b	
2	2	XXXXX1XX		010b	
3	3	XXXX1XXX		011b	
4	4	XXX1XXXX		100b	
5	5	XX1XXXXX		101b	
6	6	X1XXXXXX		110b	
7	7	1XXXXXXX		111b	

Note: 1. X is "Don't Care" for the designated segment.

Table 71: Reserved Mode Registers

Mode Register	MA	Address	Restriction	OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
MR[18:19]	MA[7:0]	12h–13h	RFU	Reserved							
MR[20:31]		14h–1Fh	NVM ¹								
MR[33:39]		21h–27h	DNU ¹								
MR[41:47]		29h–2Fh									
MR[48:62]		30h–3Eh	RFU								
MR[64:126]		40h–7Eh	RFU								
MR127		7Fh	DNU								
MR[128:190]		80h–BEh	RVU ¹								
MR191		BFh	DNU								
MR[192:254]		C0h–FEh	RVU								
MR255		FFh	DNU								

Note: 1. NVM = nonvolatile memory use only; DNU = Do not use; RVU = Reserved for vendor use.

**121-Ball NAND Flash with LPDDR2 MCP
Mode Register Definition****Table 72: MR63 RESET (MA[7:0] = 3Fh) – MRW Only**

OP7	OP6	OP5	OP4	OP3	OP2	OP1	OP0
X							

Note: 1. For additional information on MRW RESET see MODE REGISTER WRITE Command (page 162).

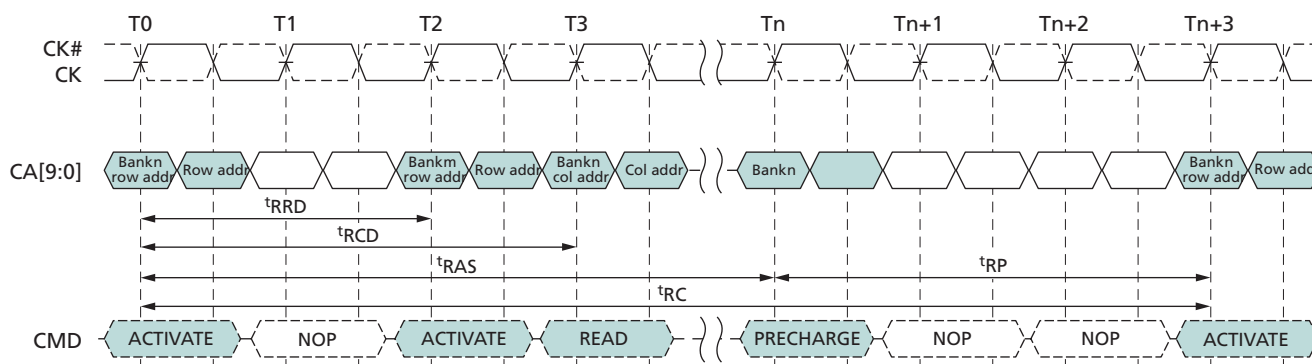


121-Ball NAND Flash with LPDDR2 MCP ACTIVATE Command

ACTIVATE Command

The ACTIVATE command is issued by holding CS# LOW, CA0 LOW, and CA1 HIGH at the rising edge of the clock. The bank addresses BA[2:0] are used to select the desired bank. Row addresses are used to determine which row to activate in the selected bank. The ACTIVATE command must be applied before any READ or WRITE operation can be executed. The device can accept a READ or WRITE command at t_{RCD} after the ACTIVATE command is issued. After a bank has been activated, it must be precharged before another ACTIVATE command can be applied to the same bank. The bank active and precharge times are defined as t_{RAS} and t_{RP} , respectively. The minimum time interval between successive ACTIVATE commands to the same bank is determined by the RAS cycle time of the device (t_{RC}). The minimum time interval between ACTIVATE commands to different banks is t_{RRD} .

Figure 77: ACTIVATE Command



- Notes:
1. $t_{RCD} = 3$, $t_{RP} = 3$, $t_{RRD} = 2$.
 2. A PRECHARGE ALL command uses t_{RPab} timing, and a single-bank PRECHARGE command uses t_{RPPb} timing. In this figure, t_{RP} is used to denote either an all-bank PRECHARGE or a single-bank PRECHARGE.

8-Bank Device Operation

Two rules regarding 8-bank device operation must be observed. One rule restricts the number of sequential ACTIVATE commands that can be issued; the second provides additional RAS precharge time for a PRECHARGE ALL command.

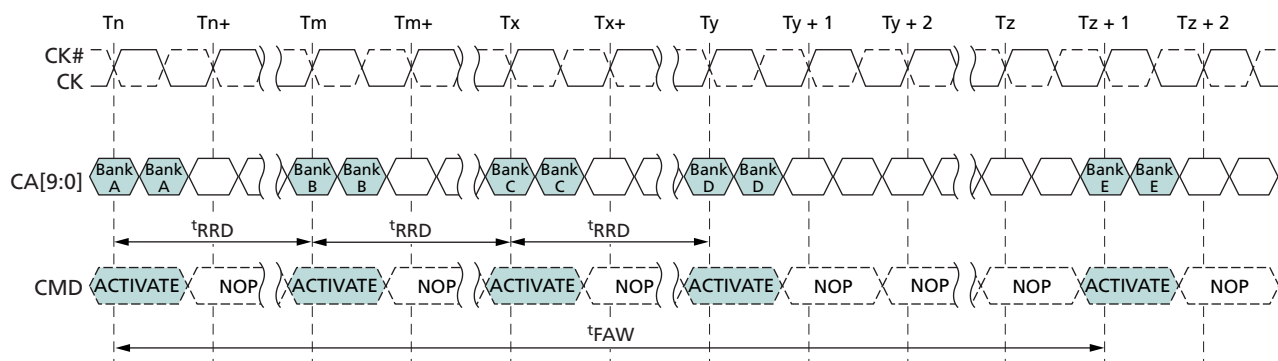
The 8-Bank Device Sequential Bank Activation Restriction: No more than four banks can be activated (or refreshed, in the case of REFpb) in a rolling t_{FAW} window. To convert to clocks, divide $t_{FAW}[ns]$ by $t_{CK}[ns]$, and round up to the next integer value. For example, if $RU(t_{FAW}/t_{CK})$ is 10 clocks, and an ACTIVATE command is issued in clock n , no more than three further ACTIVATE commands can be issued at or between clock $n + 1$ and $n + 9$. REFpb also counts as bank activation for purposes of t_{FAW} .

The 8-Bank Device PRECHARGE ALL Provision: t_{RP} for a PRECHARGE ALL command must equal t_{RPab} , which is greater than t_{RPPb} .



121-Ball NAND Flash with LPDDR2 MCP Read and Write Access Modes

Figure 78: t_{FAW} Timing (8-Bank Devices)



Note: 1. Exclusively for 8-bank devices.

Read and Write Access Modes

After a bank is activated, a READ or WRITE command can be issued with CS# LOW, CA0 HIGH, and CA1 LOW at the rising edge of the clock. CA2 must also be defined at this time to determine whether the access cycle is a READ operation (CA2 HIGH) or a WRITE operation (CA2 LOW). A single READ or WRITE command initiates a burst READ or burst WRITE operation on successive clock cycles.

A new burst access must not interrupt the previous 4-bit burst operation when BL = 4. When BL = 8 or BL = 16, READs can be interrupted by READs and WRITEs can be interrupted by WRITEs, provided that the interrupt occurs on a 4-bit boundary and that t_{CCD} is met.

Burst READ Command

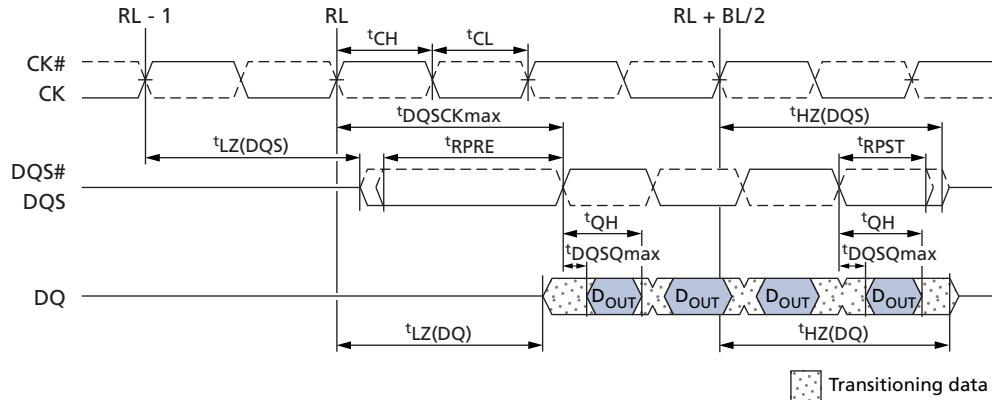
The burst READ command is initiated with CS# LOW, CA0 HIGH, CA1 LOW, and CA2 HIGH at the rising edge of the clock. The command address bus inputs, CA5r–CA6r and CA1f–CA9f, determine the starting column address for the burst. The read latency (RL) is defined from the rising edge of the clock on which the READ command is issued to the rising edge of the clock from which the t_{DQSCK} delay is measured. The first valid data is available $RL \times t_{CK} + t_{DQSCK} + t_{DQSQ}$ after the rising edge of the clock when the READ command is issued. The data strobe output is driven LOW t_{RPRE} before the first valid rising strobe edge. The first bit of the burst is synchronized with the first rising edge of the data strobe. Each subsequent data-out appears on each DQ pin, edge-aligned with the data strobe. The RL is programmed in the mode registers.

Pin input timings for the data strobe are measured relative to the crosspoint of DQS and its complement, DQS#.



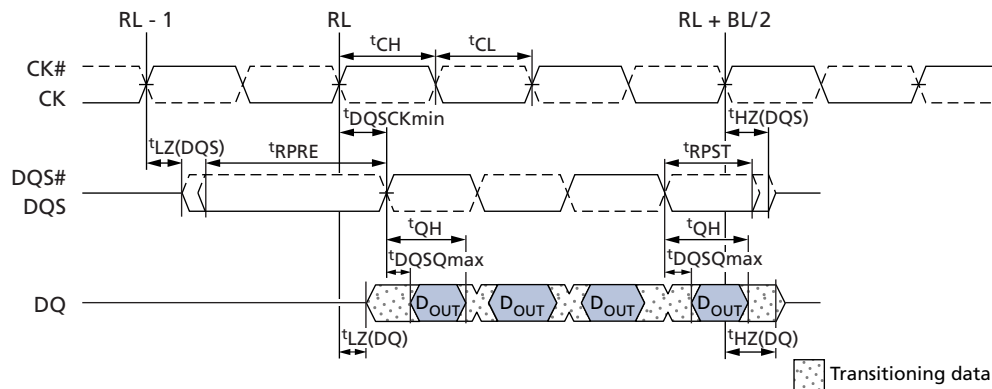
121-Ball NAND Flash with LPDDR2 MCP Burst READ Command

Figure 79: READ Output Timing – $t_{DQSK}(\text{MAX})$



- Notes:
1. t_{DQSK} can span multiple clock periods.
 2. An effective burst length of 4 is shown.

Figure 80: READ Output Timing – $t_{DQSK}(\text{MIN})$



- Note:
1. An effective burst length of 4 is shown.



121-Ball NAND Flash with LPDDR2 MCP Burst READ Command

Figure 81: Burst READ – RL = 5, BL = 4, $t_{DQSCK} > t_{CK}$

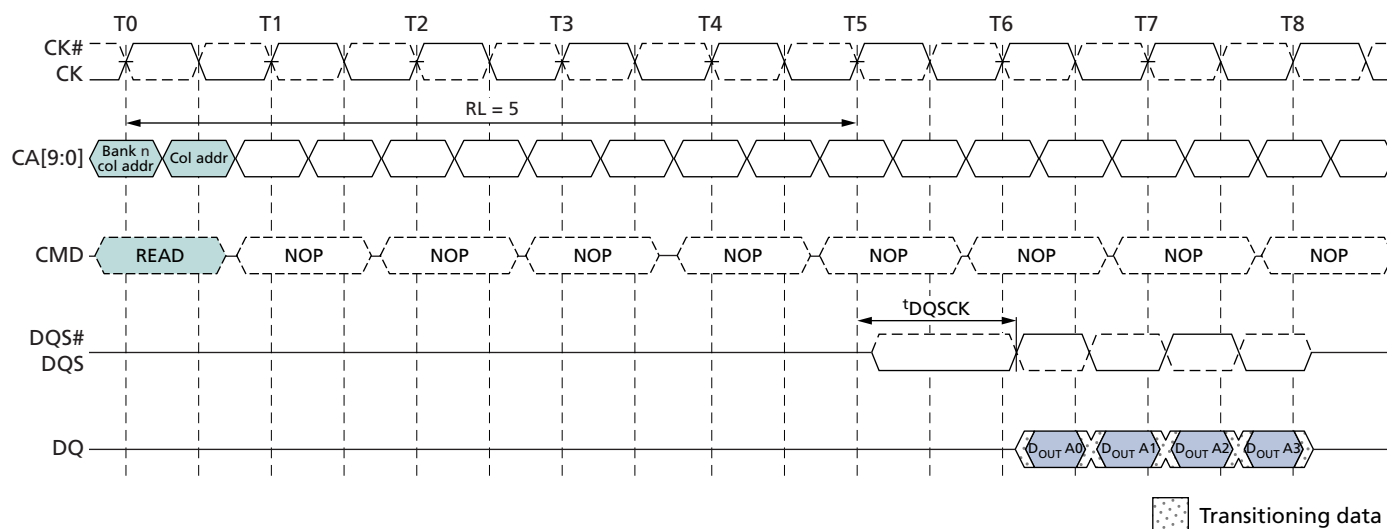
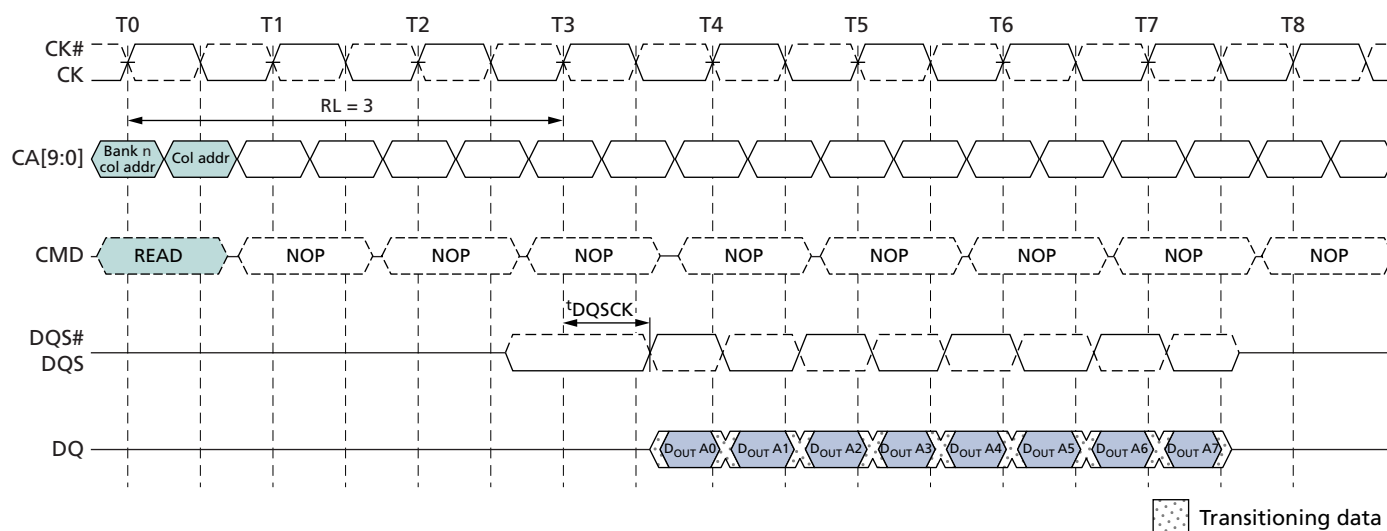


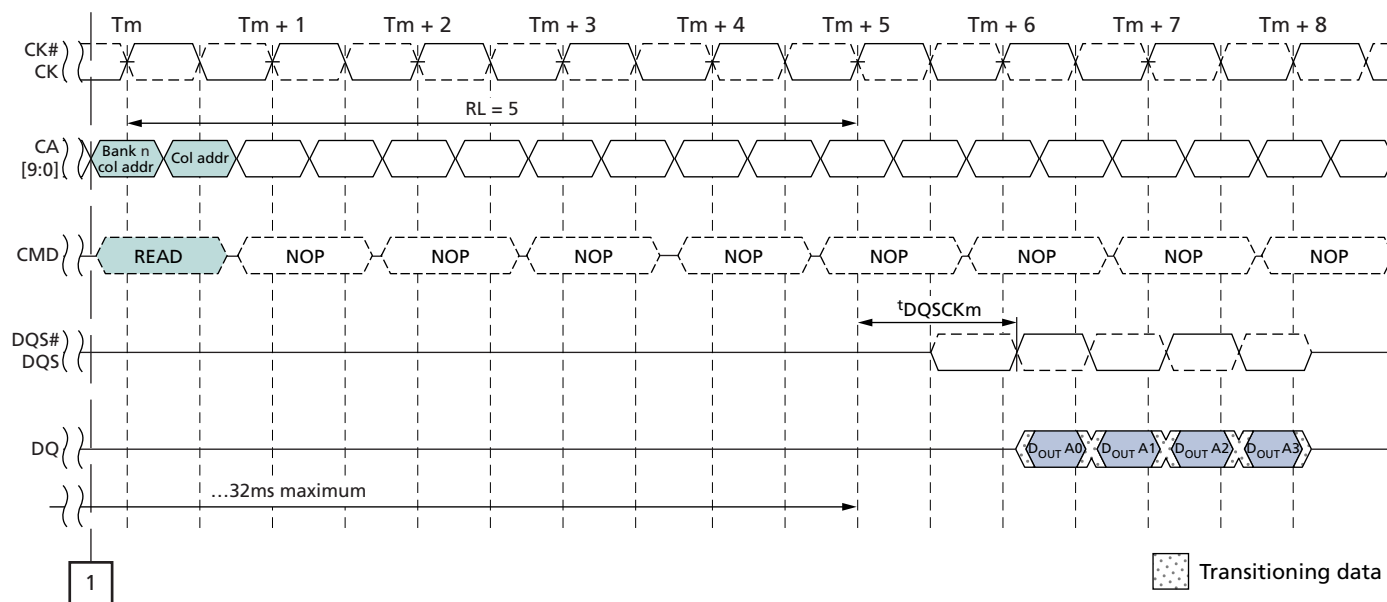
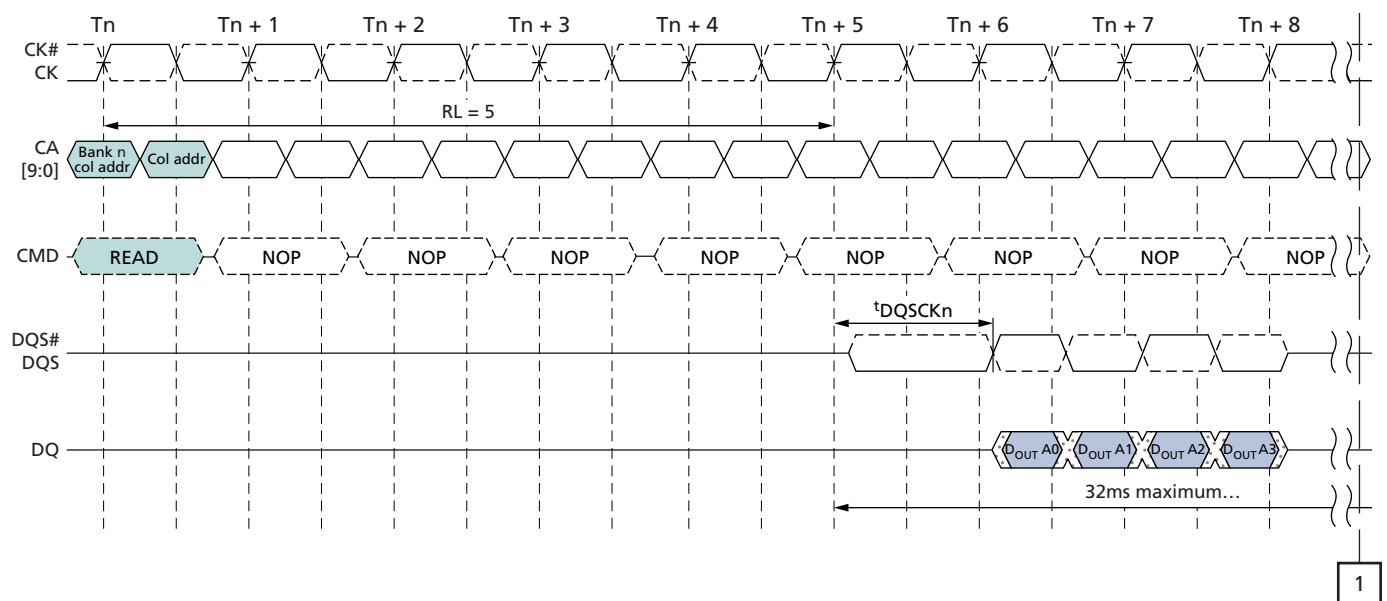
Figure 82: Burst READ – RL = 3, BL = 8, $t_{DQSCK} < t_{CK}$





121-Ball NAND Flash with LPDDR2 MCP Burst READ Command

Figure 83: t_{DQSKDL} Timing

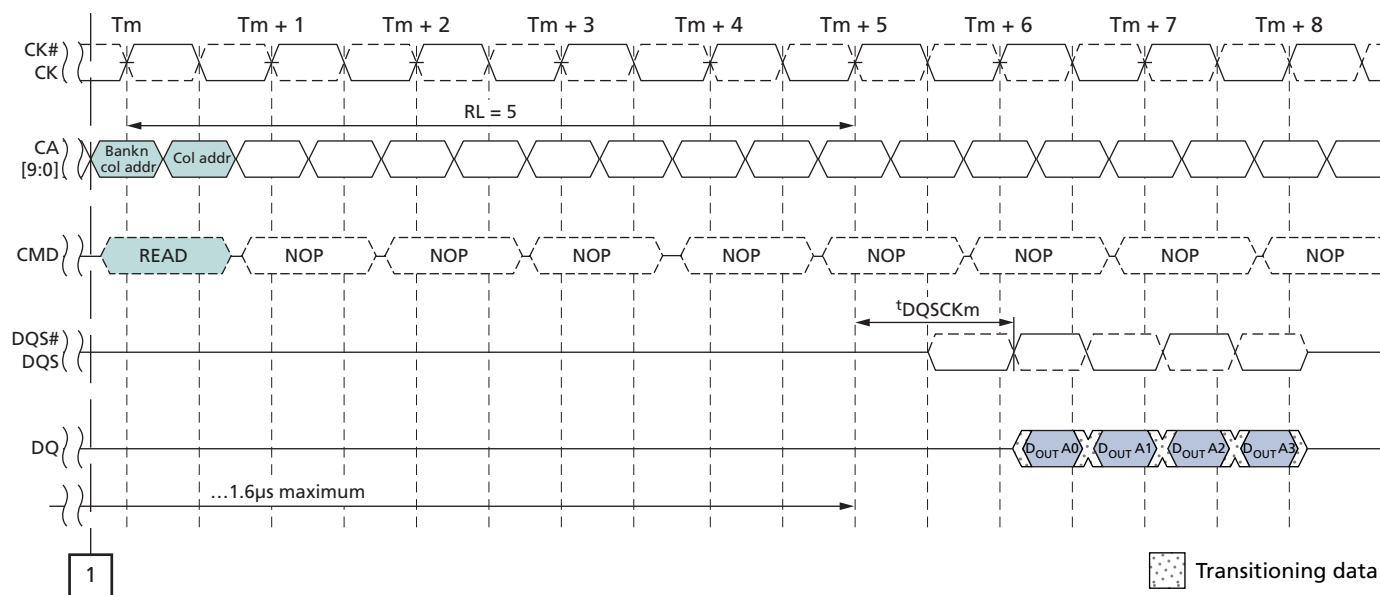
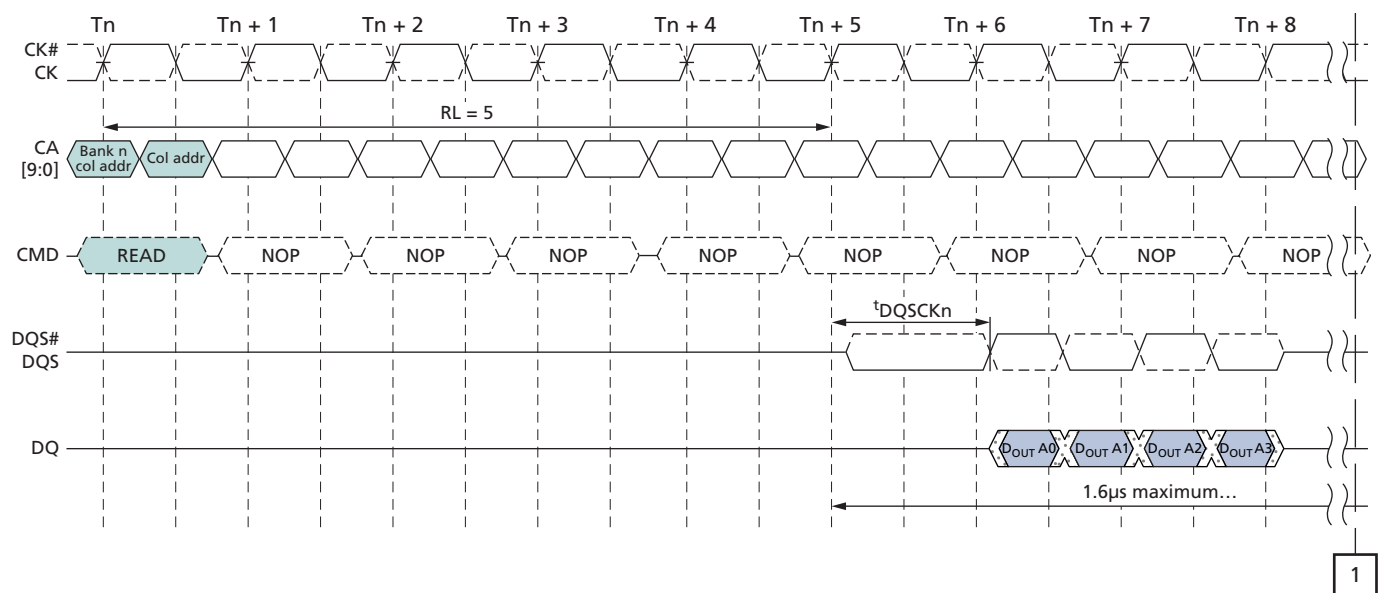


- Notes:
1. $t_{DQSKDL} = (t_{DQSKn} - t_{DQSKm})$.
 2. $t_{DQSKDL} (MAX)$ is defined as the maximum of ABS ($t_{DQSKn} - t_{DQSKm}$) for any (t_{DQSKn} , t_{DQSKm}) pair within any 32ms rolling window.



121-Ball NAND Flash with LPDDR2 MCP Burst READ Command

Figure 84: t_{DQSKDM} Timing

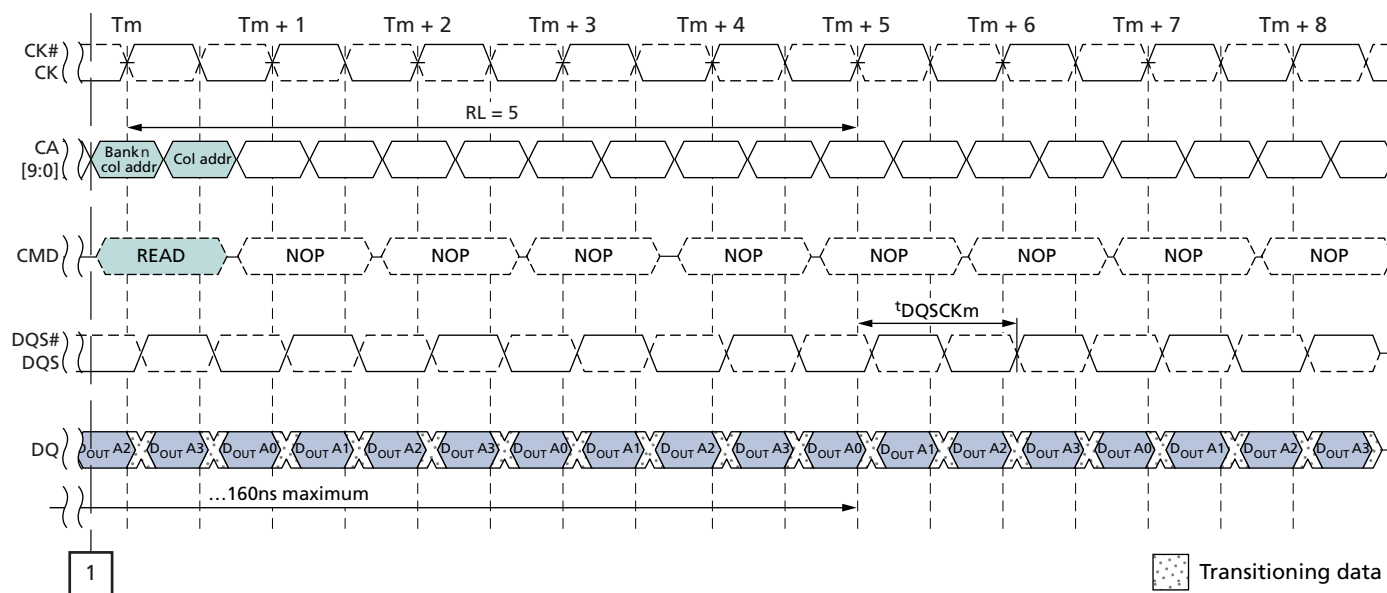
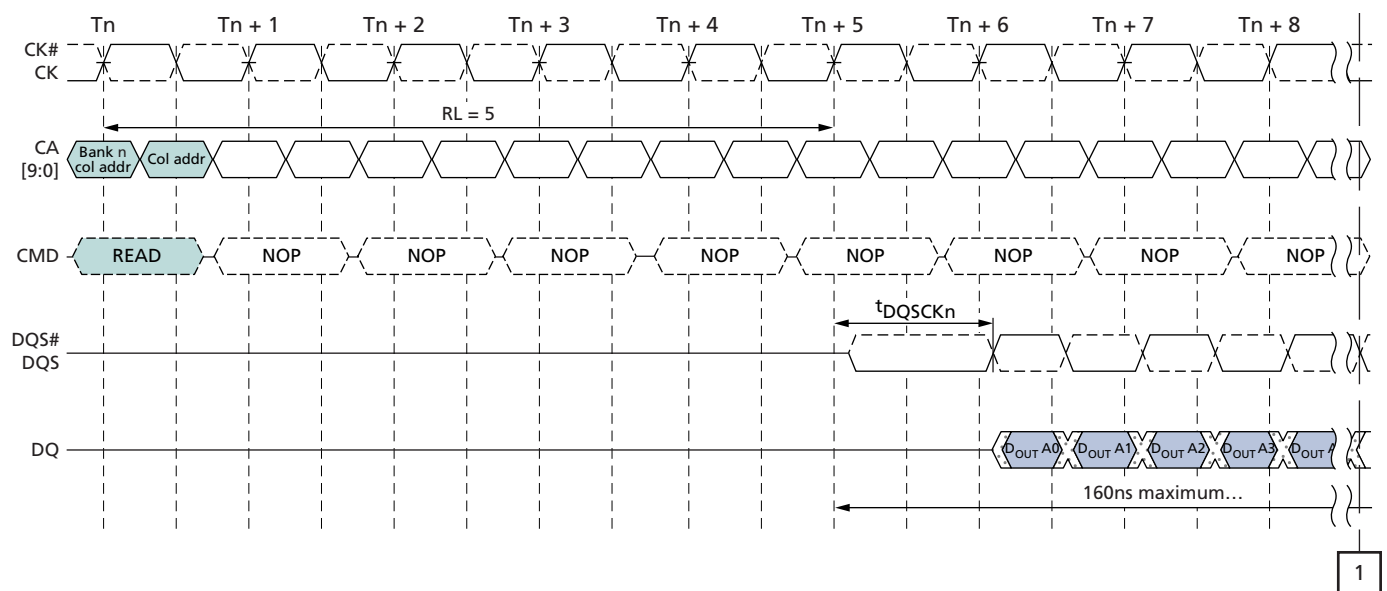


- Notes:
1. $t_{DQSKDM} = (t_{DQSKn} - t_{DQSKm})$.
 2. $t_{DQSKDM} (MAX)$ is defined as the maximum of ABS ($t_{DQSKn} - t_{DQSKm}$) for any (t_{DQSKn}, t_{DQSKm}) pair within any 1.6µs rolling window.



121-Ball NAND Flash with LPDDR2 MCP Burst READ Command

Figure 85: t_{DQSKDS} Timing

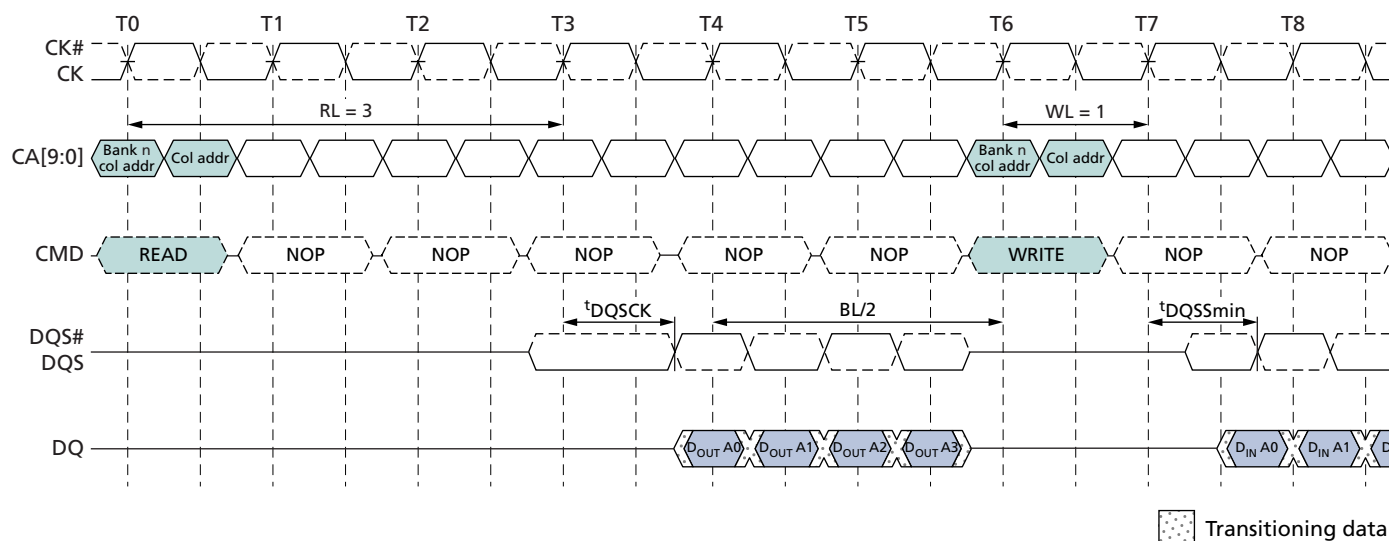


- Notes:
1. $t_{DQSKDS} = (t_{DQSKn} - t_{DQSKm})$.
 2. $t_{DQSKDS} (MAX)$ is defined as the maximum of ABS ($t_{DQSKn} - t_{DQSKm}$) for any (t_{DQSKn} , t_{DQSKm}) pair for READs within a consecutive burst, within any 160ns rolling window.



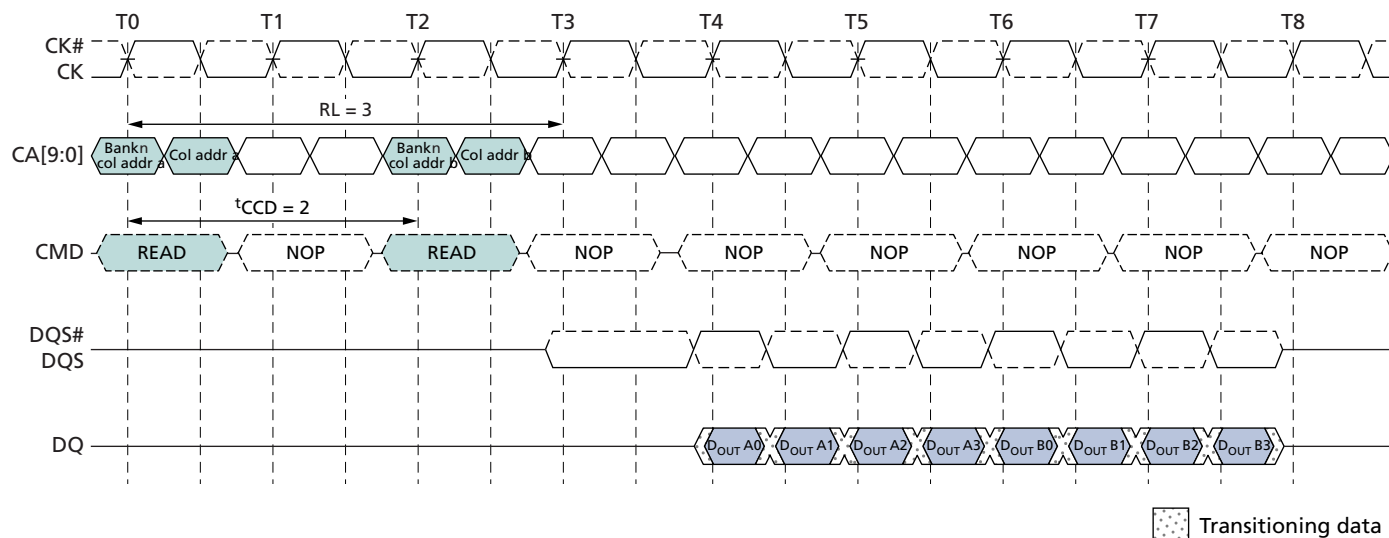
121-Ball NAND Flash with LPDDR2 MCP Burst READ Command

Figure 86: Burst READ Followed by Burst WRITE – RL = 3, WL = 1, BL = 4



The minimum time from the burst READ command to the burst WRITE command is defined by the read latency (RL) and the burst length (BL). Minimum READ-to-WRITE latency is $RL + RU(t_{DQSCK}(MAX)/t_{CK}) + BL/2 + 1 - WL$ clock cycles. Note that if a READ burst is truncated with a burst TERMINATE (BST) command, the effective burst length of the truncated READ burst should be used for BL when calculating the minimum READ-to-WRITE delay.

Figure 87: Seamless Burst READ – RL = 3, BL = 4, $t_{CCD} = 2$



A seamless burst READ operation is supported by enabling a READ command at every other clock cycle for BL = 4 operation, every fourth clock cycle for BL = 8 operation, and



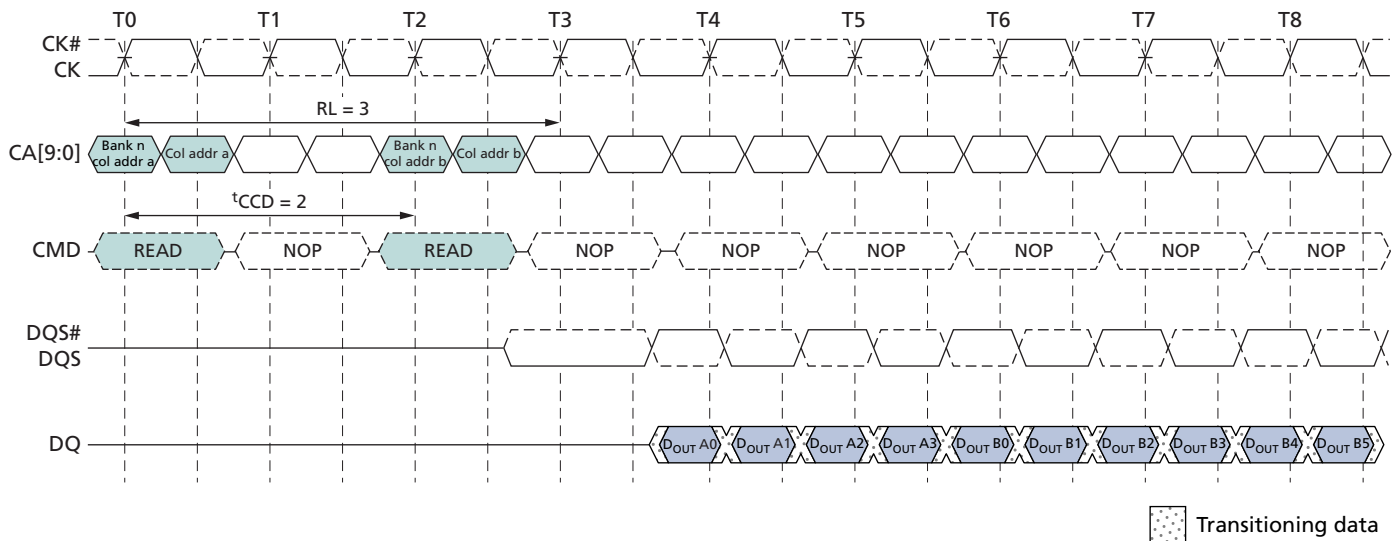
121-Ball NAND Flash with LPDDR2 MCP Burst WRITE Command

every eighth clock cycle for BL = 16 operation. This operation is supported as long as the banks are activated, whether the accesses read the same or different banks.

READs Interrupted by a READ

A burst READ can be interrupted by another READ with a 4-bit burst boundary, provided that t_{CCD} is met.

Figure 88: READ Burst Interrupt Example – RL = 3, BL = 8, $t_{CCD} = 2$



Note: 1. READs can only be interrupted by other READs or the BST command.

Burst WRITE Command

The burst WRITE command is initiated with CS# LOW, CA0 HIGH, CA1 LOW, and CA2 LOW at the rising edge of the clock. The command address bus inputs, CA5r–CA6r and CA1f–CA9f, determine the starting column address for the burst. Write latency (WL) is defined from the rising edge of the clock on which the WRITE command is issued to the rising edge of the clock from which the t_{DQSS} delay is measured. The first valid data must be driven $WL \times ^tCK + ^tDQSS$ from the rising edge of the clock from which the WRITE command is issued. The data strobe signal (DQS) must be driven LOW tWPRE prior to data input. The burst cycle data bits must be applied to the DQ pins tDS prior to the associated edge of the DQS and held valid until tDH after that edge. Burst data is sampled on successive edges of the DQS until the 4-, 8-, or 16-bit burst length is completed. After a burst WRITE operation, tWR must be satisfied before a PRECHARGE command to the same bank can be issued.

Pin input timings are measured relative to the crosspoint of DQS and its complement, DQS#.



121-Ball NAND Flash with LPDDR2 MCP Burst WRITE Command

Figure 89: Data Input (WRITE) Timing

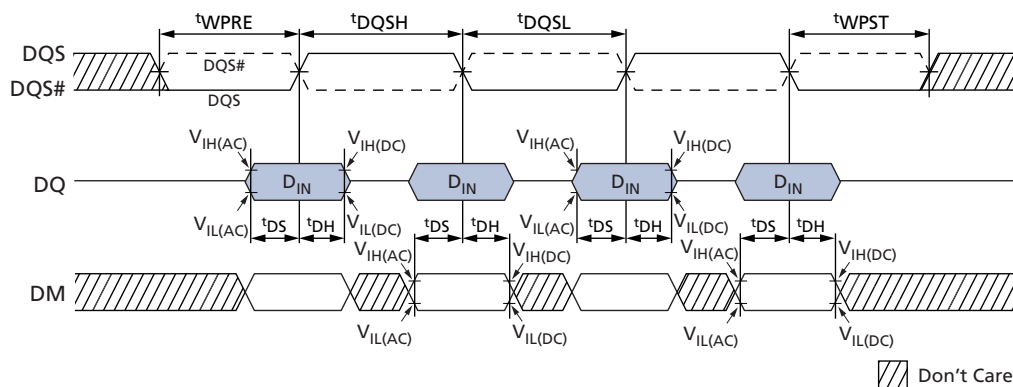
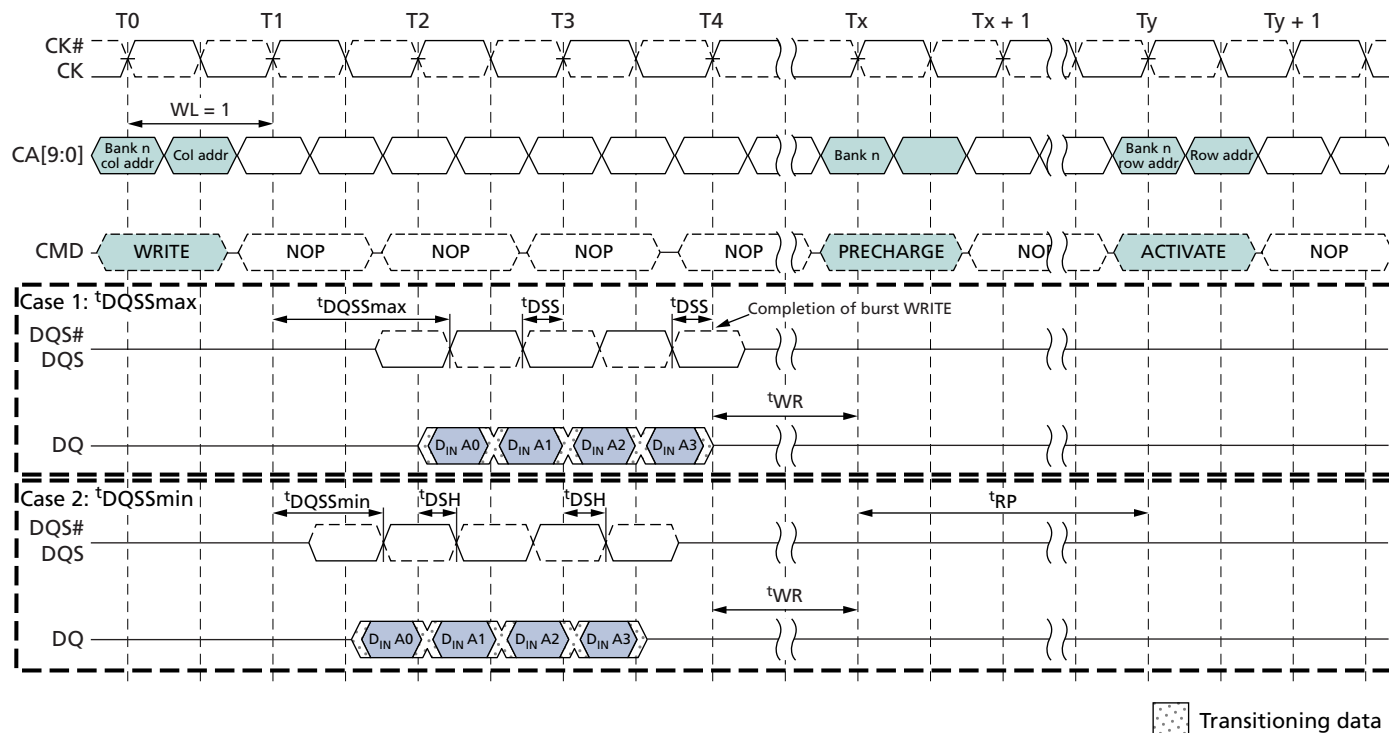


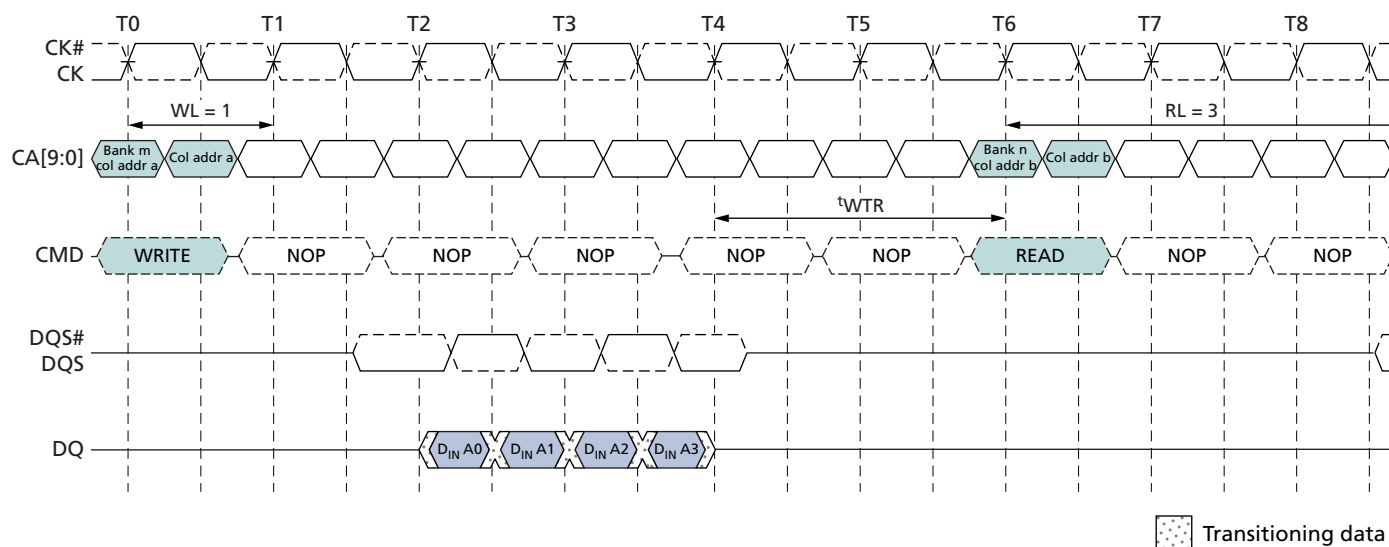
Figure 90: Burst WRITE – WL = 1, BL = 4





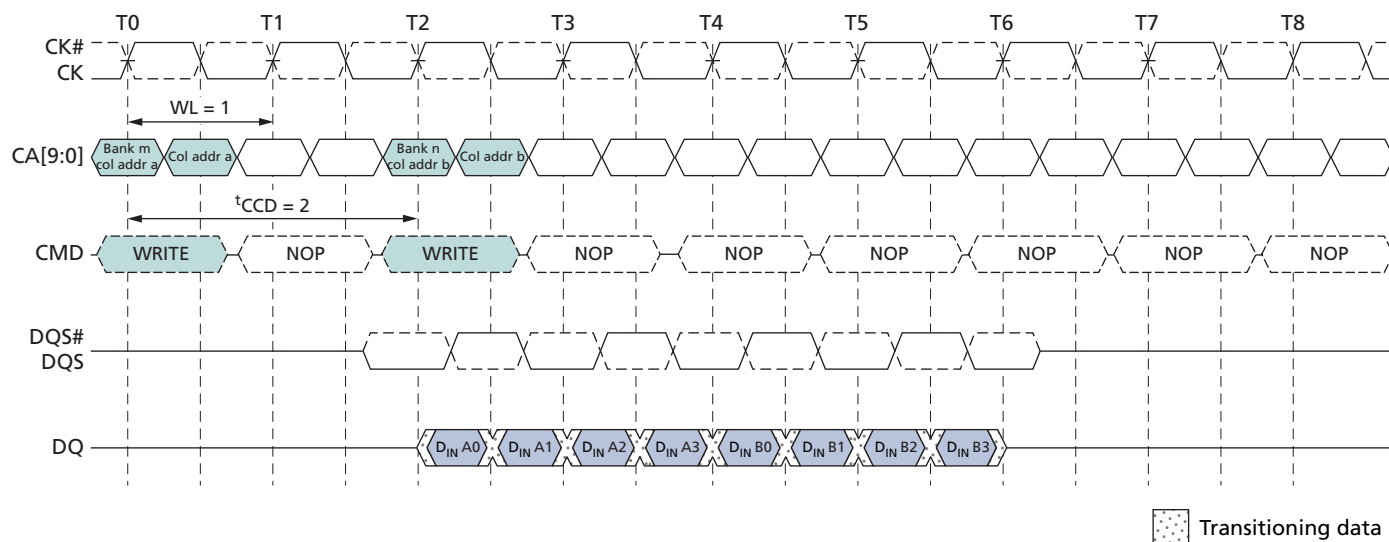
121-Ball NAND Flash with LPDDR2 MCP Burst WRITE Command

Figure 91: Burst WRITE Followed by Burst READ – RL = 3, WL = 1, BL = 4



- Notes:
1. The minimum number of clock cycles from the burst WRITE command to the burst READ command for any bank is $[WL + 1 + BL/2 + RU(t_{WTR}/t_{CK})]$.
 2. t_{WTR} starts at the rising edge of the clock after the last valid input data.
 3. If a WRITE burst is truncated with a BST command, the effective burst length of the truncated WRITE burst should be used as BL to calculate the minimum WRITE-to-READ delay.

Figure 92: Seamless Burst WRITE – WL = 1, BL = 4, $t_{CCD} = 2$



- Note:
1. The seamless burst WRITE operation is supported by enabling a WRITE command every other clock for BL = 4 operation, every four clocks for BL = 8 operation, or every eight clocks for BL = 16 operation. This operation is supported for any activated bank.



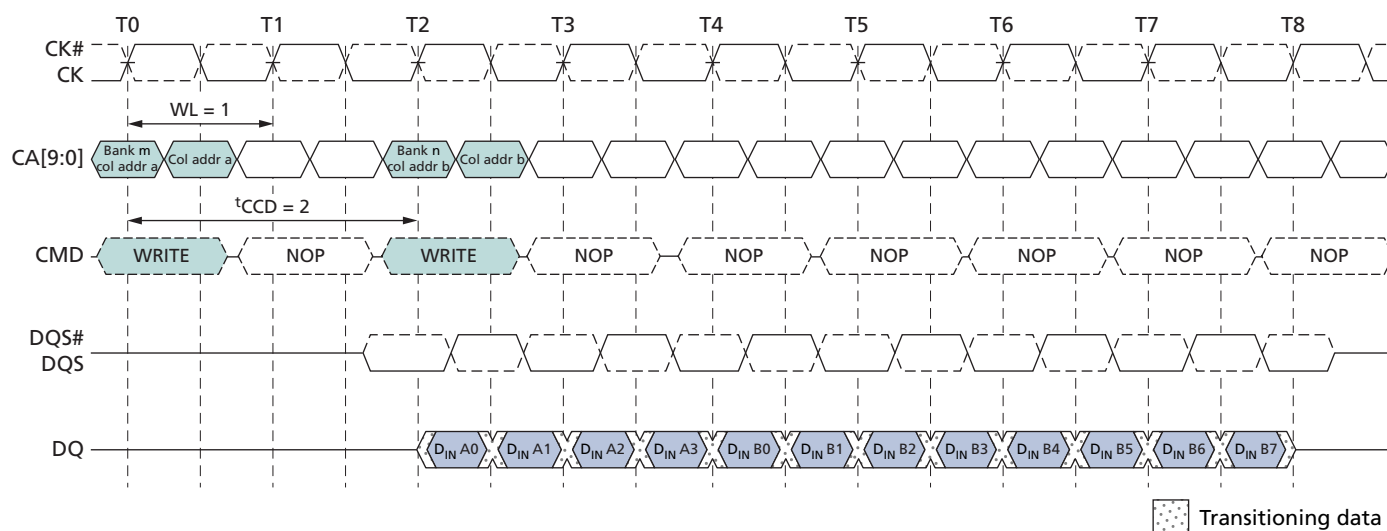
121-Ball NAND Flash with LPDDR2 MCP BURST TERMINATE Command

WRITES Interrupted by a WRITE

A burst WRITE can only be interrupted by another WRITE with a 4-bit burst boundary, provided that t_{CCD} (MIN) is met.

A WRITE burst interrupt can occur on even clock cycles after the initial WRITE command, provided that t_{CCD} (MIN) is met.

Figure 93: WRITE Burst Interrupt Timing – WL = 1, BL = 8, $t_{CCD} = 2$



- Notes:
1. WRITES can only be interrupted by other WRITES or the BST command.
 2. The effective burst length of the first WRITE equals two times the number of clock cycles between the first WRITE and the interrupting WRITE.

BURST TERMINATE Command

The BURST TERMINATE (BST) command is initiated with CS# LOW, CA0 HIGH, CA1 HIGH, CA2 LOW, and CA3 LOW at the rising edge of the clock. A BST command can only be issued to terminate an active READ or WRITE burst. Therefore, a BST command can only be issued up to and including $BL/2 - 1$ clock cycles after a READ or WRITE command. The effective burst length of a READ or WRITE command truncated by a BST command is as follows:

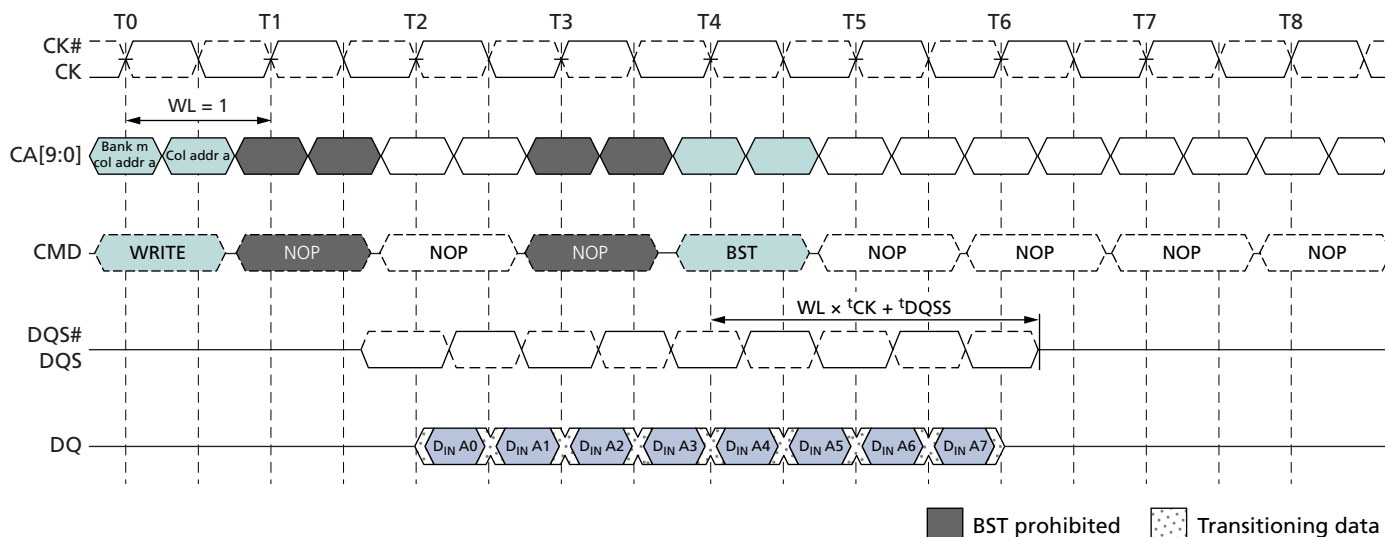
- Effective burst length = $2 \times (\text{number of clock cycles from the READ or WRITE command to the BST command})$.
- If a READ or WRITE burst is truncated with a BST command, the effective burst length of the truncated burst should be used for BL when calculating the minimum READ-to-WRITE or WRITE-to-READ delay.
- The BST command only affects the most recent READ or WRITE command. The BST command truncates an ongoing READ burst $RL \times t_{CK} + t_{DQSC} + t_{DQSQ}$ after the rising edge of the clock where the BST command is issued. The BST command truncates an ongoing WRITE burst $WL \times t_{CK} + t_{DQSS}$ after the rising edge of the clock where the BST command is issued.



121-Ball NAND Flash with LPDDR2 MCP BURST TERMINATE Command

- The 4-bit prefetch architecture enables BST command assertion on even clock cycles following a WRITE or READ command. The effective burst length of a READ or WRITE command truncated by a BST command is thus an integer multiple of four.

Figure 94: Burst WRITE Truncated by BST – WL = 1, BL = 16

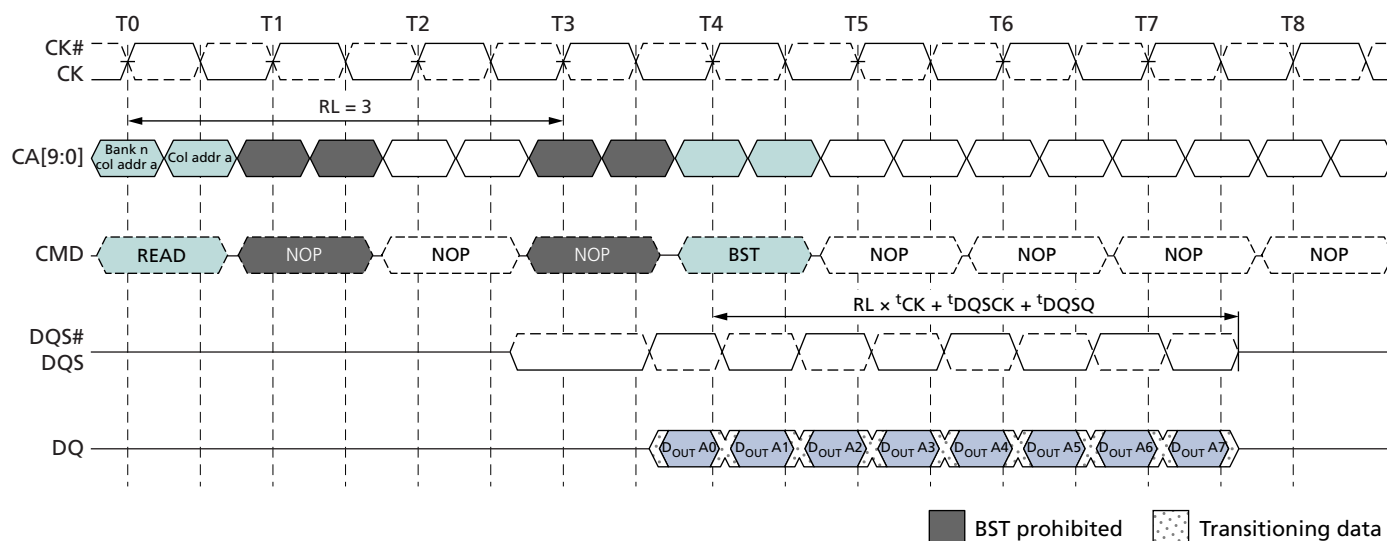


- Notes:
1. The BST command truncates an ongoing WRITE burst $WL \times t_{CK} + t_{DQSS}$ after the rising edge of the clock where the BST command is issued.
 2. BST can only be issued an even number of clock cycles after the WRITE command.
 3. Additional BST commands are not supported after T4 and must not be issued until after the next READ or WRITE command.



121-Ball NAND Flash with LPDDR2 MCP Write Data Mask

Figure 95: Burst READ Truncated by BST – RL = 3, BL = 16

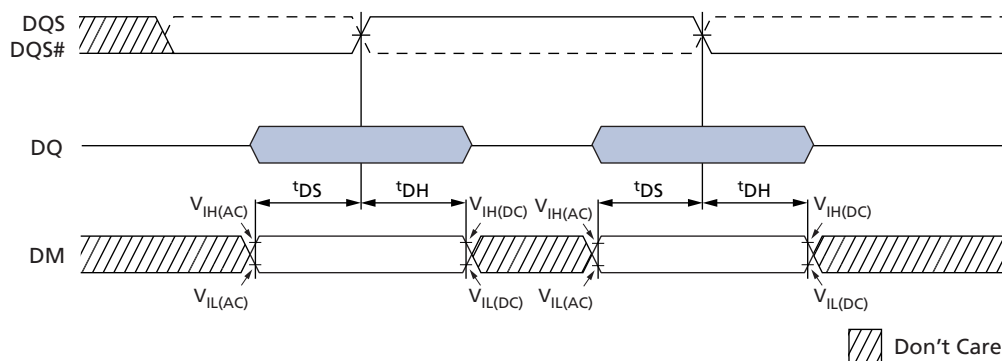


- Notes:
1. The BST command truncates an ongoing READ burst ($RL \times t_{CK} + t_{DQSK} + t_{DQSQ}$) after the rising edge of the clock where the BST command is issued.
 2. BST can only be issued an even number of clock cycles after the READ command.
 3. Additional BST commands are not supported after T4 and must not be issued until after the next READ or WRITE command.

Write Data Mask

On LPDDR2 devices, one write data mask (DM) pin for each data byte (DQ) is supported, consistent with the implementation on LPDDR SDRAM. Each DM can mask its respective DQ for any given cycle of the burst. Data mask timings match data bit timing, but are inputs only. Internal data mask loading is identical to data bit loading to ensure matched system timing.

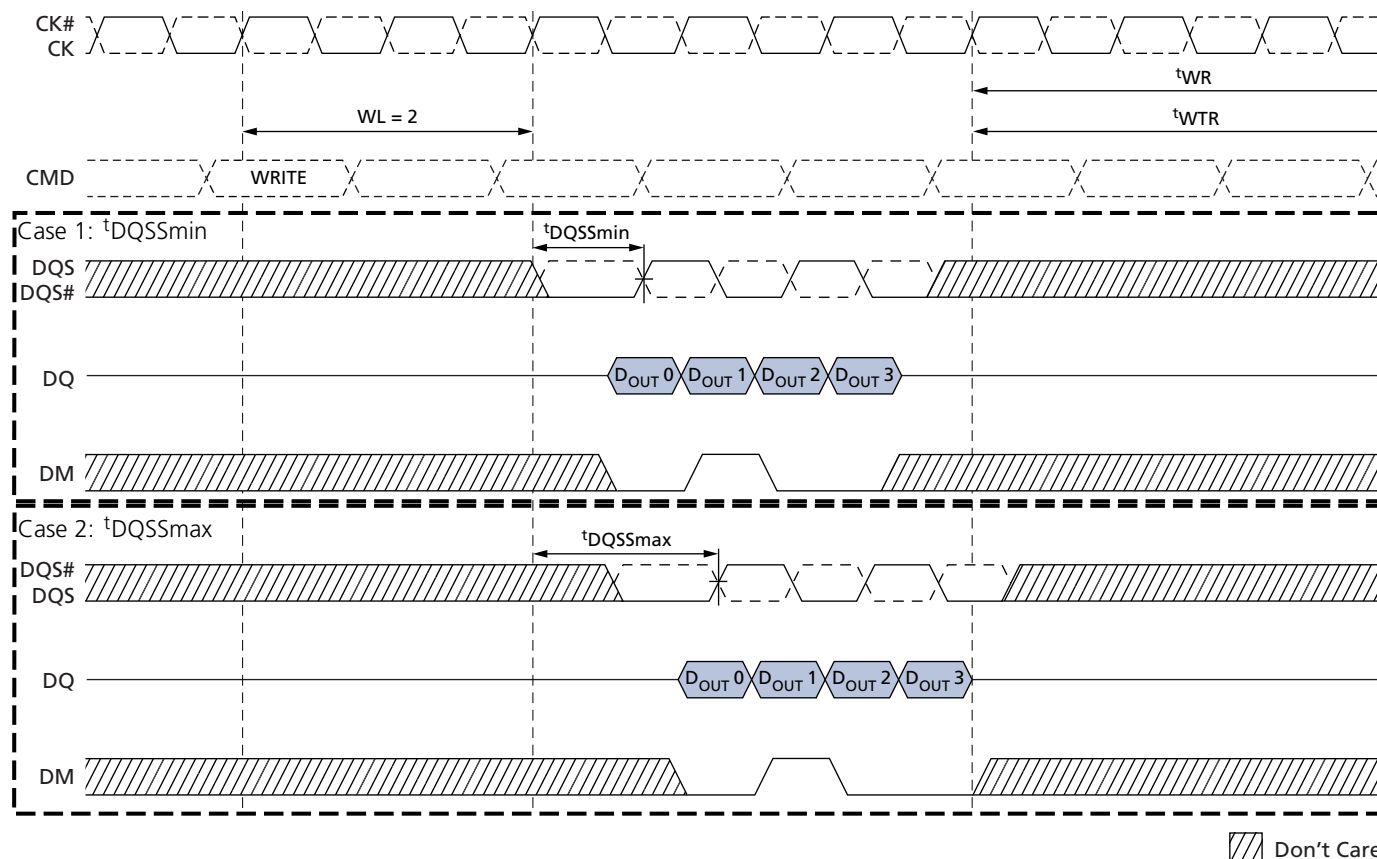
Figure 96: Data Mask Timing





121-Ball NAND Flash with LPDDR2 MCP PRECHARGE Command

Figure 97: Write Data Mask – Second Data Bit Masked



Note: 1. For the data mask function, $WL = 2$, $BL = 4$ is shown; the second data bit is masked.

PRECHARGE Command

The PRECHARGE command is used to precharge or close a bank that has been activated. The PRECHARGE command is initiated with CS# LOW, CA0 HIGH, CA1 HIGH, CA2 LOW, and CA3 HIGH at the rising edge of the clock. The PRECHARGE command can be used to precharge each bank independently or all banks simultaneously. For 4-bank devices, the AB flag and bank address bits BA0 and BA1 are used to determine which bank(s) to precharge. For 8-bank devices, the AB flag and the bank address bits BA0, BA1, and BA2 are used to determine which bank(s) to precharge. The precharged bank(s) will be available for subsequent row access t_{RPab} after an all bank PRECHARGE command is issued, or t_{RPpb} after a single-bank PRECHARGE command is issued.

To ensure that 8-bank devices can meet the instantaneous current demand required to operate, the row precharge time (t_{RP}) for an all bank PRECHARGE in 8-bank devices (t_{RPab}) will be longer than the row precharge time for a single-bank PRECHARGE (t_{RPpb}). For 4-bank devices, t_{RPab} is equal to t_{RPpb} .

ACTIVATE to PRECHARGE timing is shown in ACTIVATE Command (page 125).



121-Ball NAND Flash with LPDDR2 MCP PRECHARGE Command

Table 73: Bank Selection for PRECHARGE by Address Bits

AB (CA4r)	BA2 (CA9r)	BA1 (CA8r)	BA0 (CA7r)	Precharged Bank(s) 4-Bank Device	Precharged Bank(s) 8-Bank Device
0	0	0	0	Bank 0 only	Bank 0 only
0	0	0	1	Bank 1 only	Bank 1 only
0	0	1	0	Bank 2 only	Bank 2 only
0	0	1	1	Bank 3 only	Bank 3 only
0	1	0	0	Bank 0 only	Bank 4 only
0	1	0	1	Bank 1 only	Bank 5 only
0	1	1	0	Bank 2 only	Bank 6 only
0	1	1	1	Bank 3 only	Bank 7 only
1	Don't Care	Don't Care	Don't Care	All banks	All banks

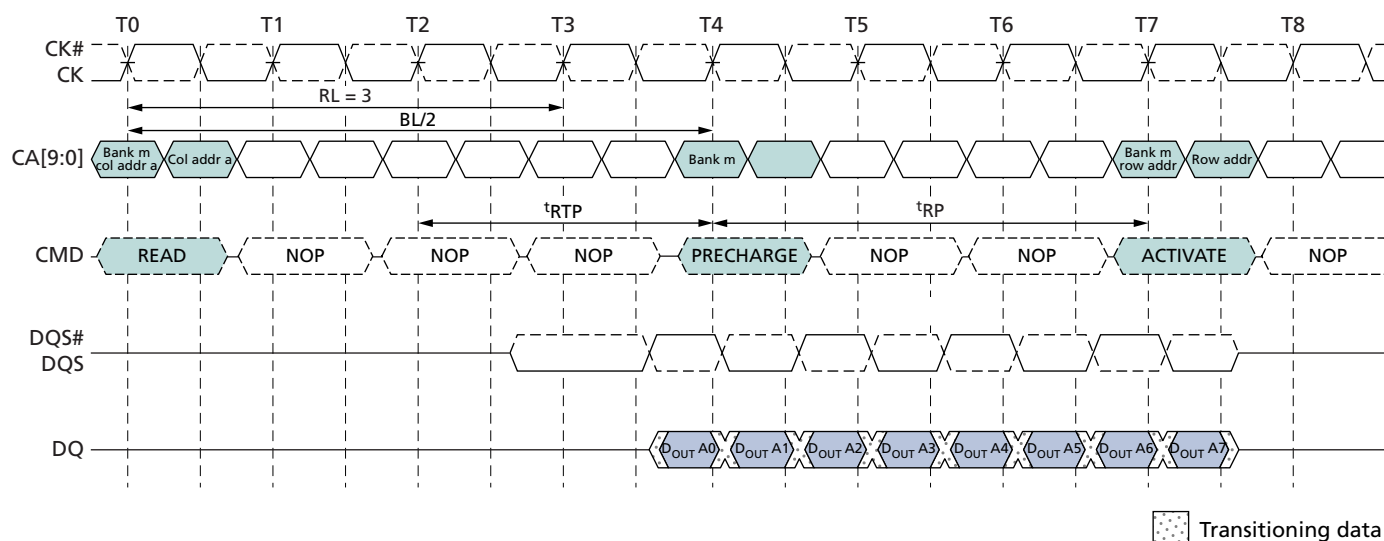
READ Burst Followed by PRECHARGE

For the earliest possible precharge, the PRECHARGE command can be issued BL/2 clock cycles after a READ command. A new bank ACTIVATE command can be issued to the same bank after the row precharge time (t_{RP}) has elapsed. A PRECHARGE command cannot be issued until after t_{RAS} is satisfied.

The minimum READ-to-PRECHARGE time (t_{RTP}) must also satisfy a minimum analog time from the rising clock edge that initiates the last 4-bit prefetch of a READ command. t_{RTP} begins BL/2 - 2 clock cycles after the READ command.

If the burst is truncated by a BST command, the effective BL value is used to calculate when t_{RTP} begins.

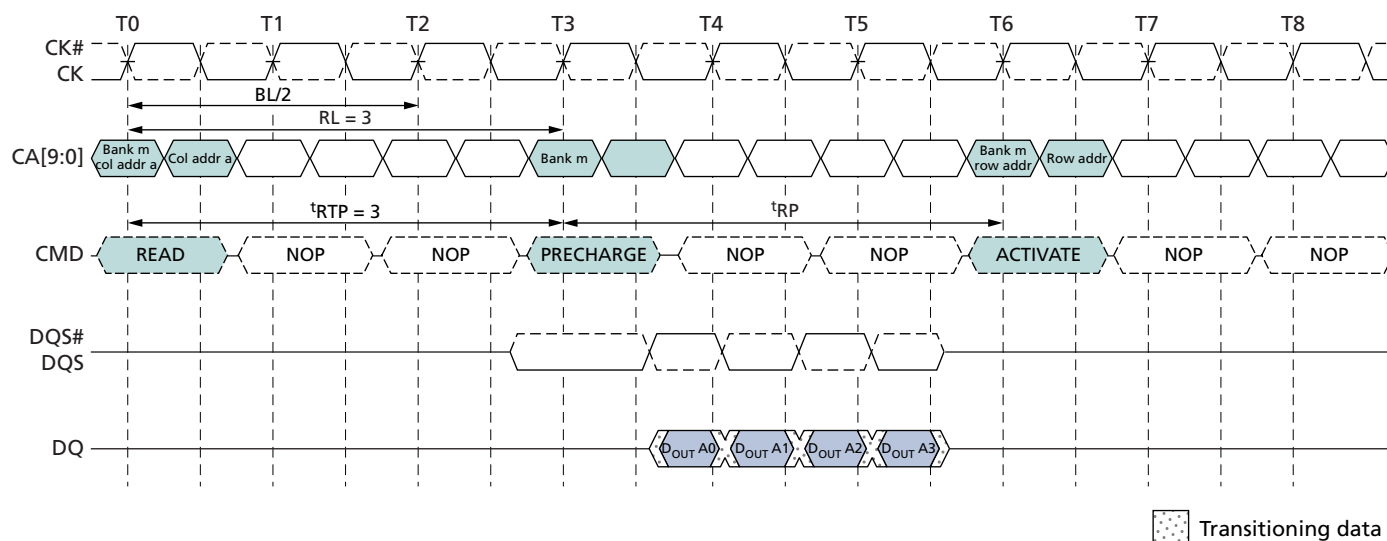
Figure 98: READ Burst Followed by PRECHARGE – RL = 3, BL = 8, $RU(t_{RTP(MIN)}/t_{CK}) = 2$





121-Ball NAND Flash with LPDDR2 MCP PRECHARGE Command

Figure 99: READ Burst Followed by PRECHARGE – RL = 3, BL = 4, $RU(t_{RTP(MIN)}/t_{CK}) = 3$



WRITE Burst Followed by PRECHARGE

For WRITE cycles, a WRITE recovery time (t_{WR}) must be provided before a PRECHARGE command can be issued. t_{WR} delay is referenced from the completion of the burst WRITE. The PRECHARGE command must not be issued prior to the t_{WR} delay. For WRITE-to-PRECHARGE timings see Table 74 (page 144).

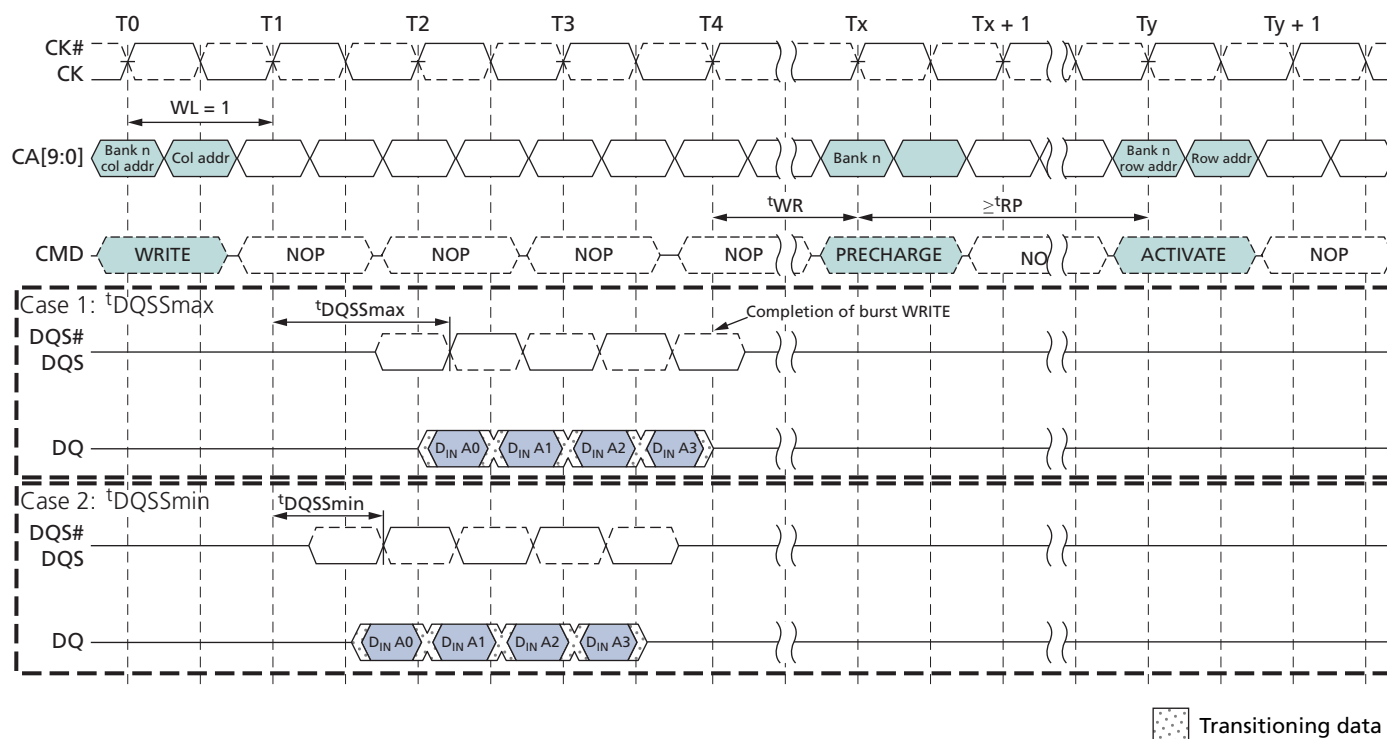
These devices write data to the array in prefetch quadruples (prefetch = 4). An internal WRITE operation can only begin after a prefetch group has been completely latched.

The minimum WRITE-to-PRECHARGE time for commands to the same bank is $WL + BL/2 + 1 + RU(t_{WR}/t_{CK})$ clock cycles. For untruncated bursts, BL is the value set in the mode register. For truncated bursts, BL is the effective burst length.



121-Ball NAND Flash with LPDDR2 MCP PRECHARGE Command

Figure 100: WRITE Burst Followed by PRECHARGE – WL = 1, BL = 4



Auto Precharge

Before a new row can be opened in an active bank, the active bank must be precharged using either the PRECHARGE command or the auto precharge function. When a READ or WRITE command is issued to the device, the auto precharge bit (AP) can be set to enable the active bank to automatically begin precharge at the earliest possible moment during the burst READ or WRITE cycle.

If AP is LOW when the READ or WRITE command is issued, then normal READ or WRITE burst operation is executed and the bank remains active at the completion of the burst.

If AP is HIGH when the READ or WRITE command is issued, the auto precharge function is engaged. This feature enables the PRECHARGE operation to be partially or completely hidden during burst READ cycles (dependent upon READ or WRITE latency), thus improving system performance for random data access.

READ Burst with Auto Precharge

If AP (CA0f) is HIGH when a READ command is issued, the READ with auto precharge function is engaged.

These devices start an auto precharge on the rising edge of the clock BL/2 or BL/2 - 2 + RU(tRTP/tCK) clock cycles later than the READ with auto precharge command, whichever is greater. For auto precharge calculations see Table 74 (page 144).

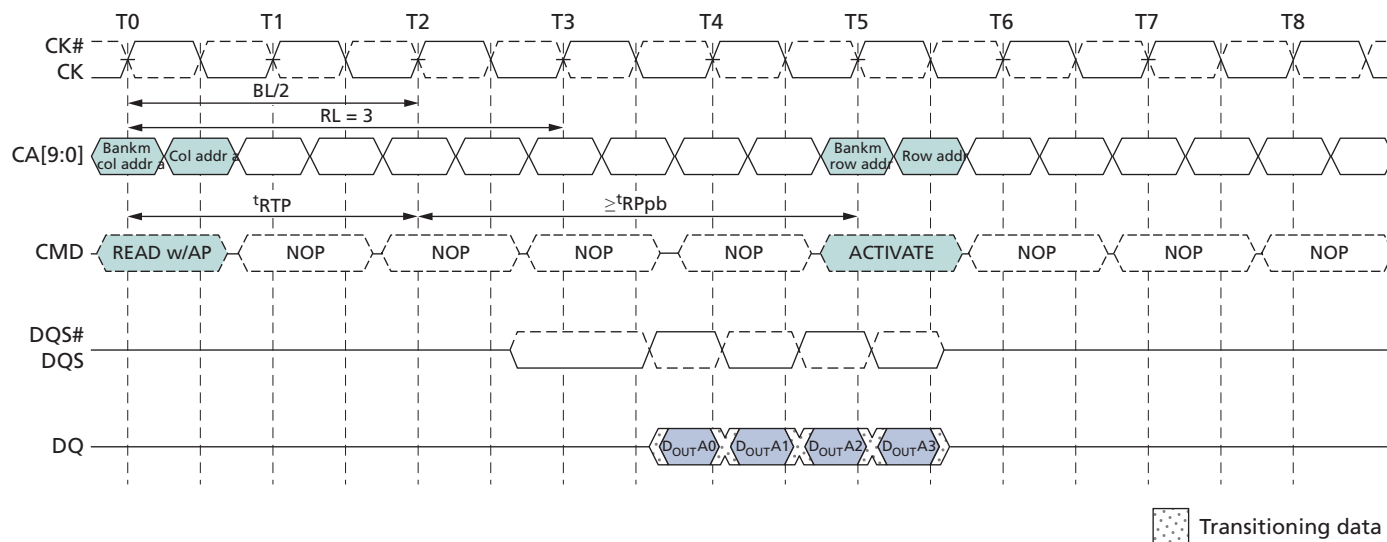


121-Ball NAND Flash with LPDDR2 MCP PRECHARGE Command

Following an auto precharge operation, an ACTIVATE command can be issued to the same bank if the following two conditions are satisfied simultaneously:

- The RAS precharge time (t_{RP}) has been satisfied from the clock at which the auto precharge begins.
- The RAS cycle time (t_{RC}) from the previous bank activation has been satisfied.

Figure 101: READ Burst with Auto Precharge – RL = 3, BL = 4, $RU(t_{RTP(MIN)}/t_{CK}) = 2$



WRITE Burst with Auto Precharge

If AP (CA0f) is HIGH when a WRITE command is issued, the WRITE with auto precharge function is engaged. The device starts an auto precharge at the clock rising edge t_{WR} cycles after the completion of the burst WRITE.

Following a WRITE with auto precharge, an ACTIVATE command can be issued to the same bank if the following two conditions are met:

- The RAS precharge time (t_{RP}) has been satisfied from the clock at which the auto precharge begins.
- The RAS cycle time (t_{RC}) from the previous bank activation has been satisfied.



121-Ball NAND Flash with LPDDR2 MCP PRECHARGE Command

Figure 102: WRITE Burst with Auto Precharge – WL = 1, BL = 4

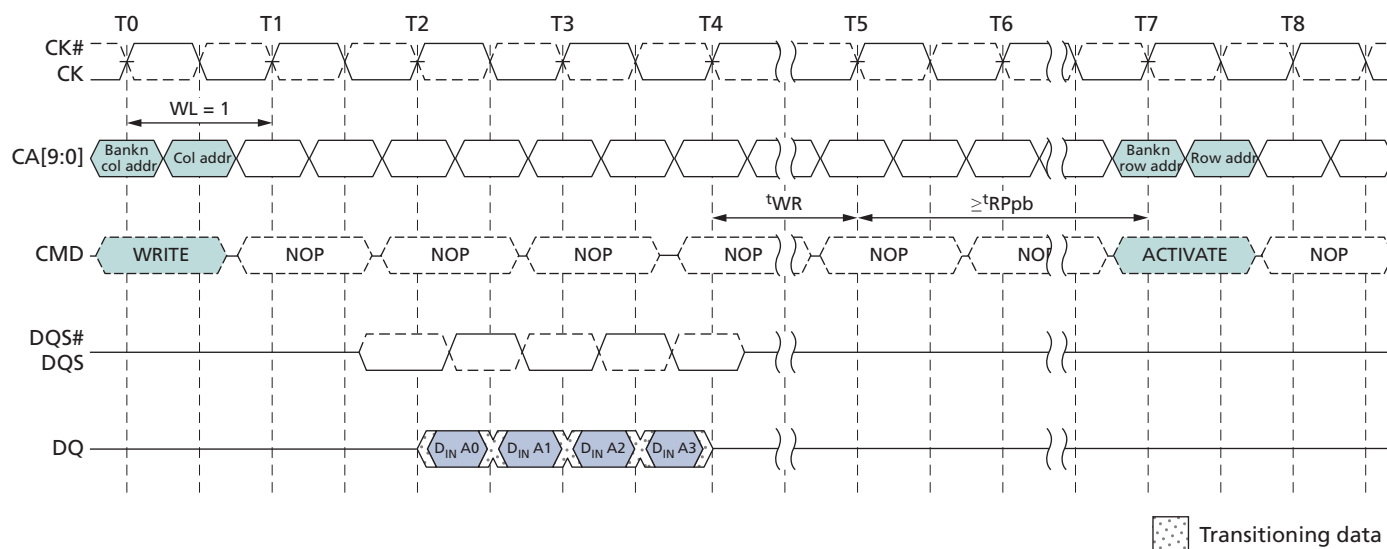


Table 74: PRECHARGE and Auto Precharge Clarification

From Command	To Command	Minimum Delay Between Commands	Unit	Notes
READ	PRECHARGE to same bank as READ	$BL/2 + \text{MAX}(2, RU(t_{RTP}/t_{CK})) - 2$	CLK	1
	PRECHARGE ALL	$BL/2 + \text{MAX}(2, RU(t_{RTP}/t_{CK})) - 2$	CLK	1
BST	PRECHARGE to same bank as READ	1	CLK	1
	PRECHARGE ALL	1	CLK	1
READ w/AP	PRECHARGE to same bank as READ w/AP	$BL/2 + \text{MAX}(2, RU(t_{RTP}/t_{CK})) - 2$	CLK	1, 2
	PRECHARGE ALL	$BL/2 + \text{MAX}(2, RU(t_{RTP}/t_{CK})) - 2$	CLK	1
	ACTIVATE to same bank as READ w/AP	$BL/2 + \text{MAX}(2, RU(t_{RTP}/t_{CK})) - 2 + RU(t_{RPpb}/t_{CK})$	CLK	1
	WRITE or WRITE w/AP (same bank)	Illegal	CLK	3
	WRITE or WRITE w/AP (different bank)	$RL + BL/2 + RU(t_{DQSCKmax}/t_{CK}) - WL + 1$	CLK	3
	READ or READ w/AP (same bank)	Illegal	CLK	3
	READ or READ w/AP (different bank)	BL/2	CLK	3
WRITE	PRECHARGE to same bank as WRITE	$WL + BL/2 + RU(t_{WR}/t_{CK}) + 1$	CLK	1
	PRECHARGE ALL	$WL + BL/2 + RU(t_{WR}/t_{CK}) + 1$	CLK	1
BST	PRECHARGE to same bank as WRITE	$WL + RU(t_{WR}/t_{CK}) + 1$	CLK	1
	PRECHARGE ALL	$WL + RU(t_{WR}/t_{CK}) + 1$	CLK	1



121-Ball NAND Flash with LPDDR2 MCP REFRESH Command

Table 74: PRECHARGE and Auto Precharge Clarification (Continued)

From Command	To Command	Minimum Delay Between Commands	Unit	Notes
WRITE w/AP	PRECHARGE to same bank as WRITE w/AP	$WL + BL/2 + RU(t^{WR}/t^{CK}) + 1$	CLK	1, 2
	PRECHARGE ALL	$WL + BL/2 + RU(t^{WR}/t^{CK}) + 1$	CLK	1
	ACTIVATE to same bank as WRITE w/AP	$WL + BL/2 + RU(t^{WR}/t^{CK}) + 1 + RU(t^{RPpb}/t^{CK})$	CLK	1
	WRITE or WRITE w/AP (same bank)	Illegal	CLK	3
	WRITE or WRITE w/AP (different bank)	BL/2	CLK	3
	READ or READ w/AP (same bank)	Illegal	CLK	3
	READ or READ w/AP (different bank)	$WL + BL/2 + RU(t^{WTR}/t^{CK}) + 1$	CLK	3
PRECHARGE	PRECHARGE to same bank as PRECHARGE	1	CLK	1
	PRECHARGE ALL	1	CLK	1
PRECHARGE ALL	PRECHARGE	1	CLK	1
	PRECHARGE ALL	1	CLK	1

- Notes:
- For a given bank, the PRECHARGE period should be counted from the latest PRECHARGE command—either a one-bank PRECHARGE or PRECHARGE ALL—issued to that bank. The PRECHARGE period is satisfied after t^{RP} , depending on the latest PRECHARGE command issued to that bank.
 - Any command issued during the specified minimum delay time is illegal.
 - After READ with auto precharge, seamless READ operations to different banks are supported. After WRITE with auto precharge, seamless WRITE operations to different banks are supported. READ with auto precharge and WRITE with auto precharge must not be interrupted or truncated.

REFRESH Command

The REFRESH command is initiated with CS# LOW, CA0 LOW, CA1 LOW, and CA2 HIGH at the rising edge of the clock. Per-bank REFRESH is initiated with CA3 LOW at the rising edge of the clock. All-bank REFRESH is initiated with CA3 HIGH at the rising edge of the clock. Per-bank REFRESH is only supported in devices with eight banks.

A per-bank REFRESH command (REFpb) performs a per-bank REFRESH operation to the bank scheduled by the bank counter in the memory device. The bank sequence for per-bank REFRESH is fixed to be a sequential round-robin: 0-1-2-3-4-5-6-7-0-1-.... The bank count is synchronized between the controller and the SDRAM by resetting the bank count to zero. Synchronization can occur upon issuing a RESET command or at every exit from self refresh.

A bank must be idle before it can be refreshed. The controller must track the bank being refreshed by the per-bank REFRESH command.

The REFpb command must not be issued to the device until the following conditions have been met:

- t^{RFCab} has been satisfied after the prior REFab command
- t^{RFCpb} has been satisfied after the prior REFpb command
- t^{RP} has been satisfied after the prior PRECHARGE command to that bank



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- t_{RRD} has been satisfied after the prior ACTIVATE command (if applicable, for example after activating a row in a different bank than the one affected by the REFpb command)

The target bank is inaccessible during per-bank REFRESH cycle time (t_{RFCpb}), however, other banks within the device are accessible and can be addressed during the cycle. During the REFpb operation, any of the banks other than the one being refreshed can be maintained in an active state or accessed by a READ or WRITE command.

When the per-bank REFRESH cycle has completed, the affected bank will be in the idle state.

After issuing REFpb, the following conditions must be met:

- t_{RFCpb} must be satisfied before issuing a REFab command
- t_{RFCpb} must be satisfied before issuing an ACTIVATE command to the same bank
- t_{RRD} must be satisfied before issuing an ACTIVATE command to a different bank
- t_{RFCpb} must be satisfied before issuing another REFpb command

An all-bank REFRESH command (REFab) issues a REFRESH command to all banks. All banks must be idle when REFab is issued (for instance, by issuing a PRECHARGE ALL command prior to issuing an all-bank REFRESH command). REFab also synchronizes the bank count between the controller and the SDRAM to zero. The REFab command must not be issued to the device until the following conditions have been met:

- t_{RFCab} has been satisfied following the prior REFab command
- t_{RFCpb} has been satisfied following the prior REFpb command
- t_{RP} has been satisfied following the prior PRECHARGE commands

After an all-bank REFRESH cycle has completed, all banks will be idle. After issuing REFab:

- t_{RFCab} latency must be satisfied before issuing an ACTIVATE command
- t_{RFCab} latency must be satisfied before issuing a REFab or REFpb command

Table 75: REFRESH Command Scheduling Separation Requirements

Symbol	Minimum Delay From	To	Notes
t_{RFCab}	REFab	REFab	
		ACTIVATE command to any bank	
		REFpb	
t_{RFCpb}	REFpb	REFab	
		ACTIVATE command to same bank as REFpb	
		REFpb	



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Table 75: REFRESH Command Scheduling Separation Requirements (Continued)

Symbol	Minimum Delay From	To	Notes
t_{RRD}	REFpb	ACTIVATE command to a different bank than REFpb	
	ACTIVATE	REFpb	1
		ACTIVATE command to a different bank than the prior ACTIVATE command	

Note: 1. A bank must be in the idle state before it is refreshed, so REFpb is prohibited following an ACTIVATE command. REFpb is supported only if it affects a bank that is in the idle state.

Mobile LPDDR2 devices provide significant flexibility in scheduling REFRESH commands as long as the required boundary conditions are met (see Figure 107 (page 152)).

In the most straightforward implementations, a REFRESH command should be scheduled every t_{REFI} . In this case, self refresh can be entered at any time.

Users may choose to deviate from this regular refresh pattern, for instance, to enable a period in which no refresh is required. As an example, using a 1Gb LPDDR2 device, the user can choose to issue a refresh burst of 4096 REFRESH commands at the maximum supported rate (limited by t_{REFBW}), followed by an extended period without issuing any REFRESH commands, until the refresh window is complete. The maximum supported time without REFRESH commands is calculated as follows: $t_{REFW} - (R/8) \times t_{REFBW} = t_{REFW} - R \times 4 \times t_{RfCab}$.

For example, a 1Gb device at $T_C \leq 85^\circ\text{C}$ can be operated without a refresh for up to 32ms - $4096 \times 4 \times 130\text{ns} \approx 30\text{ms}$.

Both the regular and the burst/pause patterns can satisfy refresh requirements if they are repeated in every 32ms window. It is critical to satisfy the refresh requirement in *every* rolling refresh window during refresh pattern transitions. The supported transition from a burst pattern to a regular distributed pattern is shown in Figure 104 (page 149). If this transition occurs immediately after the burst refresh phase, all rolling t_{REFW} intervals will meet the minimum required number of REFRESH commands.

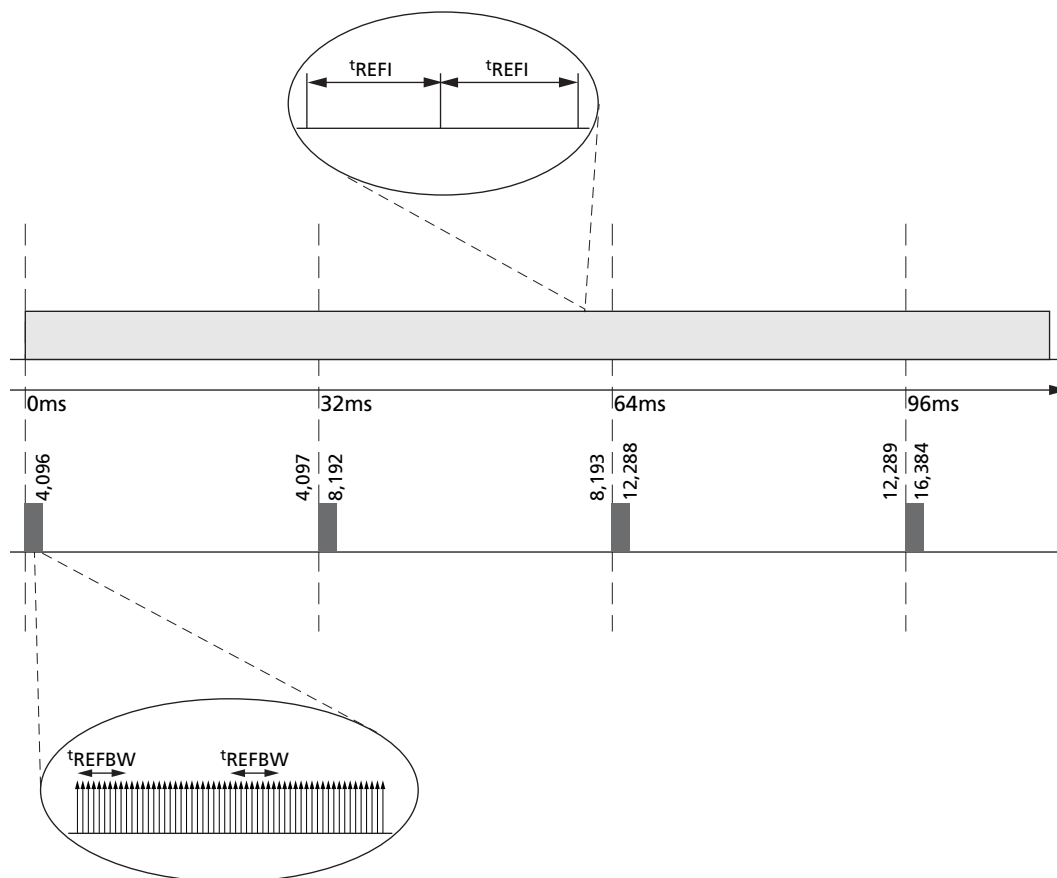
A nonsupported transition is shown in Figure 105 (page 150). In this example, the regular refresh pattern starts after the completion of the pause phase of the burst/pause refresh pattern. For several rolling t_{REFW} intervals, the minimum number of REFRESH commands is not satisfied.

Understanding this pattern transition is extremely important, even when only one pattern is employed. In self refresh mode, a regular distributed refresh pattern must be assumed. Micron recommends entering self refresh mode immediately following the burst phase of a burst/pause refresh pattern; upon exiting self refresh, begin with the burst phase (see Figure 106 (page 151)).



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Figure 103: Regular Distributed Refresh Pattern

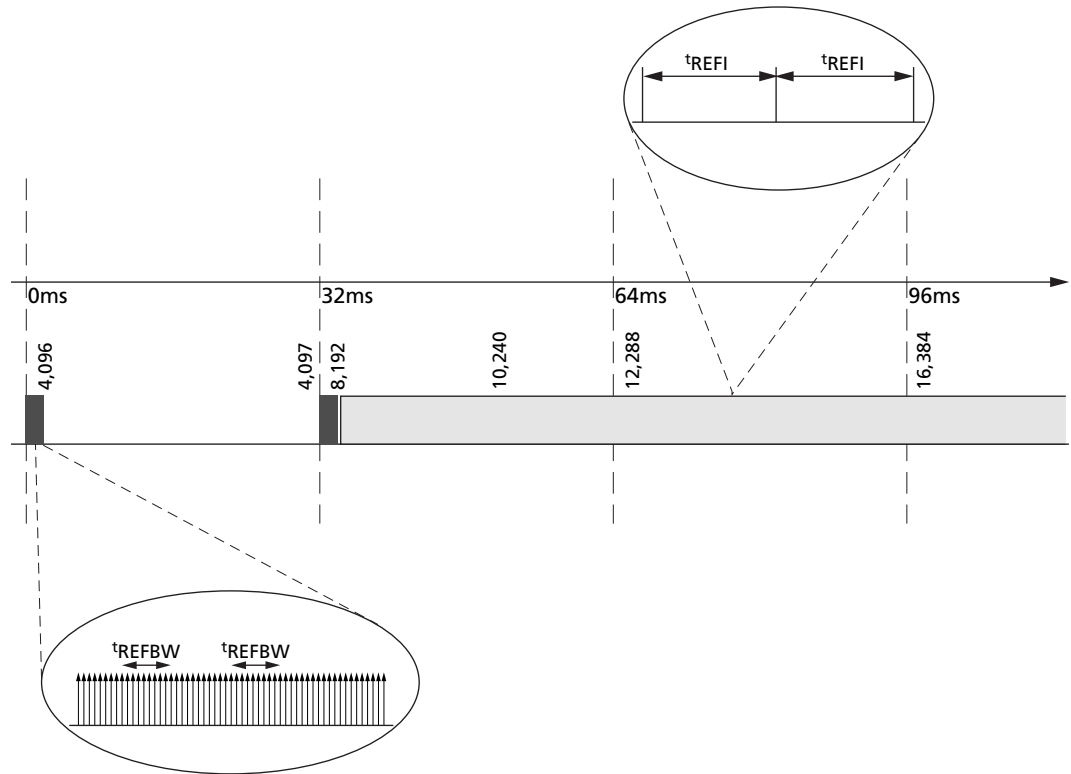


- Notes:
1. Compared to repetitive burst REFRESH with subsequent REFRESH pause.
 2. As an example, in a 1Gb LPDDR2 device at $T_C \leq 85^\circ\text{C}$, the distributed refresh pattern has one REFRESH command per $7.8\mu\text{s}$; the burst refresh pattern has one REFRESH command per $0.52\mu\text{s}$, followed by $\approx 30\text{ms}$ without any REFRESH command.



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Figure 104: Supported Transition from Repetitive REFRESH Burst

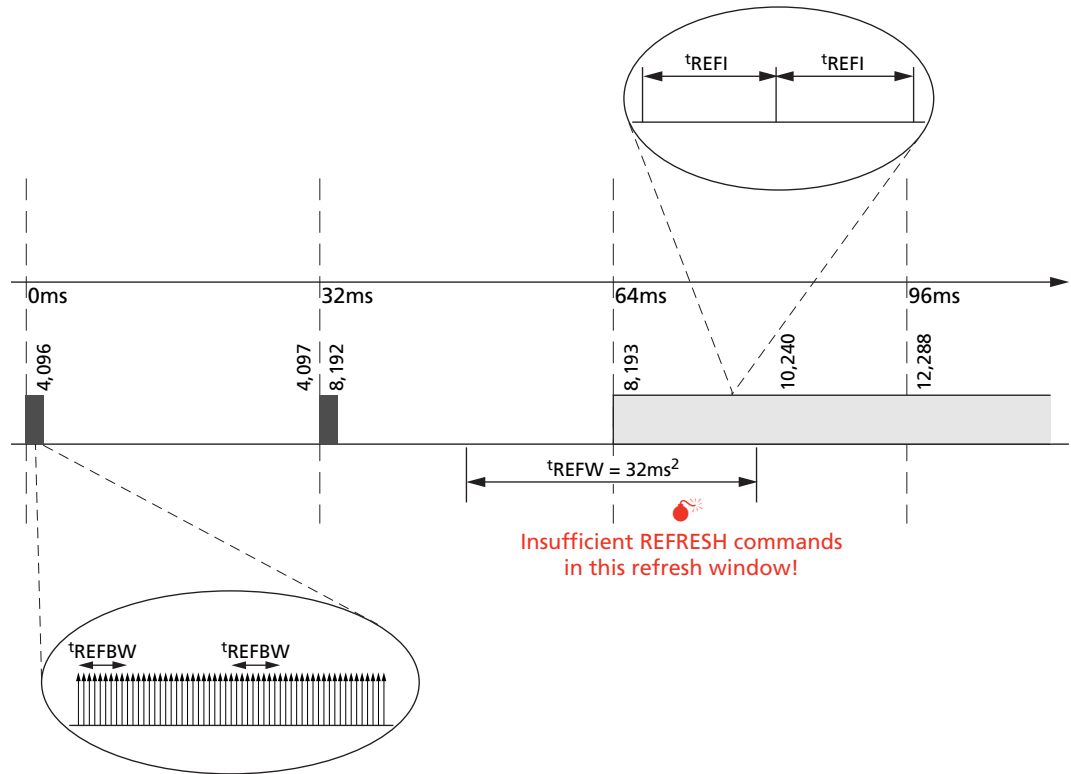


- Notes:
1. Shown with subsequent REFRESH pause to regular distributed refresh pattern.
 2. As an example, in a 1Gb LPDDR2 device at $T_C \leq 85^\circ\text{C}$, the distributed refresh pattern has one REFRESH command per $7.8\mu\text{s}$; the burst refresh pattern has one REFRESH command per $0.52\mu\text{s}$, followed by $\approx 30\text{ms}$ without any REFRESH command.



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Figure 105: Nonsupported Transition from Repetitive REFRESH Burst

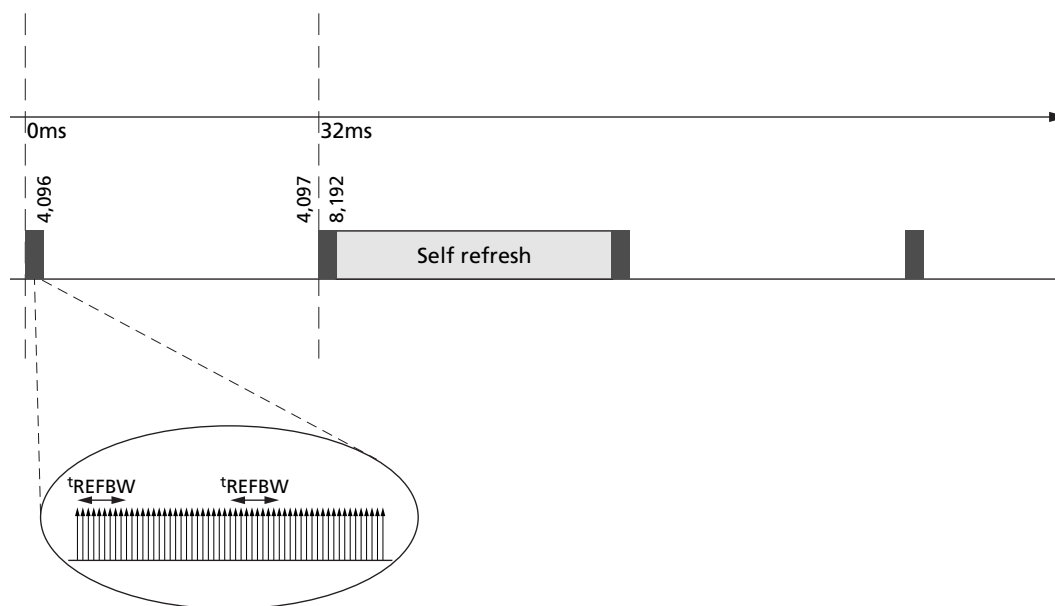


- Notes:
1. Shown with subsequent REFRESH pause to regular distributed refresh pattern.
 2. There are only ≈ 2048 REFRESH commands in the indicated t_{REFW} window. This does not provide the required minimum number of REFRESH commands (R).



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Figure 106: Recommended Self Refresh Entry and Exit



Note: 1. In conjunction with a burst/pause refresh pattern.

REFRESH Requirements

1. Minimum Number of REFRESH Commands

Mobile LPDDR2 requires a minimum number, R , of REFRESH (REFab) commands within any rolling refresh window ($t_{REFW} = 32 \text{ ms}$ @ $MR4[2:0] = 011$ or $T_C \leq 85^\circ\text{C}$). For actual values per density and the resulting average refresh interval (t_{REFI}), see Table 116 (page 212).

For t_{REFW} and t_{REFI} refresh multipliers at different $MR4$ settings, see the $MR4$ Device Temperature ($MA[7:0] = 04h$) table.

For devices supporting per-bank REFRESH, a REFab command can be replaced by a full cycle of eight REFpb commands.

2. Burst REFRESH Limitation

To limit current consumption, a maximum of eight REFab commands can be issued in any rolling t_{REFBW} ($t_{REFBW} = 4 \times 8 \times t_{RFCab}$). This condition does not apply if REFpb commands are used.

3. REFRESH Requirements and Self Refresh

If any time within a refresh window is spent in self refresh mode, the number of required REFRESH commands in that window is reduced to the following:

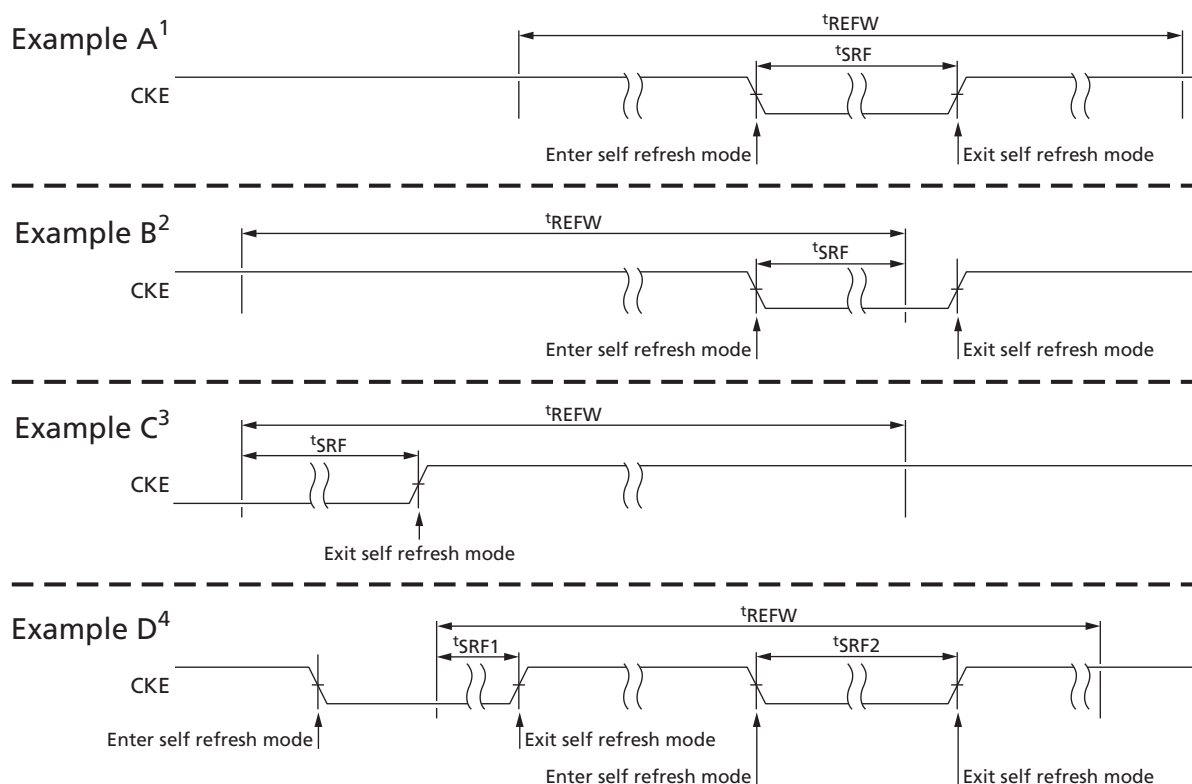
$$R' = RU\left(\frac{t_{SRF}}{t_{REFI}}\right) = R - RU\left(R \times \frac{t_{SRF}}{t_{REFW}}\right)$$

Where RU represents the round-up function.



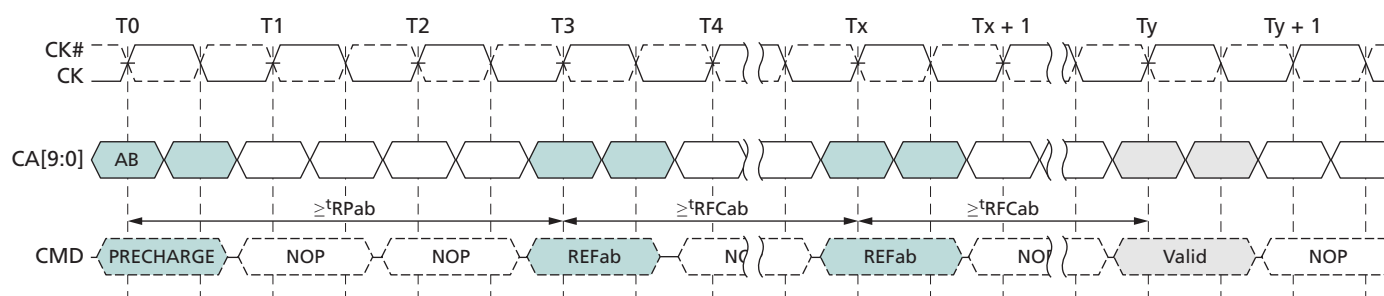
121-Ball NAND Flash with LPDDR2 MCP REFRESH Command

Figure 107: t_{SRF} Definition



- Notes:
1. Time in self refresh mode is fully enclosed in the refresh window (t_{REFW}).
 2. At self refresh entry.
 3. At self refresh exit.
 4. Several intervals in self refresh during one t_{REFW} interval. In this example, $t_{SRF} = t_{SRF1} + t_{SRF2}$.

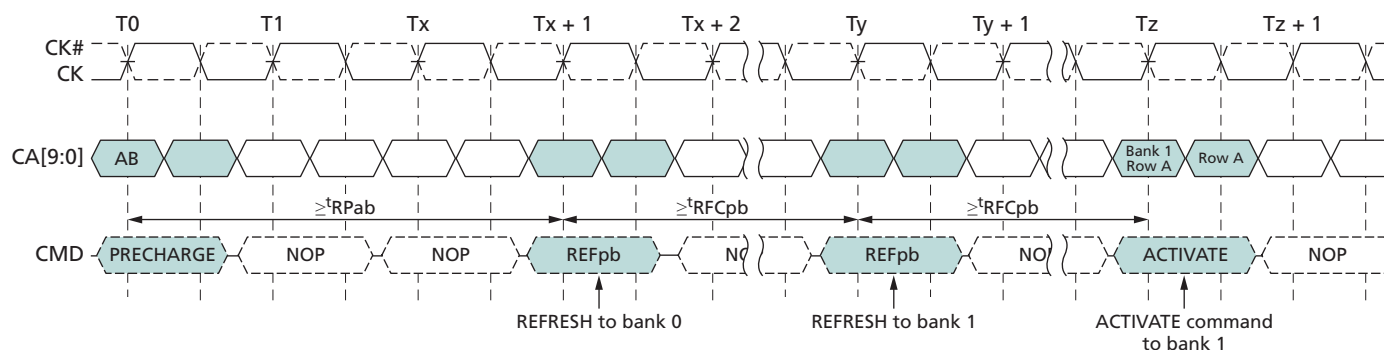
Figure 108: All-Bank REFRESH Operation





121-Ball NAND Flash with LPDDR2 MCP SELF REFRESH Operation

Figure 109: Per-Bank REFRESH Operation



- Notes:
1. Prior to T0, the REFpb bank counter points to bank 0.
 2. Operations to banks other than the bank being refreshed are supported during the t_{RFCpb} period.

SELF REFRESH Operation

The SELF REFRESH command can be used to retain data in the array, even if the rest of the system is powered down. When in the self refresh mode, the device retains data without external clocking. The device has a built-in timer to accommodate SELF REFRESH operation. The SELF REFRESH command is executed by taking CKE LOW, CS# LOW, CA0 LOW, CA1 LOW, and CA2 HIGH at the rising edge of the clock.

CKE must be HIGH during the clock cycle preceding a SELF REFRESH command. A NOP command must be driven in the clock cycle following the SELF REFRESH command. After the power-down command is registered, CKE must be held LOW to keep the device in self refresh mode.

Mobile LPDDR2 devices can operate in self refresh mode in both the standard and extended temperature ranges. These devices also manage self refresh power consumption when the operating temperature changes, resulting in the lowest possible power consumption across the operating temperature range. See Table 90 (page 186) for details.

After the device has entered self refresh mode, all external signals other than CKE are “Don’t Care.” For proper self refresh operation, power supply pins (V_{DD1} , V_{DD2} , V_{DDQ} , and V_{DDCA}) must be at valid levels. V_{DDQ} can be turned off during self refresh. If V_{DDQ} is turned off, V_{REFDQ} must also be turned off. Prior to exiting self refresh, both V_{DDQ} and V_{REFDQ} must be within their respective minimum/maximum operating ranges (see the Single-Ended AC and DC Input Levels for DQ and DM table). V_{REFDQ} can be at any level between 0 and V_{DDQ} ; V_{REFCA} can be at any level between 0 and V_{DDCA} during self refresh.

Before exiting self refresh, V_{REFDQ} and V_{REFCA} must be within specified limits (see AC and DC Logic Input Measurement Levels for Single-Ended Signals (page 190)). After entering self refresh mode, the device initiates at least one all-bank REFRESH command internally during t_{CKESR} . The clock is internally disabled during SELF REFRESH operation to save power. The device must remain in self refresh mode for at least t_{CKESR} . The user can change the external clock frequency or halt the external clock one clock after



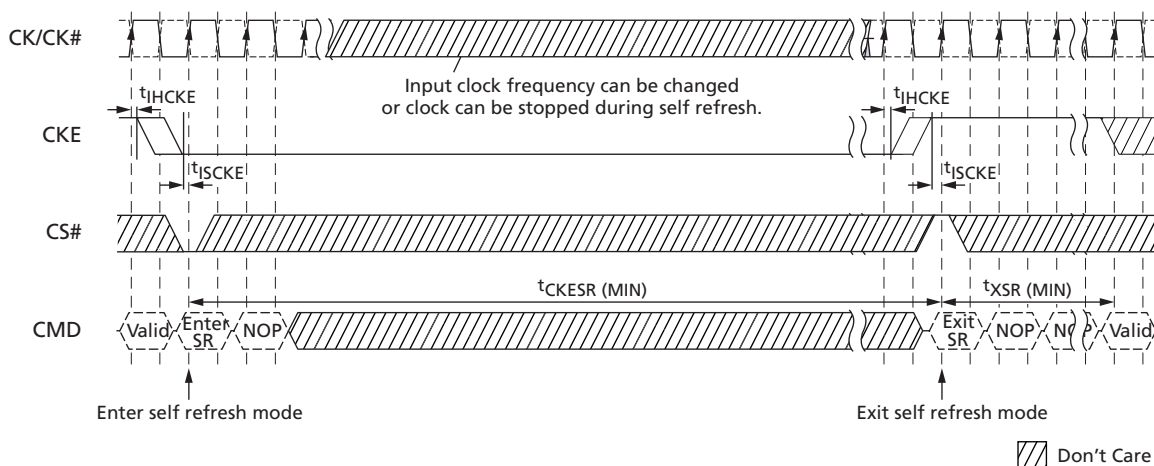
121-Ball NAND Flash with LPDDR2 MCP SELF REFRESH Operation

self refresh entry is registered; however, the clock must be restarted and stable before the device can exit SELF REFRESH operation.

Exiting self refresh requires a series of commands. First, the clock must be stable prior to CKE returning HIGH. After the self refresh exit is registered, a minimum delay, at least equal to the self refresh exit interval (t_{XSR}), must be satisfied before a valid command can be issued to the device. This provides completion time for any internal refresh in progress. For proper operation, CKE must remain HIGH throughout t_{XSR} . NOP commands must be registered on each rising clock edge during t_{XSR} .

Using self refresh mode introduces the possibility that an internally timed refresh event could be missed when CKE is driven HIGH for exit from self refresh mode. Upon exiting self refresh, at least one REFRESH command (one all-bank command or eight per-bank commands) must be issued before issuing a subsequent SELF REFRESH command.

Figure 110: SELF REFRESH Operation



- Notes:
1. Input clock frequency can be changed or stopped during self refresh, provided that upon exiting self-refresh, a minimum of two cycles of stable clocks are provided, and the clock frequency is between the minimum and maximum frequencies for the particular speed grade.
 2. The device must be in the all banks idle state prior to entering self refresh mode.
 3. t_{XSR} begins at the rising edge of the clock after CKE is driven HIGH.
 4. A valid command can be issued only after t_{XSR} is satisfied. NOPs must be issued during t_{XSR} .

Partial-Array Self Refresh – Bank Masking

Devices in densities of 64Mb–512Mb are comprised of four banks; densities of 1Gb and higher are comprised of eight banks. Each bank can be configured independently whether or not a SELF REFRESH operation will occur in that bank. One 8-bit mode register (accessible via the MRW command) is assigned to program the bank-masking status of each bank up to eight banks. For bank masking bit assignments, see the MR16 PASR Bank Mask (MA[7:0] = 010h) and MR16 Op-Code Bit Definitions tables.

The mask bit to the bank enables or disables a refresh operation of the entire memory space within the bank. If a bank is masked using the bank mask register, a REFRESH op-



121-Ball NAND Flash with LPDDR2 MCP SELF REFRESH Operation

eration to the entire bank is blocked and bank data retention is not guaranteed in self refresh mode. To enable a REFRESH operation to a bank, the corresponding bank mask bit must be programmed as “unmasked.” When a bank mask bit is unmasked, the array space being refreshed within that bank is determined by the programmed status of the segment mask bits.

Partial-Array Self Refresh – Segment Masking

Programming segment mask bits is similar to programming bank mask bits. For densities 1Gb and higher, eight segments are used for masking (see the MR17 PASR Segment Mask (MA[7:0] = 011h) and MR17 PASR Segment Mask Definitions tables). A mode register is used for programming segment mask bits up to eight bits. For densities less than 1Gb, segment masking is not supported.

When the mask bit to an address range (represented as a segment) is programmed as “masked,” a REFRESH operation to that segment is blocked. Conversely, when a segment mask bit to an address range is unmasked, refresh to that segment is enabled.

A segment masking scheme can be used in place of or in combination with a bank masking scheme. Each segment mask bit setting is applied across all banks. For segment masking bit assignments, see the tables noted above.

Table 76: Bank and Segment Masking Example

	Segment Mask (MR17)	Bank 0	Bank 1	Bank 2	Bank 3	Bank 4	Bank 5	Bank 6	Bank 7
Bank Mask (MR16)		0	1	0	0	0	0	0	1
Segment 0	0	–	M	–	–	–	–	–	M
Segment 1	0	–	M	–	–	–	–	–	M
Segment 2	1	M	M	M	M	M	M	M	M
Segment 3	0	–	M	–	–	–	–	–	M
Segment 4	0	–	M	–	–	–	–	–	M
Segment 5	0	–	M	–	–	–	–	–	M
Segment 6	0	–	M	–	–	–	–	–	M
Segment 7	1	M	M	M	M	M	M	M	M

Note: 1. This table provides values for an 8-bank device with REFRESH operations masked to banks 1 and 7, and segments 2 and 7.



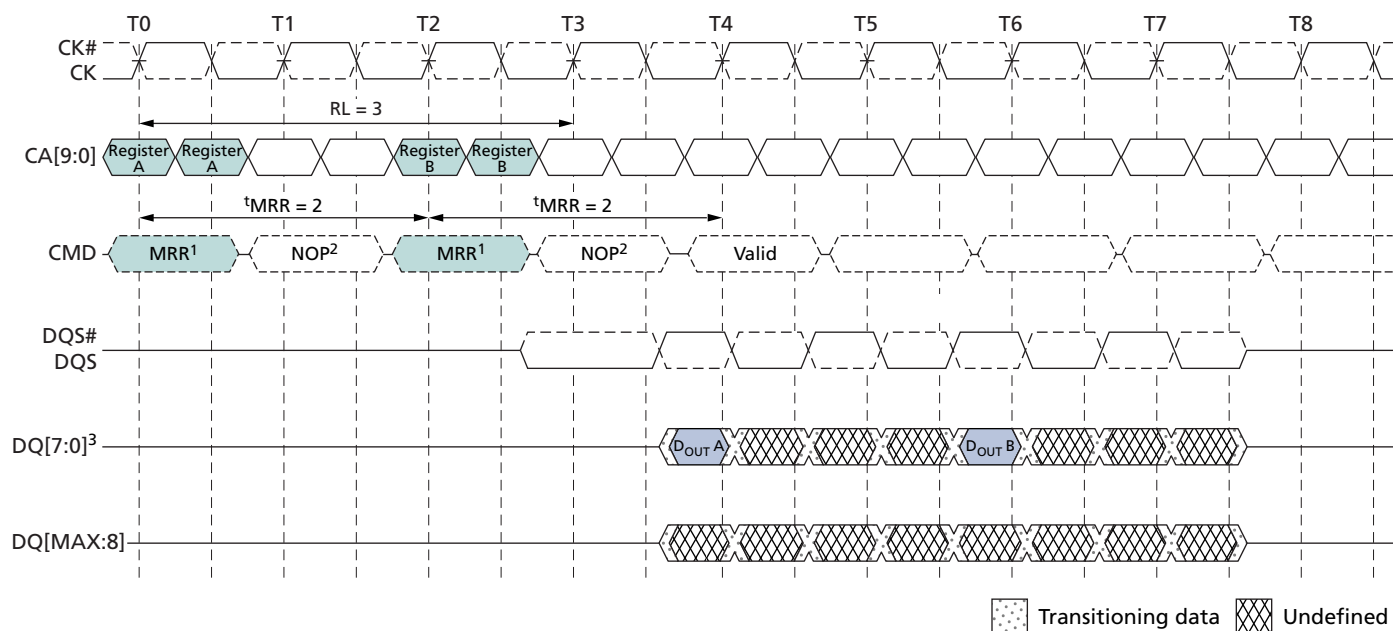
121-Ball NAND Flash with LPDDR2 MCP MODE REGISTER READ

MODE REGISTER READ

The MODE REGISTER READ (MRR) command is used to read configuration and status data from SDRAM mode registers. The MRR command is initiated with CS# LOW, CA0 LOW, CA1 LOW, CA2 LOW, and CA3 HIGH at the rising edge of the clock. The mode register is selected by CA1f–CA0f and CA9r–CA4r. The mode register contents are available on the first data beat of DQ[7:0] after $RL \times ^tCK + ^tDQSCK + ^tDQSQ$ and following the rising edge of the clock where MRR is issued. Subsequent data beats contain valid but undefined content, except in the case of the DQ calibration function, where subsequent data beats contain valid content as described in Table 78 (page 161). All DQS are toggled for the duration of the mode register READ burst.

The MRR command has a burst length of four. MRR operation (consisting of the MRR command and the corresponding data traffic) must not be interrupted. The MRR command period (t_{MRR}) is two clock cycles.

Figure 111: MRR Timing – $RL = 3$, $t_{MRR} = 2$



- Notes:
1. MRRs to DQ calibration registers MR32 and MR40 are described in DQ Calibration (page 160).
 2. Only the NOP command is supported during t_{MRR} .
 3. Mode register data is valid only on DQ[7:0] on the first beat. Subsequent beats contain valid but undefined data. DQ[MAX:8] contain valid but undefined data for the duration of the MRR burst.
 4. Minimum MRR to write latency is $RL + RU(^tDQSCK_{max}/^tCK) + 4/2 + 1 - WL$ clock cycles.
 5. Minimum MRR to MRW latency is $RL + RU(^tDQSCK_{max}/^tCK) + 4/2 + 1$ clock cycles.

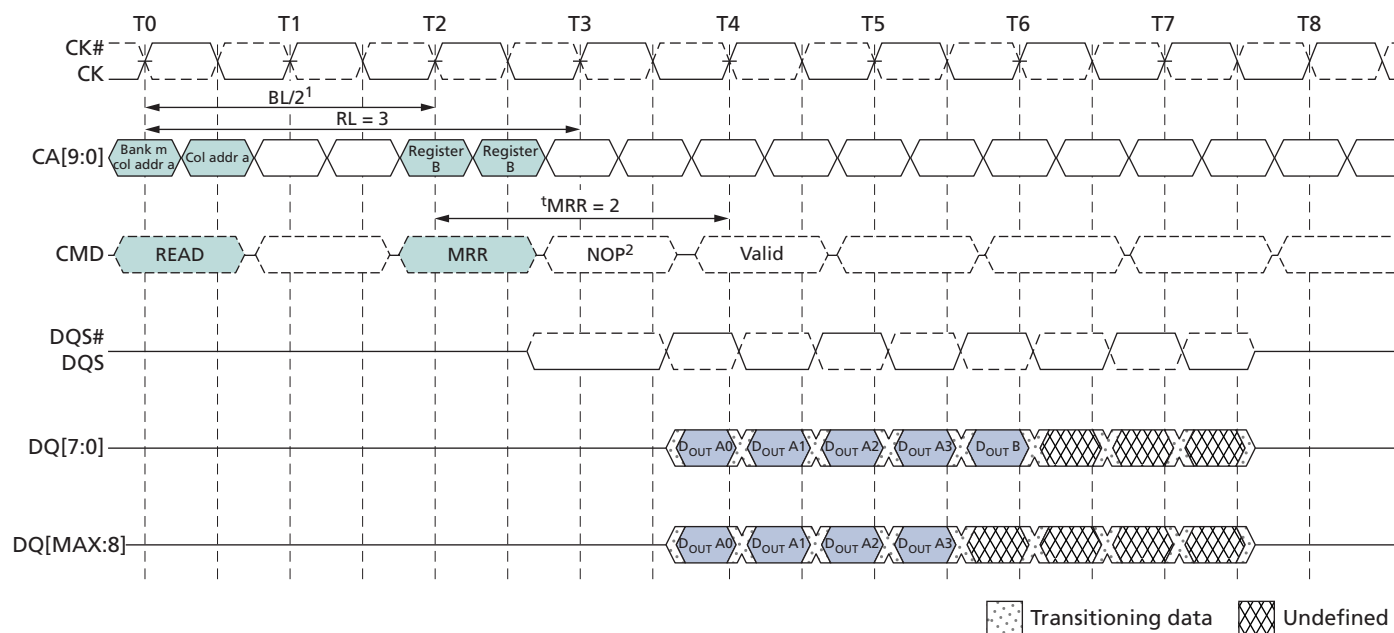
READ bursts and WRITE bursts cannot be truncated by MRR. Following a READ command, the MRR command must not be issued before $BL/2$ clock cycles have completed. Following a WRITE command, the MRR command must not be issued before $WL + 1 + BL/2 + RU(^tWTR/^tCK)$ clock cycles have completed. If a READ or WRITE burst is trunca-



121-Ball NAND Flash with LPDDR2 MCP MODE REGISTER READ

ted with a BST command, the effective burst length of the truncated burst should be used for the BL value.

Figure 112: READ to MRR Timing – RL = 3, $t_{MRR} = 2$

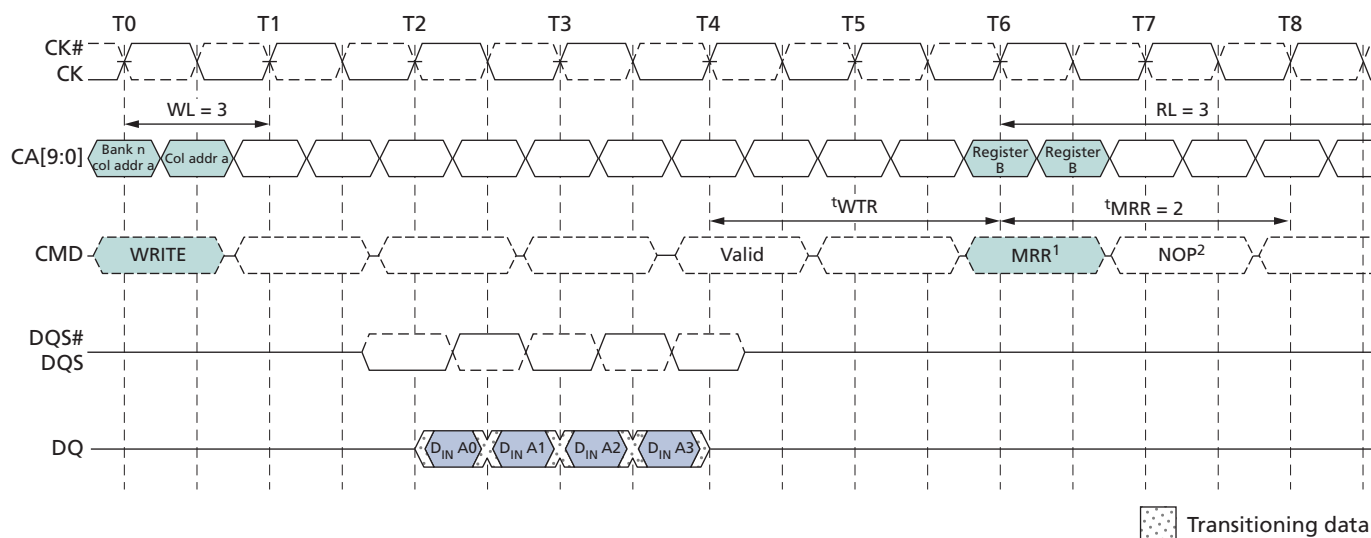


- Notes:
1. The minimum number of clock cycles from the burst READ command to the MRR command is BL/2.
 2. Only the NOP command is supported during t_{MRR} .



121-Ball NAND Flash with LPDDR2 MCP MODE REGISTER READ

Figure 113: Burst WRITE Followed by MRR – RL = 3, WL = 1, BL = 4



- Notes:
1. The minimum number of clock cycles from the burst WRITE command to the MRR command is $[WL + 1 + BL/2 + RU(t_{WTR}/t_{CK})]$.
 2. Only the NOP command is supported during t_{MRR} .

Temperature Sensor

Mobile LPDDR2 devices feature a temperature sensor whose status can be read from MR4. This sensor can be used to determine an appropriate refresh rate, determine whether AC timing derating is required in the extended temperature range, and/or monitor the operating temperature. Either the temperature sensor or the device operating temperature can be used to determine whether operating temperature requirements are being met (see Operating Temperature Range table).

Temperature sensor data can be read from MR4 using the mode register read protocol. Upon exiting self-refresh or power-down, the device temperature status bits will be no older than t_{TSI} .

When using the temperature sensor, the actual device case temperature may be higher than the operating temperature specification that applies for the standard or extended temperature ranges (see table noted above). For example, T_{CASE} could be above 85°C when MR4[2:0] equals 011b.

To ensure proper operation using the temperature sensor, applications must accommodate the parameters in the temperature sensor definitions table.



121-Ball NAND Flash with LPDDR2 MCP MODE REGISTER READ

Table 77: Temperature Sensor Definitions and Operating Conditions

Parameter	Description	Symbol	Min/Max	Value	Unit
System temperature gradient	Maximum temperature gradient experienced by the memory device at the temperature of interest over a range of 2°C	TempGradient	MAX	System-dependent	°C/s
MR4 READ interval	Time period between MR4 READs from the system	ReadInterval	MAX	System-dependent	ms
Temperature sensor interval	Maximum delay between internal updates of MR4	^t TSI	MAX	32	ms
System response delay	Maximum response time from an MR4 READ to the system response	SysRespDelay	MAX	System-dependent	ms
Device temperature margin	Margin above maximum temperature to support controller response	TempMargin	MAX	2	°C

Mobile LPDDR2 devices accommodate the temperature margin between the point at which the device temperature enters the extended temperature range and the point at which the controller reconfigures the system accordingly. To determine the required MR4 polling frequency, the system must use the maximum TempGradient and the maximum response time of the system according to the following equation:

$$\text{TempGradient} \times (\text{ReadInterval} + {}^t\text{TSI} + \text{SysRespDelay}) \leq 2^\circ\text{C}$$

For example, if TempGradient is 10°C/s and the SysRespDelay is 1ms:

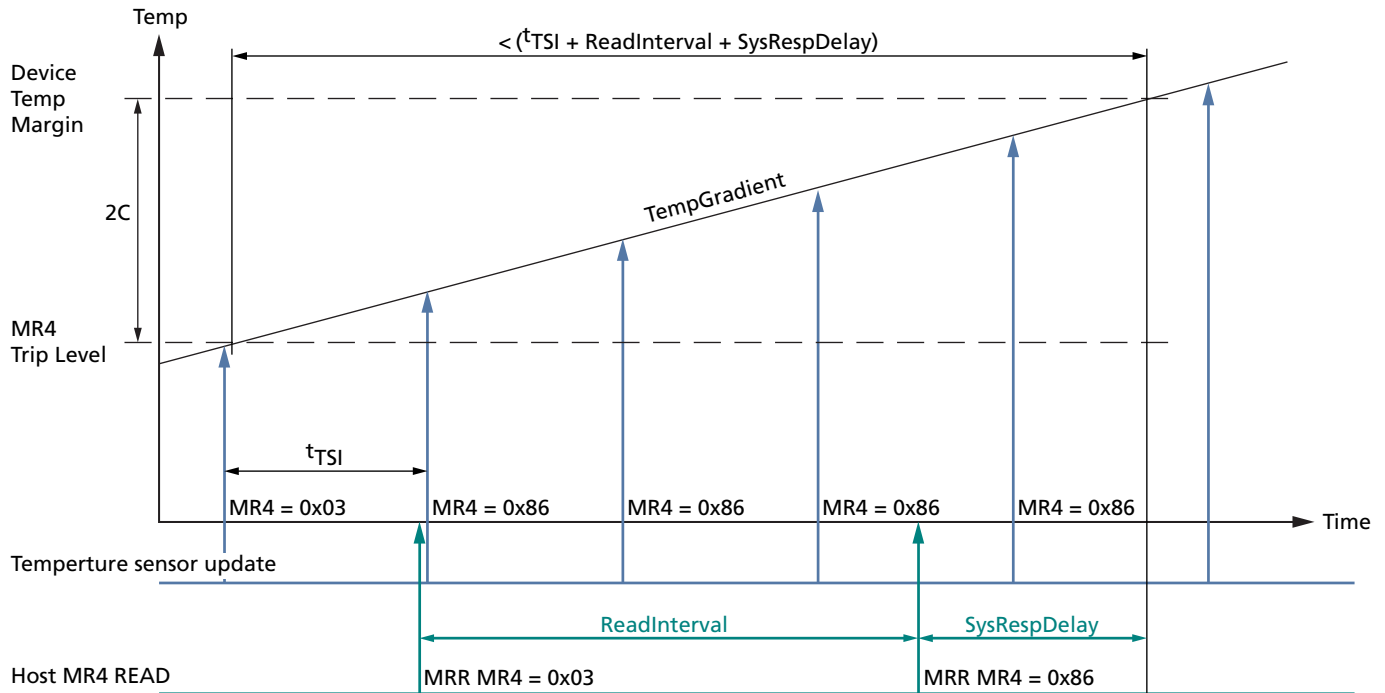
$$\frac{10^\circ\text{C}}{\text{s}} \times (\text{ReadInterval} + 32\text{ms} + 1\text{ms}) \leq 2^\circ\text{C}$$

In this case, ReadInterval must not exceed 167ms.



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Figure 114: Temperature Sensor Timing



DQ Calibration

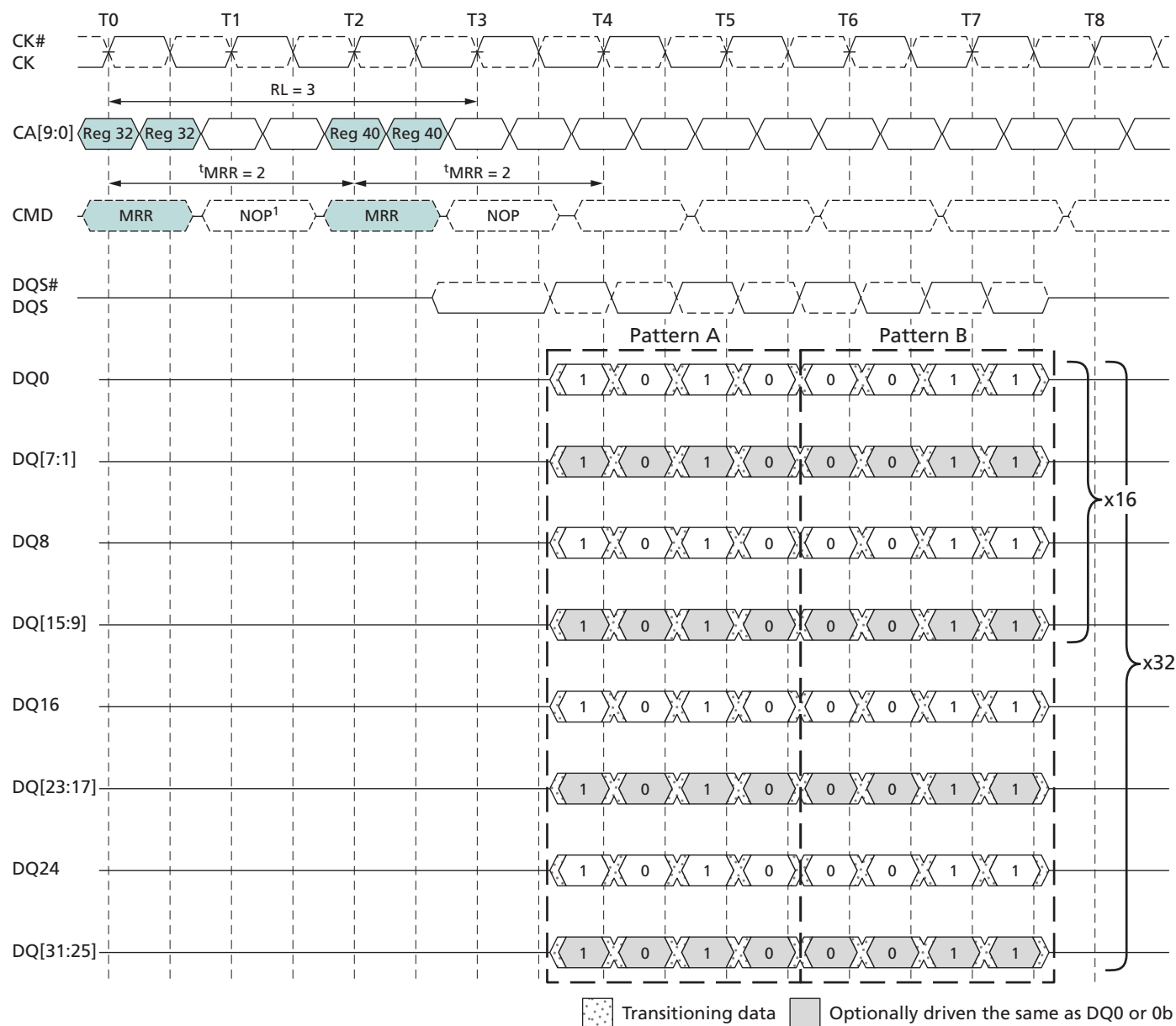
Mobile LPDDR2 devices feature a DQ calibration function that outputs one of two pre-defined system timing calibration patterns. For x16 devices, pattern A (MRR to MRR32), and pattern B (MRR to MRR40), will return the specified pattern on DQ0 and DQ8; x32 devices return the specified pattern on DQ0, DQ8, DQ16, and DQ24.

For x16 devices, DQ[7:1] and DQ[15:9] drive the same information as DQ0 during the MRR burst. For x32 devices, DQ[7:1], DQ[15:9], DQ[23:17], and DQ[31:25] drive the same information as DQ0 during the MRR burst. MRR DQ calibration commands can occur only in the idle state.



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Figure 115: MR32 and MR40 DQ Calibration Timing – RL = 3, $t_{MRR} = 2$



Note: 1. Only the NOP command is supported during t_{MRR} .

Table 78: Data Calibration Pattern Description

Pattern	MR#	Bit Time 0	Bit Time 1	Bit Time 2	Bit Time 3	Description
Pattern A	MR32	1	0	1	0	Reads to MR32 return DQ calibration pattern A
Pattern B	MR40	0	0	1	1	Reads to MR40 return DQ calibration pattern B



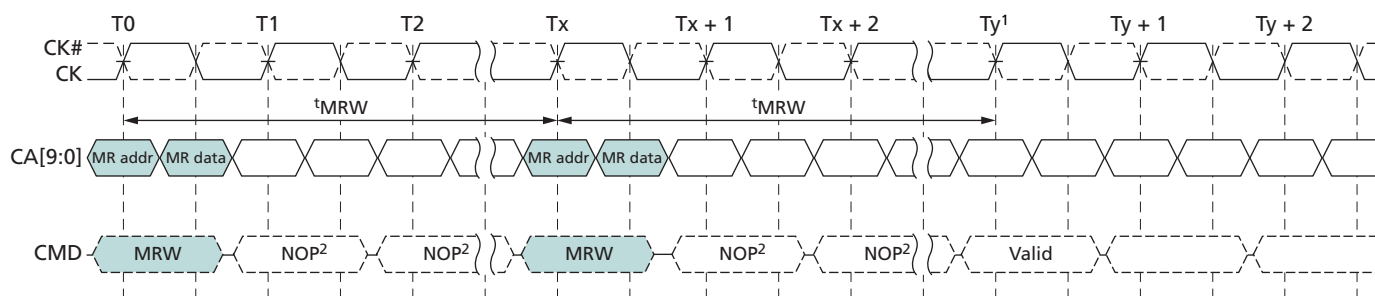
121-Ball NAND Flash with LPDDR2 MCP MODE REGISTER WRITE Command

MODE REGISTER WRITE Command

The MODE REGISTER WRITE (MRW) command is used to write configuration data to the mode registers. The MRW command is initiated with CS# LOW, CA0 LOW, CA1 LOW, CA2 LOW, and CA3 LOW at the rising edge of the clock. The mode register is selected by CA1f–CA0f, CA9r–CA4r. The data to be written to the mode register is contained in CA9f–CA2f. The MRW command period is defined by t_{MRW} . MRWs to read-only registers have no impact on the functionality of the device.

MRW can only be issued when all banks are in the idle precharge state. One method of ensuring that the banks are in this state is to issue a PRECHARGE ALL command.

Figure 116: MODE REGISTER WRITE Timing – RL = 3, t_{MRW} = 5



- Notes:
1. At time T_y , the device is in the idle state.
 2. Only the NOP command is supported during t_{MRW} .

Table 79: Truth Table for MRR and MRW

Current State	Command	Intermediate State	Next State
All banks idle	MRR	Reading mode register, all banks idle	All banks idle
	MRW	Writing mode register, all banks idle	All banks idle
	MRW (RESET)	Resetting, device auto initialization	All banks idle
Bank(s) active	MRR	Reading mode register, bank(s) idle	Bank(s) active
	MRW	Not allowed	Not allowed
	MRW (RESET)	Not allowed	Not allowed

MRW RESET Command

The MRW RESET command brings the device to the device auto initialization (resetting) state in the power-on initialization sequence (see 2. RESET Command under Power-Up (page 111)). The MRW RESET command can be issued from the idle state. This command resets all mode registers to their default values. Only the NOP command is supported during t_{INIT4} . After MRW RESET, boot timings must be observed until the device initialization sequence is complete and the device is in the idle state. Array data is undefined after the MRW RESET command has completed.

For MRW RESET timing, see Figure 76 (page 113).



121-Ball NAND Flash with LPDDR2 MCP MODE REGISTER WRITE Command

MRW ZQ Calibration Commands

The MRW command is used to initiate a ZQ calibration command that calibrates output driver impedance across process, temperature, and voltage. LPDDR2-S4 devices support ZQ calibration. To achieve tighter tolerances, proper ZQ calibration must be performed.

There are four ZQ calibration commands and related timings: 'ZQINIT, 'ZQRESET, 'ZQCL, and 'ZQCS. 'ZQINIT is used for initialization calibration; 'ZQRESET is used for resetting ZQ to the default output impedance; 'ZQCL is used for long calibration(s); and 'ZQCS is used for short calibration(s). See the MR10 Calibration (MA[7:0] = 0Ah) table for ZQ calibration command code definitions.

ZQINIT must be performed for LPDDR2 devices. ZQINIT provides an output impedance accuracy of $\pm 15\%$. After initialization, the ZQ calibration long (ZQCL) can be used to recalibrate the system to an output impedance accuracy of $\pm 15\%$. A ZQ calibration short (ZQCS) can be used periodically to compensate for temperature and voltage drift in the system.

ZQRESET resets the output impedance calibration to a default accuracy of $\pm 30\%$ across process, voltage, and temperature. This command is used to ensure output impedance accuracy to $\pm 30\%$ when ZQCS and ZQCL commands are not used.

One ZQCS command can effectively correct at least 1.5% (ZQ correction) of output impedance errors within 'ZQCS for all speed bins, assuming the maximum sensitivities specified in Table 110 and Table 111 (page 204) are met. The appropriate interval between ZQCS commands can be determined using these tables and system-specific parameters.

Mobile LPDDR2 devices are subject to temperature drift rate ($T_{\text{driftrate}}$) and voltage drift rate ($V_{\text{driftrate}}$) in various applications. To accommodate drift rates and calculate the necessary interval between ZQCS commands, apply the following formula:

$$\frac{ZQ_{\text{correction}}}{(T_{\text{sens}} \times T_{\text{driftrate}}) + (V_{\text{sens}} \times V_{\text{driftrate}})}$$

Where $T_{\text{sens}} = \text{MAX}(dR_{\text{ON}}dT)$ and $V_{\text{sens}} = \text{MAX}(dR_{\text{ON}}dV)$ define temperature and voltage sensitivities.

For example, if $T_{\text{sens}} = 0.75\%/^{\circ}\text{C}$, $V_{\text{sens}} = 0.20\%/mV$, $T_{\text{driftrate}} = 1^{\circ}\text{C}/\text{sec}$, and $V_{\text{driftrate}} = 15 \text{ mV}/\text{sec}$, then the interval between ZQCS commands is calculated as:

$$\frac{1.5}{(0.75 \times 1) + (0.20 \times 15)} = 0.4s$$

A ZQ calibration command can only be issued when the device is in the idle state with all banks precharged.

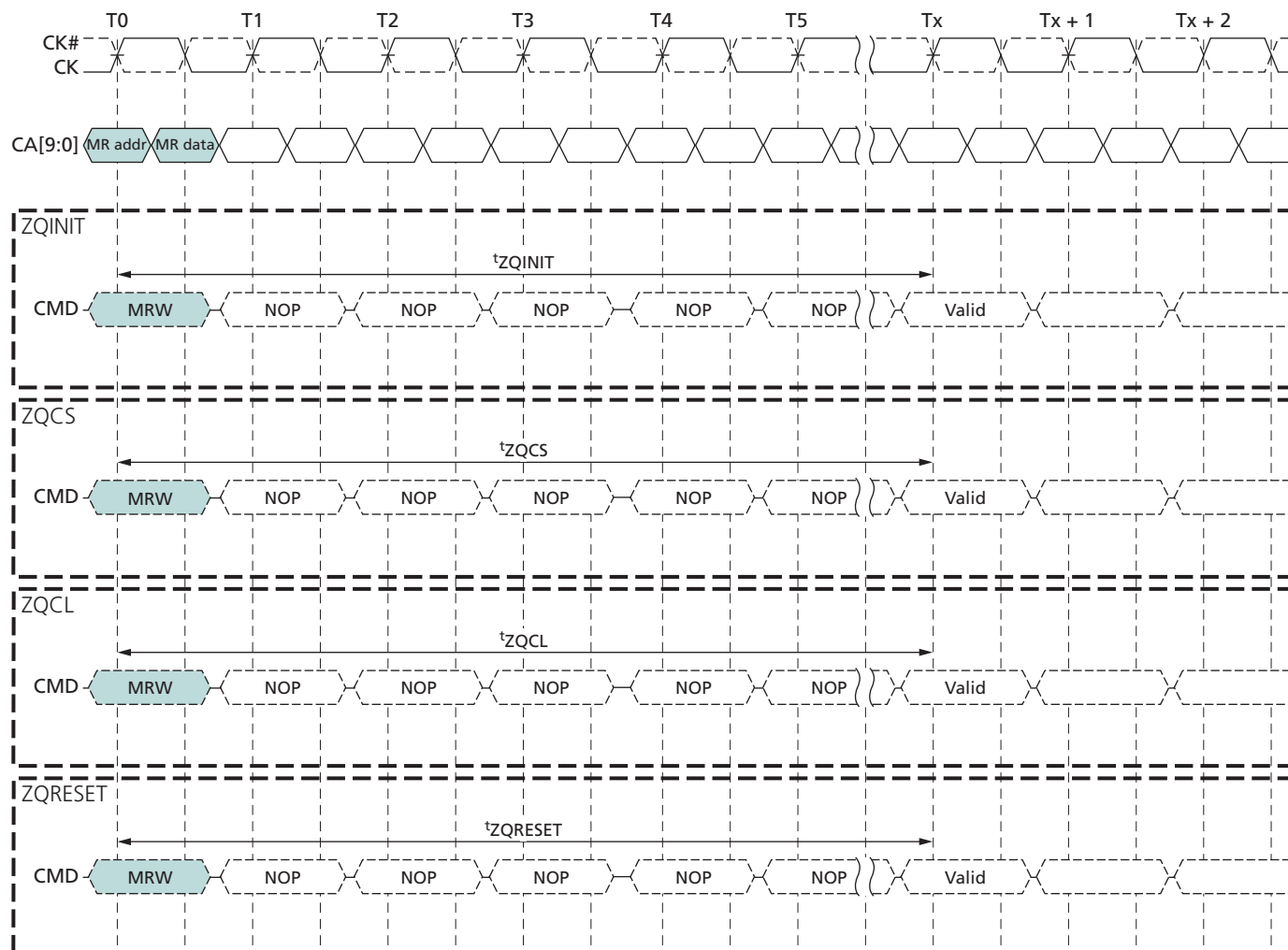
No other activities can be performed on the data bus during calibration periods ('ZQINIT, 'ZQCL, or 'ZQCS). The quiet time on the data bus helps to accurately calibrate output impedance. There is no required quiet time after the ZQRESET command. If multiple devices share a single ZQ resistor, only one device can be calibrating at any given time. After calibration is complete, the ZQ ball circuitry is disabled to reduce power consumption.



121-Ball NAND Flash with LPDDR2 MCP MODE REGISTER WRITE Command

In systems sharing a ZQ resistor between devices, the controller must prevent t_{ZQINIT} , t_{ZQCS} , and t_{ZQCL} overlap between the devices. ZQRESET overlap is acceptable. If the ZQ resistor is absent from the system, ZQ must be connected to V_{DDCA} . In this situation, the device must ignore ZQ calibration commands and the device will use the default calibration settings.

Figure 117: ZQ Timings



- Notes:
1. Only the NOP command is supported during ZQ calibrations.
 2. CKE must be registered HIGH continuously during the calibration period.
 3. All devices connected to the DQ bus should be High-Z during the calibration process.



121-Ball NAND Flash with LPDDR2 MCP Power-Down

ZQ External Resistor Value, Tolerance, and Capacitive Loading

To use the ZQ calibration function, a 240 ohm ($\pm 1\%$ tolerance) external resistor must be connected between the ZQ pin and ground. A single resistor can be used for each device or one resistor can be shared between multiple devices if the ZQ calibration timings for each device do not overlap. The total capacitive loading on the ZQ pin must be limited (see the Input/Output Capacitance table).

Power-Down

Power-down is entered synchronously when CKE is registered LOW and CS# is HIGH at the rising edge of clock. A NOP command must be driven in the clock cycle following power-down entry. CKE must not go LOW while MRR, MRW, READ, or WRITE operations are in progress. CKE can go LOW while any other operations such as ACTIVATE, PRECHARGE, auto precharge, or REFRESH are in progress, but the power-down I_{DD} specification will not be applied until such operations are complete.

If power-down occurs when all banks are idle, this mode is referred to as idle power-down; if power-down occurs when there is a row active in any bank, this mode is referred to as active power-down.

Entering power-down deactivates the input and output buffers, excluding CK, CK#, and CKE. In power-down mode, CKE must be held LOW; all other input signals are "Don't Care." CKE LOW must be maintained until t_{CKE} is satisfied. V_{REFCA} must be maintained at a valid level during power-down.

V_{DDQ} can be turned off during power-down. If V_{DDQ} is turned off, V_{REFDQ} must also be turned off. Prior to exiting power-down, both V_{DDQ} and V_{REFDQ} must be within their respective minimum/maximum operating ranges (see AC and DC Operating Conditions).

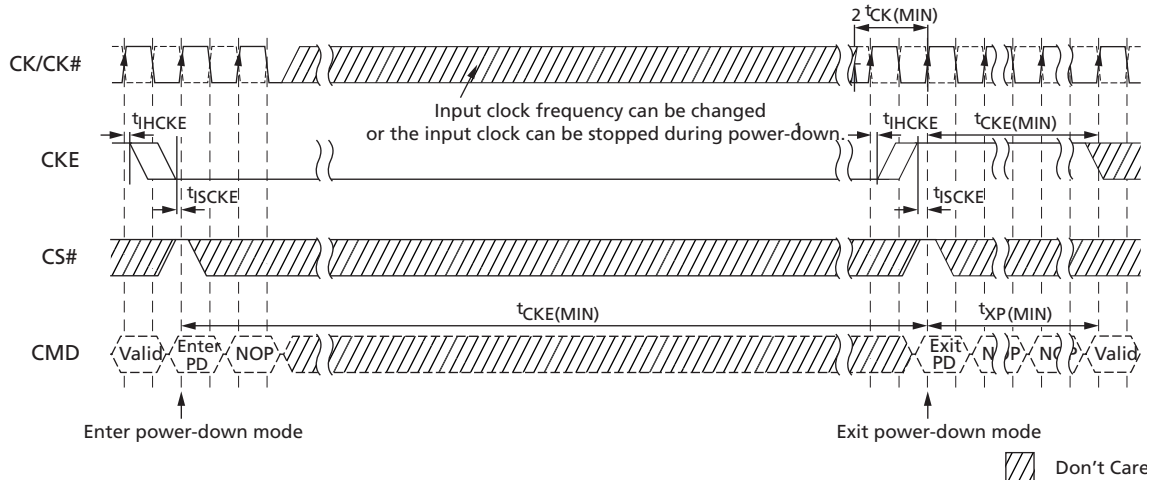
No refresh operations are performed in power-down mode. The maximum duration in power-down mode is only limited by the refresh requirements outlined in REFRESH Command.

The power-down state is exited when CKE is registered HIGH. The controller must drive CS# HIGH in conjunction with CKE HIGH when exiting the power-down state. CKE HIGH must be maintained until t_{CKE} is satisfied. A valid, executable command can be applied with power-down exit latency t_{XP} after CKE goes HIGH. Power-down exit latency is defined in the AC Timing section.



121-Ball NAND Flash with LPDDR2 MCP Power-Down

Figure 118: Power-Down Entry and Exit Timing



Note: 1. Input clock frequency can be changed or the input clock stopped during power-down, provided that the clock frequency is between the minimum and maximum specified frequencies for the speed grade in use, and that prior to power-down exit, a minimum of two stable clocks complete.

Figure 119: CKE Intensive Environment

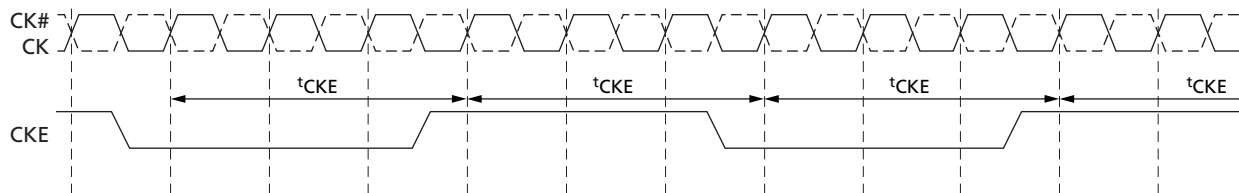
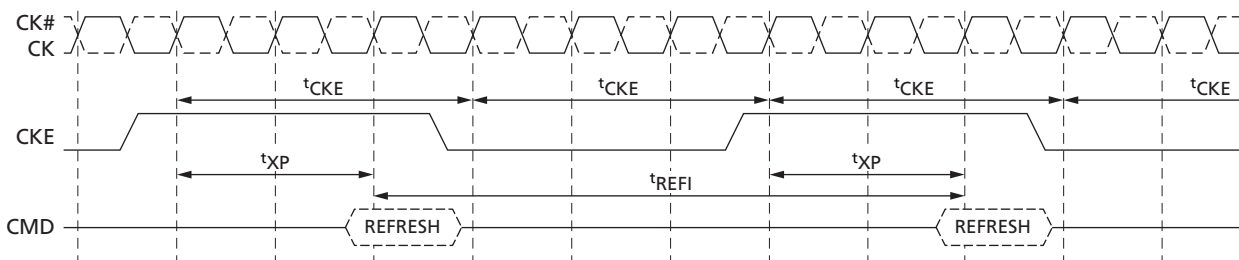


Figure 120: REFRESH-to-REFRESH Timing in CKE Intensive Environments



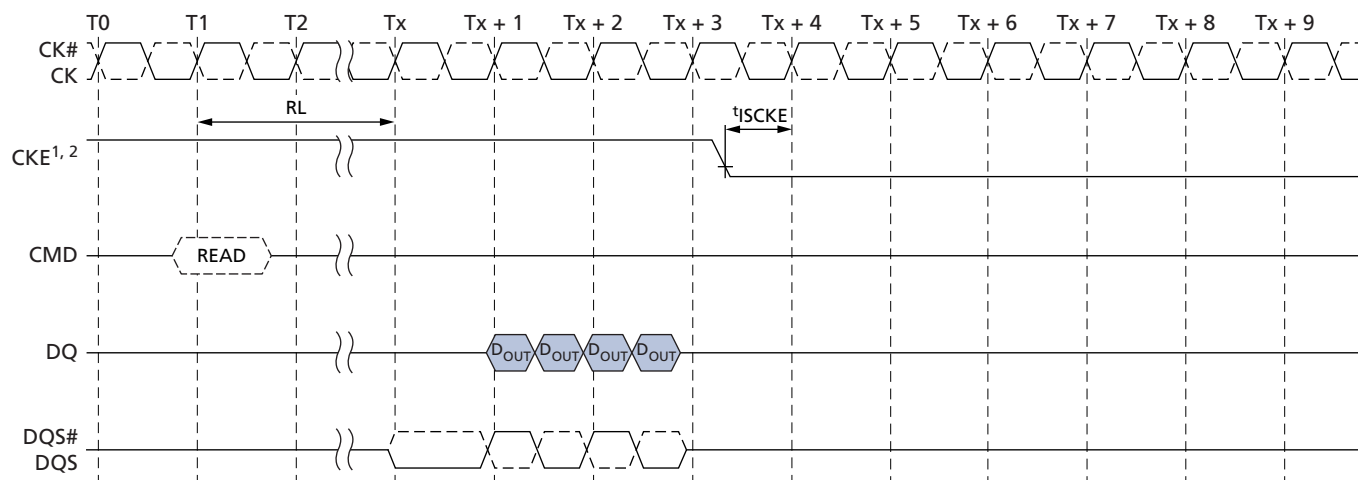
Note: 1. The pattern shown can repeat over an extended period of time. With this pattern, all AC and DC timing and voltage specifications with temperature and voltage drift are ensured.



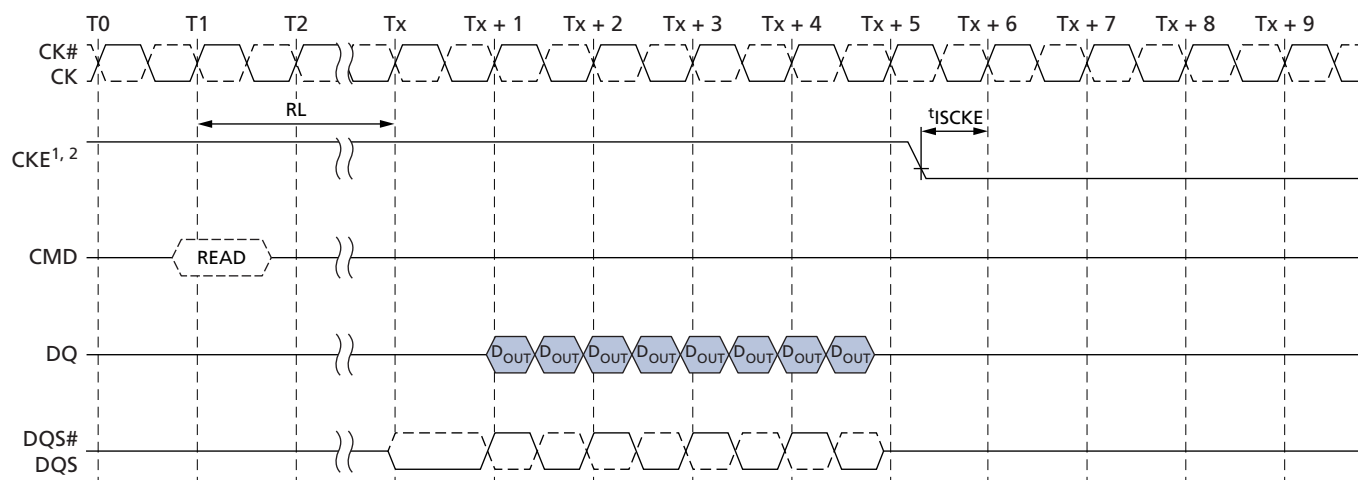
121-Ball NAND Flash with LPDDR2 MCP Power-Down

Figure 121: READ to Power-Down Entry

BL = 4



BL = 8



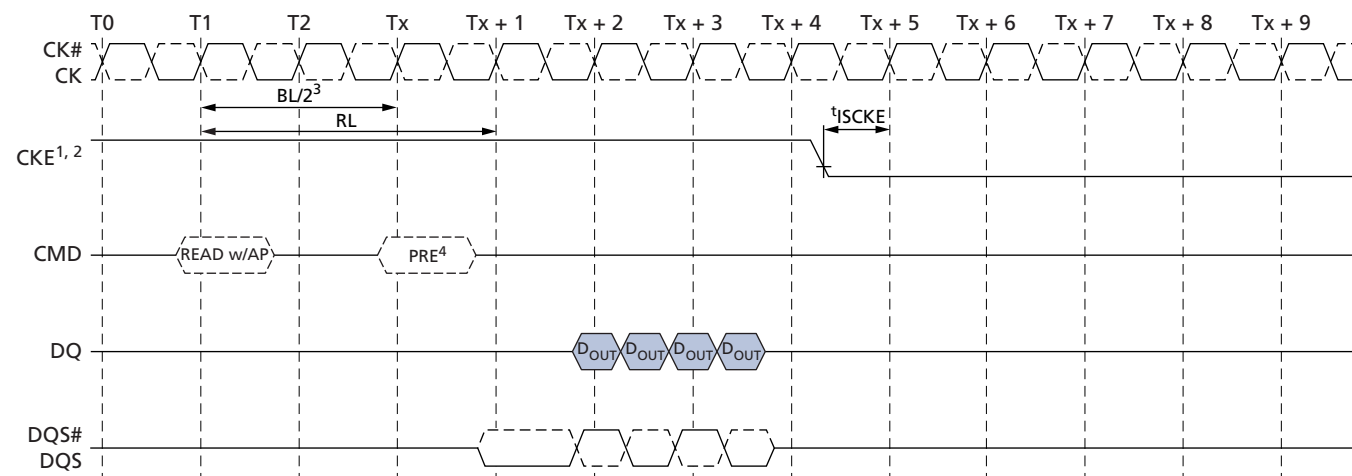
- Notes:
1. CKE must be held HIGH until the end of the burst operation.
 2. CKE can be registered LOW at $(RL + RU(t_{DQSCK(MAX)}/t_{CK}) + BL/2 + 1)$ clock cycles after the clock on which the READ command is registered.



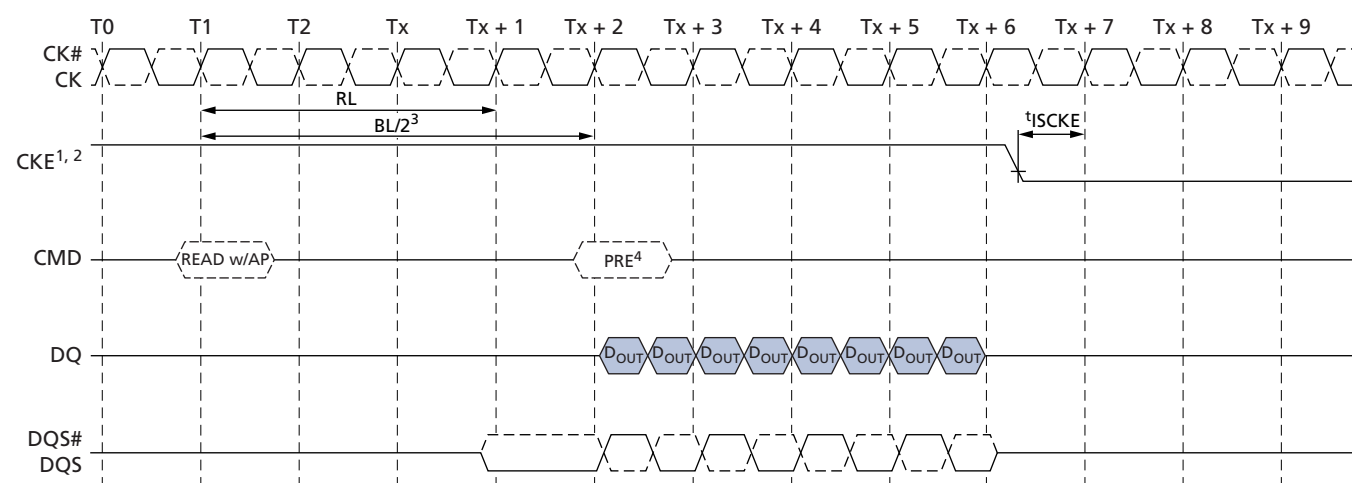
121-Ball NAND Flash with LPDDR2 MCP Power-Down

Figure 122: READ with Auto Precharge to Power-Down Entry

BL = 4



BL = 8



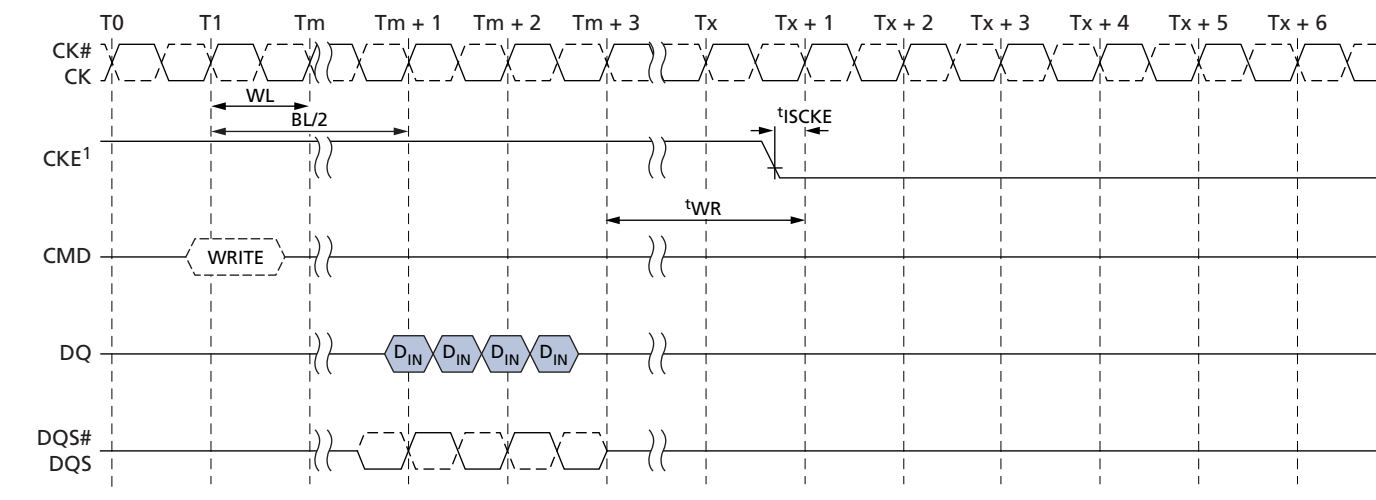
- Notes:
1. CKE must be held HIGH until the end of the burst operation.
 2. CKE can be registered LOW at $(RL + RU(t_{DQSCK}/t_{CK}) + BL/2 + 1)$ clock cycles after the clock on which the READ command is registered.
 3. BL/2 with $t_{RTP} = 7.5\text{ns}$ and $t_{RAS}(\text{MIN})$ is satisfied.
 4. Start internal PRECHARGE.



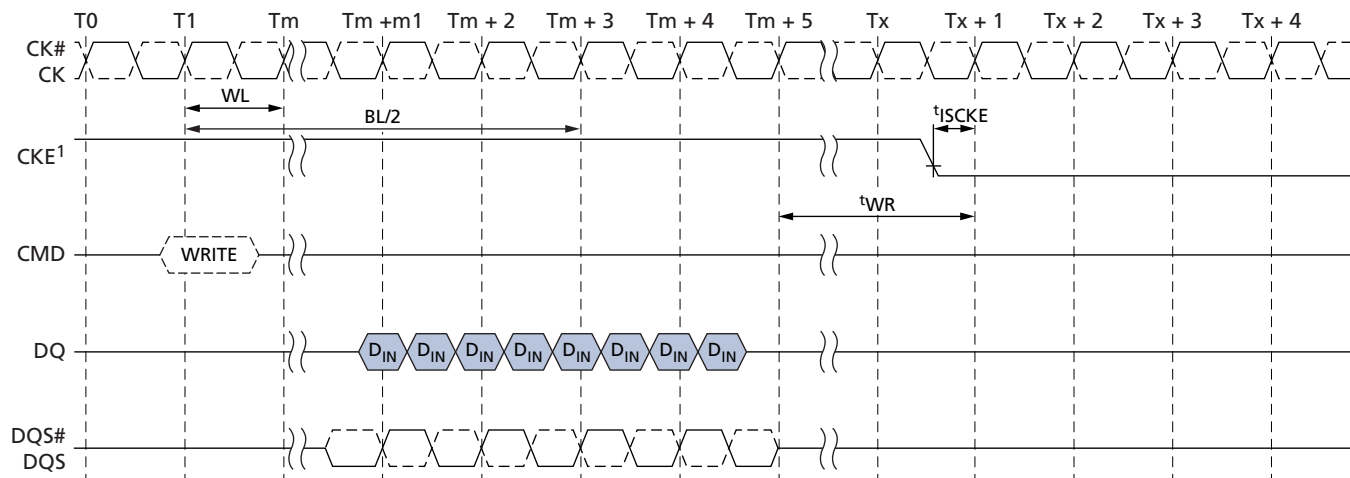
121-Ball NAND Flash with LPDDR2 MCP Power-Down

Figure 123: WRITE to Power-Down Entry

BL = 4



BL = 8



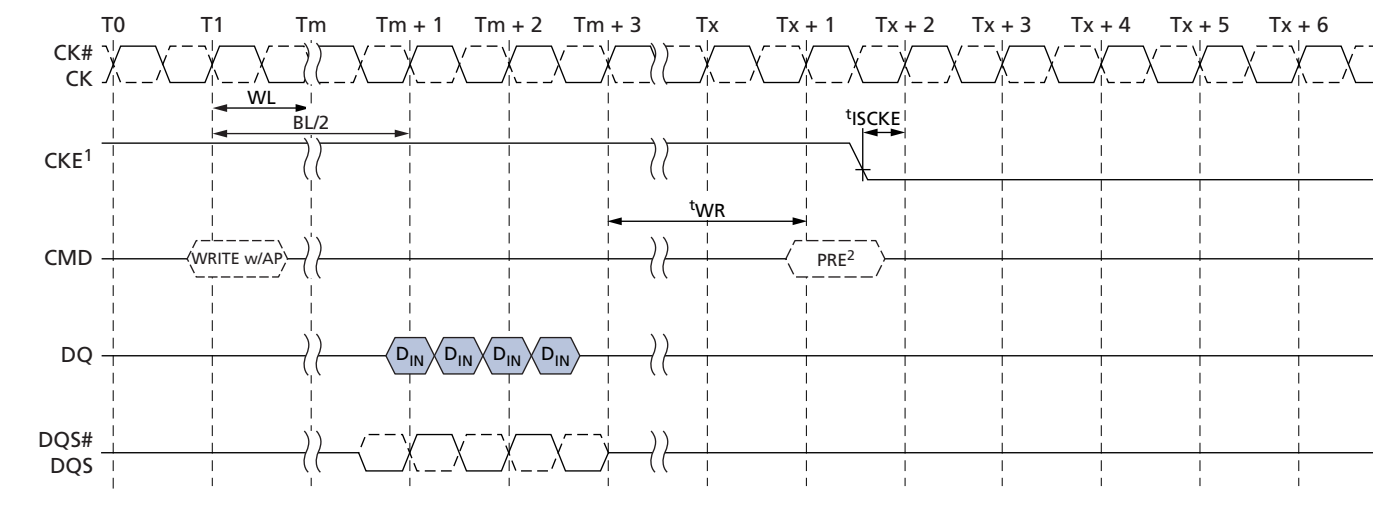
Note: 1. CKE can be registered LOW at $(WL + 1 + BL/2 + RU(t_{WR}/t_{CK}))$ clock cycles after the clock on which the WRITE command is registered.



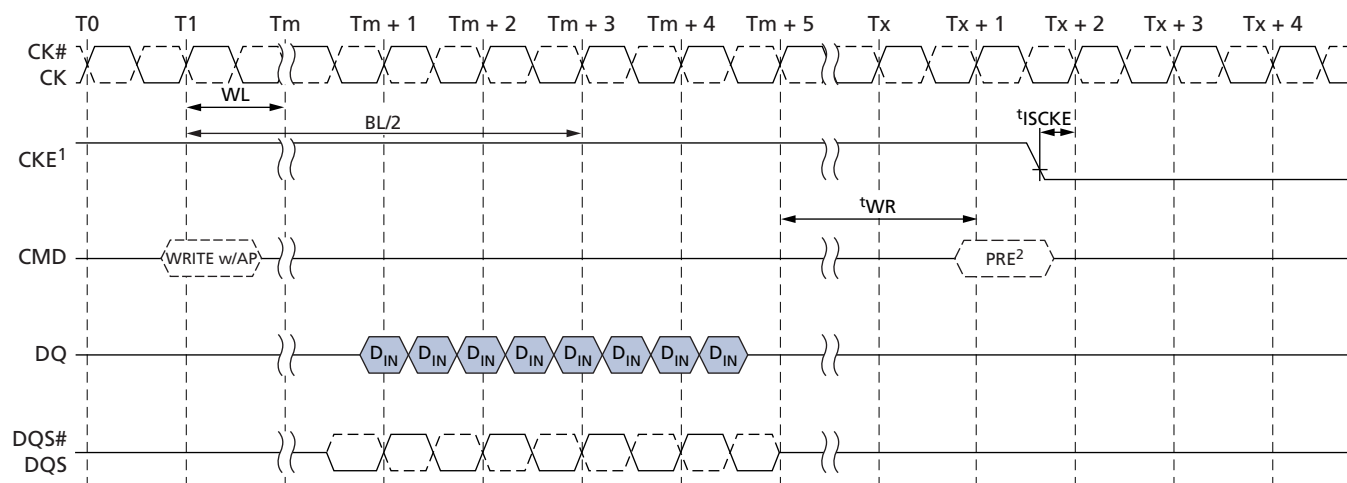
121-Ball NAND Flash with LPDDR2 MCP Power-Down

Figure 124: WRITE with Auto Precharge to Power-Down Entry

BL = 4



BL = 8

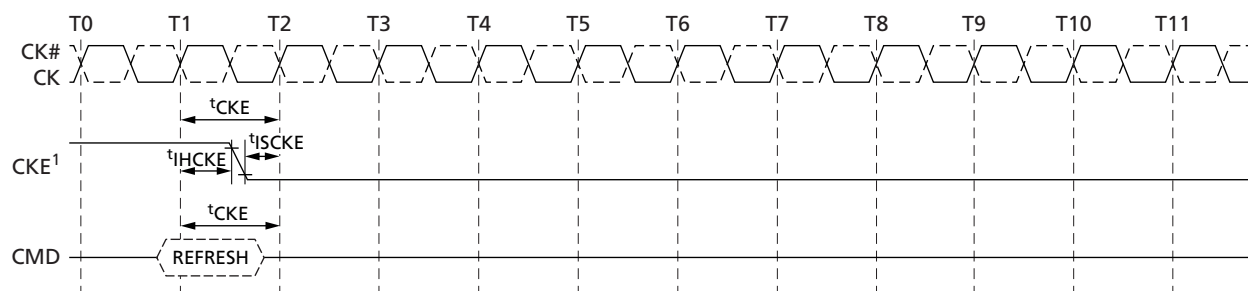


- Notes:
1. CKE can be registered LOW at $(WL + 1 + BL/2 + RU(tWR/t_{CK} + 1))$ clock cycles after the WRITE command is registered.
 2. Start internal PRECHARGE.



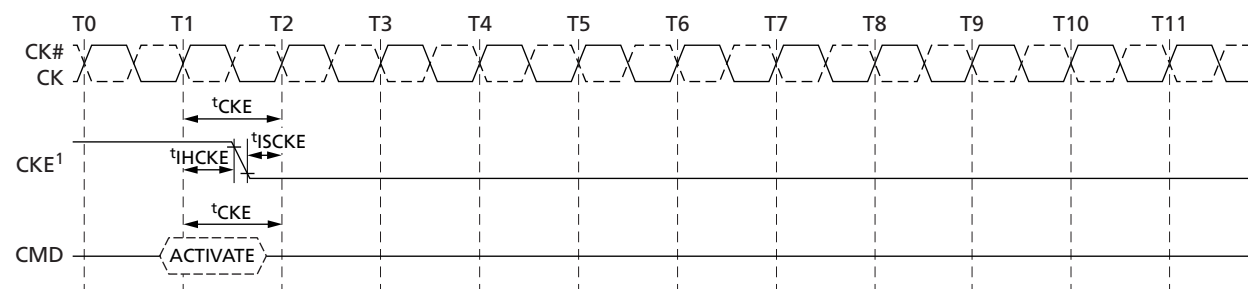
121-Ball NAND Flash with LPDDR2 MCP Power-Down

Figure 125: REFRESH Command to Power-Down Entry



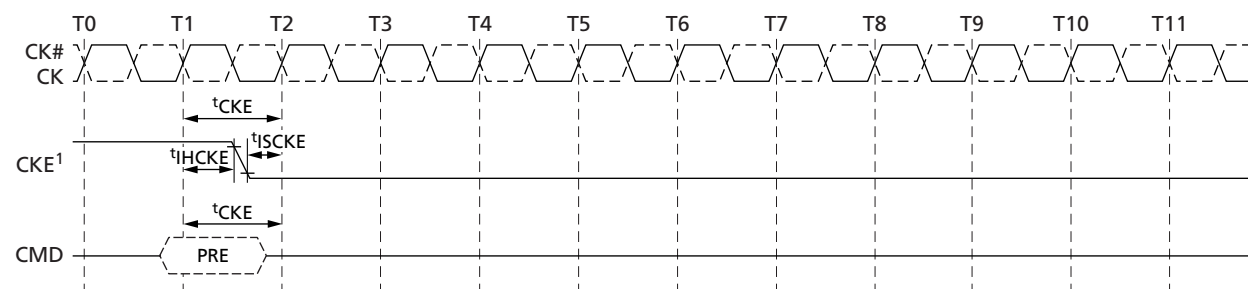
Note: 1. CKE can go LOW t_{HCKE} after the clock on which the REFRESH command is registered.

Figure 126: ACTIVATE Command to Power-Down Entry



Note: 1. CKE can go LOW at t_{HCKE} after the clock on which the ACTIVATE command is registered.

Figure 127: PRECHARGE Command to Power-Down Entry

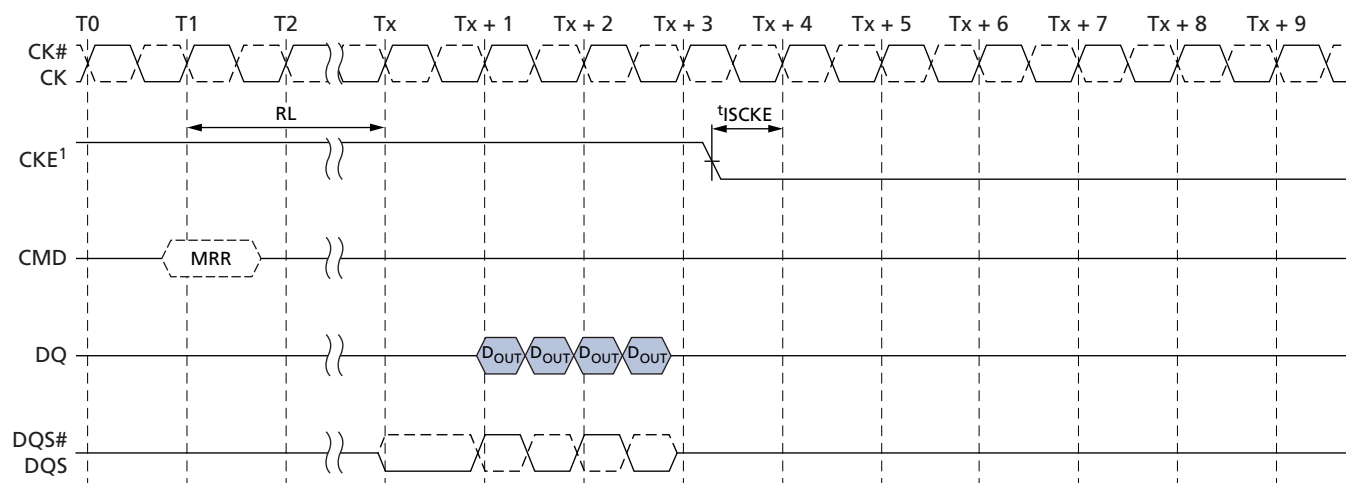


Note: 1. CKE can go LOW t_{HCKE} after the clock on which the PRECHARGE command is registered.



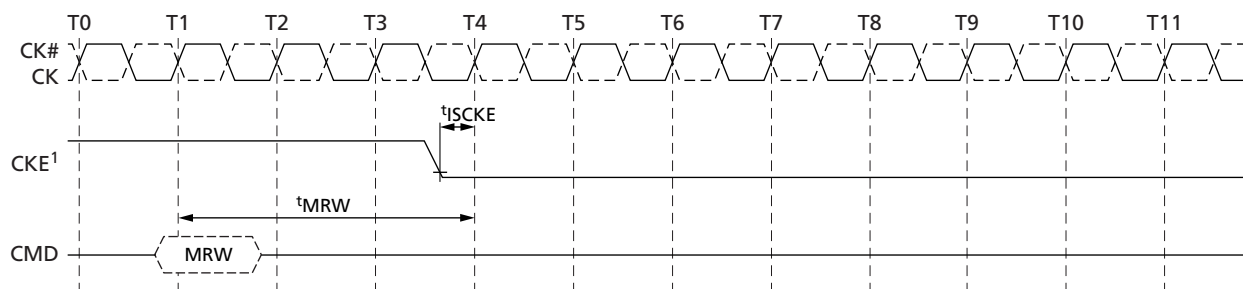
121-Ball NAND Flash with LPDDR2 MCP Deep Power-Down

Figure 128: MRR Command to Power-Down Entry



Note: 1. CKE can be registered LOW at $(RL + RU(t_{DQSC}/t_{CK}) + BL/2 + 1)$ clock cycles after the clock on which the MRR command is registered.

Figure 129: MRW Command to Power-Down Entry



Note: 1. CKE can be registered LOW t_{MRW} after the clock on which the MRW command is registered.

Deep Power-Down

Deep power-down (DPD) is entered when CKE is registered LOW with CS# LOW, CA0 HIGH, CA1 HIGH, and CA2 LOW at the rising edge of the clock. The NOP command must be driven in the clock cycle following power-down entry. CKE must not go LOW while MRR or MRW operations are in progress. CKE can go LOW while other operations such as ACTIVATE, auto precharge, PRECHARGE, or REFRESH are in progress, however, deep power-down I_{DD} specifications will not be applied until those operations complete. The contents of the array will be lost upon entering DPD mode.

In DPD mode, all input buffers except CKE, all output buffers, and the power supply to internal circuitry are disabled within the device. V_{REFDQ} can be at any level between 0 and V_{DDQ} , and V_{REFCA} can be at any level between 0 and V_{DDCA} during DPD. All power

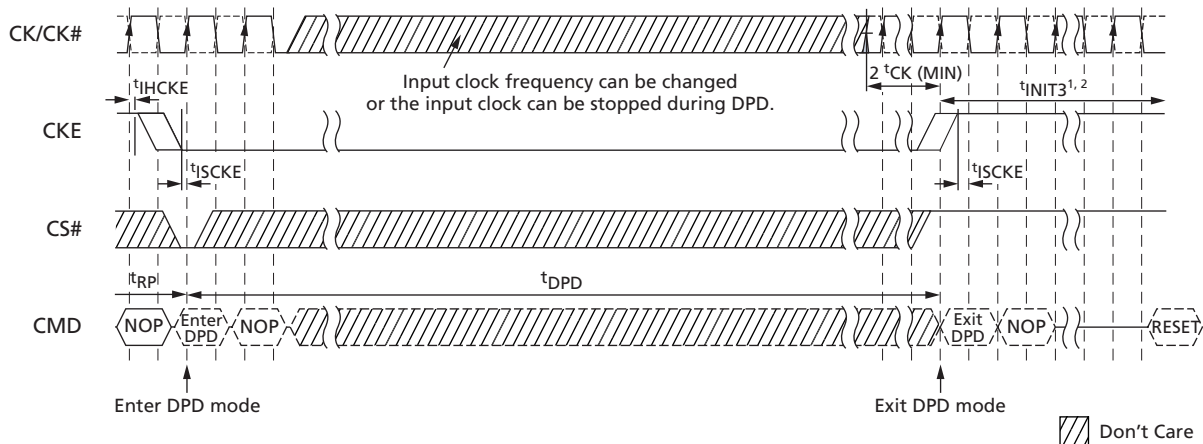


121-Ball NAND Flash with LPDDR2 MCP Input Clock Frequency Changes and Stop Events

supplies (including V_{REF}) must be within the specified limits prior to exiting DPD (see AC and DC Operating Conditions).

To exit DPD, CKE must be HIGH, t_{ISCKE} must be complete, and the clock must be stable. To resume operation, the device must be fully reinitialized using the power-up initialization sequence.

Figure 130: Deep Power-Down Entry and Exit Timing



- Notes:
1. The initialization sequence can start at any time after $T_x + 1$.
 2. t_{INIT3} and $T_x + 1$ refer to timings in the initialization sequence. For details, see Mode Register Definition.

Input Clock Frequency Changes and Stop Events

Input Clock Frequency Changes and Clock Stop with CKE LOW

During CKE LOW, Mobile LPDDR2 devices support input clock frequency changes and clock stop under the following conditions:

- Refresh requirements are met
- Only REFAb or REFpb commands can be in process
- Any ACTIVATE or PRECHARGE commands have completed prior to changing the frequency
- Related timing conditions, t_{RCD} and t_{RP} , have been met prior to changing the frequency
- The initial clock frequency must be maintained for a minimum of two clock cycles after CKE goes LOW
- The clock satisfies $t_{CH(abs)}$ and $t_{CL(abs)}$ for a minimum of two clock cycles prior to CKE going HIGH

For input clock frequency changes, $t_{CK(MIN)}$ and $t_{CK(MAX)}$ must be met for each clock cycle.

After the input clock frequency is changed and CKE is held HIGH, additional MRW commands may be required to set the WR, RL, etc. These settings may require adjustment to meet minimum timing requirements at the target clock frequency.



121-Ball NAND Flash with LPDDR2 MCP NO OPERATION Command

For clock stop, CK is held LOW and CK# is held HIGH.

Input Clock Frequency Changes and Clock Stop with CKE HIGH

During CKE HIGH, LPDDR2 devices support input clock frequency changes and clock stop under the following conditions:

- REFRESH requirements are met
- Any ACTIVATE, READ, WRITE, PRECHARGE, MRW, or MRR commands must have completed, including any associated data bursts, prior to changing the frequency
- Related timing conditions, t_{RCD} , t_{WR} , t_{WRA} , t_{RP} , t_{MRW} , and t_{MRR} , etc., are met
- CS# must be held HIGH
- Only REFab or REFpb commands can be in process

The device is ready for normal operation after the clock satisfies $t_{CH}(abs)$ and $t_{CL}(abs)$ for a minimum of $2 \times t_{CK} + t_{XP}$.

For input clock frequency changes, $t_{CK}(MIN)$ and $t_{CK}(MAX)$ must be met for each clock cycle.

After the input clock frequency is changed, additional MRW commands may be required to set the WR, RL, etc. These settings may require adjustment to meet minimum timing requirements at the target clock frequency.

For clock stop, CK is held LOW and CK# is held HIGH.

NO OPERATION Command

The NO OPERATION (NOP) command prevents the device from registering any unwanted commands issued between operations. A NOP command can only be issued at clock cycle N when the CKE level is constant for clock cycle N-1 and clock cycle N. The NOP command has two possible encodings: CS# HIGH at the clock rising edge N; and CS# LOW with CA0, CA1, CA2 HIGH at the clock rising edge N.

The NOP command will not terminate a previous operation that is still in process, such as a READ burst or WRITE burst cycle.

Simplified Bus Interface State Diagram

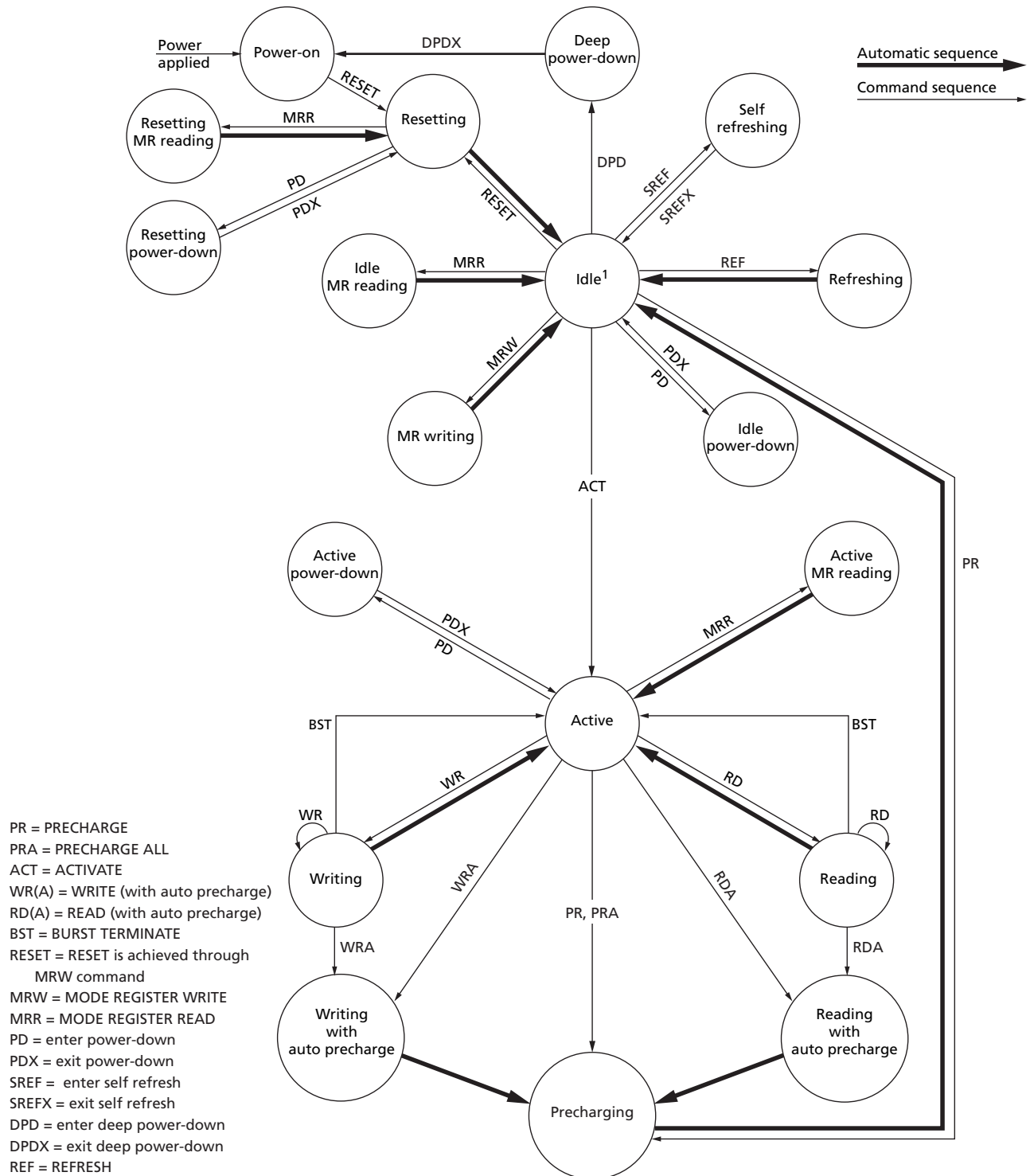
The state diagram (see Figure 131 (page 175)) provides a simplified illustration of the bus interface, supported state transitions, and the commands that control them. For a complete description of device behavior, use the information provided in the state diagram with the truth tables and timing specifications.

The truth tables describe device behavior and applicable restrictions when considering the actual state of all banks.



121-Ball NAND Flash with LPDDR2 MCP NO OPERATION Command

Figure 131: Simplified Bus Interface State Diagram



Note: 1. All banks are precharged in the idle state.



121-Ball NAND Flash with LPDDR2 MCP Truth Tables

Truth Tables

Truth tables provide complementary information to the state diagram. They also clarify device behavior and applicable restrictions when considering the actual state of the banks.

Unspecified operations and timings are illegal. To ensure proper operation after an illegal event, the device must be powered down and then restarted using the specified initialization sequence before normal operation can continue.

Table 80: Command Truth Table

Notes 1–11 apply to all parameters conditions

Command	Command Pins			CA Pins										CK Edge
	CKE		CS#	CA0	CA1	CA2	CA3	CA4	CA5	CA6	CA7	CA8	CA9	
	CK(n-1)	CK(n)												
MRW	H	H	L	L	L	L	L	MA0	MA1	MA2	MA3	MA4	MA5	
	H	H	X	MA6	MA7	OP0	OP1	OP2	OP3	OP4	OP5	OP6	OP7	
MRR	H	H	L	L	L	L	H	MA0	MA1	MA2	MA3	MA4	MA5	
	H	H	X	MA6	MA7	X								
REFRESH (per bank)	H	H	L	L	L	H	L	X						
	H	H	X	X										
REFRESH (all banks)	H	H	L	L	L	H	H	X						
	H	H	X	X										
Enter self refresh	H	L	L	L	L	H	X							
	X	L	X	X										
ACTIVATE (bank)	H	H	L	L	H	R8	R9	R10	R11	R12	BA0	BA1	BA2	
	H	H	X	R0	R1	R2	R3	R4	R5	R6	R7	R13	R14	
WRITE (bank)	H	H	L	H	L	L	RFU	RFU	C1	C2	BA0	BA1	BA2	
	H	H	X	AP	C3	C4	C5	C6	C7	C8	C9	C10	C11	
READ (bank)	H	H	L	H	L	H	RFU	RFU	C1	C2	BA0	BA1	BA2	
	H	H	X	AP	C3	C4	C5	C6	C7	C8	C9	C10	C11	
PRECHARGE (bank)	H	H	L	H	H	L	H	AB	X	X	BA0	BA1	BA2	
	H	H	X	X										
BST	H	H	L	H	H	L	L	X						
	H	H	X	X										
Enter DPD	H	L	L	H	H	L	X							
	X	L	X	X										
NOP	H	H	L	H	H	H	X							
	H	H	X	X										
Maintain PD, SREF, DPD, (NOP)	L	L	L	H	H	H	X							
	L	L	X	X										











121-Ball NAND Flash with LPDDR2 MCP Truth Tables

Table 80: Command Truth Table (Continued)

Notes 1–11 apply to all parameters conditions

Notes: 1. The following apply to all parameter combinations.

Command	Command Pins			CA Pins										CK Edge
	CKE		CS#	CA0	CA1	CA2	CA3	CA4	CA5	CA6	CA7	CA8	CA9	
	CK(n-1)	CK(n)												
NOP	H	H	H	X										
	H	H	X	X										
Maintain PD, SREF, DPD, (NOP)	L	L	H	X										
	L	L	X	X										
Enter power-down	H	L	H	X										
	X	L	X	X										
Exit PD, SREF, DPD	L	H	H	X										
	X	H	X	X										

- Notes:
1. All commands are defined by the current state of CS#, CA0, CA1, CA2, CA3, and CKE at the rising edge of the clock.
 2. Bank addresses (BA) determine which bank will be operated upon.
 3. AP HIGH during a READ or WRITE command indicates that an auto precharge will occur to the bank associated with the READ or WRITE command.
 4. X indicates a "Don't Care" state, with a defined logic level, either HIGH (H) or LOW (L).
 5. Self refresh exit and DPD exit are asynchronous.
 6. V_{REF} must be between 0 and V_{DDQ} during self refresh and DPD operation.
 7. CA_{xr} refers to command/address bit "x" on the rising edge of clock.
 8. CA_{xf} refers to command/address bit "x" on the falling edge of clock.
 9. CS# and CKE are sampled on the rising edge of the clock.
 10. Per-bank refresh is only supported in devices with eight banks.
 11. The least-significant column address C0 is not transmitted on the CA bus, and is inferred to be zero.

Table 81: CKE Truth Table

Notes 1–5 apply to all parameters and conditions; L = LOW, H = HIGH, X = "Don't Care"

Current State	CKEn-1	CKEn	CS#	Command <i>n</i>	Operation <i>n</i>	Next State	Notes
Active power-down	L	L	X	X	Maintain active power-down	Active power-down	
	L	H	H	NOP	Exit active power-down	Active	6, 7
Idle power-down	L	L	X	X	Maintain idle power-down	Idle power-down	
	L	H	H	NOP	Exit idle power-down	Idle	6, 7
Resetting idle power-down	L	L	X	X	Maintain resetting power-down	Resetting power-down	
	L	H	H	NOP	Exit resetting power-down	Idle or resetting	6, 7, 8



121-Ball NAND Flash with LPDDR2 MCP Truth Tables

Table 81: CKE Truth Table (Continued)

Notes 1–5 apply to all parameters and conditions; L = LOW, H = HIGH, X = "Don't Care"

Current State	CKEn-1	CKEn	CS#	Command <i>n</i>	Operation <i>n</i>	Next State	Notes
Deep power-down	L	L	X	X	Maintain deep power-down	Deep power-down	
	L	H	H	NOP	Exit deep power-down	Power-on	9
Self refresh	L	L	X	X	Maintain self refresh	Self refresh	
	L	H	H	NOP	Exit self refresh	Idle	10, 11
Bank(s) active	H	L	H	NOP	Enter active power-down	Active power-down	
All banks idle	H	L	H	NOP	Enter idle power-down	Idle power-down	
	H	L	L	Enter self refresh	Enter self refresh	Self refresh	
	H	L	L	DPD	Enter deep power-down	Deep power-down	
Resetting	H	L	H	NOP	Enter resetting power-down	Resetting power-down	
Other states	H	H	Refer to the command truth table				

- Notes:
1. Current state = the state of the device immediately prior to the clock rising edge *n*.
 2. All states and sequences not shown are illegal or reserved unless explicitly described elsewhere in this document.
 3. CKEn = the logic state of CKE at clock rising edge *n*; CKEn-1 was the state of CKE at the previous clock edge.
 4. CS# = the logic state of CS# at the clock rising edge *n*.
 5. Command *n* = the command registered at clock edge *n*, and operation *n* is a result of command *n*.
 6. Power-down exit time (*t*_{XP}) must elapse before any command other than NOP is issued.
 7. The clock must toggle at least twice prior to the *t*_{XP} period.
 8. Upon exiting the resetting power-down state, the device will return to the idle state if *t*_{INIT5} has expired.
 9. The DPD exit procedure must be followed as described in Deep Power-Down (page 172).
 10. Self refresh exit time (*t*_{XSR}) must elapse before any command other than NOP is issued.
 11. The clock must toggle at least twice prior to the *t*_{XSR} time.

Table 82: Current State Bank *n* to Command to Bank *n* Truth Table

Notes 1–5 apply to all parameters and conditions

Current State	Command	Operation	Next State	Notes
Any	NOP	Continue previous operation	Current state	



121-Ball NAND Flash with LPDDR2 MCP Truth Tables

Table 82: Current State Bank *n* to Command to Bank *n* Truth Table (Continued)

Notes 1–5 apply to all parameters and conditions

Current State	Command	Operation	Next State	Notes
Idle	ACTIVATE	Select and activate row	Active	
	Refresh (per bank)	Begin to refresh	Refreshing (per bank)	6
	Refresh (all banks)	Begin to refresh	Refreshing (all banks)	7
	MRW	Load value to mode register	MR writing	7
	MRR	Read value from mode register	Idle, MR reading	
	RESET	Begin device auto initialization	Resetting	7, 8
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	9, 10
Row active	READ	Select column and start read burst	Reading	
	WRITE	Select column and start write burst	Writing	
	MRR	Read value from mode register	Active MR reading	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	9
Reading	READ	Select column and start new read burst	Reading	11, 12
	WRITE	Select column and start write burst	Writing	11, 12, 13
	BST	Read burst terminate	Active	14
Writing	WRITE	Select column and start new write burst	Writing	11, 12
	READ	Select column and start read burst	Reading	11, 12, 15
	BST	Write burst terminate	Active	14
Power-on	MRW RESET	Begin device auto initialization	Resetting	7, 9
Resetting	MRR	Read value from mode register	Resetting MR reading	

- Notes:
- Values in this table apply when both $CKEn-1$ and $CKEn$ are HIGH, and after t_{XSR} or t_{XP} has been met, if the previous state was power-down.
 - All states and sequences not shown are illegal or reserved.
 - Current state definitions:

Idle: The bank or banks have been precharged, and t_{RP} has been met.

Active: A row in the bank has been activated, and t_{RCD} has been met. No data bursts or accesses and no register accesses are in progress.

Reading: A READ burst has been initiated with auto precharge disabled and has not yet terminated or been terminated.

Writing: A WRITE burst has been initiated with auto precharge disabled and has not yet terminated or been terminated.

- The states listed below must not be interrupted by a command issued to the same bank. NOP commands or supported commands to the other bank must be issued on any clock edge occurring during these states. Supported commands to the other banks are determined by that bank's current state, and the definitions given in Table 83 (page 180).

Precharge: Starts with registration of a PRECHARGE command and ends when t_{RP} is met. After t_{RP} is met, the bank is in the idle state.

Row activate: Starts with registration of an ACTIVATE command and ends when t_{RCD} is met. After t_{RCD} is met, the bank is in the active state.



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READ with AP enabled: Starts with registration of a READ command with auto pre-charge enabled and ends when t_{RP} is met. After t_{RP} is met, the bank is in the idle state.

WRITE with AP enabled: Starts with registration of a WRITE command with auto pre-charge enabled and ends when t_{RP} is met. After t_{RP} is met, the bank is in the idle state.

5. The states listed below must not be interrupted by any executable command. NOP commands must be applied to each rising clock edge during these states.

Refresh (per bank): Starts with registration of a REFRESH (per bank) command and ends when t_{RFCpb} is met. After t_{RFCpb} is met, the bank is in the idle state.

Refresh (all banks): Starts with registration of a REFRESH (all banks) command and ends when t_{RFCab} is met. After t_{RFCab} is met, the device is in the all banks idle state.

Idle MR reading: Starts with registration of the MRR command and ends when t_{MRR} is met. After t_{MRR} is met, the device is in the all banks idle state.

Resetting MR reading: Starts with registration of the MRR command and ends when t_{MRR} is met. After t_{MRR} is met, the device is in the all banks idle state.

Active MR reading: Starts with registration of the MRR command and ends when t_{MRR} is met. After t_{MRR} is met, the bank is in the active state.

MR writing: Starts with registration of the MRW command and ends when t_{MRW} is met. After t_{MRW} is met, the device is in the all banks idle state.

Precharging all: Starts with registration of a PRECHARGE ALL command and ends when t_{RP} is met. After t_{RP} is met, the device is in the all banks idle state.

6. Bank-specific; requires that the bank is idle and no bursts are in progress.
7. Not bank-specific; requires that all banks are idle and no bursts are in progress.
8. Not bank-specific.
9. This command may or may not be bank specific. If all banks are being precharged, they must be in a valid state for precharging.
10. If a PRECHARGE command is issued to a bank in the idle state, t_{RP} still applies.
11. A command other than NOP should not be issued to the same bank while a burst READ or burst WRITE with auto precharge is enabled.
12. The new READ or WRITE command could be auto precharge enabled or auto precharge disabled.
13. A WRITE command can be issued after the completion of the READ burst; otherwise, a BST must be issued to end the READ prior to asserting a WRITE command.
14. Not bank-specific. The BST command affects the most recent READ/WRITE burst started by the most recent READ/WRITE command, regardless of bank.
15. A READ command can be issued after completion of the WRITE burst; otherwise, a BST must be used to end the WRITE prior to asserting another READ command.

Table 83: Current State Bank n to Command to Bank m Truth Table

Notes 1–6 apply to all parameters and conditions

Current State of Bank n	Command to Bank m	Operation	Next State for Bank m	Notes
Any	NOP	Continue previous operation	Current state of bank m	
Idle	Any	Any command supported to bank m	–	7



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Table 83: Current State Bank *n* to Command to Bank *m* Truth Table (Continued)

Notes 1–6 apply to all parameters and conditions

Current State of Bank <i>n</i>	Command to Bank <i>m</i>	Operation	Next State for Bank <i>m</i>	Notes
Row activating, active, or pre-charging	ACTIVATE	Select and activate row in bank <i>m</i>	Active	8
	READ	Select column and start READ burst from bank <i>m</i>	Reading	9
	WRITE	Select column and start WRITE burst to bank <i>m</i>	Writing	9
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	10
	MRR	READ value from mode register	Idle MR reading or active MR reading	11, 12, 13
	BST	READ or WRITE burst terminates an on-going READ/WRITE from/to bank <i>m</i>	Active	7
Reading (auto precharge disabled)	READ	Select column and start READ burst from bank <i>m</i>	Reading	9
	WRITE	Select column and start WRITE burst to bank <i>m</i>	Writing	9, 14
	ACTIVATE	Select and activate row in bank <i>m</i>	Active	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	10
Writing (auto precharge disabled)	READ	Select column and start READ burst from bank <i>m</i>	Reading	9, 15
	WRITE	Select column and start WRITE burst to bank <i>m</i>	Writing	9
	ACTIVATE	Select and activate row in bank <i>m</i>	Active	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	10
Reading with auto precharge	READ	Select column and start READ burst from bank <i>m</i>	Reading	9, 16
	WRITE	Select column and start WRITE burst to bank <i>m</i>	Writing	9, 14, 16
	ACTIVATE	Select and activate row in bank <i>m</i>	Active	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	10
Writing with auto precharge	READ	Select column and start READ burst from bank <i>m</i>	Reading	9, 15, 16
	WRITE	Select column and start WRITE burst to bank <i>m</i>	Writing	9, 16
	ACTIVATE	Select and activate row in bank <i>m</i>	Active	
	PRECHARGE	Deactivate row(s) in bank or banks	Precharging	10
Power-on	MRW RESET	Begin device auto initialization	Resetting	17, 18
Resetting	MRR	Read value from mode register	Resetting MR reading	

- Notes:
1. This table applies when: the previous state was self refresh or power-down; after t_{XSR} or t_{XP} has been met; and both $CKEn-1$ and $CKEn$ are HIGH.
 2. All states and sequences not shown are illegal or reserved.



121-Ball NAND Flash with LPDDR2 MCP Truth Tables

3. Current state definitions:

Idle: The bank has been precharged and t_{RP} has been met.

Active: A row in the bank has been activated, t_{RCD} has been met, no data bursts or accesses and no register accesses are in progress.

Read: A READ burst has been initiated with auto precharge disabled and the READ has not yet terminated or been terminated.

Write: A WRITE burst has been initiated with auto precharge disabled and the WRITE has not yet terminated or been terminated.

4. Refresh, self refresh, and MRW commands can only be issued when all banks are idle.
5. A BST command cannot be issued to another bank; it applies only to the bank represented by the current state.
6. The states listed below must not be interrupted by any executable command. NOP commands must be applied during each clock cycle while in these states:

Idle MRR: Starts with registration of the MRR command and ends when t_{MRR} has been met. After t_{MRR} is met, the device is in the all banks idle state.

Reset MRR: Starts with registration of the MRR command and ends when t_{MRR} has been met. After t_{MRR} is met, the device is in the all banks idle state.

Active MRR: Starts with registration of the MRR command and ends when t_{MRR} has been met. After t_{MRR} is met, the bank is in the active state.

MRW: Starts with registration of the MRW command and ends when t_{MRW} has been met. After t_{MRW} is met, the device is in the all banks idle state.

7. BST is supported only if a READ or WRITE burst is ongoing.
8. t_{RRD} must be met between the ACTIVATE command to bank n and any subsequent ACTIVATE command to bank m .
9. READs or WRITEs listed in the command column include READs and WRITEs with or without auto precharge enabled.
10. This command may or may not be bank-specific. If all banks are being precharged, they must be in a valid state for precharging.
11. MRR is supported in the row-activating state.
12. MRR is supported in the precharging state.
13. The next state for bank m depends on the current state of bank m (idle, row-activating, precharging, or active).
14. A WRITE command can be issued after the completion of the READ burst; otherwise a BST must be issued to end the READ prior to asserting a WRITE command.
15. A READ command can be issued after the completion of the WRITE burst; otherwise, a BST must be issued to end the WRITE prior to asserting another READ command.
16. A READ with auto precharge enabled or a WRITE with auto precharge enabled can be followed by any valid command to other banks provided that the timing restrictions in the PRECHARGE and Auto Precharge Clarification table are met.
17. Not bank-specific; requires that all banks are idle and no bursts are in progress.
18. RESET command is achieved through MODE REGISTER WRITE command.

**121-Ball NAND Flash with LPDDR2 MCP
Truth Tables****Table 84: DM Truth Table**

Functional Name	DM	DQ	Notes
Write enable	L	Valid	1
Write inhibit	H	X	1

Note: 1. Used to mask write data, and is provided simultaneously with the corresponding input data.



121-Ball NAND Flash with LPDDR2 MCP Electrical Specifications

Electrical Specifications

Absolute Maximum Ratings

Stresses greater than those listed below may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions outside those indicated in the operational sections of this document is not implied. Exposure to absolute maximum rating conditions for extended periods may adversely affect reliability.

Table 85: Absolute Maximum DC Ratings

Parameter	Symbol	Min	Max	Unit	Notes
V _{DD1} supply voltage relative to V _{SS}	V _{DD1}	−0.4	+2.3	V	1
V _{DD2} supply voltage relative to V _{SS}	V _{DD2} (1.2V)	−0.4	+1.6	V	1
V _{DDCA} supply voltage relative to V _{SSCA}	V _{DDCA}	−0.4	+1.6	V	1, 2
V _{DDQ} supply voltage relative to V _{SSQ}	V _{DDQ}	−0.4	+1.6	V	1, 3
Voltage on any ball relative to V _{SS}	V _{IN} , V _{OUT}	−0.4	+1.6	V	
Storage temperature	T _{STG}	−55	+125	°C	4

- Notes:
1. See 1. Voltage Ramp under Power-Up (page 111).
 2. V_{REFCA} 0.6 ≤ V_{DDCA}; however, V_{REFCA} may be ≥ V_{DDCA} provided that V_{REFCA} ≤ 300mV.
 3. V_{REFDQ} 0.6 ≤ V_{DDQ}; however, V_{REFDQ} may be ≥ V_{DDQ} provided that V_{REFDQ} ≤ 300mV.
 4. Storage temperature is the case surface temperature on the center/top side of the device. For measurement conditions, refer to the JE5D51-2 standard.

Input/Output Capacitance

Table 86: Input/Output Capacitance

Note 1 applies to all parameters and conditions

Parameter	Symbol	LPDDR2 1066-466		LPDDR2 400-200		Unit	Notes
		MIN	MAX	MIN	MAX		
Input capacitance, CK and CK#	C _{CK}	1.0	2.0	1.0	2.0	pF	2, 3
Input capacitance delta, CK and CK#	C _{DCK}	0	0.20	0	0.25	pF	2, 3, 4
Input capacitance, all other input-only pins	C _I	1.0	2.0	1.0	2.0	pF	2, 3, 5
Input capacitance delta, all other input-only pins	C _{DI}	−0.40	+0.40	−0.50	+0.50	pF	2, 3, 6
Input/output capacitance, DQ, DM, DQS, DQS#	C _{IO}	1.25	2.5	1.25	2.5	pF	2, 3, 7, 8
Input/output capacitance delta, DQS, DQS#	C _{DDQS}	0	0.25	0	0.30	pF	2, 3, 8, 9
Input/output capacitance delta, DQ, DM	C _{DIO}	−0.5	+0.5	−0.6	+0.6	pF	2, 3, 8, 10
Input/output capacitance ZQ	C _{ZQ}	0	2.5	0	2.5	pF	2, 3, 11

- Notes:
1. T_C −25°C to +105°C; V_{DDQ} = 1.14–1.3V; V_{DDCA} = 1.14–1.3V; V_{DD1} = 1.7–1.95V; V_{DD2} = 1.14–1.3V.



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2. This parameter applies to die devices only (does not include package capacitance).
3. This parameter is not subject to production testing. It is verified by design and characterization. The capacitance is measured according to JEP147 (procedure for measuring input capacitance using a vector network analyzer), with V_{DD1}, V_{DD2}, V_{DDQ}, V_{SS}, V_{SSCA}, and V_{SSQ} applied; all other pins are left floating.
4. Absolute value of C_{CK} - C_{CK#}.
5. C_I applies to CS#, CKE, and CA[9:0].
6. C_{DI} = C_I - 0.5 × (C_{CK} + C_{CK#}).
7. DM loading matches DQ and DQS.
8. MR3 I/O configuration drive strength OP[3:0] = 0001b (34.3 ohm typical).
9. Absolute value of C_{DQS} and C_{DQS#}.
10. C_{DIO} = C_{IO} - 0.5 × (C_{DQS} + C_{DQS#}) in byte-lane.
11. Maximum external load capacitance on ZQ pin: 5pF.

Electrical Specifications – I_{DD} Specifications and Conditions

The following definitions and conditions are used in the I_{DD} measurement tables unless stated otherwise:

- LOW: V_{IN} ≤ V_{IL(DC)max}
- HIGH: V_{IN} ≥ V_{IH(DC)min}
- STABLE: Inputs are stable at a HIGH or LOW level
- SWITCHING: See the following three tables

Table 87: Switching for CA Input Signals

Notes 1–3 apply to all parameters and conditions

	CK Rising/ CK#Falling	CK Falling/ CK# Rising	CK Rising/ CK#Falling	CK Falling/ CK# Rising	CK Rising/ CK#Falling	CK Falling/ CK# Rising	CK Rising/ CK#Falling	CK Falling/ CK# Rising
Cycle	N		N + 1		N + 2		N + 3	
CS#	HIGH		HIGH		HIGH		HIGH	
CA0	H	L	L	L	L	H	H	H
CA1	H	H	H	L	L	L	L	H
CA2	H	L	L	L	L	H	H	H
CA3	H	H	H	L	L	L	L	H
CA4	H	L	L	L	L	H	H	H
CA5	H	H	H	L	L	L	L	H
CA6	H	L	L	L	L	H	H	H
CA7	H	H	H	L	L	L	L	H
CA8	H	L	L	L	L	H	H	H
CA9	H	H	H	L	L	L	L	H

- Notes:
1. CS# must always be driven HIGH.
 2. For each clock cycle, 50% of the CA bus is changing between HIGH and LOW.
 3. The noted pattern (N, N + 1, N + 2, N + 3...) is used continuously during I_{DD} measurement for I_{DD} values that require switching on the CA bus.



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Electrical Specifications – I_{DD} Specifications and Conditions

Table 88: Switching for I_{DD4R}

Clock	CKE	CS#	Clock Cycle Number	Command	CA[2:0]	CA[9:3]	All DQ
Rising	H	L	N	Read_Rising	HLH	LHLHLHL	L
Falling	H	L	N	Read_Falling	LLL	LLLLLLL	L
Rising	H	H	N + 1	NOP	LLL	LLLLLLL	H
Falling	H	H	N + 1	NOP	HLH	LHLHLHL	L
Rising	H	L	N + 2	Read_Rising	HLH	LHLHLHL	H
Falling	H	L	N + 2	Read_Falling	LLL	HHHHHHH	H
Rising	H	H	N + 3	NOP	LLL	HHHHHHH	H
Falling	H	H	N + 3	NOP	HLH	LHLHLHL	L

- Notes: 1. Data strobe (DQS) is changing between HIGH and LOW with every clock cycle.
 2. The noted pattern (N, N + 1...) is used continuously during I_{DD} measurement for I_{DD4R}.

Table 89: Switching for I_{DD4W}

Clock	CKE	CS#	Clock Cycle Number	Command	CA[2:0]	CA[9:3]	All DQ
Rising	H	L	N	Write_Rising	LLH	LHLHLHL	L
Falling	H	L	N	Write_Falling	LLL	LLLLLLL	L
Rising	H	H	N + 1	NOP	LLL	LLLLLLL	H
Falling	H	H	N + 1	NOP	HLH	LHLHLHL	L
Rising	H	L	N + 2	Write_Rising	LLH	LHLHLHL	H
Falling	H	L	N + 2	Write_Falling	LLL	HHHHHHH	H
Rising	H	H	N + 3	NOP	LLL	HHHHHHH	H
Falling	H	H	N + 3	NOP	HLH	LHLHLHL	L

- Notes: 1. Data strobe (DQS) is changing between HIGH and LOW with every clock cycle.
 2. Data masking (DM) must always be driven LOW.
 3. The noted pattern (N, N + 1...) is used continuously during I_{DD} measurement for I_{DD4W}.

Table 90: I_{DD} Specification Parameters and Operating Conditions

Notes 1–3 apply to all parameters and conditions

Parameter/Condition	Symbol	Power Supply	Notes
Operating one bank active-precharge current (SDRAM): $t_{CK} = t_{CKmin}$; $t_{RC} = t_{RCmin}$; CKE is HIGH; CS# is HIGH between valid commands; CA bus inputs are switching; Data bus inputs are stable	I _{DD01}	V _{DD1}	
	I _{DD02}	V _{DD2}	
	I _{DD0in}	V _{DDCA} , V _{DDQ}	4
Idle power-down standby current: $t_{CK} = t_{CKmin}$; CKE is LOW; CS# is HIGH; All banks are idle; CA bus inputs are switching; Data bus inputs are stable	I _{DD2P1}	V _{DD1}	
	I _{DD2P2}	V _{DD2}	
	I _{DD2P,in}	V _{DDCA} , V _{DDQ}	4



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Electrical Specifications – I_{DD} Specifications and Conditions

Table 90: I_{DD} Specification Parameters and Operating Conditions (Continued)

Notes 1–3 apply to all parameters and conditions

Parameter/Condition	Symbol	Power Supply	Notes
Idle power-down standby current with clock stop: CK = LOW, CK# = HIGH; CKE is LOW; CS# is HIGH; All banks are idle; CA bus inputs are stable; Data bus inputs are stable	I _{DD2PS1}	V _{DD1}	
	I _{DD2PS2}	V _{DD2}	
	I _{DD2PS,in}	V _{DDCA} , V _{DDQ}	4
Idle non-power-down standby current: ^t CK = ^t CKmin; CKE is HIGH; CS# is HIGH; All banks are idle; CA bus inputs are switching; Data bus inputs are stable	I _{DD2N1}	V _{DD1}	
	I _{DD2N2}	V _{DD2}	
	I _{DD2N,in}	V _{DDCA} , V _{DDQ}	4
Idle non-power-down standby current with clock stopped: CK = LOW; CK# = HIGH; CKE is HIGH; CS# is HIGH; All banks are idle; CA bus inputs are stable; Data bus inputs are stable	I _{DD2NS1}	V _{DD1}	
	I _{DD2NS2}	V _{DD2}	
	I _{DD2NS,in}	V _{DDCA} , V _{DDQ}	4
Active power-down standby current: ^t CK = ^t CKmin; CKE is LOW; CS# is HIGH; One bank is active; CA bus inputs are switching; Data bus inputs are stable	I _{DD3P1}	V _{DD1}	
	I _{DD3P2}	V _{DD2}	
	I _{DD3P,in}	V _{DDCA} , V _{DDQ}	4
Active power-down standby current with clock stop: CK = LOW, CK# = HIGH; CKE is LOW; CS# is HIGH; One bank is active; CA bus inputs are stable; Data bus inputs are stable	I _{DD3PS1}	V _{DD1}	
	I _{DD3PS2}	V _{DD2}	
	I _{DD3PS,in}	V _{DDCA} , V _{DDQ}	4
Active non-power-down standby current: ^t CK = ^t CKmin; CKE is HIGH; CS# is HIGH; One bank is active; CA bus inputs are switching; Data bus inputs are stable	I _{DD3N1}	V _{DD1}	
	I _{DD3N2}	V _{DD2}	
	I _{DD3N,in}	V _{DDCA} , V _{DDQ}	4
Active non-power-down standby current with clock stopped: CK = LOW, CK# = HIGH; CKE is HIGH; CS# is HIGH; One bank is active; CA bus inputs are stable; Data bus inputs are stable	I _{DD3NS1}	V _{DD1}	
	I _{DD3NS2}	V _{DD2}	
	I _{DD3NS,in}	V _{DDCA} , V _{DDQ}	4
Operating burst READ current: ^t CK = ^t CKmin; CS# is HIGH between valid commands; One bank is active; BL = 4; RL = RL (MIN); CA bus inputs are switching; 50% data change each burst transfer	I _{DD4R1}	V _{DD1}	
	I _{DD4R2}	V _{DD2}	
	I _{DD4R,in}	V _{DDCA}	
	I _{DD4RQ}	V _{DDQ}	5
Operating burst WRITE current: ^t CK = ^t CKmin; CS# is HIGH between valid commands; One bank is active; BL = 4; WL = WLmin; CA bus inputs are switching; 50% data change each burst transfer	I _{DD4W1}	V _{DD1}	
	I _{DD4W2}	V _{DD2}	
	I _{DD4W,in}	V _{DDCA} , V _{DDQ}	4
All-bank REFRESH burst current: ^t CK = ^t CKmin; CKE is HIGH between valid commands; ^t RC = ^t RFCabmin; Burst refresh; CA bus inputs are switching; Data bus inputs are stable	I _{DD51}	V _{DD1}	
	I _{DD52}	V _{DD2}	
	I _{DD5IN}	V _{DDCA} , V _{DDQ}	4
All-bank REFRESH average current: ^t CK = ^t CKmin; CKE is HIGH between valid commands; ^t RC = ^t REFI; CA bus inputs are switching; Data bus inputs are stable	I _{DD5AB1}	V _{DD1}	
	I _{DD5AB2}	V _{DD2}	
	I _{DD5AB,in}	V _{DDCA} , V _{DDQ}	4
Per-bank REFRESH average current: ^t CK = ^t CKmin; CKE is HIGH between valid commands; ^t RC = ^t REFI/8; CA bus inputs are switching; Data bus inputs are stable	I _{DD5PB1}	V _{DD1}	6
	I _{DD5PB2}	V _{DD2}	6
	I _{DD5PB,in}	V _{DDCA} , V _{DDQ}	4, 6



121-Ball NAND Flash with LPDDR2 MCP AC and DC Operating Conditions

Table 90: I_{DD} Specification Parameters and Operating Conditions (Continued)

Notes 1–3 apply to all parameters and conditions

Parameter/Condition	Symbol	Power Supply	Notes
Self refresh current (–25°C to +85°C): CK = LOW, CK# = HIGH; CKE is LOW; CA bus inputs are stable; Data bus inputs are stable; Maximum 1x self refresh rate	I _{DD61}	V _{DD1}	7
	I _{DD62}	V _{DD2}	7
	I _{DD6IN}	V _{DDCA} , V _{DDQ}	4, 7
Self refresh current (+85°C to +105°C): CK = LOW, CK# = HIGH; CKE is LOW; CA bus inputs are stable; Data bus inputs are stable	I _{DD6ET1}	V _{DD1}	7, 8
	I _{DD6ET2}	V _{DD2}	7, 8
	I _{DD6ET,in}	V _{DDCA} , V _{DDQ}	4, 7, 8
Deep power-down current: CK = LOW, CK# = HIGH; CKE is LOW; CA bus inputs are stable; Data bus inputs are stable	I _{DD81}	V _{DD1}	8
	I _{DD82}	V _{DD2}	8
	I _{DD8IN}	V _{DDCA} , V _{DDQ}	4, 8

- Notes:
1. I_{DD} values are the maximum of the distribution of the arithmetic mean.
 2. I_{DD} current specifications are tested after the device is properly initialized.
 3. The 1x self refresh rate is the rate at which the device is refreshed internally during self refresh, before going into the extended temperature range.
 4. Measured currents are the sum of V_{DDQ} and V_{DDCA}.
 5. Guaranteed by design with output reference load and R_{ON} = 40 ohm.
 6. Per-bank REFRESH is only applicable for LPDDR2-S4 device densities 1Gb or higher.
 7. This is the general definition that applies to full-array self refresh.
 8. I_{DD6ET} and I_{DD8} are typical values, are sampled only, and are not tested.

AC and DC Operating Conditions

Operation or timing that is not specified is illegal. To ensure proper operation, the device must be initialized properly.

Table 91: Recommended DC Operating Conditions

Symbol	LPDDR2-S4B			Power Supply	Unit
	Min	Typ	Max		
V _{DD1} ¹	1.70	1.80	1.95	Core power 1	V
V _{DD2}	1.14	1.20	1.30	Core power 2	V
V _{DDCA}	1.14	1.20	1.30	Input buffer power	V
V _{DDQ}	1.14	1.20	1.30	I/O buffer power	V

Note: 1. V_{DD1} uses significantly less power than V_{DD2}.



121-Ball NAND Flash with LPDDR2 MCP AC and DC Operating Conditions

Table 92: Input Leakage Current

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Input leakage current: For CA, CKE, CS#, CK, CK#; Any input $0V \leq V_{IN} \leq V_{DDCA}$; (All other pins not under test = 0V)	I_L	-2	2	μA	1
V_{REF} supply leakage current: $V_{REFDQ} = V_{DDQ}/2$, or $V_{REFCA} = V_{DDCA}/2$; (All other pins not under test = 0V)	I_{VREF}	-1	1	μA	2

- Notes:
1. Although DM is for input only, the DM leakage must match the DQ and DQS/DQS# output leakage specification.
 2. The minimum limit requirement is for testing purposes. The leakage current on V_{REFCA} and V_{REFDQ} pins should be minimal.

Table 93: Operating Temperature Range

Parameter/Condition	Symbol	Min	Max	Unit
WT temperature range	T_{CASE}^1	-25	+85	$^{\circ}C$
AT temperature range		-40	+105	$^{\circ}C$

- Notes:
1. Operating temperature is the case surface temperature at the center of the top side of the device. For measurement conditions, refer to the JESD51-2 standard.
 2. Some applications require operation in the maximum case temperature range, between 85°C and 105°C. For some LPDDR2 devices, derating may be necessary to operate in this range (see the MR4 Device Temperature (MA[7:0] = 04h) table).
 3. Either the device operating temperature or the temperature sensor can be used to set an appropriate refresh rate, determine the need for AC timing derating, and/or monitor the operating temperature (see Temperature Sensor (page 158)). When using the temperature sensor, the actual device case temperature may be higher than the T_{CASE} rating that applies for the operating temperature range. For example, T_{CASE} could be above 85°C when the temperature sensor indicates a temperature of less than 85°C.



121-Ball NAND Flash with LPDDR2 MCP

AC and DC Logic Input Measurement Levels for Single-Ended Signals

AC and DC Logic Input Measurement Levels for Single-Ended Signals

Table 94: Single-Ended AC and DC Input Levels for CA and CS# Inputs

Symbol	Parameter	LPDDR2-1066 to LPDDR2-466		LPDDR2-400 to LPDDR2-200		Unit	Notes
		Min	Max	Min	Max		
$V_{IHCA(AC)}$	AC input logic HIGH	$V_{REF} + 0.220$	Note 2	$V_{REF} + 0.300$	Note 2	V	1, 2
$V_{ILCA(AC)}$	AC input logic LOW	Note 2	$V_{REF} - 0.220$	Note 2	$V_{REF} - 0.300$	V	1, 2
$V_{IHCA(DC)}$	DC input logic HIGH	$V_{REF} + 0.130$	V_{DDCA}	$V_{REF} + 0.200$	V_{DDCA}	V	1
$V_{ILCA(DC)}$	DC input logic LOW	V_{SSCA}	$V_{REF} - 0.130$	V_{SSCA}	$V_{REF} - 0.200$	V	1
$V_{REFCA(DC)}$	Reference voltage for CA and CS# inputs	$0.49 \times V_{DDCA}$	$0.51 \times V_{DDCA}$	$0.49 \times V_{DDCA}$	$0.51 \times V_{DDCA}$	V	3, 4

- Notes:
1. For CA and CS# input-only pins. $V_{REF} = V_{REFCA(DC)}$.
 2. See Figure 141 (page 201).
 3. The AC peak noise on V_{REFCA} could prevent V_{REFCA} from deviating more than $\pm 1\% V_{DDCA}$ from $V_{REFCA(DC)}$ (for reference, approximately $\pm 12mV$).
 4. For reference, approximately $V_{DDCA}/2 \pm 12mV$.

Table 95: Single-Ended AC and DC Input Levels for CKE

Symbol	Parameter	Min	Max	Unit	Notes
V_{IHCKE}	CKE input HIGH level	$0.8 \times V_{DDCA}$	Note 1	V	1
V_{ILCKE}	CKE input LOW level	Note 1	$0.2 \times V_{DDCA}$	V	1

- Note:
1. See Figure 141 (page 201).

Table 96: Single-Ended AC and DC Input Levels for DQ and DM

Symbol	Parameter	LPDDR2-1066 to LPDDR2-466		LPDDR2-400 to LPDDR2-200		Unit	Notes
		Min	Max	Min	Max		
$V_{IHDQ(AC)}$	AC input logic HIGH	$V_{REF} + 0.220$	Note 2	$V_{REF} + 0.300$	Note 2	V	1, 2
$V_{ILDQ(AC)}$	AC input logic LOW	Note 2	$V_{REF} - 0.220$	Note 2	$V_{REF} - 0.300$	V	1, 2
$V_{IHDQ(DC)}$	DC input logic HIGH	$V_{REF} + 0.130$	V_{DDQ}	$V_{REF} + 0.200$	V_{DDQ}	V	1
$V_{ILDQ(DC)}$	DC input logic LOW	V_{SSQ}	$V_{REF} - 0.130$	V_{SSQ}	$V_{REF} - 0.200$	V	1
$V_{REFDQ(DC)}$	Reference voltage for DQ and DM inputs	$0.49 \times V_{DDQ}$	$0.51 \times V_{DDQ}$	$0.49 \times V_{DDQ}$	$0.51 \times V_{DDQ}$	V	3, 4

- Notes:
1. For DQ input-only pins. $V_{REF} = V_{REFDQ(DC)}$.
 2. See Figure 141 (page 201).
 3. The AC peak noise on V_{REFDQ} could prevent V_{REFDQ} from deviating more than $\pm 1\% V_{DDQ}$ from $V_{REFDQ(DC)}$ (for reference, approximately $\pm 12mV$).
 4. For reference, approximately $V_{DDQ}/2 \pm 12mV$.



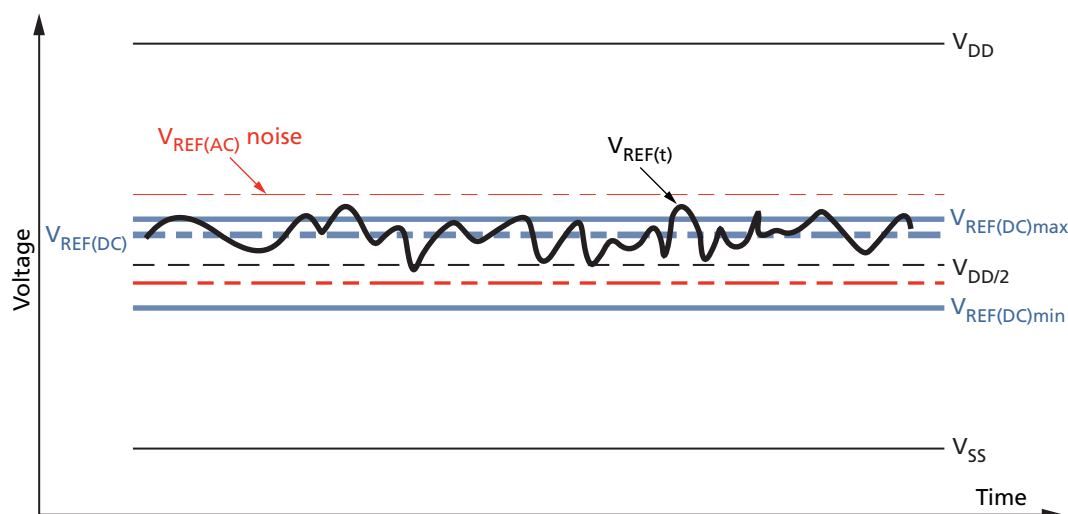
121-Ball NAND Flash with LPDDR2 MCP

AC and DC Logic Input Measurement Levels for Single-Ended Signals

V_{REF} Tolerances

The DC tolerance limits and AC noise limits for the reference voltages V_{REFCA} and V_{REFDQ} are illustrated below. This figure shows a valid reference voltage $V_{REF}(t)$ as a function of time. V_{DD} is used in place of V_{DDCA} for V_{REFCA} , and V_{DDQ} for V_{REFDQ} . $V_{REF(DC)}$ is the linear average of $V_{REF}(t)$ over a very long period of time (for example, 1 second) and is specified as a fraction of the linear average of V_{DDQ} or V_{DDCA} , also over a very long period of time (for example, 1 second). This average must meet the MIN/MAX requirements in Table 94 (page 190). Additionally, $V_{REF}(t)$ can temporarily deviate from $V_{REF(DC)}$ by no more than $\pm 1\% V_{DD}$. $V_{REF}(t)$ cannot track noise on V_{DDQ} or V_{DDCA} if doing so would force V_{REF} outside these specifications.

Figure 132: V_{REF} DC Tolerance and V_{REF} AC Noise Limits



The voltage levels for setup and hold time measurements $V_{IH(AC)}$, $V_{IH(DC)}$, $V_{IL(AC)}$, and $V_{IL(DC)}$ are dependent on V_{REF} .

V_{REF} DC variations affect the absolute voltage a signal must reach to achieve a valid HIGH or LOW, as well as the time from which setup and hold times are measured. When V_{REF} is outside the specified levels, devices will function correctly with appropriate timing deratings as long as:

- V_{REF} is maintained between $0.44 \times V_{DDQ}$ (or V_{DDCA}) and $0.56 \times V_{DDQ}$ (or V_{DDCA}), and
- the controller achieves the required single-ended AC and DC input levels from instantaneous V_{REF} (see Table 94 (page 190)).

System timing and voltage budgets must account for V_{REF} deviations outside this range.

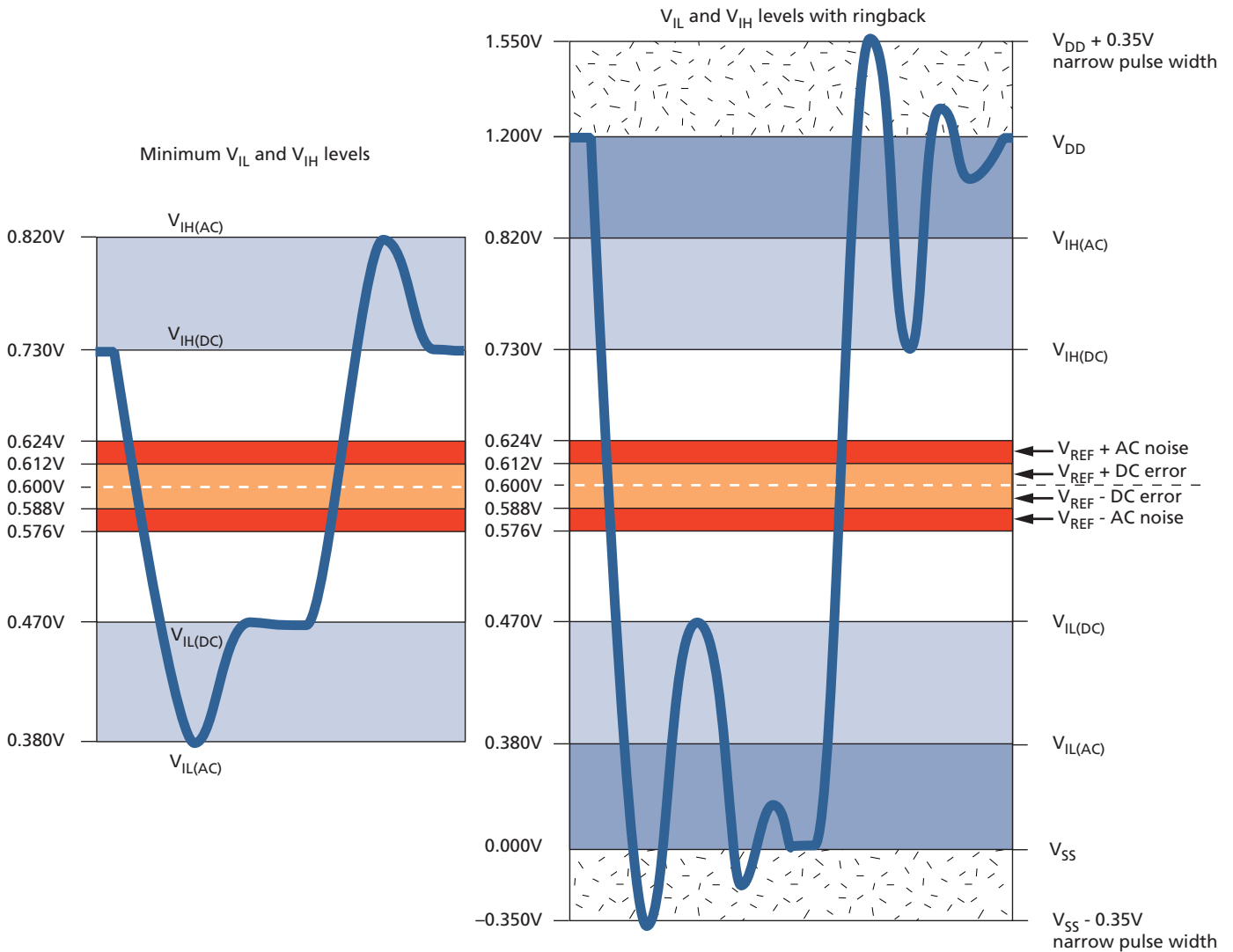
The setup/hold specification and derating values must include time and voltage associated with V_{REF} AC noise. Timing and voltage effects due to AC noise on V_{REF} up to the specified limit ($\pm 1\% V_{DD}$) are included in LPDDR2 timings and their associated deratings.



121-Ball NAND Flash with LPDDR2 MCP AC and DC Logic Input Measurement Levels for Single-Ended Signals

Input Signal

Figure 133: LPDDR2-466 to LPDDR2-1066 Input Signal



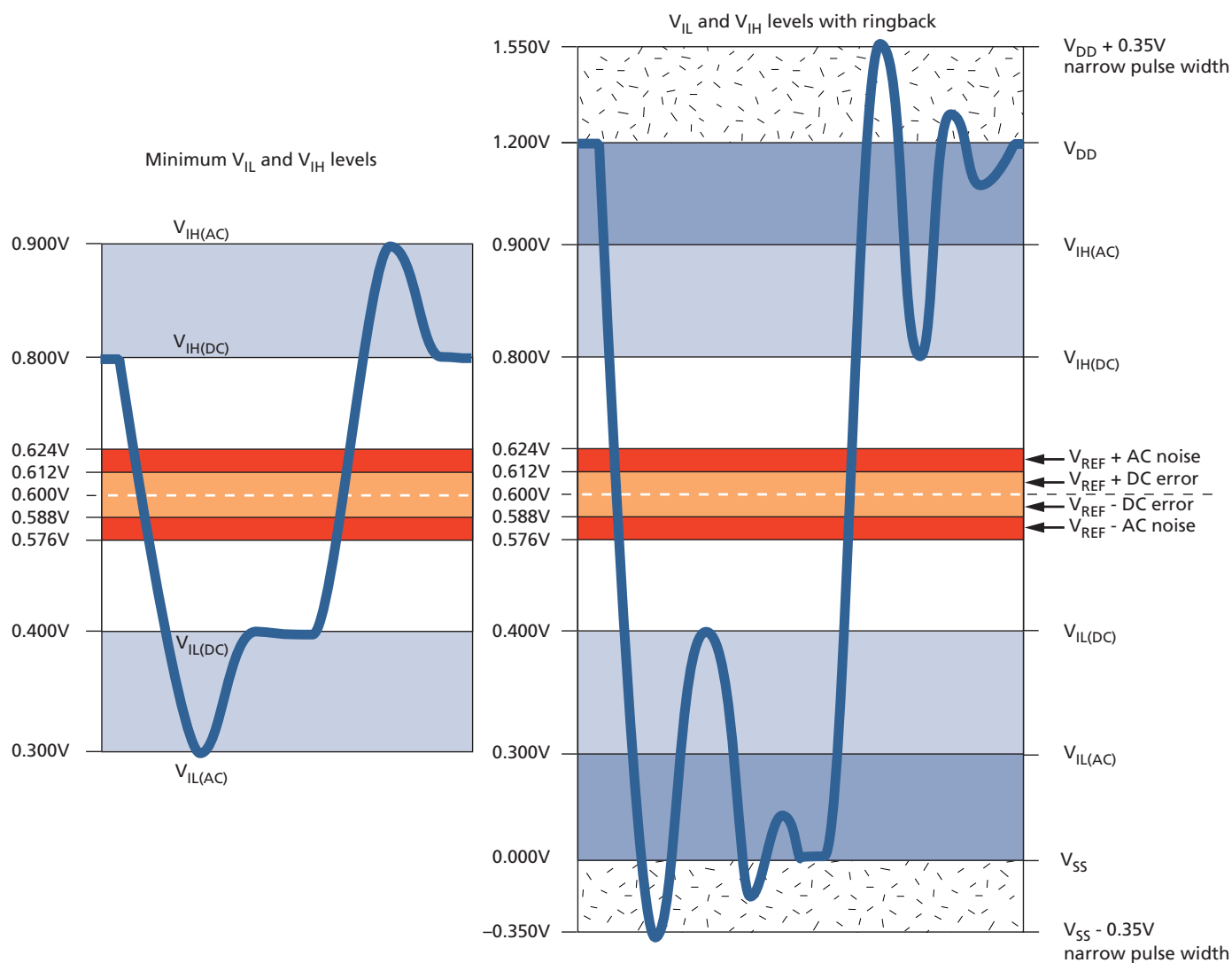
- Notes:
1. Numbers reflect typical values.
 2. For CA[9:0], CK, CK#, and CS# V_{DD} stands for V_{DDCA} . For DQ, DM, DQS, and DQS#, V_{DD} stands for V_{DDQ} .
 3. For CA[9:0], CK, CK#, and CS# V_{SS} stands for V_{SSCA} . For DQ, DM, DQS, and DQS#, V_{SS} stands for V_{SSQ} .



121-Ball NAND Flash with LPDDR2 MCP

AC and DC Logic Input Measurement Levels for Single-Ended Signals

Figure 134: LPDDR2-200 to LPDDR2-400 Input Signal



- Notes:
1. Numbers reflect typical values.
 2. For CA[9:0], CK, CK#, and CS# V_{DD} stands for V_{DDCA} . For DQ, DM, DQS, and DQS#, V_{DD} stands for V_{DDQ} .
 3. For CA[9:0], CK, CK#, and CS# V_{SS} stands for V_{SSCA} . For DQ, DM, DQS, and DQS#, V_{SS} stands for V_{SSQ} .



121-Ball NAND Flash with LPDDR2 MCP

AC and DC Logic Input Measurement Levels for Differential Signals

AC and DC Logic Input Measurement Levels for Differential Signals

Figure 135: Differential AC Swing Time and t_{DVAC}

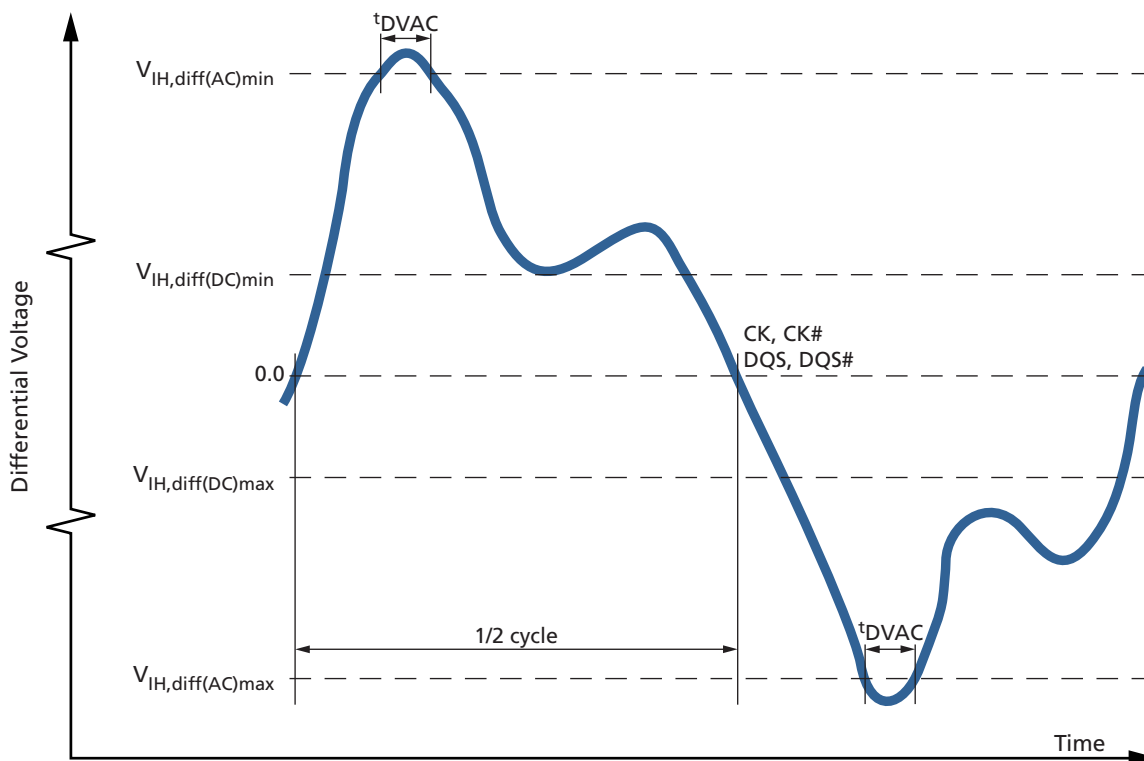


Table 97: Differential AC and DC Input Levels

For CK and CK#, $V_{REF} = V_{REFCA(DC)}$; For DQS and DQS# $V_{REF} = V_{REFDQ(DC)}$

Symbol	Parameter	LPDDR2-1066 to LPDDR2-466		LPDDR2-400 to LPDDR2-200		Unit	Notes
		Min	Max	Min	Max		
$V_{IH,diff(AC)}$	Differential input HIGH AC	$2 \times (V_{IH(AC)} - V_{REF})$	Note 1	$2 \times (V_{IH(AC)} - V_{REF})$	Note 1	V	2
$V_{IL,diff(AC)}$	Differential input LOW AC	Note 1	$2 \times (V_{REF} - V_{IL(AC)})$	Note 1	$2 \times (V_{REF} - V_{IL(AC)})$	V	2
$V_{IH,diff(DC)}$	Differential input HIGH	$2 \times (V_{IH(DC)} - V_{REF})$	Note 1	$2 \times (V_{IH(DC)} - V_{REF})$	Note 1	V	3
$V_{IL,diff(DC)}$	Differential input LOW	Note 1	$2 \times (V_{REF} - V_{IL(DC)})$	Note 1	$2 \times (V_{REF} - V_{IL(DC)})$	V	3

Notes: 1. These values are not defined, however the single-ended signals CK, CK#, DQS, and DQS# must be within the respective limits ($V_{IH(DC)max}$, $V_{IL(DC)min}$) for single-ended signals and must comply with the specified limitations for overshoot and undershoot (see Figure 141 (page 201)).



121-Ball NAND Flash with LPDDR2 MCP AC and DC Logic Input Measurement Levels for Differential Signals

- For CK and CK#, use $V_{IH}/V_{IL(AC)}$ of CA and V_{REFCA} ; for DQS and DQS#, use $V_{IH}/V_{IL(AC)}$ of DQ and V_{REFDQ} . If a reduced AC HIGH or AC LOW is used for a signal group, the reduced voltage level also applies.
- Used to define a differential signal slew rate.

Table 98: CK/CK# and DQS/DQS# Time Requirements Before Ringback (t_{DVAC})

Slew Rate (V/ns)	t_{DVAC} (ps) at $V_{IH}/V_{ILdiff(AC)} = 440mV$	t_{DVAC} (ps) at $V_{IH}/V_{ILdiff(AC)} = 600mV$
	Min	Min
> 4.0	175	75
4.0	170	57
3.0	167	50
2.0	163	38
1.8	162	34
1.6	161	29
1.4	159	22
1.2	155	13
1.0	150	0
< 1.0	150	0

Single-Ended Requirements for Differential Signals

Each individual component of a differential signal (CK, CK#, DQS, and DQS#) must also comply with certain requirements for single-ended signals.

CK and CK# must meet $V_{SEH(AC)min}/V_{SEL(AC)max}$ in every half cycle. DQS, DQS# must meet $V_{SEH(AC)min}/V_{SEL(AC)max}$ in every half cycle preceding and following a valid transition.

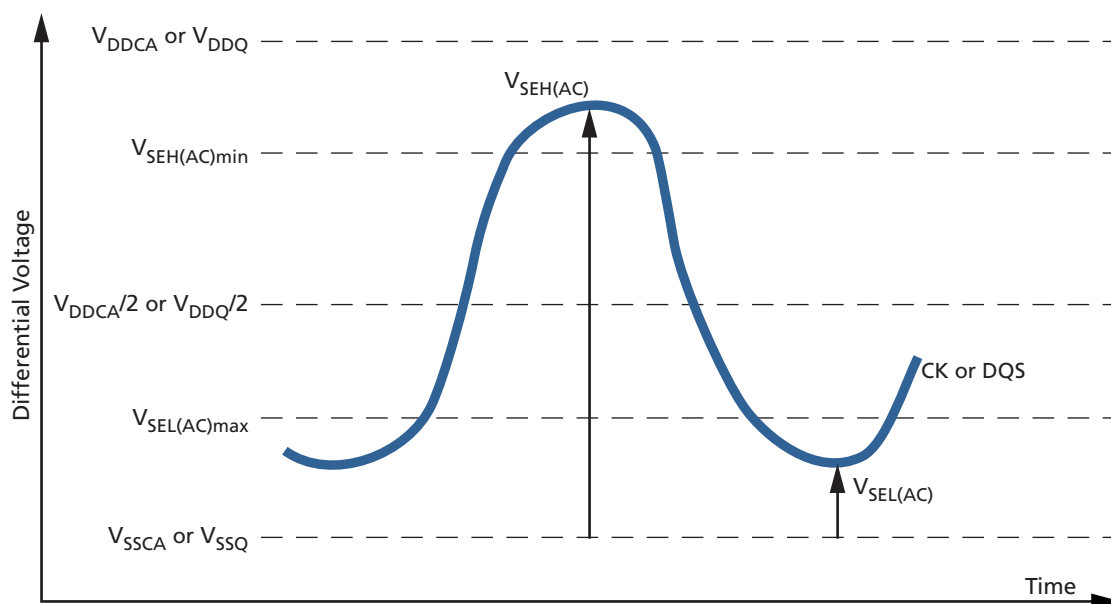
The applicable AC levels for CA and DQ differ by speed bin.



121-Ball NAND Flash with LPDDR2 MCP

AC and DC Logic Input Measurement Levels for Differential Signals

Figure 136: Single-Ended Requirements for Differential Signals



Note that while CA and DQ signal requirements are referenced to V_{REF} , the single-ended components of differential signals also have a requirement with respect to $V_{DDQ}/2$ for DQS, and $V_{DDCA}/2$ for CK.

The transition of single-ended signals through the AC levels is used to measure setup time. For single-ended components of differential signals, the requirement to reach $V_{SEL(AC)max}$ or $V_{SEH(AC)min}$ has no bearing on timing. This requirement does, however, add a restriction on the common mode characteristics of these signals (see Table 94 (page 190) for CK/CK# single-ended requirements, and Table 96 (page 190) for DQ and DQM single-ended requirements).

Table 99: Single-Ended Levels for CK, CK#, DQS, DQS#

Symbol	Parameter	LPDDR2-1066 to LPDDR2-466		LPDDR2-400 to LPDDR2-200		Unit	Notes
		Min	Max	Min	Max		
$V_{SEH(AC)}$	Single-ended HIGH level for strobes	$(V_{DDQ}/2) + 0.220$	Note 1	$(V_{DDQ}/2) + 0.300$	Note 1	V	2, 3
	Single-ended HIGH level for CK, CK#	$(V_{DDCA}/2) + 0.220$	Note 1	$(V_{DDCA}/2) + 0.300$	Note 1	V	2, 3
$V_{SEL(AC)}$	Single-ended LOW level for strobes	Note 1	$(V_{DDQ}/2) - 0.220$	Note 1	$(V_{DDQ}/2) + 0.300$	V	2, 3
	Single-ended LOW level for CK, CK#	Note 1	$(V_{DDCA}/2) - 0.220$	Note 1	$(V_{DDCA}/2) + 0.300$	V	2, 3

Notes: 1. These values are not defined, however, the single-ended signals CK, CK#, DQS0, DQS#0, DQS1, DQS#1, DQS2, DQS#2, DQS3, DQS#3 must be within the respective limits $(V_{IH(DC)max}/V_{IL(DC)min})$ for single-ended signals, and must comply with the specified limitations for overshoot and undershoot (see Figure 141 (page 201)).



121-Ball NAND Flash with LPDDR2 MCP AC and DC Logic Input Measurement Levels for Differential Signals

- For CK and CK#, use $V_{SEH}/V_{SEL(AC)}$ of CA; for strobes (DQS[3:0] and DQS#[3:0]), use $V_{IH}/V_{IL(AC)}$ of DQ.
- $V_{IH(AC)}$ and $V_{IL(AC)}$ for DQ are based on V_{REFDQ} ; $V_{SEH(AC)}$ and $V_{SEL(AC)}$ for CA are based on V_{REFCA} . If a reduced AC HIGH or AC LOW is used for a signal group, the reduced level applies.

Differential Input Crosspoint Voltage

To ensure tight setup and hold times as well as output skew parameters with respect to clock and strobe, each crosspoint voltage of differential input signals (CK, CK#, DQS, and DQS#) must meet the specifications in Table 99 (page 196). The differential input crosspoint voltage (V_{IX}) is measured from the actual crosspoint of the true signal and its complement to the midlevel between V_{DD} and V_{SS} .

Figure 137: V_{IX} Definition

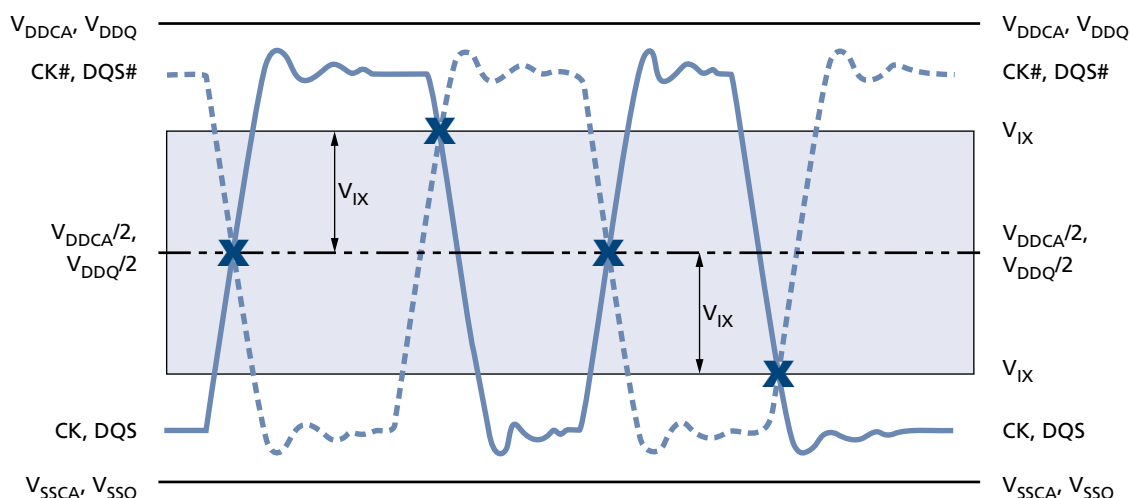


Table 100: Crosspoint Voltage for Differential Input Signals (CK, CK#, DQS, DQS#)

Symbol	Parameter	LPDDR2-1066 to LPDDR2-200		Unit	Notes
		Min	Max		
$V_{IXCA(AC)}$	Differential input crosspoint voltage relative to $V_{DDCA}/2$ for CK and CK#	-120	120	mV	1, 2
$V_{IXDQ(AC)}$	Differential input crosspoint voltage relative to $V_{DDQ}/2$ for DQS and DQ#	-120	120	mV	1, 2

- Notes:
- The typical value of $V_{IX(AC)}$ is expected to be about $0.5 \times V_{DD}$ of the transmitting device, and it is expected to track variations in V_{DD} . $V_{IX(AC)}$ indicates the voltage at which differential input signals must cross.
 - For CK and CK#, $V_{REF} = V_{REFCA(DC)}$. For DQS and DQS#, $V_{REF} = V_{REFDQ(DC)}$.



121-Ball NAND Flash with LPDDR2 MCP Output Characteristics and Operating Conditions

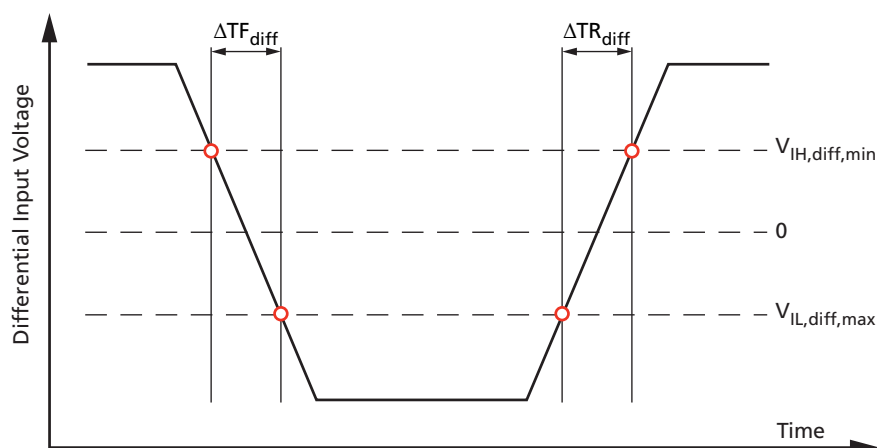
Input Slew Rate

Table 101: Differential Input Slew Rate Definition

Description	Measured ¹		Defined by
	From	To	
Differential input slew rate for rising edge (CK/CK# and DQS/DQS#)	$V_{IL,diff,max}$	$V_{IH,diff,min}$	$[V_{IH,diff,min} - V_{IL,diff,max}] / \Delta TR_{diff}$
Differential input slew rate for falling edge (CK/CK# and DQS/DQS#)	$V_{IH,diff,min}$	$V_{IL,diff,max}$	$[V_{IH,diff,min} - V_{IL,diff,max}] / \Delta TF_{diff}$

Note: 1. The differential signals (CK/CK# and DQS/DQS#) must be linear between these thresholds.

Figure 138: Differential Input Slew Rate Definition for CK, CK#, DQS, and DQS#



Output Characteristics and Operating Conditions

Table 102: Single-Ended AC and DC Output Levels

Symbol	Parameter		Value	Unit	Notes
$V_{OH(AC)}$	AC output HIGH measurement level (for output slew rate)		$V_{REF} + 0.12$	V	
$V_{OL(AC)}$	AC output LOW measurement level (for output slew rate)		$V_{REF} - 0.12$	V	
$V_{OH(DC)}$	DC output HIGH measurement level (for I-V curve linearity)		$0.9 \times V_{DDQ}$	V	1
$V_{OL(DC)}$	DC output LOW measurement level (for I-V curve linearity)		$0.1 \times V_{DDQ}$	V	2
I_{OZ}	Output leakage current (DQ, DM, DQS, DQS#); DQ, DQS, DQS# are disabled; $0V \leq V_{OUT} \leq V_{DDQ}$	MIN	-5	μA	
		MAX	+5	μA	
MMpupd	Delta output impedance between pull-up and pull-down for DQ/DM	MIN	-15	%	
		MAX	+15	%	

Notes: 1. $I_{OH} = -0.1mA$.
2. $I_{OL} = 0.1mA$.



121-Ball NAND Flash with LPDDR2 MCP Output Characteristics and Operating Conditions

Table 103: Differential AC and DC Output Levels

Symbol	Parameter	Value	Unit
$V_{OHdiff(AC)}$	AC differential output HIGH measurement level (for output SR)	$+ 0.2 \times V_{DDQ}$	V
$V_{OLdiff(AC)}$	AC differential output LOW measurement level (for output SR)	$- 0.2 \times V_{DDQ}$	V

Single-Ended Output Slew Rate

With the reference load for timing measurements, the output slew rate for falling and rising edges is defined and measured between $V_{OL(AC)}$ and $V_{OH(AC)}$ for single-ended signals.

Table 104: Single-Ended Output Slew Rate Definition

Description	Measured		Defined by
	From	To	
Single-ended output slew rate for rising edge	$V_{OL(AC)}$	$V_{OH(AC)}$	$[V_{OH(AC)} - V_{OL(AC)}] / \Delta TR_{SE}$
Single-ended output slew rate for falling edge	$V_{OH(AC)}$	$V_{OL(AC)}$	$[V_{OH(AC)} - V_{OL(AC)}] / \Delta TF_{SE}$

Note: 1. Output slew rate is verified by design and characterization and may not be subject to production testing.

Figure 139: Single-Ended Output Slew Rate Definition

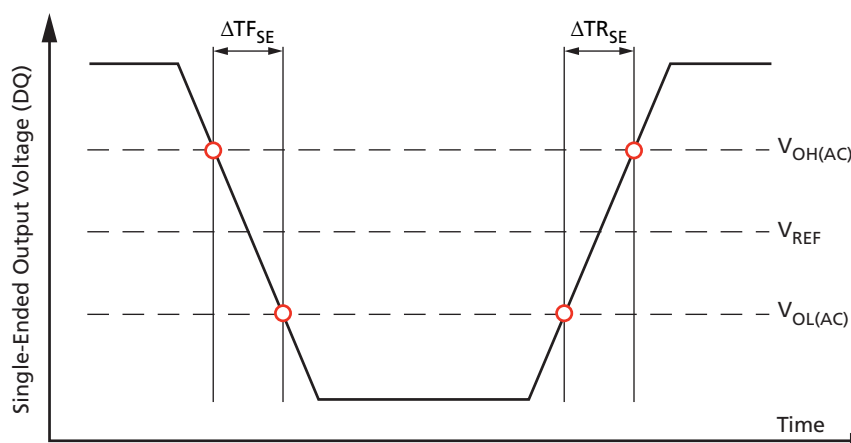


Table 105: Single-Ended Output Slew Rate

Notes 1–5 apply to all parameters conditions

Parameter	Symbol	Value		Unit
		Min	Max	
Single-ended output slew rate (output impedance = $40\Omega \pm 30\%$)	SRQ_{SE}	1.5	3.5	V/ns
Single-ended output slew rate (output impedance = $60\Omega \pm 30\%$)	SRQ_{SE}	1.0	2.5	V/ns
Output slew-rate-matching ratio (pull-up to pull-down)		0.7	1.4	–

Notes: 1. Definitions: SR = slew rate; Q = output (similar to DQ = data-in, data-out); SE = single-ended signals.



121-Ball NAND Flash with LPDDR2 MCP Output Characteristics and Operating Conditions

2. Measured with output reference load.
3. The ratio of pull-up to pull-down slew rate is specified for the same temperature and voltage over the entire temperature and voltage range. For a given output, the ratio represents the maximum difference between pull-up and pull-down drivers due to process variation.
4. The output slew rate for falling and rising edges is defined and measured between $V_{OL(AC)}$ and $V_{OH(AC)}$.
5. Slew rates are measured under typical simultaneous switching output (SSO) conditions, with one-half of DQ signals per data byte driving HIGH and one-half of DQ signals per data byte driving LOW.

Differential Output Slew Rate

With the reference load for timing measurements, the output slew rate for falling and rising edges is defined and measured between $V_{OL,diff(AC)}$ and $V_{OH,diff(AC)}$ for differential signals.

Table 106: Differential Output Slew Rate Definition

Description	Measured		Defined by
	From	To	
Differential output slew rate for rising edge	$V_{OL,diff(AC)}$	$V_{OH,diff(AC)}$	$[V_{OH,diff(AC)} - V_{OL,diff(AC)}] / \Delta TR_{diff}$
Differential output slew rate for falling edge	$V_{OH,diff(AC)}$	$V_{OL,diff(AC)}$	$[V_{OH,diff(AC)} - V_{OL,diff(AC)}] / \Delta TF_{diff}$

Note: 1. Output slew rate is verified by design and characterization and may not be subject to production testing.

Figure 140: Differential Output Slew Rate Definition

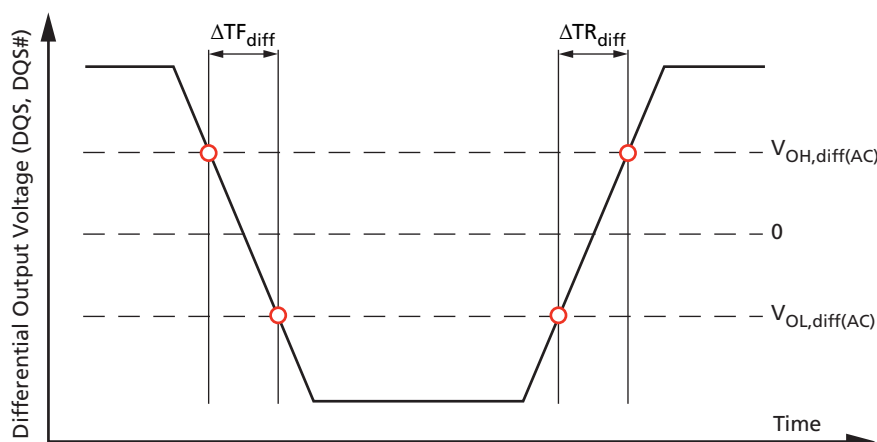


Table 107: Differential Output Slew Rate

Parameter	Symbol	Value		Unit
		Min	Max	
Differential output slew rate (output impedance = $40\Omega \pm 30\%$)	SRQ_{diff}	3.0	7.0	V/ns



121-Ball NAND Flash with LPDDR2 MCP Output Characteristics and Operating Conditions

Table 107: Differential Output Slew Rate (Continued)

Parameter	Symbol	Value		Unit
		Min	Max	
Differential output slew rate (output impedance = $60\Omega \pm 30\%$)	SRQ_{diff}	2.0	5.0	V/ns

- Notes:
1. Definitions: SR = slew rate; Q = output (similar to DQ = data-in, data-out); SE = single-ended signals.
 2. Measured with output reference load.
 3. The output slew rate for falling and rising edges is defined and measured between $V_{OL(AC)}$ and $V_{OH(AC)}$.
 4. Slew rates are measured under typical simultaneous switching output (SSO) conditions, with one-half of DQ signals per data byte driving HIGH and one-half of DQ signals per data byte driving LOW.

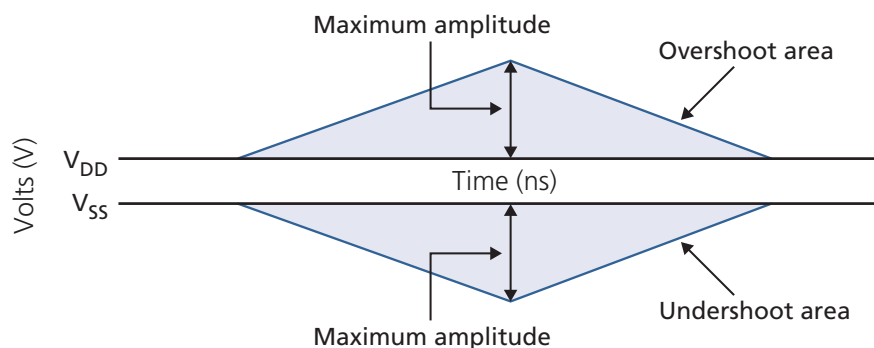
Table 108: AC Overshoot/Undershoot Specification

Applies for CA[9:0], CS#, CE, CK, CK#, DQ, DQS, DQS#, DM

Parameter	1066	933	800	667	533	400	333	Unit
Maximum peak amplitude provided for overshoot area	0.35	0.35	0.35	0.35	0.35	0.35	0.35	V
Maximum peak amplitude provided for undershoot area	0.35	0.35	0.35	0.35	0.35	0.35	0.35	V
Maximum area above V_{DD}^1	0.15	0.17	0.20	0.24	0.30	0.40	0.48	V/ns
Maximum area below V_{SS}^2	0.15	0.17	0.20	0.24	0.30	0.40	0.48	V/ns

- Notes:
1. V_{DD} stands for V_{DDCA} for CA[9:0], CK, CK#, CS#, and CE. V_{DD} stands for V_{DDQ} for DQ, DM, DQS, and DQS#.
 2. V_{SS} stands for V_{SSCA} for CA[9:0], CK, CK#, CS#, and CE. V_{SS} stands for V_{SSQ} for DQ, DM, DQS, and DQS#.

Figure 141: Overshoot and Undershoot Definition



- Notes:
1. V_{DD} stands for V_{DDCA} for CA[9:0], CK, CK#, CS#, and CE. V_{DD} stands for V_{DDQ} for DQ, DM, DQS, and DQS#.
 2. V_{SS} stands for V_{SSCA} for CA[9:0], CK, CK#, CS#, and CE. V_{SS} stands for V_{SSQ} for DQ, DM, DQS, and DQS#.

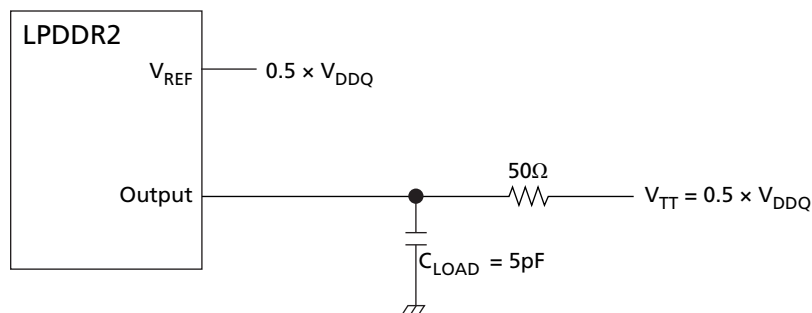


121-Ball NAND Flash with LPDDR2 MCP Output Driver Impedance

HSUL_12 Driver Output Timing Reference Load

The timing reference loads are not intended as a precise representation of any particular system environment or a depiction of the actual load presented by a production tester. System designers should use IBIS or other simulation tools to correlate the timing reference load to a system environment. Manufacturers correlate to their production test conditions, generally with one or more coaxial transmission lines terminated at the tester electronics.

Figure 142: HSUL_12 Driver Output Reference Load for Timing and Slew Rate



Note: 1. All output timing parameter values (t_{DQSCK} , t_{DQSQ} , t_{QHS} , t_{HZ} , t_{RPRE} etc.) are reported with respect to this reference load. This reference load is also used to report slew rate.

Output Driver Impedance

Output driver impedance is selected by a mode register during initialization. To achieve tighter tolerances, ZQ calibration is required. Output specifications refer to the default output drive unless specifically stated otherwise. The output driver impedance R_{ON} is defined by the value of the external reference resistor R_{ZQ} as follows:

$$R_{ONPU} = \frac{V_{DDQ} - V_{OUT}}{ABS(I_{OUT})}$$

When R_{ONPD} is turned off.

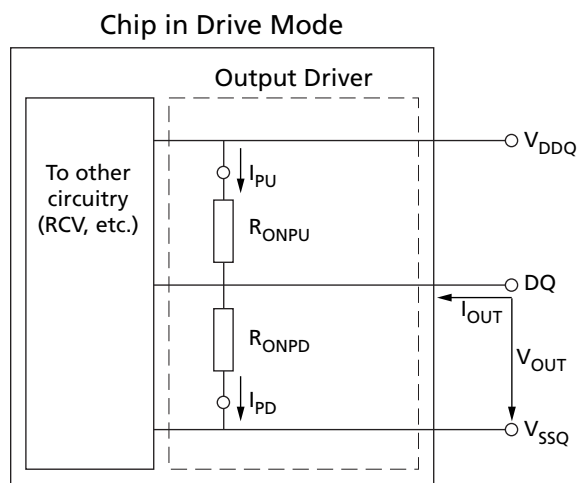
$$R_{ONPD} = \frac{V_{OUT}}{ABS(I_{OUT})}$$

When R_{ONPU} is turned off.



121-Ball NAND Flash with LPDDR2 MCP Output Driver Impedance

Figure 143: Output Driver



Output Driver Impedance Characteristics with ZQ Calibration

Output driver impedance is defined by the value of the external reference resistor R_{ZQ} . Typical R_{ZQ} is 240 ohms.

Table 109: Output Driver DC Electrical Characteristics with ZQ Calibration

Notes 1–4 apply to all parameters and conditions

R_{ONnom}	Resistor	V_{OUT}	Min	Typ	Max	Unit	Notes
34.3 Ω	R_{ON34PD}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/7$	
	R_{ON34PU}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/7$	
40.0 Ω	R_{ON40PD}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/6$	
	R_{ON40PU}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/6$	
48.0 Ω	R_{ON48PD}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/5$	
	R_{ON48PU}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/5$	
60.0 Ω	R_{ON60PD}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/4$	
	R_{ON60PU}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/4$	
80.0 Ω	R_{ON80PD}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/3$	
	R_{ON80PU}	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/3$	
120.0 Ω	$R_{ON120PD}$	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/2$	
	$R_{ON120PU}$	$0.5 \times V_{DDQ}$	0.85	1.00	1.15	$R_{ZQ}/2$	
Mismatch between pull-up and pull-down	MM_{PUPD}		-15.00		+15.00	%	5

- Notes:
1. Applies across entire operating temperature range after calibration.
 2. $R_{ZQ} = 240\Omega$.
 3. The tolerance limits are specified after calibration, with fixed voltage and temperature. For behavior of the tolerance limits if temperature or voltage changes after calibration.
 4. Pull-down and pull-up output driver impedances should be calibrated at $0.5 \times V_{DDQ}$.
 5. Measurement definition for mismatch between pull-up and pull-down, MM_{PUPD} : Measure R_{ONPU} and R_{ONPD} , both at $0.5 \times V_{DDQ}$:



121-Ball NAND Flash with LPDDR2 MCP Output Driver Impedance

$$MM_{PUPD} = \frac{R_{ONPU} - R_{ONPD}}{R_{ON,nom}} \times 100$$

For example, with $MM_{PUPD}(\text{MAX}) = 15\%$ and $R_{ONPD} = 0.85$, R_{ONPU} must be less than 1.0.

Output Driver Temperature and Voltage Sensitivity

If temperature and/or voltage change after calibration, the tolerance limits widen.

Table 110: Output Driver Sensitivity Definition

Resistor	V _{OUT}	Min	Max	Unit
R _{ONPD}	0.5 × V _{DDQ}	85 – (dR _{OND} T · ΔT) – (dR _{OND} V · ΔV)	115 – (dR _{OND} T · ΔT) – (dR _{OND} V · ΔV)	%
R _{ONPU}				

- Notes: 1. ΔT = T – T (at calibration). ΔV = V – V (at calibration).
 2. dR_{OND}T and dR_{OND}V are not subject to production testing; they are verified by design and characterization.

Table 111: Output Driver Temperature and Voltage Sensitivity

Symbol	Parameter	Min	Max	Unit
R _{OND} T	R _{ON} temperature sensitivity	0.00	0.75	%/°C
R _{OND} V	R _{ON} voltage sensitivity	0.00	0.20	%/mV

Output Impedance Characteristics Without ZQ Calibration

Output driver impedance is defined by design and characterization as the default setting.

Table 112: Output Driver DC Electrical Characteristics Without ZQ Calibration

R _{ON,nom}	Resistor	V _{OUT}	Min	Typ	Max	Unit
34.3Ω	R _{ON34PD}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /7
	R _{ON34PU}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /7
40.0Ω	R _{ON40PD}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /6
	R _{ON40PU}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /6
48.0Ω	R _{ON48PD}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /5
	R _{ON48PU}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /5
60.0Ω	R _{ON60PD}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /4
	R _{ON60PU}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /4
80.0Ω	R _{ON80PD}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /3
	R _{ON80PU}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /3
120.0Ω	R _{ON120PD}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /2
	R _{ON120PU}	0.5 × V _{DDQ}	0.70	1.00	1.30	R _{ZQ} /2

- Notes: 1. Applies across entire operating temperature range without calibration.
 2. R_{ZQ} = 240Ω.



121-Ball NAND Flash with LPDDR2 MCP Output Driver Impedance

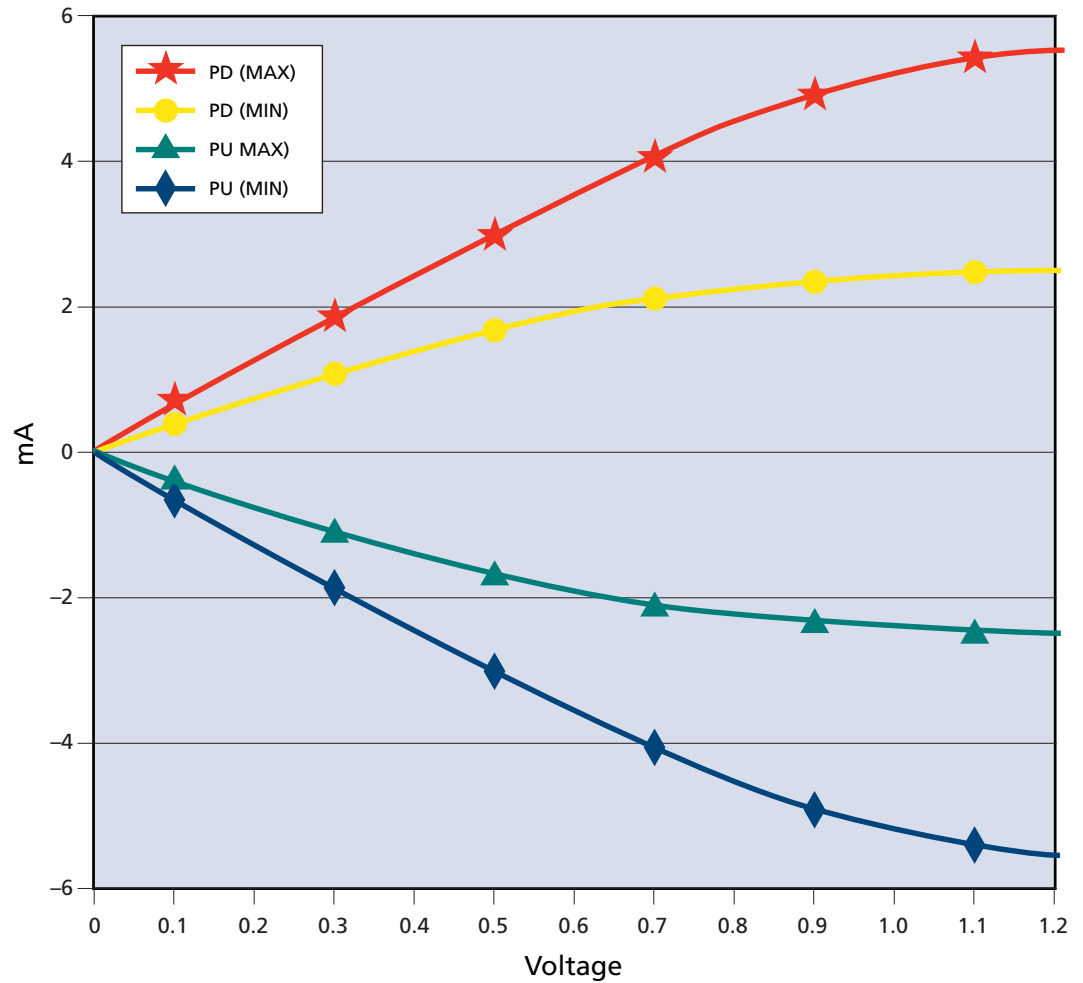
Table 113: I-V Curves

Voltage (V)	$R_{ON} = 240\Omega (R_{ZQ})$							
	Pull-Down				Pull-Up			
	Current (mA) / R_{ON} (ohms)				Current (mA) / R_{ON} (ohms)			
	Default Value after ZQRESET		With Calibration		Default Value after ZQRESET		With Calibration	
	Min (mA)	Max (mA)	Min (mA)	Max (mA)	Min (mA)	Max (mA)	Min (mA)	Max (mA)
0.00	0.00	0.00	0.00	0.00	0.00	0.00	0.00	0.00
0.05	0.19	0.32	0.21	0.26	-0.19	-0.32	-0.21	-0.26
0.10	0.38	0.64	0.40	0.53	-0.38	-0.64	-0.40	-0.53
0.15	0.56	0.94	0.60	0.78	-0.56	-0.94	-0.60	-0.78
0.20	0.74	1.26	0.79	1.04	-0.74	-1.26	-0.79	-1.04
0.25	0.92	1.57	0.98	1.29	-0.92	-1.57	-0.98	-1.29
0.30	1.08	1.86	1.17	1.53	-1.08	-1.86	-1.17	-1.53
0.35	1.25	2.17	1.35	1.79	-1.25	-2.17	-1.35	-1.79
0.40	1.40	2.46	1.52	2.03	-1.40	-2.46	-1.52	-2.03
0.45	1.54	2.74	1.69	2.26	-1.54	-2.74	-1.69	-2.26
0.50	1.68	3.02	1.86	2.49	-1.68	-3.02	-1.86	-2.49
0.55	1.81	3.30	2.02	2.72	-1.81	-3.30	-2.02	-2.72
0.60	1.92	3.57	2.17	2.94	-1.92	-3.57	-2.17	-2.94
0.65	2.02	3.83	2.32	3.15	-2.02	-3.83	-2.32	-3.15
0.70	2.11	4.08	2.46	3.36	-2.11	-4.08	-2.46	-3.36
0.75	2.19	4.31	2.58	3.55	-2.19	-4.31	-2.58	-3.55
0.80	2.25	4.54	2.70	3.74	-2.25	-4.54	-2.70	-3.74
0.85	2.30	4.74	2.81	3.91	-2.30	-4.74	-2.81	-3.91
0.90	2.34	4.92	2.89	4.05	-2.34	-4.92	-2.89	-4.05
0.95	2.37	5.08	2.97	4.23	-2.37	-5.08	-2.97	-4.23
1.00	2.41	5.20	3.04	4.33	-2.41	-5.20	-3.04	-4.33
1.05	2.43	5.31	3.09	4.44	-2.43	-5.31	-3.09	-4.44
1.10	2.46	5.41	3.14	4.52	-2.46	-5.41	-3.14	-4.52
1.15	2.48	5.48	3.19	4.59	-2.48	-5.48	-3.19	-4.59
1.20	2.50	5.55	3.23	4.65	-2.50	-5.55	-3.23	-4.65



121-Ball NAND Flash with LPDDR2 MCP Output Driver Impedance

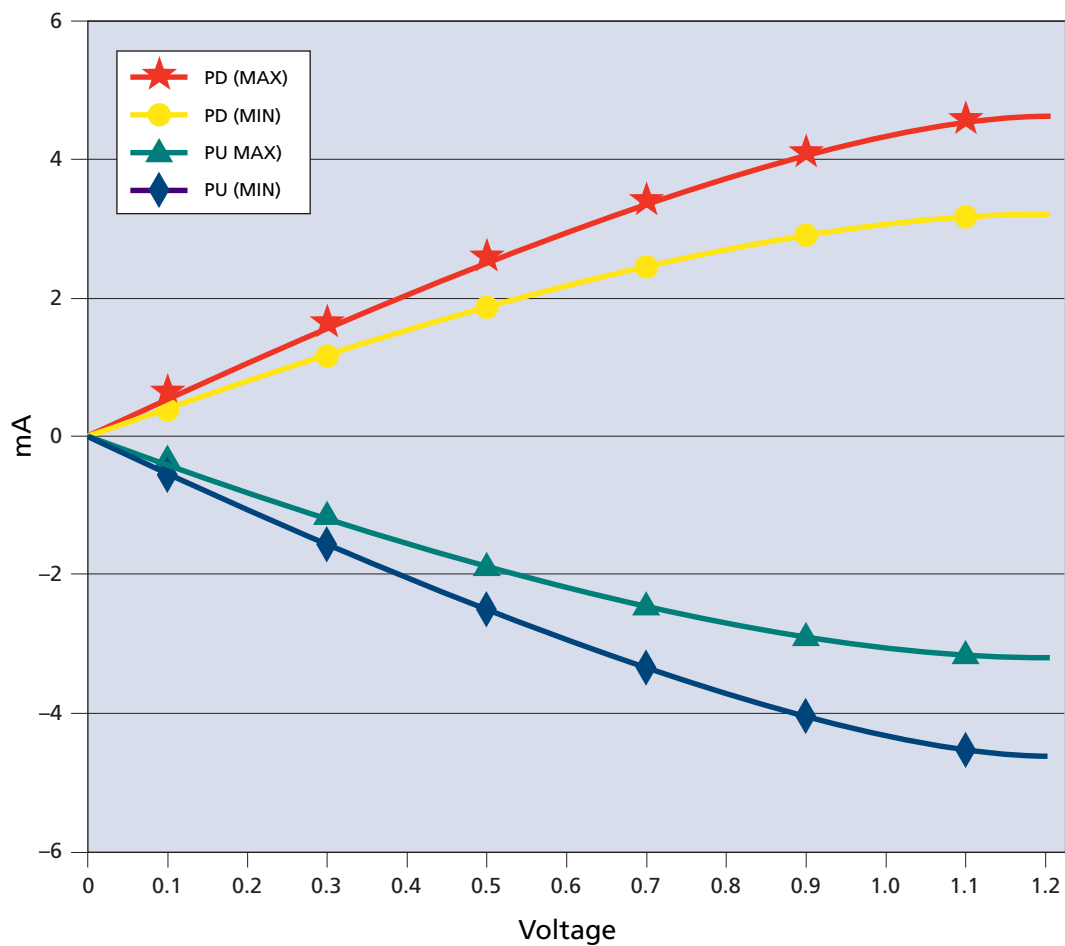
Figure 144: Output Impedance = 240 Ohms, I-V Curves After ZQRESET





121-Ball NAND Flash with LPDDR2 MCP Output Driver Impedance

Figure 145: Output Impedance = 240 Ohms, I-V Curves After Calibration





121-Ball NAND Flash with LPDDR2 MCP Clock Specification

Clock Specification

The specified clock jitter is a random jitter with Gaussian distribution. Input clocks violating minimum or maximum values may result in device malfunction.

Table 114: Definitions and Calculations

Symbol	Description	Calculation	Notes
$t_{CK(avg)}$ and n_{CK}	The average clock period across any consecutive 200-cycle window. Each clock period is calculated from rising clock edge to rising clock edge. Unit $t_{CK(avg)}$ represents the actual clock average $t_{CK(avg)}$ of the input clock under operation. Unit n_{CK} represents one clock cycle of the input clock, counting from actual clock edge to actual clock edge. $t_{CK(avg)}$ can change no more than $\pm 1\%$ within a 100-clock-cycle window, provided that all jitter and timing specifications are met.	$t_{CK(avg)} = \left(\sum_{j=1}^N t_{CKj} \right) / N$ Where $N = 200$	
$t_{CK(abs)}$	The absolute clock period, as measured from one rising clock edge to the next consecutive rising clock edge.		1
$t_{CH(avg)}$	The average HIGH pulse width, as calculated across any 200 consecutive HIGH pulses.	$t_{CH(avg)} = \left(\sum_{j=1}^N t_{CHj} \right) / (N \times t_{CK(avg)})$ Where $N = 200$	
$t_{CL(avg)}$	The average LOW pulse width, as calculated across any 200 consecutive LOW pulses.	$t_{CL(avg)} = \left(\sum_{j=1}^N t_{CLj} \right) / (N \times t_{CK(avg)})$ Where $N = 200$	
$t_{JIT(per)}$	The single-period jitter defined as the largest deviation of any signal t_{CK} from $t_{CK(avg)}$.	$t_{JIT(per)} = \min/\max \text{ of } \left(t_{CKi} - t_{CK(avg)} \right)$ Where $i = 1 \text{ to } 200$	1
$t_{JIT(per),act}$	The actual clock jitter for a given system.		
$t_{JIT(per),allowed}$	The specified clock period jitter allowance.		
$t_{JIT(cc)}$	The absolute difference in clock periods between two consecutive clock cycles. $t_{JIT(cc)}$ defines the cycle-to-cycle jitter.	$t_{JIT(cc)} = \max \text{ of } \left(t_{CK_{i+1}} - t_{CK_i} \right)$	1
$t_{ERR(nper)}$	The cumulative error across n multiple consecutive cycles from $t_{CK(avg)}$.	$t_{ERR(nper)} = \left(\sum_{j=i}^{i+n-1} t_{CKj} \right) - (n \times t_{CK(avg)})$	1
$t_{ERR(nper),act}$	The actual cumulative error over n cycles for a given system.		
$t_{ERR(nper),allowed}$	The specified cumulative error allowance over n cycles.		
$t_{ERR(nper),min}$	The minimum $t_{ERR(nper)}$.	$t_{ERR(nper),min} = (1 + 0.68LN(n)) \times t_{JIT(per),min}$	2



121-Ball NAND Flash with LPDDR2 MCP Clock Period Jitter

Table 114: Definitions and Calculations (Continued)

Symbol	Description	Calculation	Notes
$t_{ERR(nper),max}$	The maximum $t_{ERR(nper)}$.	$t_{ERR(nper),max} = (1 + 0.68LN(n)) \times t_{JIT(per),max}$	2
$t_{JIT(duty)}$	Defined with absolute and average specifications for t_{CH} and t_{CL} , respectively.	$t_{JIT(duty),min} =$ $\text{MIN}((t_{CH(abs),min} - t_{CH(avg),min}),$ $(t_{CL(abs),min} - t_{CL(avg),min})) \times t_{CK(avg)}$ $t_{JIT(duty),max} =$ $\text{MAX}((t_{CH(abs),max} - t_{CH(avg),max}),$ $(t_{CL(abs),max} - t_{CL(avg),max})) \times t_{CK(avg)}$	

- Notes: 1. Not subject to production testing.
 2. Using these equations, $t_{ERR(nper)}$ tables can be generated for each $t_{JIT(per),act}$ value.

$t_{CK(abs)}$, $t_{CH(abs)}$, and $t_{CL(abs)}$

These parameters are specified with their average values; however, the relationship between the average timing and the absolute instantaneous timing (defined in the following table) is applicable at all times.

Table 115: $t_{CK(abs)}$, $t_{CH(abs)}$, and $t_{CL(abs)}$ Definitions

Parameter	Symbol	Minimum	Unit
Absolute clock period	$t_{CK(abs)}$	$t_{CK(avg),min} + t_{JIT(per),min}$	ps ¹
Absolute clock HIGH pulse width	$t_{CH(abs)}$	$t_{CH(avg),min} + t_{JIT(duty),min}^2/t_{CK(avg),min}$	$t_{CK(avg)}$
Absolute clock LOW pulse width	$t_{CL(abs)}$	$t_{CL(avg),min} + t_{JIT(duty),min}^2/t_{CK(avg),min}$	$t_{CK(avg)}$

- Notes: 1. $t_{CK(avg),min}$ is expressed in ps for this table.
 2. $t_{JIT(duty),min}$ is a negative value.

Clock Period Jitter

LPDDR2 devices can tolerate some clock period jitter without core timing parameter derating. This section describes device timing requirements with clock period jitter ($t_{JIT(per)}$) in excess of the values found in the AC Timing section. Calculating cycle time derating and clock cycle derating are also described.

Clock Period Jitter Effects on Core Timing Parameters

Core timing parameters (t_{RCD} , t_{RP} , t_{RTP} , t_{WR} , t_{WRA} , t_{WTR} , t_{RC} , t_{RAS} , t_{RRD} , t_{FAW}) extend across multiple clock cycles. Clock period jitter impacts these parameters when measured in numbers of clock cycles. Within the specification limits, the device is characterized and verified to support $t_{nPARAM} = RU[t_{PARAM}/t_{CK(avg)}]$. During device operation where clock jitter is outside specification limits, the number of clocks or $t_{CK(avg)}$, may need to be increased based on the values for each core timing parameter.



121-Ball NAND Flash with LPDDR2 MCP Clock Period Jitter

Cycle Time Derating for Core Timing Parameters

For a given number of clocks (t_{nPARAM}), when $t_{CK(avg)}$ and $t_{ERR}(t_{nPARAM})_{act}$ exceed $t_{ERR}(t_{nPARAM})_{allowed}$, cycle time derating may be required for core timing parameters.

$$\text{CycleTimeDerating} = \max \left\{ \left[\frac{t_{PARAM} + t_{ERR}(t_{nPARAM})_{act} - t_{ERR}(t_{nPARAM})_{allowed}}{t_{nPARAM}} - t_{CK(avg)} \right], 0 \right\}$$

Cycle time derating analysis should be conducted for each core timing parameter. The amount of cycle time derating required is the maximum of the cycle time deratings determined for each individual core timing parameter.

Clock Cycle Derating for Core Timing Parameters

For each core timing parameter and a given number of clocks (t_{nPARAM}), clock cycle derating should be specified with $t_{JIT(per)}$.

For a given number of clocks (t_{nPARAM}), when $t_{CK(avg)}$ plus $t_{ERR}(t_{nPARAM})_{act}$ exceed the supported cumulative $t_{ERR}(t_{nPARAM})_{allowed}$, derating is required. If the equation below results in a positive value for a core timing parameter (t_{CORE}), the required clock cycle derating will be that positive value (in clocks).

$$\text{ClockCycleDerating} = RU \left\{ \frac{t_{PARAM} + t_{ERR}(t_{nPARAM})_{act} - t_{ERR}(t_{nPARAM})_{allowed}}{t_{CK(avg)}} \right\} - t_{nPARAM}$$

Cycle-time derating analysis should be conducted for each core timing parameter.

Clock Jitter Effects on Command/Address Timing Parameters

Command/address timing parameters (t_{IS} , t_{IH} , t_{ISCKE} , t_{IHCKE} , t_{ISb} , t_{IHb} , t_{ISCKEb} , t_{IHCKEb}) are measured from a command/address signal (CKE, CS, or CA[9:0]) transition edge to its respective clock signal (CK/CK#) crossing. The specification values are not affected by the $t_{JIT(per)}$ applied, because the setup and hold times are relative to the clock signal crossing that latches the command/address. Regardless of clock jitter values, these values must be met.

Clock Jitter Effects on READ Timing Parameters

t_{RPRE}

When the device is operated with input clock jitter, t_{RPRE} must be derated by the $t_{JIT(per),act,max}$ of the input clock that exceeds $t_{JIT(per),allowed,max}$. Output deratings are relative to the input clock:

$$t_{RPRE(min,derated)} = 0.9 - \left(\frac{t_{JIT(per),act,max} - t_{JIT(per),allowed,max}}{t_{CK(avg)}} \right)$$

For example, if the measured jitter into a LPDDR2-800 device has $t_{CK(avg)} = 2500ps$, $t_{JIT(per),act,min} = -172ps$, and $t_{JIT(per),act,max} = +193ps$, then $t_{RPRE,min,derated} = 0.9 - (t_{JIT(per),act,max} - t_{JIT(per),allowed,max})/t_{CK(avg)} = 0.9 - (193 - 100)/2500 = 0.8628 t_{CK(avg)}$.



121-Ball NAND Flash with LPDDR2 MCP Clock Period Jitter

$t_{LZ}(DQ)$, $t_{HZ}(DQ)$, t_{DQSCK} , $t_{LZ}(DQS)$, $t_{HZ}(DQS)$

These parameters are measured from a specific clock edge to a data signal transition (DM_n or DQ_m , where: $n = 0, 1, 2$, or 3 ; and $m = DQ[31:0]$), and specified timings must be met with respect to that clock edge. Therefore, they are not affected by $t_{JIT}(per)$.

t_{QSH} , t_{QSL}

These parameters are affected by duty cycle jitter, represented by $t_{CH}(abs)min$ and $t_{CL}(abs)min$. These parameters determine the absolute data valid window at the device pin. The absolute minimum data valid window at the device pin = $\min [(t_{QSH}(abs)min \times t_{CK}(avg)min - t_{DQSQ}max - t_{QHS}max), (t_{QSL}(abs)min \times t_{CK}(avg)min - t_{DQSQ}max - t_{QHS}max)]$. This minimum data valid window must be met at the target frequency regardless of clock jitter.

t_{RPST}

t_{RPST} is affected by duty cycle jitter, represented by $t_{CL}(abs)$. Therefore, $t_{RPST}(abs)min$ can be specified by $t_{CL}(abs)min$. $t_{RPST}(abs)min = t_{CL}(abs)min - 0.05 = t_{QSL}(abs)min$.

Clock Jitter Effects on WRITE Timing Parameters

t_{DS} , t_{DH}

These parameters are measured from a data signal (DM_n or DQ_m , where $n = 0, 1, 2, 3$; and $m = DQ[31:0]$) transition edge to its respective data strobe signal (DQS_n , $DQS_n\#$: $n = 0, 1, 2, 3$) crossing. The specification values are not affected by the amount of $t_{JIT}(per)$ applied, because the setup and hold times are relative to the clock signal crossing that latches the command/address. Regardless of clock jitter values, these values must be met.

t_{DSS} , t_{DSH}

These parameters are measured from a data strobe signal crossing (DQS_x , $DQS_x\#$) to its clock signal crossing ($CK/CK\#$). The specification values are not affected by the amount of $t_{JIT}(per)$ applied, because the setup and hold times are relative to the clock signal crossing that latches the command/address. Regardless of clock jitter values, these values must be met.

t_{DQSS}

t_{DQSS} is measured from the clock signal crossing ($CK/CK\#$) to the first latching data strobe signal crossing (DQS_x , $DQS_x\#$). When the device is operated with input clock jitter, this parameter must be derated by the actual $t_{JIT}(per)_{act}$ of the input clock in excess of $t_{JIT}(per)_{allowed}$.

$$t_{DQSS}(min, derated) = 0.75 - \left(\frac{t_{JIT}(per)_{act, min} - t_{JIT}(per)_{allowed, min}}{t_{CK}(avg)} \right)$$

$$t_{DQSS}(max, derated) = 1.25 - \left(\frac{t_{JIT}(per)_{act, max} - t_{JIT}(per)_{allowed, max}}{t_{CK}(avg)} \right)$$

For example, if the measured jitter into an LPDDR2-800 device has $t_{CK}(avg) = 2500ps$, $t_{JIT}(per)_{act, min} = -172ps$, and $t_{JIT}(per)_{act, max} = +193ps$, then:

$$t_{DQSS}(min, derated) = 0.75 - (t_{JIT}(per)_{act, min} - t_{JIT}(per)_{allowed, min}) / t_{CK}(avg) = 0.75 - (-172 + 100) / 2500 = 0.7788 \text{ } t_{CK}(avg), \text{ and}$$



121-Ball NAND Flash with LPDDR2 MCP Refresh Requirements

$${}^tDQSS, (max, derated) = 1.25 - ({}^tJIT(per), act, max - {}^tJIT(per), allowed, max) / {}^tCK(avg) = 1.25 - (193 - 100) / 2500 = 1.2128 {}^tCK(avg).$$

Refresh Requirements

Table 116: Refresh Requirement Parameters (Per Density)

Parameter		Symbol	64Mb	128Mb	256Mb	512Mb	1Gb	2Gb	4Gb	8Gb	Unit
Number of banks			4	4	4	4	8	8	8	8	
Refresh window: T _{CASE} ≤ 85°		^t REFW	32	32	32	32	32	32	32	32	ms
Refresh window: 85°C < T _{CASE} ≤ 105°C		^t REFW	8	8	8	8	8	8	8	8	ms
Required number of REFRESH commands (MIN)		R	2048	2048	4096	4096	4096	8192	8192	8192	
Average time between REFRESH commands (for reference only) T _{CASE} ≤ 85°C	REFab	^t REFI	15.6	15.6	7.8	7.8	7.8	3.9	3.9	3.9	μs
	REFpb	^t REFIpb	(REFpb not supported below 1Gb)				0.975	0.4875	0.4875	0.4875	μs
Refresh cycle time		^t RFCab	90	90	90	90	130	130	130	210	ns
Per-bank REFRESH cycle time		^t RFCpb	na				60	60	60	90	ns
Burst REFRESH window = 4 × 8 × ^t RFCab		^t REFBW	2.88	2.88	2.88	2.88	4.16	4.16	4.16	6.72	μs



121-Ball NAND Flash with LPDDR2 MCP AC Timing

AC Timing

Table 117: AC Timing

Notes 1–2 apply to all parameters and conditions. AC timing parameters must satisfy the t_{CK} minimum conditions (in multiples of t_{CK}) as well as the timing specifications when values for both are indicated.

Parameter	Symbol	Min/ Max	t_{CK} Min	Data Rate							Unit	Notes
				1066	933	800	667	533	400	333		
Maximum frequency		–	–	533	466	400	333	266	200	166	MHz	
Clock Timing												
Average clock period	$t_{CK(avg)}$	MIN	–	1.875	2.15	2.5	3	3.75	5	6	ns	
		MAX	–	100	100	100	100	100	100	100		
Average HIGH pulse width	$t_{CH(avg)}$	MIN	–	0.45	0.45	0.45	0.45	0.45	0.45	0.45	t_{CK} (avg)	
		MAX	–	0.55	0.55	0.55	0.55	0.55	0.55	0.55		
Average LOW pulse width	$t_{CL(avg)}$	MIN	–	0.45	0.45	0.45	0.45	0.45	0.45	0.45	t_{CK} (avg)	
		MAX	–	0.55	0.55	0.55	0.55	0.55	0.55	0.55		
Absolute clock period	$t_{CK(abs)}$	MIN	–	$t_{CK(avg)min} \pm t_{JIT(per)min}$							ps	
Absolute clock HIGH pulse width	$t_{CH(abs)}$	MIN	–	0.43	0.43	0.43	0.43	0.43	0.43	0.43	t_{CK} (avg)	
		MAX	–	0.57	0.57	0.57	0.57	0.57	0.57	0.57		
Absolute clock LOW pulse width	$t_{CL(abs)}$	MIN	–	0.43	0.43	0.43	0.43	0.43	0.43	0.43	t_{CK} (avg)	
		MAX	–	0.57	0.57	0.57	0.57	0.57	0.57	0.57		
Clock period jitter (with supported jitter)	$t_{JIT(per)}$, allowed	MIN	–	-90	-95	-100	-110	-120	-140	-150	ps	
		MAX	–	90	95	100	110	120	140	150		
Maximum clock jitter between two consecutive clock cycles (with supported jitter)	$t_{JIT(cc)}$, allowed	MAX	–	180	190	200	220	240	280	300	ps	
Duty cycle jitter (with supported jitter)	$t_{JIT(duty)}$, allowed	MIN	–	MIN ($(t_{CH(abs),min} - t_{CH(avg),min})$, $(t_{CL(abs),min} - t_{CL(avg),min}) \times t_{CK(avg)}$)							ps	
		MAX	–	MAX ($(t_{CH(abs),max} - t_{CH(avg),max})$, $(t_{CL(abs),max} - t_{CL(avg),max}) \times t_{CK(avg)}$)								
Cumulative errors across 2 cycles	$t_{ERR(2per)}$, allowed	MIN	–	-132	-140	-147	-162	-177	-206	-221	ps	
		MAX	–	132	140	147	162	177	206	221		
Cumulative errors across 3 cycles	$t_{ERR(3per)}$, allowed	MIN	–	-157	-166	-175	-192	-210	-245	-262	ps	
		MAX	–	157	166	175	192	210	245	262		
Cumulative errors across 4 cycles	$t_{ERR(4per)}$, allowed	MIN	–	-175	-185	-194	-214	-233	-272	-291	ps	
		MAX	–	175	185	194	214	233	272	291		
Cumulative errors across 5 cycles	$t_{ERR(5per)}$, allowed	MIN	–	-188	-199	-209	-230	-251	-293	-314	ps	
		MAX	–	188	199	209	230	251	293	314		
Cumulative errors across 6 cycles	$t_{ERR(6per)}$, allowed	MIN	–	-200	-211	-222	-244	-266	-311	-333	ps	
		MAX	–	200	211	222	244	266	311	333		
Cumulative errors across 7 cycles	$t_{ERR(7per)}$, allowed	MIN	–	-209	-221	-232	-256	-279	-325	-348	ps	
		MAX	–	209	221	232	256	279	325	348		



121-Ball NAND Flash with LPDDR2 MCP AC Timing

Table 117: AC Timing (Continued)

Notes 1–2 apply to all parameters and conditions. AC timing parameters must satisfy the t_{CK} minimum conditions (in multiples of t_{CK}) as well as the timing specifications when values for both are indicated.

Parameter	Symbol	Min/ Max	tCK Min	Data Rate							Unit	Notes
				1066	933	800	667	533	400	333		
Cumulative errors across 8 cycles	tERR(8per), allowed	MIN	–	-217	-229	-241	-266	-290	-338	-362	ps	
		MAX	–	217	229	241	266	290	338	362		
Cumulative errors across 9 cycles	tERR(9per), allowed	MIN	–	-224	-237	-249	-274	-299	-349	-374	ps	
		MAX	–	224	237	249	274	299	349	374		
Cumulative errors across 10 cycles	tERR(10per), allowed	MIN	–	-231	-244	-257	-282	-308	-359	-385	ps	
		MAX	–	231	244	257	282	308	359	385		
Cumulative errors across 11 cycles	tERR(11per), allowed	MIN	–	-237	-250	-263	-289	-316	-368	-395	ps	
		MAX	–	237	250	263	289	316	368	395		
Cumulative errors across 12 cycles	tERR(12per), allowed	MIN	–	-242	-256	-269	-296	-323	-377	-403	ps	
		MAX	–	242	256	269	296	323	377	403		
Cumulative errors across $n = 13, 14, 15 \dots, 49, 50$ cycles	tERR(nper), allowed	MIN	tERR(nper),allowed,min = $(1 + 0.68\ln(n)) \times$ tJIT(per),allowed,min								ps	
		MAX	tERR(nper), allowed,max = $(1 + 0.68\ln(n)) \times$ tJIT(per),allowed,max									
ZQ Calibration Parameters												
Initialization calibration time	tZQINIT	MIN	–	1	1	1	1	1	1	1	μs	
Long calibration time	tZQCL	MIN	6	360	360	360	360	360	360	360	ns	
Short calibration time	tZQCS	MIN	6	90	90	90	90	90	90	90	ns	
Calibration RESET time	tZQRESET	MIN	3	50	50	50	50	50	50	50	ns	
READ Parameters ³												
DQS output access time from CK/CK#	tDQSCK	MIN	–	2500	2500	2500	2500	2500	2500	2500	ps	
		MAX	–	5500	5500	5500	5500	5500	5500	5500		
DQSCK delta short	tDQSCKDS	MAX	–	330	380	450	540	670	900	1080	ps	4
DQSCK delta medium	tDQSCKDM	MAX	–	680	780	900	1050	1350	1800	1900	ps	5
DQSCK delta long	tDQSCKDL	MAX	–	920	1050	1200	1400	1800	2400	–	ps	6
DQS-DQ skew	tDQSQ	MAX	–	200	220	240	280	340	400	500	ps	
Data-hold skew factor	tQHS	MAX	–	230	260	280	340	400	480	600	ps	
DQS output HIGH pulse width	tQSH	MIN	–	tCH(abs) - 0.05							tCK (avg)	
DQS output LOW pulse width	tQSL	MIN	–	tCL(abs) - 0.05							tCK (avg)	
Data half period	tQHP	MIN	–	MIN (tQSH, tQSL)							tCK (avg)	
DQ/DQS output hold time from DQS	tQH	MIN	–	tQHP - tQHS							ps	



121-Ball NAND Flash with LPDDR2 MCP AC Timing

Table 117: AC Timing (Continued)

Notes 1–2 apply to all parameters and conditions. AC timing parameters must satisfy the t_{CK} minimum conditions (in multiples of t_{CK}) as well as the timing specifications when values for both are indicated.

Parameter	Symbol	Min/ Max	^t CK Min	Data Rate							Unit	Notes
				1066	933	800	667	533	400	333		
READ preamble	^t RPRE	MIN	–	0.9	0.9	0.9	0.9	0.9	0.9	0.9	^t CK (avg)	7
READ postamble	^t RPST	MIN	–	^t CL(abs) - 0.05							^t CK (avg)	8
DQS Low-Z from clock	^t LZ(DQS)	MIN	–	^t DQSCK (MIN) - 300							ps	
DQ Low-Z from clock	^t LZ(DQ)	MIN	–	^t DQSCK(MIN) - (1.4 × ^t QH5(MAX))							ps	
DQS High-Z from clock	^t HZ(DQS)	MAX	–	^t DQSCK (MAX) - 100							ps	
DQ High-Z from clock	^t HZ(DQ)	MAX	–	^t DQSCK(MAX) + (1.4 × ^t DQSQ(MAX))							ps	
WRITE Parameters ³												
DQ and DM input hold time (V _{REF} based)	^t DH	MIN	–	210	235	270	350	430	480	600	ps	
DQ and DM input setup time (V _{REF} based)	^t DS	MIN	–	210	235	270	350	430	480	600	ps	
DQ and DM input pulse width	^t DIPW	MIN	–	0.35	0.35	0.35	0.35	0.35	0.35	0.35	^t CK (avg)	
Write command to first DQS latching transition	^t DQSS	MIN	–	0.75	0.75	0.75	0.75	0.75	0.75	0.75	^t CK (avg)	
		MAX	–	1.25	1.25	1.25	1.25	1.25	1.25	1.25	^t CK (avg)	
DQS input high-level width	^t DQSH	MIN	–	0.4	0.4	0.4	0.4	0.4	0.4	0.4	^t CK (avg)	
DQS input low-level width	^t DQSL	MIN	–	0.4	0.4	0.4	0.4	0.4	0.4	0.4	^t CK (avg)	
DQS falling edge to CK setup time	^t DSS	MIN	–	0.2	0.2	0.2	0.2	0.2	0.2	0.2	^t CK (avg)	
DQS falling edge hold time from CK	^t DSH	MIN	–	0.2	0.2	0.2	0.2	0.2	0.2	0.2	^t CK (avg)	
Write postamble	^t WPST	MIN	–	0.4	0.4	0.4	0.4	0.4	0.4	0.4	^t CK (avg)	
Write preamble	^t WPRE	MIN	–	0.35	0.35	0.35	0.35	0.35	0.35	0.35	^t CK (avg)	
CKE Input Parameters												
CKE minimum pulse width (HIGH and LOW pulse width)	^t CKE	MIN	3	3	3	3	3	3	3	3	^t CK (avg)	
CKE input setup time	^t ISCKE	MIN	–	0.25	0.25	0.25	0.25	0.25	0.25	0.25	^t CK (avg)	9
CKE input hold time	^t IHCKE	MIN	–	0.25	0.25	0.25	0.25	0.25	0.25	0.25	^t CK (avg)	10



121-Ball NAND Flash with LPDDR2 MCP AC Timing

Table 117: AC Timing (Continued)

Notes 1–2 apply to all parameters and conditions. AC timing parameters must satisfy the t_{CK} minimum conditions (in multiples of t_{CK}) as well as the timing specifications when values for both are indicated.

Parameter	Symbol	Min/ Max	tCK Min	Data Rate							Unit	Notes
				1066	933	800	667	533	400	333		
Command Address Input Parameters ³												
Address and control input setup time	t ¹ IS	MIN	–	220	250	290	370	460	600	740	ps	11
Address and control input hold time	t ¹ IH	MIN	–	220	250	290	370	460	600	740	ps	11
Address and control input pulse width	t ¹ IPW	MIN	–	0.40	0.40	0.40	0.40	0.40	0.40	0.40	tCK (avg)	
Boot Parameters (10 MHz–55 MHz) ^{12, 13, 14}												
Clock cycle time	tCKb	MAX	–	100	100	100	100	100	100	100	ns	
		MIN	–	18	18	18	18	18	18	18		
CKE input setup time	t ¹ ISCKEb	MIN	–	2.5	2.5	2.5	2.5	2.5	2.5	2.5	ns	
CKE input hold time	t ¹ IHCKEb	MIN	–	2.5	2.5	2.5	2.5	2.5	2.5	2.5	ns	
Address and control input setup time	t ¹ ISb	MIN	–	1150	1150	1150	1150	1150	1150	1150	ps	
Address and control input hold time	t ¹ IHb	MIN	–	1150	1150	1150	1150	1150	1150	1150	ps	
DQS output data access time from CK/CK#	tDQSCKb	MIN	–	2.0	2.0	2.0	2.0	2.0	2.0	2.0	ns	
		MAX	–	10.0	10.0	10.0	10.0	10.0	10.0	10.0		
Data strobe edge to output data edge	tDQSQb	MAX	–	1.2	1.2	1.2	1.2	1.2	1.2	1.2	ns	
Data hold skew factor	tQHSb	MAX	–	1.2	1.2	1.2	1.2	1.2	1.2	1.2	ns	
Mode Register Parameters												
MODE REGISTER WRITE command period	tMRW	MIN	5	5	5	5	5	5	5	5	tCK (avg)	
MODE REGISTER READ command period	tMRR	MIN	2	2	2	2	2	2	2	2	tCK (avg)	
Core Parameters ¹⁵												
READ latency	RL	MIN	3	8	7	6	5	4	3	3	tCK (avg)	
WRITE latency	WL	MIN	1	4	4	3	2	2	1	1	tCK (avg)	
ACTIVATE-to-ACTIVATE command period	tRC	MIN	–	tRAS + tRPab (with all-bank precharge), tRAS + tRPpb (with per-bank precharge)							ns	17
CKE minimum pulse width during SELF REFRESH (low pulse width during SELF REFRESH)	tCKESR	MIN	3	15	15	15	15	15	15	15	ns	
SELF REFRESH exit to next valid command delay	tXSR	MIN	2	tRFCab + 10							ns	



121-Ball NAND Flash with LPDDR2 MCP AC Timing

Table 117: AC Timing (Continued)

Notes 1–2 apply to all parameters and conditions. AC timing parameters must satisfy the t_{CK} minimum conditions (in multiples of t_{CK}) as well as the timing specifications when values for both are indicated.

Parameter	Symbol	Min/ Max	t_{CK} Min	Data Rate							Unit	Notes
				1066	933	800	667	533	400	333		
Exit power-down to next valid command delay	t_{XP}	MIN	2	7.5	7.5	7.5	7.5	7.5	7.5	7.5	ns	
CAS-to-CAS delay	t_{CCD}	MIN	2	2	2	2	2	2	2	2	t_{CK} (avg)	
Internal READ to PRECHARGE command delay	t_{RTP}	MIN	2	7.5	7.5	7.5	7.5	7.5	7.5	7.5	ns	
RAS-to-CAS delay	t_{RCD}	Fast	3	15	15	15	15	15	15	15	ns	
		TYP	3	18	18	18	18	18	18	18		
Row precharge time (single bank)	t_{RPpb}	Fast	3	15	15	15	15	15	15	15	ns	
		TYP	3	18	18	18	18	18	18	18		
Row precharge time (all banks)	t_{RPab} 4-bank	Fast	3	15	15	15	15	15	15	15	ns	
		TYP	3	18	18	18	18	18	18	18		
Row precharge time (all banks)	t_{RPab} 8-bank	Fast	3	18	18	18	18	18	18	18	ns	
		TYP	3	21	21	21	21	21	21	21		
Row active time	t_{RAS}	MIN	3	42	42	42	42	42	42	42	ns	
		MAX	–	70	70	70	70	70	70	70	μs	
WRITE recovery time	t_{WR}	MIN	3	15	15	15	15	15	15	15	ns	
Internal WRITE-to-READ command delay	t_{WTR}	MIN	2	7.5	7.5	7.5	7.5	7.5	10	10	ns	
Active bank <i>a</i> to active bank <i>b</i>	t_{RRD}	MIN	2	10	10	10	10	10	10	10	ns	
Four-bank activate window	t_{FAW}	MIN	8	50	50	50	50	50	50	60	ns	
Minimum deep power-down time	t_{DPD}	MIN	–	500	500	500	500	500	500	500	μs	
Temperature Derating¹⁶												
t_{DQSCK} derating	t_{DQSCK} (derated)	MAX	–	5620	6000	6000	6000	6000	6000	6000	ps	
Core timing temperature derating	t_{RCD} (derated)	MIN	–	$t_{RCD} + 1.875$							ns	
	t_{RC} (derated)	MIN	–	$t_{RC} + 1.875$							ns	
	t_{RAS} (derated)	MIN	–	$t_{RAS} + 1.875$							ns	
	t_{RP} (derated)	MIN	–	$t_{RP} + 1.875$							ns	
	t_{RRD} (derated)	MIN	–	$t_{RRD} + 1.875$							ns	

Notes: 1. Frequency values are for reference only. Clock cycle time (t_{CK}) is used to determine device capabilities.

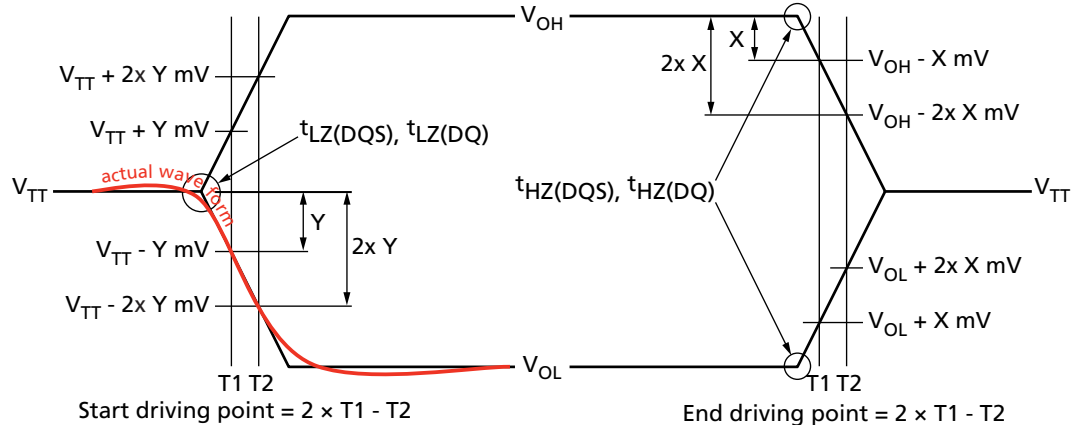


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2. All AC timings assume an input slew rate of 1 V/ns.
3. READ, WRITE, and input setup and hold values are referenced to V_{REF} .
4. t_{DQCKDS} is the absolute value of the difference between any two t_{DQCK} measurements (in a byte lane) within a contiguous sequence of bursts in a 160ns rolling window. t_{DQCKDS} is not tested and is guaranteed by design. Temperature drift in the system is $<10^{\circ}\text{C/s}$. Values do not include clock jitter.
5. t_{DQCKDM} is the absolute value of the difference between any two t_{DQCK} measurements (in a byte lane) within a 1.6 μs rolling window. t_{DQCKDM} is not tested and is guaranteed by design. Temperature drift in the system is $<10^{\circ}\text{C/s}$. Values do not include clock jitter.
6. t_{DQCKDL} is the absolute value of the difference between any two t_{DQCK} measurements (in a byte lane) within a 32ms rolling window. t_{DQCKDL} is not tested and is guaranteed by design. Temperature drift in the system is $<10^{\circ}\text{C/s}$. Values do not include clock jitter.

For LOW-to-HIGH and HIGH-to-LOW transitions, the timing reference is at the point when the signal crosses the transition threshold (V_{TT}). t_{HZ} and t_{LZ} transitions occur in the same access time (with respect to clock) as valid data transitions. These parameters are not referenced to a specific voltage level but to the time when the device output is no longer driving (for t_{RPST} , $t_{HZ}(\text{DQS})$ and $t_{HZ}(\text{DQ})$), or begins driving (for t_{RPRE} , $t_{LZ}(\text{DQS})$ and $t_{LZ}(\text{DQ})$). The figure below shows a method to calculate the point when the device is no longer driving $t_{HZ}(\text{DQS})$ and $t_{HZ}(\text{DQ})$ or begins driving $t_{LZ}(\text{DQS})$ and $t_{LZ}(\text{DQ})$ by measuring the signal at two different voltages. The actual voltage measurement points are not critical as long as the calculation is consistent. The parameters $t_{LZ}(\text{DQS})$, $t_{LZ}(\text{DQ})$, $t_{HZ}(\text{DQS})$, and $t_{HZ}(\text{DQ})$ are defined as single-ended. The timing parameters t_{RPRE} and t_{RPST} are determined from the differential signal $\text{DQS}/\text{DQS}\#$.

Output Transition Timing



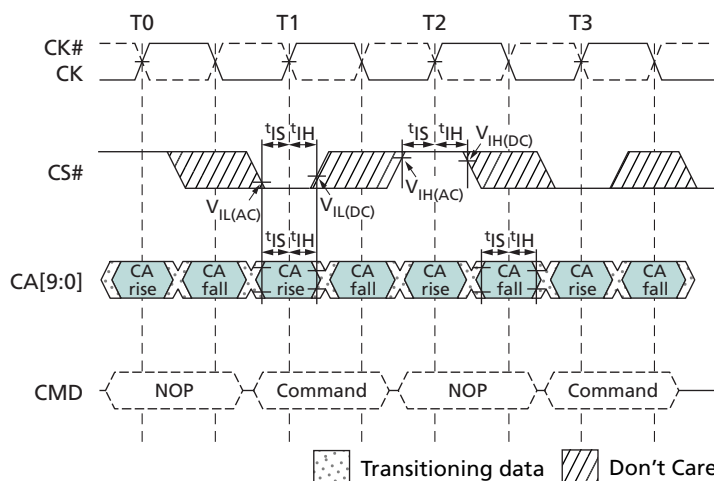
7. Measured from the point when $\text{DQS}/\text{DQS}\#$ begins driving the signal, to the point when $\text{DQS}/\text{DQS}\#$ begins driving the first rising strobe edge.
8. Measured from the last falling strobe edge of $\text{DQS}/\text{DQS}\#$ to the point when $\text{DQS}/\text{DQS}\#$ finishes driving the signal.
9. t_{CKE} input setup time is measured from CKE reaching a HIGH/LOW voltage level to $\text{CK}/\text{CK}\#$ crossing.
10. t_{CKE} input hold time is measured from $\text{CK}/\text{CK}\#$ crossing to CKE reaching a HIGH/LOW voltage level.
11. Input setup/hold time for signal ($\text{CA}[9:0]$, $\text{CS}\#$).
12. To ensure device operation before the device is configured, a number of AC boot timing parameters are defined in this table. The letter b is appended to the boot parameter symbols (for example, t_{CK} during boot is t_{CKb}).



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13. Mobile LPDDR2 devices set some mode register default values upon receiving a RESET (MRW) command, as specified in Mode Register Definition.
14. The output skew parameters are measured with default output impedance settings using the reference load.
15. The minimum t_{CK} column applies only when t_{CK} is greater than 6ns.
16. Timing derating applies for operation at 85°C to 105°C when the requirement to derate is indicated by mode register 4 op-code (see the MR4 Device Temperature (MA[7:0] = 04h) table).
17. DRAM devices should be evenly addressed when being accessed. Disproportionate accesses to a particular row address may result in reduction of the product lifetime.

Figure 146: Command Input Setup and Hold Timing



- Notes:
1. The setup and hold timing shown applies to all commands.
 2. Setup and hold conditions also apply to the CKE pin. For timing diagrams related to the CKE pin, see Power-Down (page 165).

CA and CS# Setup, Hold, and Derating

For all input signals (CA and CS#), the total required setup time (t_{IS}) and hold time (t_{IH}) is calculated by adding the data sheet t_{IS} (base) and t_{IH} (base) values to the Δt_{IS} and Δt_{IH} derating values, respectively. Example: t_{IS} (total setup time) = $t_{IS}(\text{base}) + \Delta t_{IS}$. (See the series of tables following this section.)

The typical setup slew rate (t_{IS}) for a rising signal is defined as the slew rate between the last crossing of $V_{REF(DC)}$ and the first crossing of $V_{IH(AC)min}$. The typical setup slew rate for a falling signal is defined as the slew rate between the last crossing of $V_{REF(DC)}$ and the first crossing of $V_{IL(AC)max}$. If the actual signal is consistently earlier than the typical slew rate line between the shaded $V_{REF(DC)}$ -to-(AC) region, use the typical slew rate for the derating value (see Figure 147 (page 222)). If the actual signal is later than the typical slew rate line anywhere between the shaded $V_{REF(DC)}$ -to-AC region, the slew rate of a tangent line to the actual signal from the AC level to the DC level is used for the derating value (see Figure 149 (page 224)).

The hold (t_{IH}) typical slew rate for a rising signal is defined as the slew rate between the last crossing of $V_{IL(DC)max}$ and the first crossing of $V_{REF(DC)}$. The hold (t_{IH}) typical slew rate for a falling signal is defined as the slew rate between the last crossing of $V_{IH(DC)min}$ and the first crossing of $V_{REF(DC)}$. If the actual signal is consistently later than the typical



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slew rate line between the shaded DC-to- $V_{REF(DC)}$ region, use the typical slew rate for the derating value (see Figure 148 (page 223)). If the actual signal is earlier than the typical slew rate line anywhere between the shaded DC-to- $V_{REF(DC)}$ region, the slew rate of a tangent line to the actual signal from the DC level to $V_{REF(DC)}$ level is used for the derating value (see Figure 150 (page 225)).

For a valid transition, the input signal must remain above or below $V_{IH}/V_{IL(AC)}$ for a specified time, t_{VAC} (see Table 122 (page 221)).

For slow slew rates the total setup time could be a negative value (that is, a valid input signal will not have reached $V_{IH}/V_{IL(AC)}$ at the time of the rising clock transition). A valid input signal is still required to complete the transition and reach $V_{IH}/V_{IL(AC)}$.

For slew rates between the values listed in Table 120, the derating values are obtained using linear interpolation. Slew rate values are not typically subject to production testing. They are verified by design and characterization.

Table 118: CA and CS# Setup and Hold Base Values (>400 MHz, 1 V/ns Slew Rate)

Parameter	Data Rate						Reference
	1066	933	800	667	533	466	
t_{IS} (base)	0	30	70	150	240	300	$V_{IH}/V_{IL(AC)} = V_{REF(DC)} \pm 220mV$
t_{IH} (base)	90	120	160	240	330	390	$V_{IH}/V_{IL(DC)} = V_{REF(DC)} \pm 130mV$

Note: 1. AC/DC referenced for 1 V/ns CA and CS# slew rate, and 2 V/ns differential CK/CK# slew rate.

Table 119: CA and CS# Setup and Hold Base Values (<400 MHz, 1 V/ns Slew Rate)

Parameter	Data Rate				Reference
	400	333	255	200	
t_{IS} (base)	300	440	600	850	$V_{IH}/V_{IL(AC)} = V_{REF(DC)} \pm 300mV$
t_{IH} (base)	400	540	700	950	$V_{IH}/V_{IL(DC)} = V_{REF(DC)} \pm 200mV$

Note: 1. AC/DC referenced for 1 V/ns CA and CS# slew rate, and 2 V/ns differential CK/CK# slew rate.



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Table 120: Derating Values for AC/DC-Based t_{IS}/t_{IH} (AC220)
 Δt_{IS} , Δt_{IH} derating in ps

		CK, CK# Differential Slew Rate															
		4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns	
		Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}
CA, CS# slew rate V/ns	2.0	110	65	110	65	110	65										
	1.5	74	43	73	43	73	43	89	59								
	1.0	0	0	0	0	0	0	16	16	32	32						
	0.9			-3	-5	-3	-5	13	11	29	27	45	43				
	0.8					-8	-13	8	3	24	19	40	35	56	55		
	0.7							2	-6	18	10	34	26	50	46	66	78
	0.6									10	-3	26	13	42	33	58	65
	0.5											4	-4	20	16	36	48
	0.4													-7	2	17	34

Note: 1. Shaded cells are not supported.

Table 121: Derating Values for AC/DC-Based t_{IS}/t_{IH} (AC300)
 Δt_{IS} , Δt_{IH} derating in ps

		CK, CK# Differential Slew Rate															
		4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns	
		Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}	Δt_{IS}	Δt_{IH}
CA, CS# slew rate V/ns	2.0	150	100	150	100	150	100										
	1.5	100	67	100	67	100	67	116	83								
	1.0	0	0	0	0	0	0	16	16	32	32						
	0.9			-4	-8	-4	-8	12	8	28	24	44	40				
	0.8					-12	-20	4	-4	20	12	36	28	52	48		
	0.7							-3	-18	13	-2	29	14	45	34	61	66
	0.6									2	-21	18	-5	34	15	50	47
	0.5											-12	-32	4	-12	20	20
	0.4													-35	-40	-11	-8

Note: 1. Shaded cells are not supported.

Table 122: Required Time for Valid Transition – $t_{VAC} > V_{IH(AC)}$ and $< V_{IL(AC)}$

Slew Rate (V/ns)	t_{VAC} at 300mV (ps)		t_{VAC} at 220mV (ps)	
	Min	Max	Min	Max
>2.0	75	–	175	–
2.0	57	–	170	–
1.5	50	–	167	–
1.0	38	–	163	–

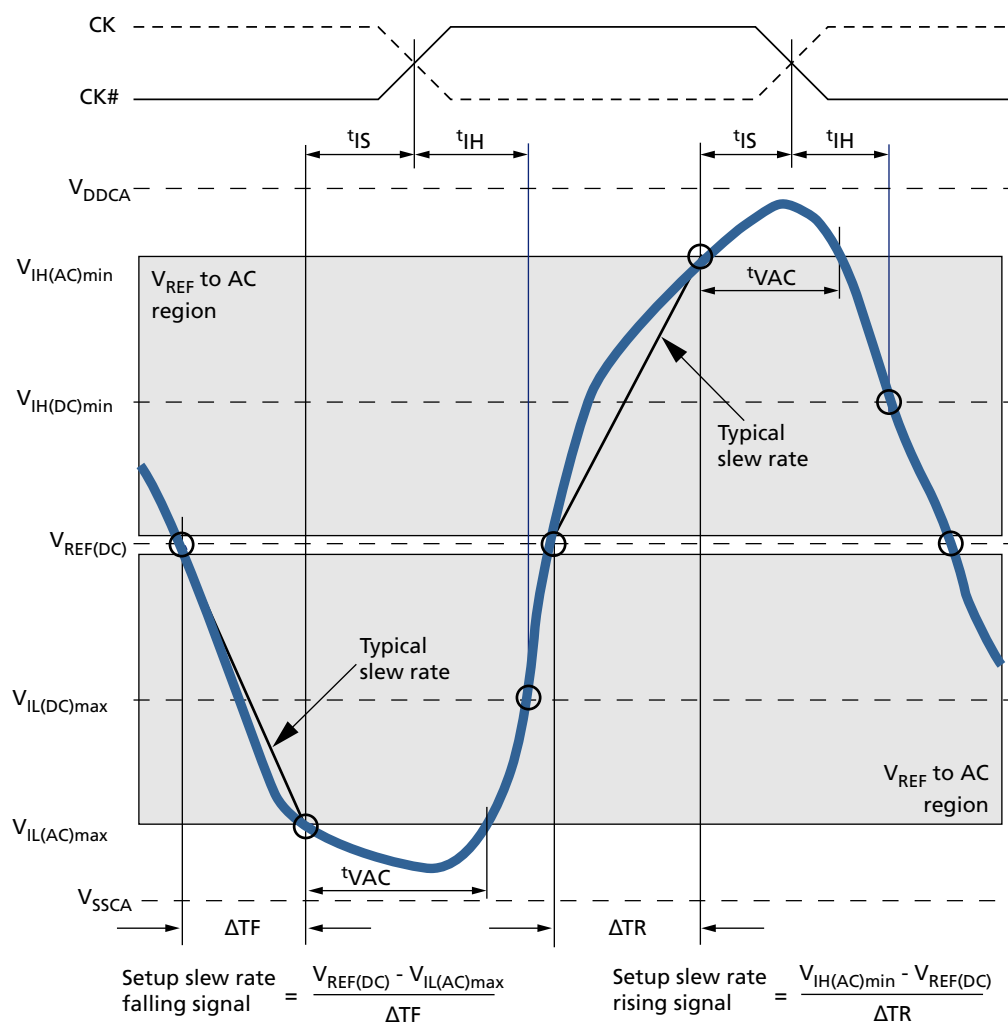


121-Ball NAND Flash with LPDDR2 MCP CA and CS# Setup, Hold, and Derating

Table 122: Required Time for Valid Transition – $t_{VAC} > V_{IH(AC)}$ and $< V_{IL(AC)}$ (Continued)

Slew Rate (V/ns)	t_{VAC} at 300mV (ps)		t_{VAC} at 220mV (ps)	
	Min	Max	Min	Max
0.9	34	–	162	–
0.8	29	–	161	–
0.7	22	–	159	–
0.6	13	–	155	–
0.5	0	–	150	–
<0.5	0	–	150	–

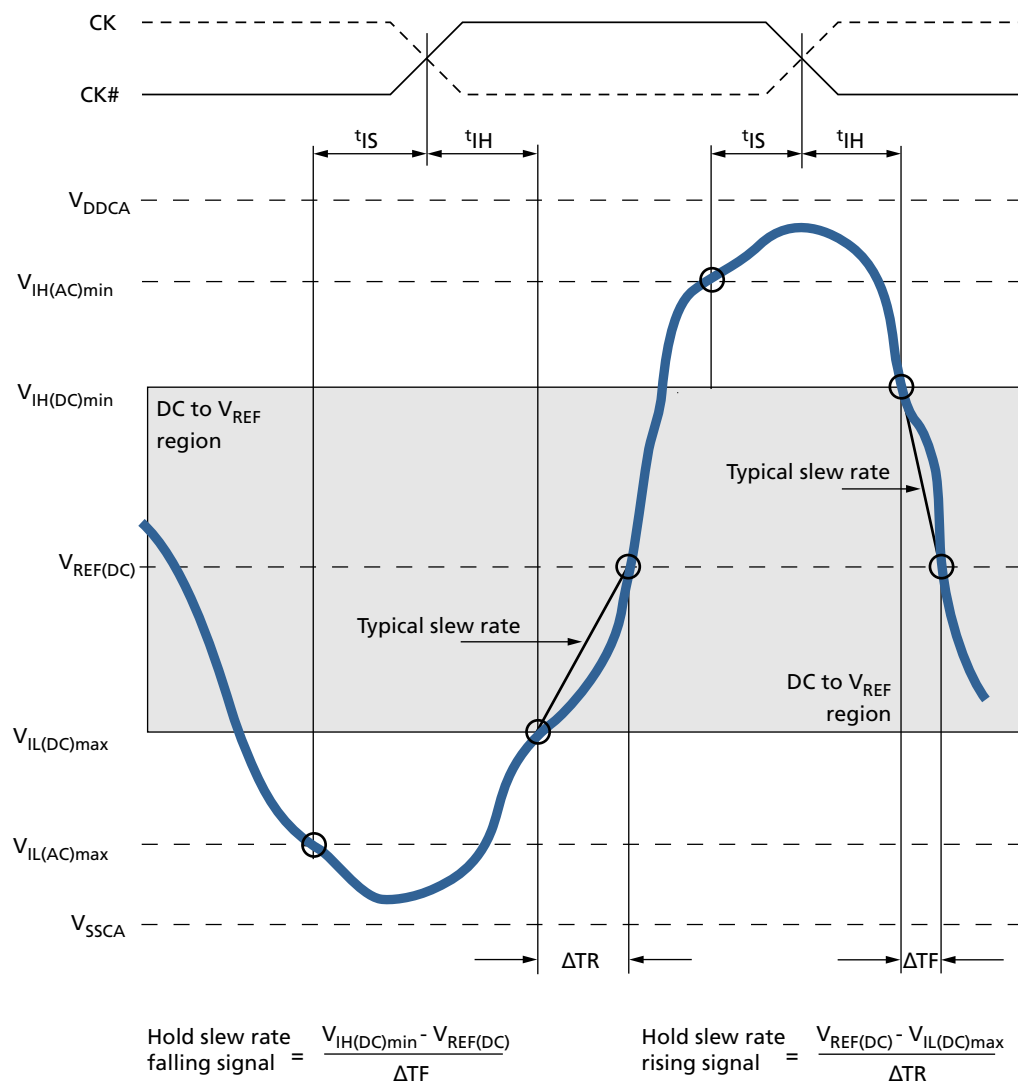
Figure 147: Typical Slew Rate and t_{VAC} – t_{IS} for CA and CS# Relative to Clock





121-Ball NAND Flash with LPDDR2 MCP CA and CS# Setup, Hold, and Derating

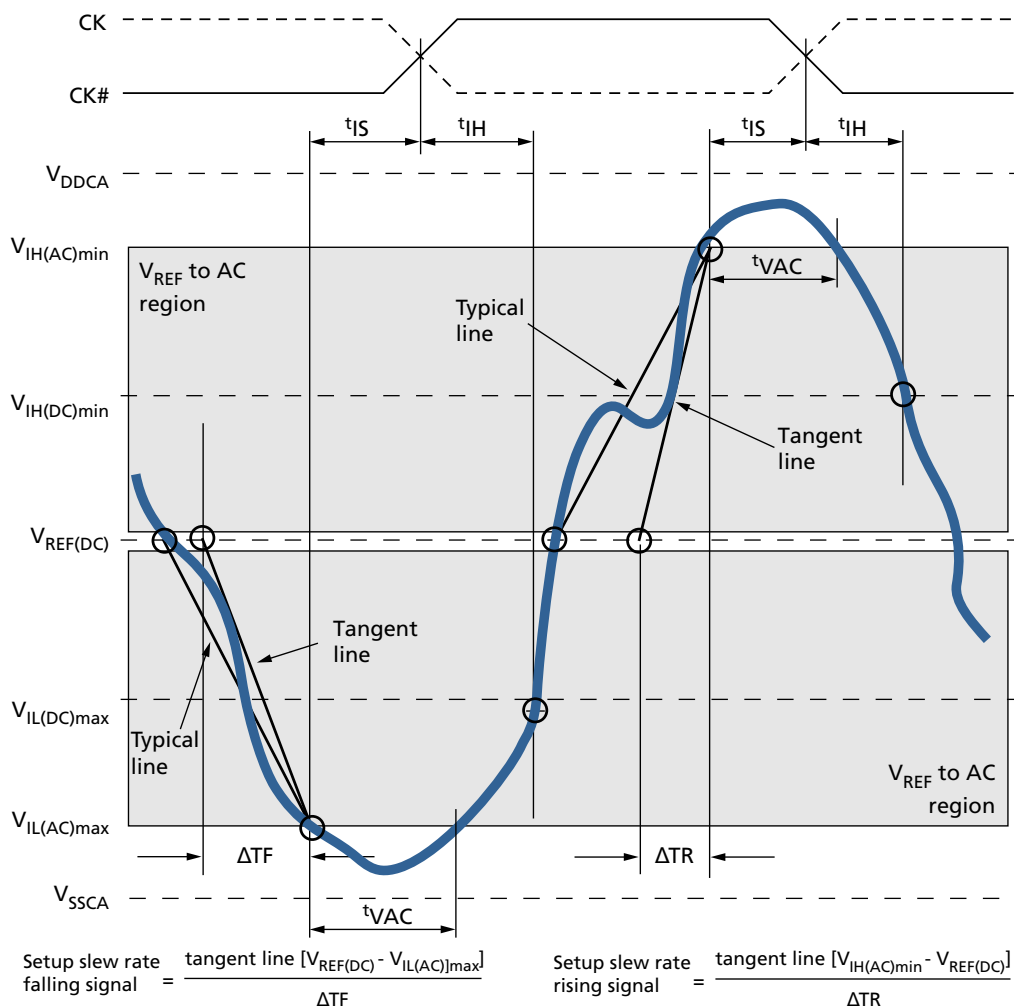
Figure 148: Typical Slew Rate – t_{IH} for CA and CS# Relative to Clock





121-Ball NAND Flash with LPDDR2 MCP CA and CS# Setup, Hold, and Derating

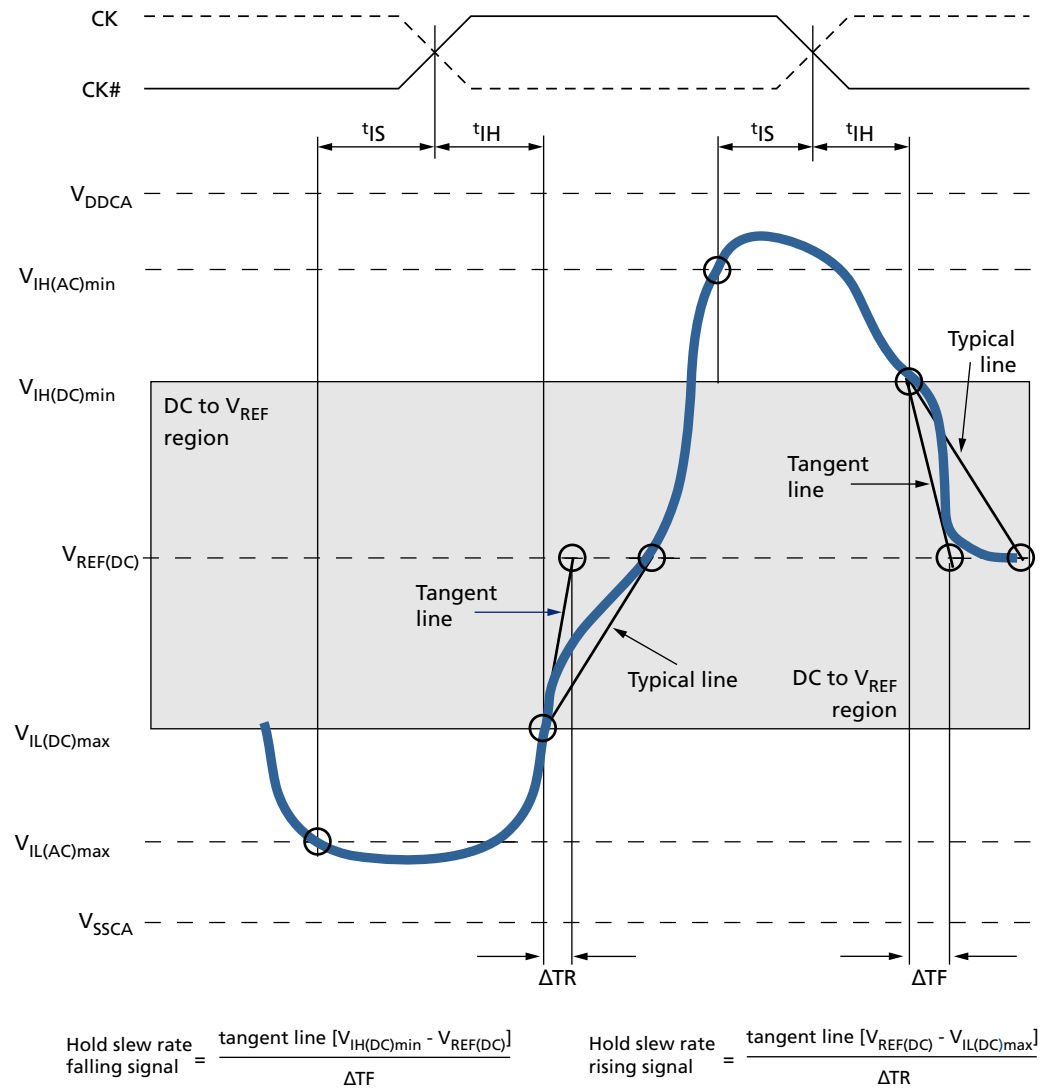
Figure 149: Tangent Line – t_{IS} for CA and CS# Relative to Clock





121-Ball NAND Flash with LPDDR2 MCP CA and CS# Setup, Hold, and Derating

Figure 150: Tangent Line – t_{IH} for CA and CS# Relative to Clock





121-Ball NAND Flash with LPDDR2 MCP Data Setup, Hold, and Slew Rate Derating

Data Setup, Hold, and Slew Rate Derating

For all input signals (DQ, DM) calculate the total required setup time (t_{DS}) and hold time (t_{DH}) by adding the data sheet $t_{DS}(\text{base})$ and $t_{DH}(\text{base})$ values (see Table 123 (page 226)) to the Δt_{DS} and Δt_{DH} derating values, respectively (see Table 125 and Table 126 (page 227)). Example: $t_{DS} = t_{DS}(\text{base}) + \Delta t_{DS}$.

The typical t_{DS} slew rate for a rising signal is defined as the slew rate between the last crossing of $V_{REF(DC)}$ and the first crossing of $V_{IH(AC)\min}$. The typical t_{DS} slew rate for a falling signal is defined as the slew rate between the last crossing of $V_{REF(DC)}$ and the first crossing of $V_{IL(AC)\max}$ (see Figure 151 (page 228)).

If the actual signal is consistently earlier than the typical slew rate line in Figure 147 (page 222) the area shaded gray between the $V_{REF(DC)}$ region and the AC region, use the typical slew rate for the derating value. If the actual signal is later than the typical slew rate line anywhere between the shaded $V_{REF(DC)}$ region and the AC region, the slew rate of a tangent line to the actual signal from the AC level to the DC level is used for the derating value (see Figure 149 (page 224)).

The typical t_{DH} slew rate for a rising signal is defined as the slew rate between the last crossing of $V_{IL(DC)\max}$ and the first crossing of $V_{REF(DC)}$. The typical t_{DH} slew rate for a falling signal is defined as the slew rate between the last crossing of $V_{IH(DC)\min}$ and the first crossing of $V_{REF(DC)}$ (see Figure 152 (page 229)).

If the actual signal is consistently later than the typical slew rate line between the shaded DC-level-to- $V_{REF(DC)}$ region, use the typical slew rate for the derating value. If the actual signal is earlier than the typical slew rate line anywhere between shaded DC-to- $V_{REF(DC)}$ region, the slew rate of a tangent line to the actual signal from the DC level to the $V_{REF(DC)}$ level is used for the derating value (see Figure 154 (page 231)).

For a valid transition, the input signal must remain above or below $V_{IH}/V_{IL(AC)}$ for the specified time, t_{VAC} (see Table 127 (page 228)).

The total setup time for slow slew rates could be negative (that is, a valid input signal may not have reached $V_{IH}/V_{IL(AC)}$ at the time of the rising clock transition). A valid input signal is still required to complete the transition and reach $V_{IH}/V_{IL(AC)}$.

For slew rates between the values listed in Table 123 and Table 124, the derating values can be obtained using linear interpolation. Slew rate values are not typically subject to production testing. They are verified by design and characterization.

Table 123: Data Setup and Hold Base Values (>400 MHz, 1 V/ns Slew Rate)

Parameter	Data Rate						Reference
	1066	933	800	667	533	466	
$t_{DS}(\text{base})$	-10	15	50	130	210	230	$V_{IH}/V_{IL(AC)} = V_{REF(DC)} \pm 220\text{mV}$
$t_{DH}(\text{base})$	80	105	140	220	300	320	$V_{IH}/V_{IL(DC)} = V_{REF(DC)} \pm 130\text{mV}$

Note: 1. AC/DC referenced for 1 V/ns DQ, DM slew rate, and 2 V/ns differential DQS/DQS# slew rate.



121-Ball NAND Flash with LPDDR2 MCP Data Setup, Hold, and Slew Rate Derating

Table 124: Data Setup and Hold Base Values (<400 MHz, 1 V/ns Slew Rate)

Parameter	Data Rate				Reference
	400	333	255	200	
t_{DS} (base)	180	300	450	700	$V_{IH}/V_{IL(AC)} = V_{REF(DC)} \pm 300mV$
t_{DH} (base)	280	400	550	800	$V_{IH}/V_{IL(DC)} = V_{REF(DC)} \pm 200mV$

Note: 1. AC/DC referenced for 1 V/ns DQ, DM slew rate, and 2 V/ns differential DQS/DQS# slew rate.

Table 125: Derating Values for AC/DC-Based t_{DS}/t_{DH} (AC220)

Δt_{DS} , Δt_{DH} derating in ps

		DQS, DQS# Differential Slew Rate															
		4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns	
		Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}
DQ, DM slew rate V/ns	2.0	110	65	110	65	110	65										
	1.5	74	43	73	43	73	43	89	59								
	1.0	0	0	0	0	0	0	16	16	32	32						
	0.9			-3	-5	-3	-5	13	11	29	27	45	43				
	0.8					-8	-13	8	3	24	19	40	35	56	55		
	0.7							2	-6	18	10	34	26	50	46	66	78
	0.6									10	-3	26	13	42	33	58	65
	0.5											4	-4	20	16	36	48
	0.4													-7	2	17	34

Note: 1. Shaded cells are not supported.

Table 126: Derating Values for AC/DC-Based t_{DS}/t_{DH} (AC300)

Δt_{DS} , Δt_{DH} derating in ps

		DQS, DQS# Differential Slew Rate															
		4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns	
		Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}	Δt_{DS}	Δt_{DH}
DQ, DM slew rate V/ns	2.0	150	100	150	100	150	100										
	1.5	100	67	100	67	100	67	116	83								
	1.0	0	0	0	0	0	0	16	16	32	32						
	0.9			-4	-8	-4	-8	12	8	28	24	44	40				
	0.8					-12	-20	4	-4	20	12	36	28	52	48		
	0.7							-3	-18	13	-2	29	14	45	34	61	66
	0.6									2	-21	18	-5	34	15	50	47
	0.5											-12	-32	4	-12	20	20
	0.4											4	-35	-40	-11	-8	

Note: 1. Shaded cells are not supported.



121-Ball NAND Flash with LPDDR2 MCP Data Setup, Hold, and Slew Rate Derating

Table 127: Required Time for Valid Transition – $t_{VAC} > V_{IH(AC)}$ or $< V_{IL(AC)}$

Slew Rate (V/ns)	t_{VAC} at 300mV (ps)		t_{VAC} at 220mV (ps)	
	Min	Max	Min	Max
>2.0	75	–	175	–
2.0	57	–	170	–
1.5	50	–	167	–
1.0	38	–	163	–
0.9	34	–	162	–
0.8	29	–	161	–
0.7	22	–	159	–
0.6	13	–	155	–
0.5	0	–	150	–
<0.5	0	–	150	–

Figure 151: Typical Slew Rate and $t_{VAC} - t_{DS}$ for DQ Relative to Strobe



121-Ball NAND Flash with LPDDR2 MCP Data Setup, Hold, and Slew Rate Derating

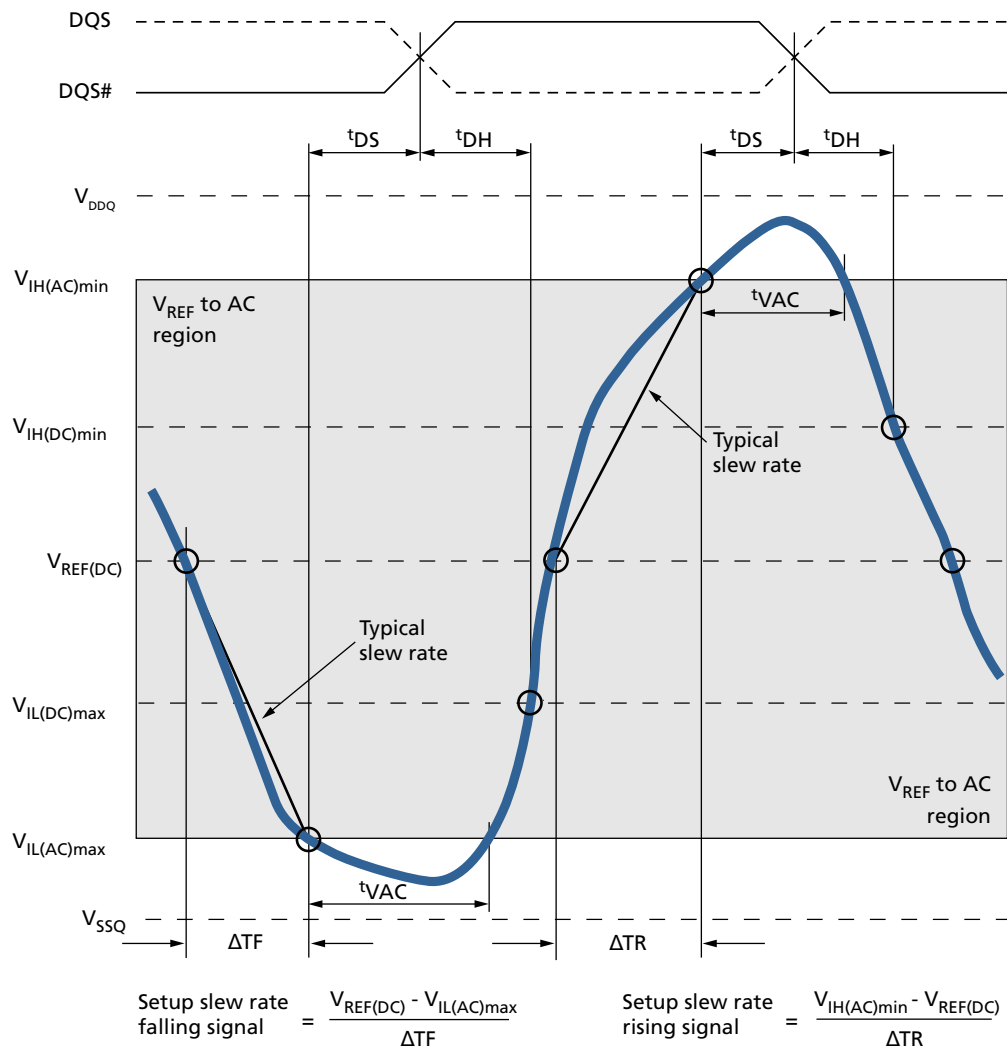


Figure 152: Typical Slew Rate – t_{DH} for DQ Relative to Strobe



121-Ball NAND Flash with LPDDR2 MCP Data Setup, Hold, and Slew Rate Derating

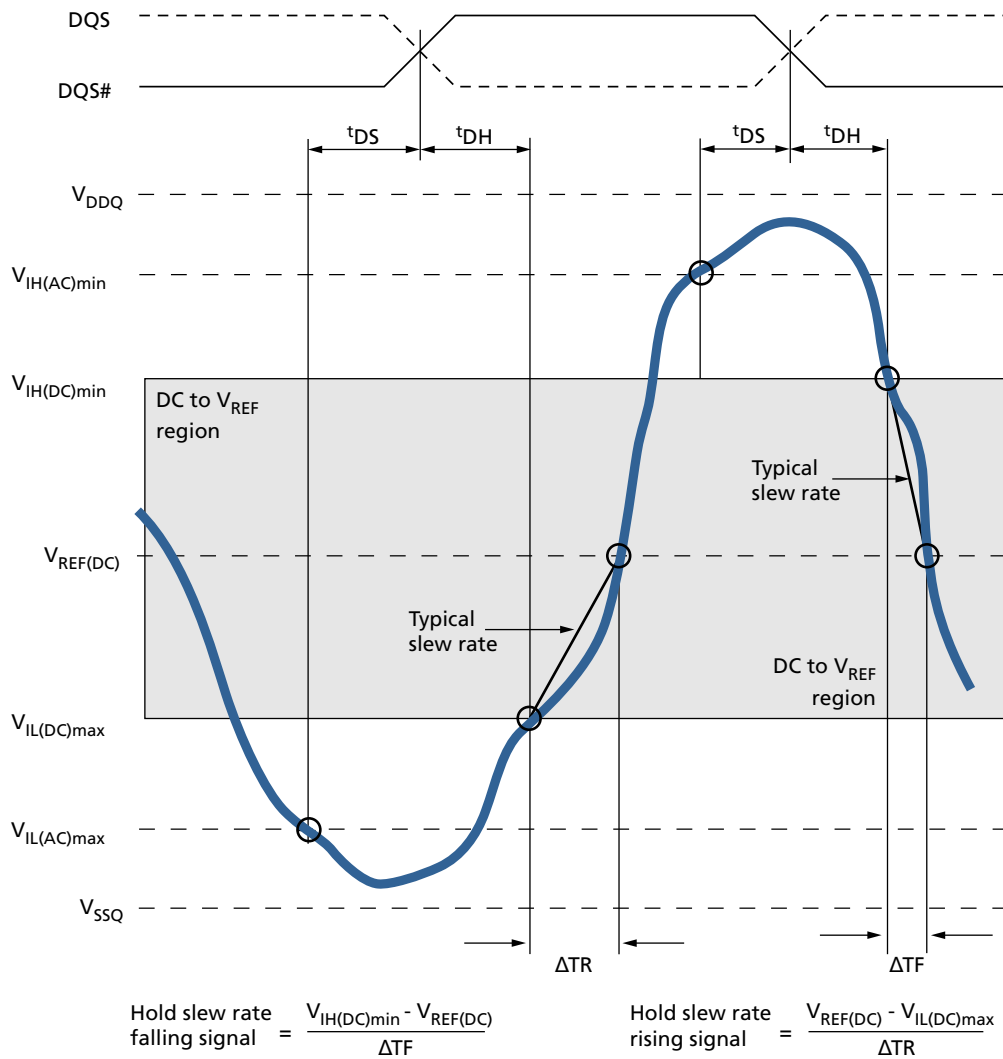


Figure 153: Tangent Line – t_{DS} for DQ with Respect to Strobe



121-Ball NAND Flash with LPDDR2 MCP Data Setup, Hold, and Slew Rate Derating

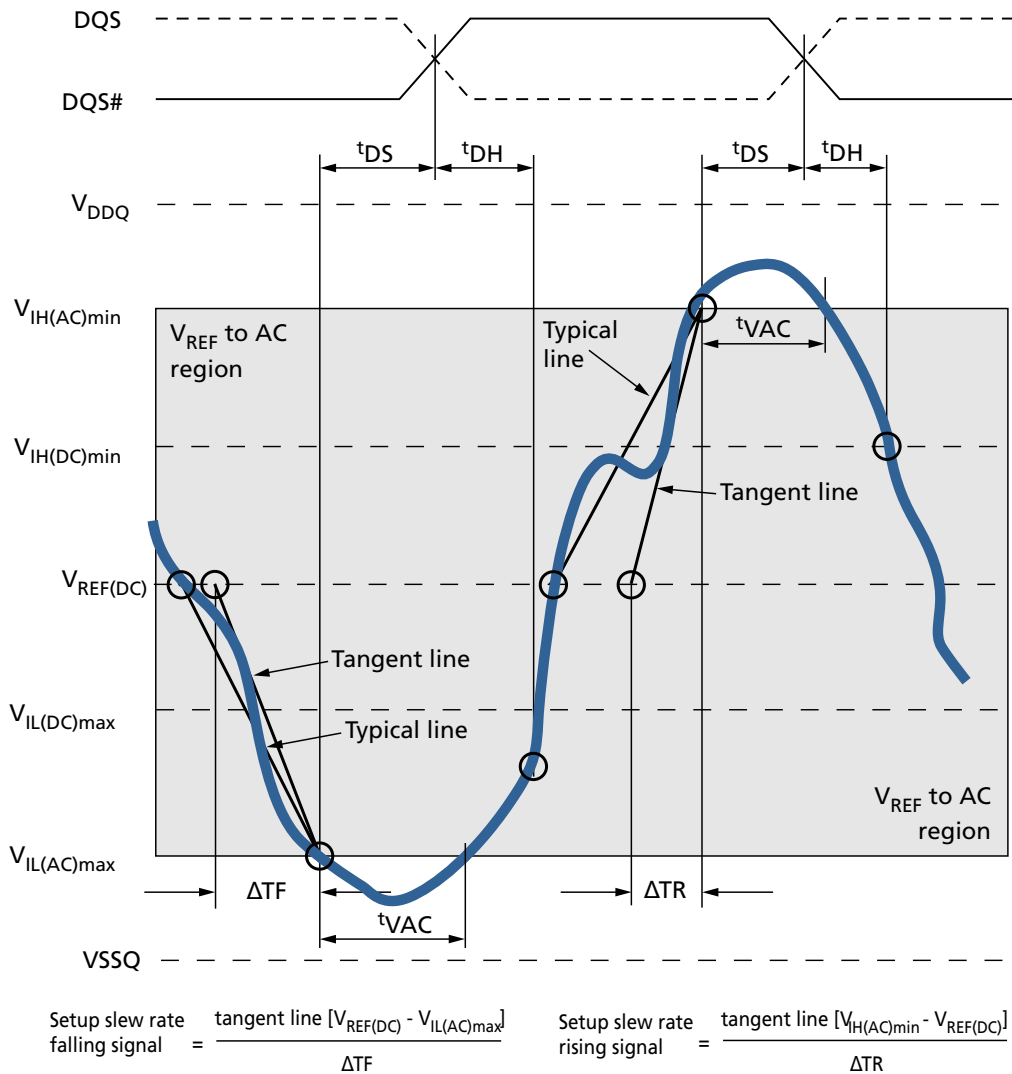
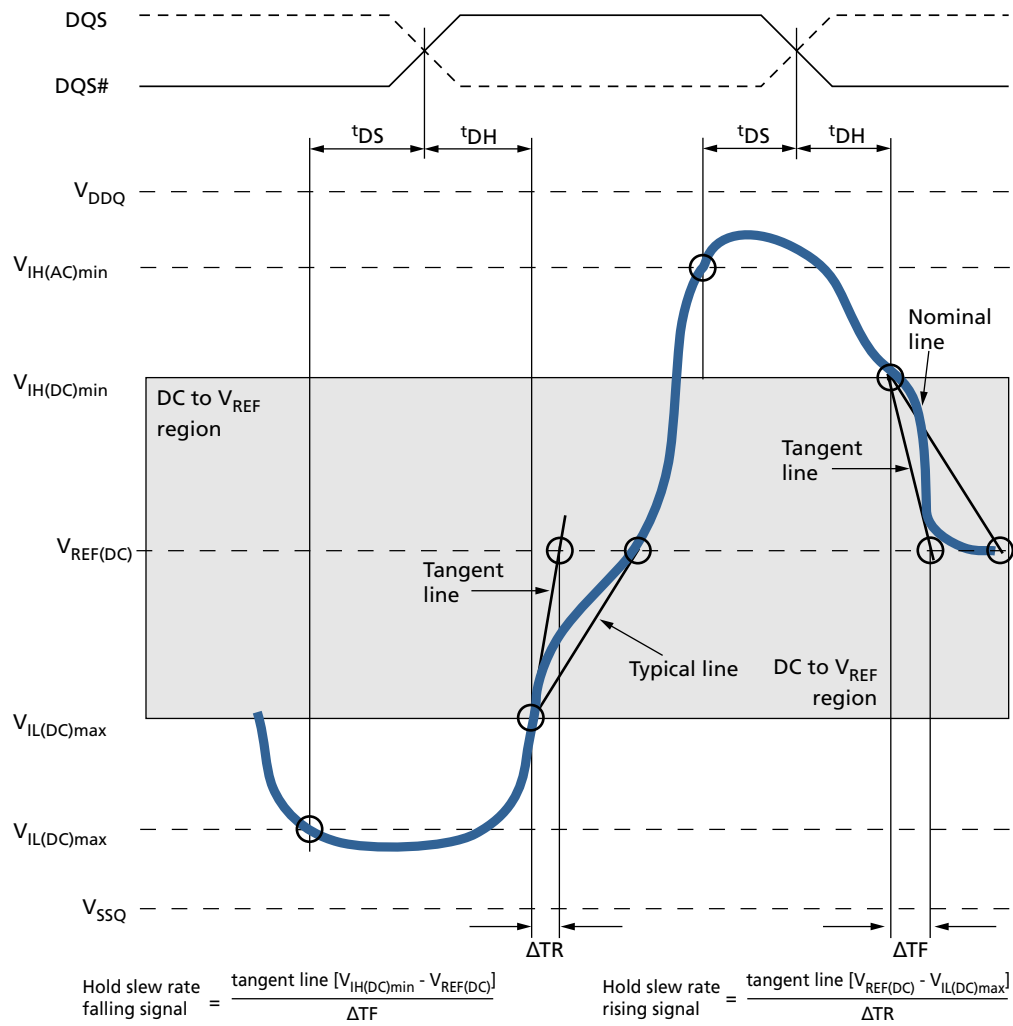


Figure 154: Tangent Line – t_{DH} for DQ with Respect to Strobe



121-Ball NAND Flash with LPDDR2 MCP Data Setup, Hold, and Slew Rate Derating





121-Ball NAND Flash with LPDDR2 MCP Revision History

Revision History

Rev. A – 04/13

- Initial release

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